

CCSL

## COMPATIBLE CURRENT SINKING LOGIC NUMERICAL INDEX

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## CROSS REFERENCE — CCSL AND SPECIAL CIRCUITS

Function	LPDT $\mu$ L Typ Tpd 65 MHz	DT $\mu$ L Typ Tpd 25 MHz	TT $\mu$ L Typ Tpd 10 MHz	CCSL MSI	HLLDT $\mu$ L	RT $\mu$ L Typ Tpd 15 MHz	LPRT $\mu$ L Typ Tpd 40 MHz	M $\mu$ L	CT $\mu$ L Typ Tpd 3.0 MHz	C $\mu$ L	Special
<b>Gate</b>											
Hex Inverter NAND Gate	F, D	F, D, C	FP, F, D		D						
Quad 2-input NAND Gate	F, D	F, D, C	FP, F, D								
Triple 3-input NAND Gate	F, D	F, D, C	FP, F, D								
Dual 4-input NAND Gate	F, D	F, D, C	FP, F, D								
8-input NAND Gate			FP, F, D								
Dual 2-wide Expandable AND/NOR Gate			F, FP, D								
4-wide Expandable AND/NOR Gate			F, FP, D								
Dual 4-input Power Gate	F, C, D	F, C, D	F, FP, D								
3-input NOR Gate						C, F					
4-input NOR Gate						C, F	C				
Dual 2-input NOR Gate						C, F, E	C		D		
Dual 3-input NOR Gate						C, F					
Quad Inverter NOR Gate						C, F					
2-2-3 Input AND Gate									D		
Dual 4-input AND Gate									D		
Dual Output, 8 Input AND Gate									D		
3-3-1 Input AND Gate									D		
Quad 1 AND Gate									D		
3 Output Quad 2 Input AND/OR Gate									D		
2 Output Quad 2 Input AND/OR Gate									D		
Buffer						C, FP, E	C		D		
Dual 2 Input									D		
Dual Buffer							C				
Counter Adapter						F, C					
<b>Decoders</b>											
1 of 10 Decoder				F, D		Typ Tpd 10 MHz			Typ Tpd 25 MHz	Typ Tpd 2 MHz	
1 of 16 Decoder				F, D							
7 Segment Decoder				F, D							
<b>Multiplexers</b>											
Dual 4-input Multiplexer				F, D							
8-input Multiplexer				F, D							
Dual 8-input Multiplexer				F, D							
<b>Counters</b>											
BCD Up/Down Counter				F, D							
Decade Counter				F, D							
Hexidecimal Counter				F, D							
Hexidecimal Up/Down Counter				F, D							
<b>Registers</b>											
4 Bit Shift Register				F		D					
Dual 8 Bit Shift Register				D							
<b>Adders &amp; Comparators</b>											
Dual Full Adder				F, D							
Dual Four-bit Comparator				F, D							
Half Adder						F, C	C				
Adder							C				

Legend: F = Flat Pak FP = Fairpak® D = Dip C = TO - 5 E = TO - 5 Epoxy

## CROSS REFERENCE — CCSL AND SPECIAL CIRCUITS

Function	LPDT $\mu$ L Typ Tpd 65 MHz	DT $\mu$ L Typ Tpd 25 MHz	TT $\mu$ L Typ Tpd 10 MHz	CCSL MSI	HLLDT $\mu$ L	RT $\mu$ L Typ Tpd 15 MHz	LPRT $\mu$ L Typ Tpd 40 MHz	M $\mu$ L	CT $\mu$ L Typ Tpd 3.0 MHz	C $\mu$ L	Special
<b>Memory &amp; Latches</b> Dual 4 Input Latch 16-bit Memory Cell 256 Bit ROM Dual 4-bit Latch Buffer Memory Decimal DEC/DR				F, D F, D F, D					D	D D	
<b>Micromatrices</b> 32 Gate Customizable Array 48 Gate Customizable Array 96 Gate Customizable Array		F, D	F, D F, D								
<b>Kit Parts</b> 4501 4522		D	D								
<b>Gate Expanders</b> Expander	Typ Tpd 130 MHz F, C, D	Typ Tpd 20 MHz F, C, D	Typ Tpd 25 MHz FP, F, D			Typ Tpd 30 MHz	Typ Tpd 20 MHz C		Typ Tpd 15 MHz		
<b>Binary Elements</b> RS Flip Flop Buffered JK Flip Flop Dual Flip Flop AC Coupled Flip Flop Type D Flip Flop Dual Rank Flip Flop One Half Shift Register With Inverter One Half Shift Register Without Inverter	F, D	F, C, D F, D F, C, D	FP, F, D FP, F, D			F, C, E  F, C F, C	C C  C		D  D		
<b>Interface Functions</b> Line Receiver Line Driver CCSL to MOS MOS to CCSL		Typ Tpd 100 MHz									Typ Tpd 2 MHz F, D F, D F, D F, D
<b>Multivibrators</b> AC Coupled One Shot Retriggerable One Shot		F, C, D	F, D								

Legend: F = Flat Pak FP = Fairpak® D = Dip C = TO - 5 E = TO - 5 Epoxy

# DT $\mu$ L COMPOSITE DATA SHEET

## DIODE-TRANSISTOR MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS

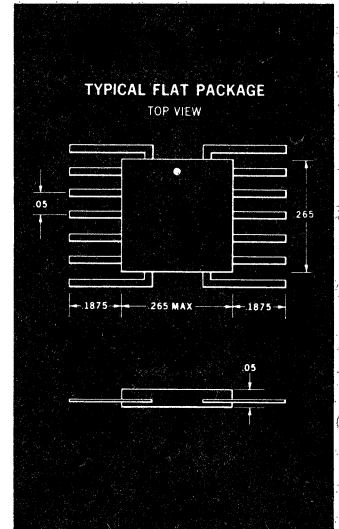
Diode Transistor Micrologic (DT $\mu$ L) is the first diode transistor logic circuit expressly designed for integrated circuit technology. As a consequence, DT $\mu$ L requires only one power supply, which may vary over a wide range without impairing circuit performance. High tolerance to electrical noise, along with ample drive capability is characteristic. Indeed, the designer may exchange one for the other to strike the balance most appropriate to the situation at hand. DT $\mu$ L is completely characterized and specified over the entire military temperature range of -55°C to +125°C.

### CONTENTS OF THIS SPECIFICATION

The optimum operating supply voltage for the full military temperature range is 5.0 volts. The data of this specification enumerated on pages 2 and 3 and the loading rules on page 8 are valid for supply voltages ranging from 4.5 to 5.5 volts. Power dissipation may be reduced by using  $V_{CC} = 4V$  without sacrificing noise immunity or speed if operating temperature is held to a minimum of -20°C, or if fanout is restricted. The Fairchild epitaxial integrated circuit process also permits an operating supply voltage of 6.0 volts over the full temperature range with a slight decrease in fanout or noise immunity at temperatures in excess of 100°C. (See page 8).

For guidance, when designing outside the limits guaranteed by the tests given on pages 2 and 3, graphs of minimum and maximum limits of circuit operation are shown on Pages 6 and 7. These graphs will permit the designer to optimize fanout, noise immunity, supply voltage and temperature for the specific application. Examples using these graphs are given on Page 7.

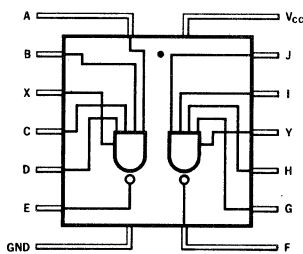
Very extensive noise threshold and propagation delay data are given in the individual DT $\mu$ L 930 and 931 specification sheets (available on request). Additional propagation delay data is given on Pages 4 and 5 of this specification. Specific characteristics of the Dual Buffer and the Dual Power Gate may be found in the individual DT $\mu$ L 932 and DT $\mu$ L 944 specification, while data concerning the effects of input extension appear in the individual DT $\mu$ L 933 specification.



### ABSOLUTE MAXIMUM RATINGS (above which useful life may be impaired)

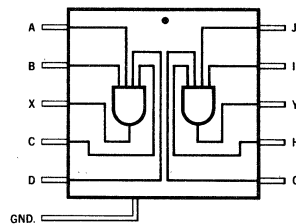
Supply Voltage ( $V_{CC}$ ), -55°C to +125°C, continuous	+8 Volts	Input Forward Current	-10 mA
Supply Voltage ( $V_{CC}$ ), pulsed, <1sec	+12 Volts	Input Reverse Current	1 mA
Output Current, into outputs DT $\mu$ L 932, 944	100 mA	Operating Temperature	-55°C to +125°C
Output Current, into outputs DT $\mu$ L 930, 931, 946, 962	30 mA	Storage Temperature	-65°C to +150°C

#### DT $\mu$ L 930 DUAL GATE DT $\mu$ L 932 DUAL BUFFER DT $\mu$ L 944 DUAL POWER GATE

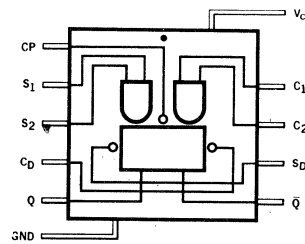


**POSITIVE (NAND) LOGIC**  
 $E = A \cdot B \cdot C \cdot D \cdot (X)$   
 $F = G \cdot H \cdot I \cdot J \cdot (Y)$

#### DT $\mu$ L 933 DUAL EXTENDER



#### DT $\mu$ L 931 CLOCKED FLIP-FLOP



J-K MODE TRUTH TABLE

$t_n$	$t_{n+1}$	Q
S <sub>2</sub> C <sub>2</sub>	Q	
0 0	Q <sub>n</sub>	
0 1	0	
1 0	1	
1 1	Q <sub>n</sub>	

R-S MODE TRUTH TABLE

$t_n$	$t_{n+1}$	Q
S <sub>1</sub> S <sub>2</sub> C <sub>1</sub> C <sub>2</sub>	Q	
0 X 0 X	Q <sub>n</sub>	
0 X X 0	Q <sub>n</sub>	
X 0 0 X	Q <sub>n</sub>	
X 0 X 0	Q <sub>n</sub>	
0 X 1 1	0	
X 0 1 1	0	
1 1 0 X	1	
1 1 X 0	1	
1 1 1 1	Undetermined	

X - Either a one or a zero can be present  
 "1" more positive than "0"  
 For J-K Mode Operation:  
 Connect S<sub>1</sub> to Q-bar and C<sub>1</sub> to Q

# DIODE-TRANSISTOR MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS

## TEST SEQUENCES — DT $\mu$ L ELEMENTS 930, 931, 932, 933

Abbreviated Test Sequences for the DT $\mu$ L family of elements are shown below. The ground pin is grounded on all tests. Page 3 of this composite gives a glossary of terms used, tables of test conditions and limits, and LTPD percentages by group.

### DT $\mu$ L 930 & 932 ELEMENTS

NOTE: Both elements are dual "NAND" gates; therefore, the test sequences for each are identical. Tests on each side of the dual are identical; therefore, matching test and pin numbers are shown in parentheses.

Test No.	LTPD** Group	Notes	FORCING CONDITIONS								LIMITS			
			Pin A (G)	Pin B (H)	Pin C (I)	Pin D (J)	Pin X (Y)	Pin E (F)	V <sub>CC</sub>	Sense	Min.	Max.		
1, (2)	A		V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IH</sub>				I <sub>OL</sub>	V <sub>CCL</sub>	V <sub>E</sub> (V <sub>F</sub> )		V <sub>OL</sub>
3, 4, 5, 6 (7, 8, 9, 10)	B	1, 3	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>				I <sub>OH</sub>	V <sub>CCL</sub>	V <sub>E</sub> (V <sub>F</sub> )	V <sub>OH</sub>	
11, (12)	C		V <sub>R</sub>	GND	GND	GND					V <sub>CCH</sub>	I <sub>A</sub> I <sub>G</sub>		I <sub>R</sub>
13, (14)	C		GND	V <sub>R</sub>	GND	GND					V <sub>CCH</sub>	I <sub>B</sub> I <sub>H</sub>		I <sub>R</sub>
15, (16)	C	3	GND	GND	V <sub>R</sub>	GND					V <sub>CCH</sub>	I <sub>C</sub> I <sub>J</sub>		I <sub>R</sub>
17, (18)	C	3	GND	GND	GND	V <sub>R</sub>					V <sub>CCH</sub>	I <sub>D</sub> I <sub>J</sub>		I <sub>R</sub>
19, (20)	D		V <sub>F</sub>	V <sub>R</sub>	V <sub>R</sub>	V <sub>R</sub>					V <sub>CCH</sub>	I <sub>A</sub> (I <sub>G</sub> )		I <sub>F</sub>
21, (22)	D		V <sub>R</sub>	V <sub>F</sub>	V <sub>R</sub>	V <sub>R</sub>					V <sub>CCH</sub>	I <sub>B</sub> (I <sub>H</sub> )		I <sub>F</sub>
23, (24)	D	3	V <sub>R</sub>	V <sub>R</sub>	V <sub>F</sub>	V <sub>R</sub>					V <sub>CCH</sub>	I <sub>C</sub> (I <sub>J</sub> )		I <sub>F</sub>
25, (26)	D	3	V <sub>R</sub>	V <sub>R</sub>	V <sub>R</sub>	V <sub>F</sub>					V <sub>CCH</sub>	I <sub>D</sub> (I <sub>J</sub> )		I <sub>F</sub>
27, (28)	C		GND							V <sub>CEX</sub>	V <sub>CEX</sub>	I <sub>E</sub> (I <sub>F</sub> )		I <sub>CEX</sub>
29, (30)	B	2	GND							GND	V <sub>CCH</sub>	I <sub>E</sub> (I <sub>F</sub> )	I <sub>SC</sub>	I <sub>SC</sub>
31	E										V <sub>PD</sub>	I <sub>VCC</sub>		I <sub>PDH</sub>
32	E		GND								V(max)	I <sub>VCC</sub>		I(max)
33, (34)	E	3						V <sub>X</sub>		I <sub>OH</sub>	V <sub>CCL</sub>	V <sub>E</sub> (V <sub>F</sub> )	V <sub>OH</sub>	
35, 36	F	t <sub>pd+</sub> , t <sub>pd-</sub>	— See table of test circuit conditions and limits, Page 3.											

NOTES: 1. V<sub>IL</sub> applied individually to 1 input each test. Other inputs open. 2. I<sub>SC</sub>(max) only for 930; I<sub>SC</sub>(min) only for 932. \*\* See LTPD group, Page 5.  
3. Delete these tests for 10-pin TO-5 package: 6, 9, 10, 16, 17, 18, 24, 25, 26, 33.

### DT $\mu$ L 931 ELEMENT

Test No.	LTPD** Group	Notes	FORCING CONDITIONS										LIMITS			
			CP	C <sub>1</sub>	C <sub>2</sub>	S <sub>1</sub>	S <sub>2</sub>	C <sub>D</sub>	S <sub>D</sub>	Q	Q̄	V <sub>CC</sub>	Sense	Min.	Max.	
1	C		V <sub>R</sub>	GND	GND	GND	GND						V <sub>CCH</sub>	I <sub>CP</sub>		I <sub>RCP</sub>
2, 3, 4, 5	C	1	GND	V <sub>R</sub>	V <sub>R</sub>	V <sub>R</sub>	V <sub>R</sub>						V <sub>CCH</sub>	I <sub>C1</sub> , I <sub>C2</sub> , I <sub>S1</sub> , I <sub>S2</sub>		I <sub>R</sub>
6, 7, 8, 9	D	3		V <sub>F</sub>	V <sub>F</sub>	V <sub>F</sub>	V <sub>F</sub>						V <sub>CCH</sub>	I <sub>C1</sub> , I <sub>C2</sub> , I <sub>S1</sub> , I <sub>S2</sub>	2/3	I <sub>F</sub>
10, 25	D	2	CP <sub>b</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>						V <sub>CCH</sub>	I <sub>CP</sub>		I <sub>F</sub>
11, 12	B	2	CP <sub>a</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub>			*I <sub>OH</sub>			V <sub>CCL</sub>	V <sub>Q</sub>	V <sub>OH</sub>	
13, 14	B	2	CP <sub>a</sub>	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IL</sub>				*I <sub>OH</sub>		V <sub>CCL</sub>	V <sub>Q</sub>	V <sub>OH</sub>	
15	A		CP <sub>c</sub>	GND						*	I <sub>OL</sub>		V <sub>CCL</sub>	V <sub>Q</sub>		V <sub>OL</sub>
16	A		CP <sub>c</sub>								I <sub>OL</sub>		V <sub>CCL</sub>	V <sub>Q</sub>		V <sub>OL</sub>
17	E		GND	GND	GND	GND	GND						V(max)	I <sub>VCC</sub>		I(max)
18	E												V <sub>PD</sub>	I <sub>VCC</sub>		I <sub>PDH</sub>
19	B		CP <sub>a</sub>			GND	GND	V <sub>IH</sub>	V <sub>ILS</sub>	I <sub>OH</sub>			V <sub>CCL</sub>	V <sub>Q</sub>	V <sub>OH</sub>	
20	B		CP <sub>a</sub>	GND	GND			V <sub>ILS</sub>	V <sub>IH</sub>		I <sub>OH</sub>		V <sub>CCL</sub>	V <sub>Q</sub>	V <sub>OH</sub>	
21	C		CP <sub>a</sub>			GND	GND	V <sub>R</sub>					V <sub>CCH</sub>	I <sub>CD</sub>		I <sub>R</sub>
22	C		CP <sub>a</sub>	GND	GND			V <sub>R</sub>					V <sub>CCH</sub>	I <sub>SD</sub>		I <sub>R</sub>
23	D					*		GND	V <sub>F</sub>		GND		V <sub>CCH</sub>	I <sub>CD</sub>		I <sub>FS</sub>
24	D							GND	V <sub>F</sub>	GND			V <sub>CCH</sub>	I <sub>SD</sub>		I <sub>FS</sub>
25, 26	F	t <sub>pd+</sub> , t <sub>pd-</sub>	— See table of test circuit conditions and limits, Page 3.													

NOTES: 1. V<sub>R</sub> applied individually to 1 input each test. Other inputs open. 2. V<sub>IL</sub> applied individually to 1 input each test. Other inputs open. 3. V<sub>F</sub> applied individually to 1 input each test. Other inputs open. \* Momentary Ground. \*\* See LTPD group, page 5.

### DT $\mu$ L 933 ELEMENT

Test No.	LTPD** Group	Notes	FORCING CONDITIONS						LIMITS			
			Pin A (G)	Pin B (H)	Pin C (I)	Pin D (J)	Pin X (Y)	Sense	Min.	Max.		
1, 2, 3, 4 (5, 6, 7, 8)	B	1	GND	GND	GND	GND		I <sub>FD</sub>	V <sub>X</sub> (V <sub>Y</sub> )		V <sub>FD</sub>	V <sub>FD</sub>
11, (12)	A		V <sub>R</sub>	GND	GND	GND			I <sub>A</sub> (I <sub>G</sub> )			I <sub>R</sub>
13, (14)	A		GND	V <sub>R</sub>	GND	GND			I <sub>B</sub> (I <sub>H</sub> )			I <sub>R</sub>
15, (16)	A		GND	GND	V <sub>R</sub>	GND			I <sub>C</sub> (I <sub>J</sub> )			I <sub>R</sub>
17, (18)	A		GND	GND	GND	V <sub>R</sub>			I <sub>D</sub> (I <sub>J</sub> )			I <sub>R</sub>
19, (20)	A							V <sub>R</sub>	I <sub>X</sub> (I <sub>Y</sub> )			5 I <sub>R</sub>

NOTE 1. GND applied individually to 1 input each test. Other inputs open. \*\* See LTPD group, page 5.

# DIODE-TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS

## GLOSSARY OF TERMS USED WITH DTμL

### In General, Subscripts are used as follows:

- O = output
- I = input
- R = reverse, applying to high inputs.
- F = forward, applying to low inputs.
- L = low, applying to a low signal level or when used with  $V_{CC}$  to low  $V_{CC}$  value.
- H = high, applying to a high-signal level or when used with  $V_{CC}$  to high  $V_{CC}$  value.

### Non-operational Terms:

- $V(\max)$  = Maximum rated  $V_{CC}$  pin voltage.
- $I(\max)$  = Maximum rated current into  $V_{CC}$  pin, with  $V(\max)$  applied.
- $V_{PD}$  =  $V_{CC}$  pin voltage applied during power dissipation test.
- $I_{PD}$  = Current into  $V_{CC}$  pin with  $V_{PD}$  applied.  $I_{PDL}$  means gate or buffer inputs are low or 931 clock pin input is low.  $I_{PDH}$  means the inputs are high.
- $V_R$  = Input reverse (high) voltage for input diode leakage test.
- $I_R$  = Reverse input diode current with  $V_R$  applied to input.
- $I_{RCP}$  = Reverse 931 clock pin input leakage current with  $V_R$  applied to input.
- $V_{CEX}$  = Output transistor collector to emitter voltage. With output pull-up resistor connected,  $V_{CEX} = V_{CC}$  to avoid drop across output pull-up resistor.

### Operational Terms:

- $V_{IL}$  = Input low (threshold) voltage.
- $V_{OL}$  = Output low voltage, with rated fanout current  $I_{OL}$  into output.

- $I_{CEX}$  = Output transistor collector to emitter leakage current with  $V_{CEX}$  applied to output.
- $V_{FD}$  = Forward diode drop in 933 Element.
- $I_{FD}$  = Forward diode current in 933 Element.
- $V_{IH}$  = Input high (threshold) voltage.
- $V_{OH}$  = Output high voltage, with high output current ( $I_{OH}$ ) flowing out of output.
- $V_F$  = Forward (low) input voltage, for forward input current ( $I_F$ ) test.  $V_F$  is usually ground.
- $I_F$  = Forward input diode current, for unit input load. Also shown will be  $2/3 I_F$ ,  $I_{FCP}$ , and  $I_{FS}$ .
- $I_{OL}$  = Output low current.
- $I_{OH}$  = Output high current, flowing out of output in  $V_{OH}$  test.
- $I_{SC}$  = Short circuit output current to ground, with one or more inputs low.  $I_{SC}$  minimum confirms output ability to pull up capacitive loads;  $I_{SC}$  maximum confirms subtraction of fanout rules when "OR"ing outputs.
- $V_{CCL}$  = Low  $V_{CC}$  pin voltage. Used for  $V_{OL}$  ( $I_{OL}$ ) and  $V_{OH}$  ( $I_{OH}$ ) tests.
- $V_{CCH}$  = High  $V_{CC}$  pin voltage. Used for  $V_{IF} - I_F$  input forward diode current tests.
- $CP_x$  = Clock Pin, pulsed. The subscript if any refers to pulse waveshape. Used in testing binary elements. (See page 5).
- $V_{CP TH}$  = Input Clock Pin threshold voltage (low). With Clock Pin at or below  $V_{CP TH}$ , the 931 "master" Flip-Flop holds the proper "slave" (output) Flip-Flop output high.
- $V_X$  = Input low (threshold) voltage extendable inputs.

**TABLE OF CONDITIONS & LIMITS, TPD TESTS**  
(See Test Circuits, Page 5)

( $V_{CC} = 5V$ ,  $T = 25^\circ C$ )

		R	C <sub>2</sub>	Min.	Max.
$t_{pd+}$	930	3.9 K	30 pf	25 nsec	80 nsec
$t_{pd-}$	930	400 Ω	50 pf	10 nsec	30 nsec
$t_{pd+}$	932	510 Ω	500 pf	25 nsec	80 nsec
$t_{pd-}$	932	150 Ω	500 pf	15 nsec	40 nsec
$t_{pd+}$	930	400 Ω	50 pf	15 nsec	40 nsec <sup>1</sup>
$t_{pd-}$	930	3.9 K	20 pf	5 nsec	20 nsec <sup>1</sup>
$t_{pd+}$	932	150 Ω	500 pf	20 nsec	65 nsec <sup>1</sup>
$t_{pd-}$	932	510 Ω	200 pf	8 nsec	30 nsec <sup>1</sup>

( $V_{CC} = 5V$ ,  $T = 25^\circ C$ )

		R	C <sub>2</sub>	Min.	Max.
$t_{pd+}$	931	3.9 K	30 pf	35 nsec	75 nsec
$t_{pd-}$	931	400 Ω	30 pf	35 nsec	75 nsec
$t_{pd+}$	931	400 Ω	30 pf	20 nsec	50 nsec <sup>1</sup>
$t_{pd-}$	931	3.9 K	30 pf	30 nsec	70 nsec <sup>1</sup>

NOTE 1: Correlating limit provided as design information only.

**TABLE OF TEST LIMITS**

	Units	-55°C		+25°C		+125°C	
		Min.	Max.	Min.	Max.	Min.	Max.
$V_{OL}$	Volts		.40		.40		.45
$V_{OH}$	Volts	2.5		2.6		2.5	
$I_R$	μA		2.0		2.0		5.0
$I_{RCP}$	μA		20.0		20.0		30.0
$1 I_F$	mA		-1.60		-1.60		-1.50
$2/3 I_F$	mA		-1.07		-1.07		-1.00
$I_{FCP}$	mA		-3.4		-3.40		-3.00
$I_{CEX}$	μA				50.0		
$I_{SC}$ 930	mA		-1.34	-.60	-1.34		-1.30
$I_{SC}(\min)$ 932	mA	-16.		-18.		-16.	
$V_{FD}$	Volts	.85	.98	.70	.82	.50	.65
$I(\max)$ 930	mA				5.50		
$I(\max)$ 931	mA				14.5		
$I(\max)$ 932	mA				6.0		
$I_{PDH}$ 930	mA				6.50		
$I_{PDH}$ 931	mA				11.0		
$I_{PDH}$ 932	mA				26.6		
$5 I_R$	μA		10.0		10.0		25.
$I_{FS}$	mA		-1.20		-1.20		-1.10

**TABLE OF FORCING CONDITIONS**

	Units	-55°C	+25°C	+125°C		Units	-55°C	+25°C	+125°C		Units	-55°C	+25°C	+125°C
$V(\max)$	Volts	--	8	--	$V_{CEX}$	Volts	4.5			$I_{OL}$ 932	mA	34	36	32
$V_{PD}$	Volts	--	5	--	$I_{OH}$	mA	-12	-12	-12	$I_{OH}$ 932	mA	-2.0	-2.5	-4.0
$V_{CCH}$	Volts	5.5	5.5	5.5	$I_{OL}$ 930	mA	11.4	12.0	10.8	$V_{IL}$	Volts	1.4	1.10	.80
$V_{CCL}$	Volts	4.5	4.5	4.5	$I_{FD}$	mA	2	2	2	$V_{IH}$	Volts	2.1	1.9	1.7
$V_R$	Volts	4.0	4.0	4.0	$V_{ILS}$	Volts	1.40	1.10	.80	$V_{CP TH}$	Volts	1.10	.95	.75
$V_F$	Volts	0	0	0	$I_{OL}$ 931	mA	10.0	10.6	9.5	$V_X$	Volts		1.80	

## ADDITIONAL DELAY TIME CHARACTERIZATION INTO CAPACITIVE LOADS

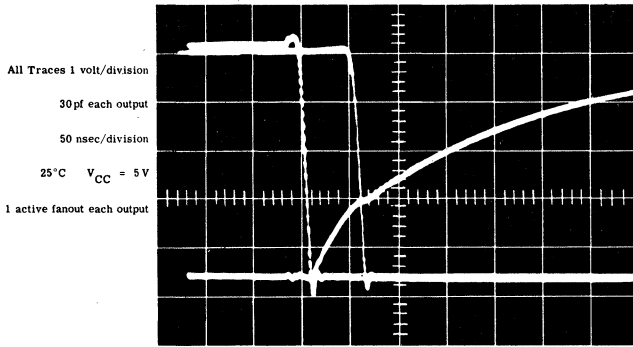
The individual specifications on DT $\mu$ L 930 and DT $\mu$ L 931 give extensive delay characterizations as functions of  $V_{CC}$ , temperature, fanout and ratio of active to inactive fanout. For each fanout, active or inactive, 5 pf wiring capacity was added. This page will show the effects of greater wiring capacities.

Most delay attributable to capacitive loads is associated with the positive going output. Two R-C time constants are seen in the positive going output, as shown in the pictures below. In the 1st time period, from the saturated low level to threshold, the R of the R-C time constant can be given by  $6K\Omega$  in parallel with  $\frac{3.75 K\Omega}{\text{active fanout}}$ . Above the threshold which occurs at about 1.4 to 1.5 volts at 25°C, the R of the 2nd R-C time constant is  $6K\Omega$  and the rate of the voltage rise above threshold is slow. The logic signal propagates through

at the threshold level; so voltage rise above threshold does not affect speed. By noting that both rise domains drive toward  $V_{CC}$ , the voltage rise waveform may be calculated. DT $\mu$ L 930, 932, 933, and 931 inputs (except CP) are  $\sim 2$  pf per input for active or inactive fanout; the remaining capacitance is from board, wiring, and connectors.

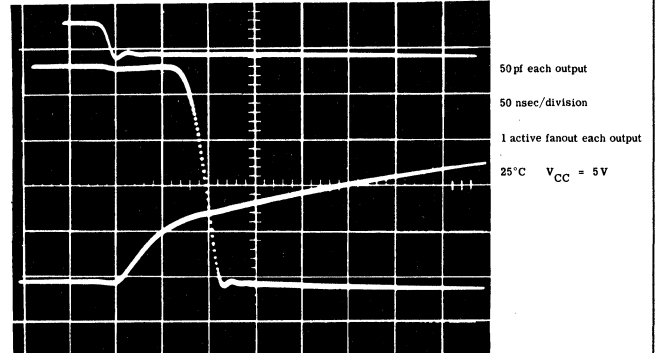
The  $t_{pd}$  average curves, with 1 active fanout, Fig. 1 below, and the typical maximum toggling frequency curve, Fig. 2, give the prediction of capacitive effects on switching speeds. For frequency division or ripple carry counting, use of  $3K\Omega$  external resistors tied from output to  $V_{CC}$  in the least significant bit will increase the maximum frequency. In Fig. 1 each output has 1 active fanout, which is worst case.

**DT $\mu$ L 930 - INVERTER PAIR DELAY**



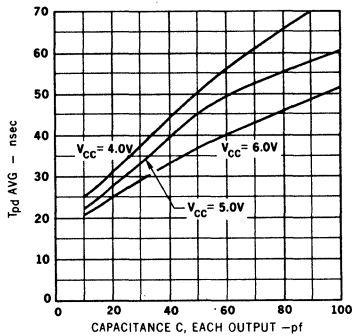
1st Negative Going Trace - Input to 1st Gate  
 Positive Going Trace - Output of 1st Gate = Input to 2nd Gate  
 2nd Negative Going Trace - Output of 2nd Gate

**DT $\mu$ L 931 - DIVIDING BY 2**

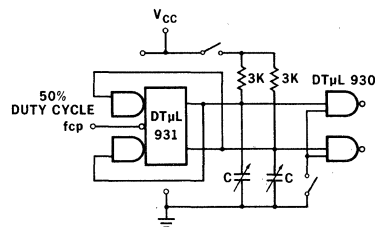
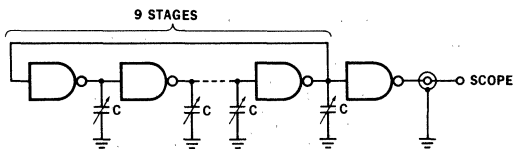
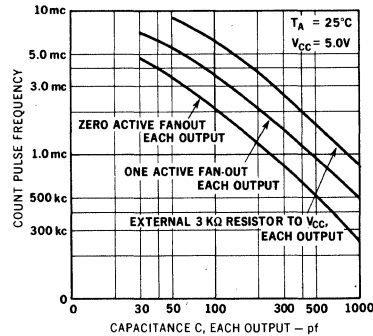


Upper Trace - Input to CP (5 volts/division)  
 Positive Going Trace - Output Going High (1 volt/division)  
 Negative Going Trace - Output Going Low (which starts going low as the positive going trace reaches threshold) (1 volt/division).

**FIG. 1**  
 $T_{pd}$  AVERAGE VS. CAPACITY  
 (DT $\mu$ L 930, 25°C)



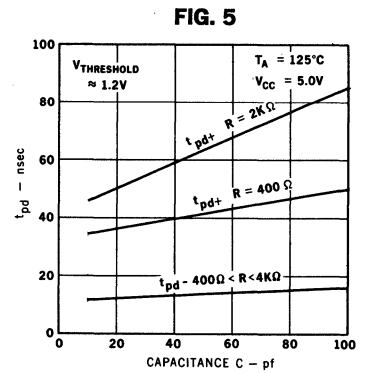
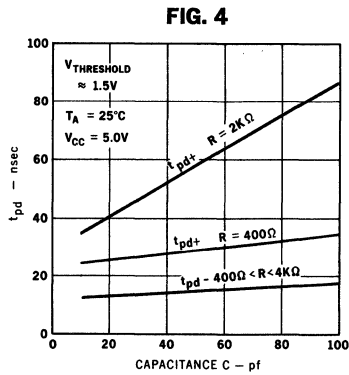
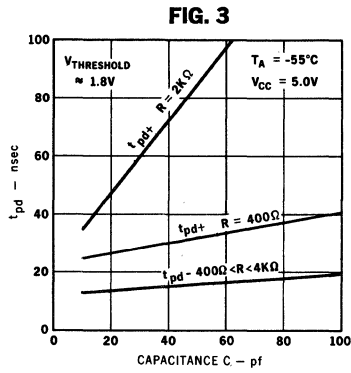
**FIG. 2**  
 TYPICAL MAXIMUM BINARY  
 COUNTING RATE VS. CAPACITY





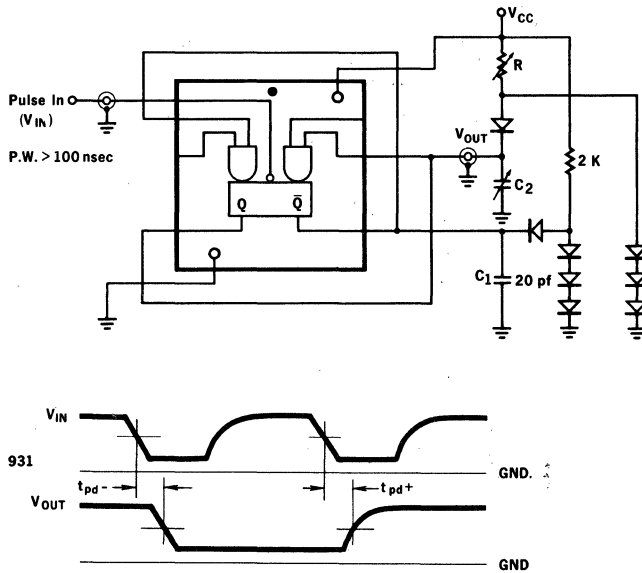
# DIODE-TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS

## DT $\mu$ L 930 TIME DELAYS VS. CAPACITIVE LOADS



$t_{pd}$  test circuit for 930 & 932 used (see below)

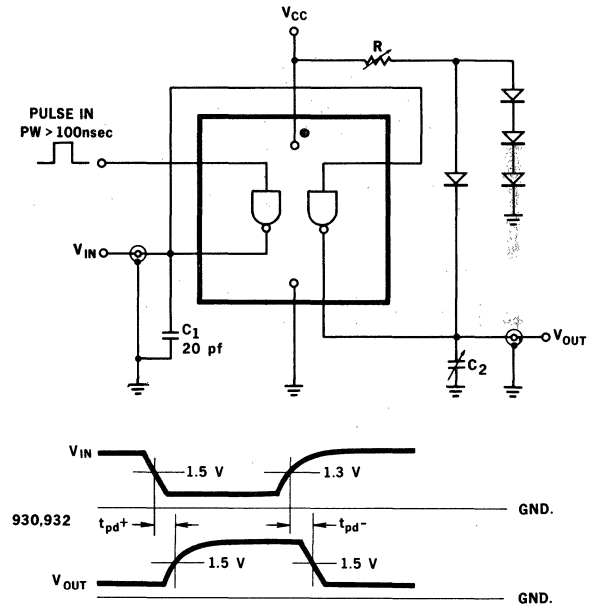
$t_{pd}$  TEST CIRCUIT DT $\mu$ L 931



$C_1$  and  $C_2$  includes probe and jig capacitance

$V_{Threshold} = 1.5V$  at  $25^\circ C$ ; at other temperatures  $V_{Threshold}$  will be stated.

$t_{pd}$  TEST CIRCUIT DT $\mu$ L 930, 932



$t_{pd}$  of 930, 932, and 946 elements will be read from input at 1.3 V.

All diodes FD600 or equivalent.

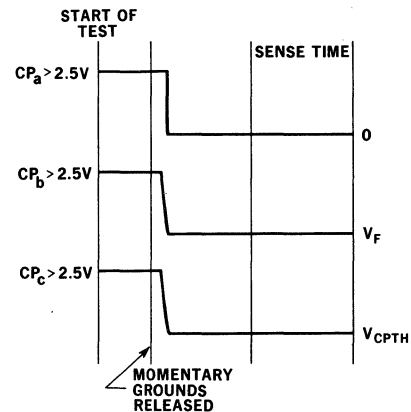
### TABLE OF LTPD's

(These apply to the test sequence on page 2)

Group	-55°C	+25°C	+125°C
A	15%	10%	15%
B	-	10%	15%
C	-	10%	15%
D	-	10%	15%
E	-	10%	15%
F	-	10%	-

### CLOCK PIN WAVEFORMS

(For 931 Test Sequence, Page 2)



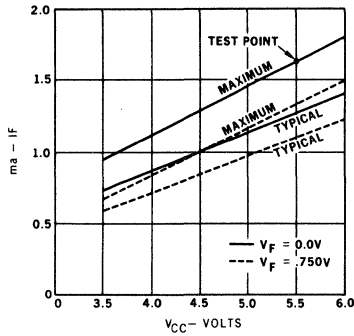
# DIODE-TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS

## MINIMUM-MAXIMUM DC CURVES $I_F$ VS. $V_F$ & $V_{CC}$

**FIG. 1**

$-1 I_F$  DT $\mu$ L 930, 932, 944, 946, 962  
MAXIMUM VS. TYPICAL

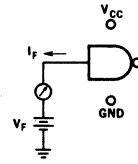
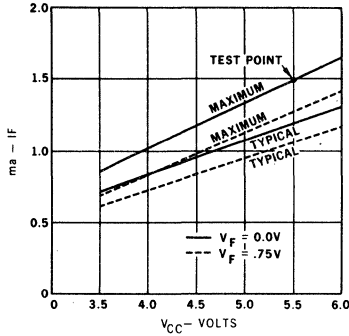
( $V_F = 0V$  &  $V_F = .750V$   $T_A = -55^\circ C$  &  $+25^\circ C$ )



**FIG. 2**

$-1 I_F$  DT $\mu$ L 930, 932, 944, 946, 962  
MAXIMUM VS. TYPICAL

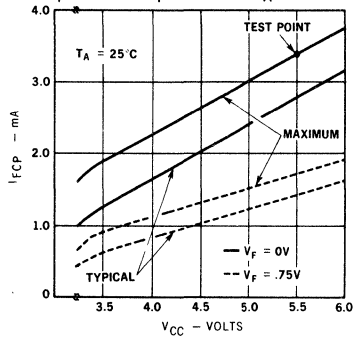
( $V_F = 0V$  &  $V_F = .750V$   $T_A = +125^\circ C$ )



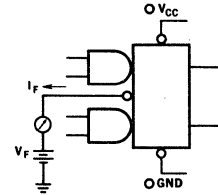
**FIG. 3**

$I_{FCP}$  DT $\mu$ L 931  
MAXIMUM VS. TYPICAL

( $V_F = 0V$  &  $V_F = .750V$   $T_A = +25^\circ C$ )



Note that with  $V_F = 0$  and Inputs  $S_1$ ,  $S_2$ ,  $C_1$ , and  $C_2$  at  $V_{OL}$ ,  $I_{FCP}$  current is summed through three diodes—both input AND Gate diodes and one of the Clock-coupling transistor emitters. As the Clock Pin voltage ( $V_F$ ) rises to approach  $V_{OL}$ , current starts to flow into one of pins  $S_1$ ,  $S_2$ ,  $C_1$ , or  $C_2$  (since all of these pins high is not an allowed logic state). Also when the collector of the Clock-coupling transistor rises (the collector is at  $V_{CE(sat)} + V_F$ ), current flows into the low output of the cross-connected output Flip-Flop. Therefore,  $I_{FCP}$  equal to  $2 I_F$  is a conservative rating and test current is much higher than will flow "in use."

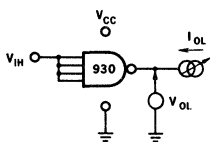
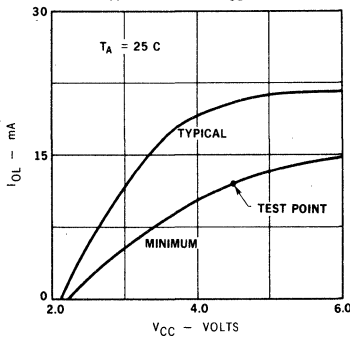


## OUTPUT LOW CURRENT VS. $V_{CC}$ OR $V_{OL}$ FOR 930 AND 931 ELEMENTS

**FIG. 4**

$I_{OL}$  VS.  $V_{CC}$

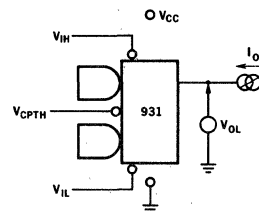
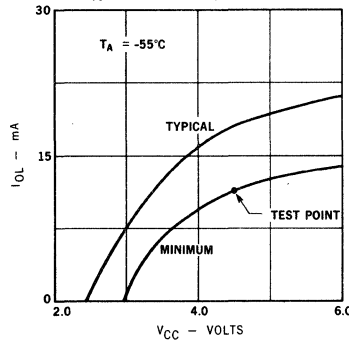
( $T_A = +25^\circ C$ ,  $V_{OL} = .400V$ )



**FIG. 5**

$I_{OL}$  VS.  $V_{CC}$

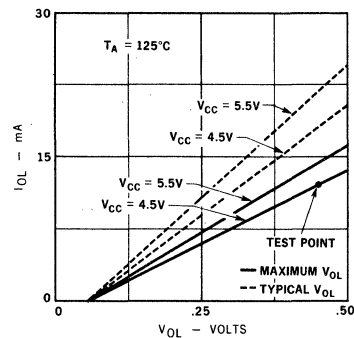
( $T_A = -55^\circ C$ ,  $V_{OL} = .400V$ )



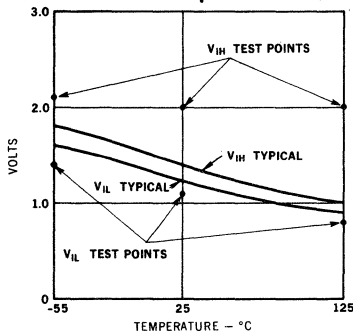
**FIG. 6**

$I_{OL}$  VS.  $V_{OL}$  VS.  $V_{CC}$

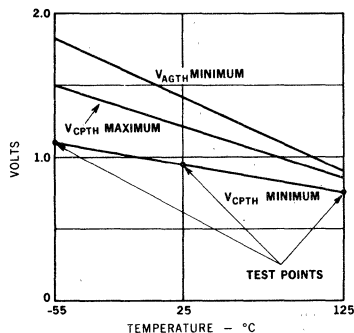
TYPICAL VS. MAXIMUM ( $T_A = +125^\circ C$ )



**DT  $\mu$ L INPUT THRESHOLDS  
VS. TEMPERATURE  
(except DT  $\mu$ L 931 CP)**



**DT  $\mu$ L CLOCK PIN THRESHOLDS  
VS. TEMPERATURE**



**DEFINITIONS OF 931 CLOCK PIN THRESHOLDS**

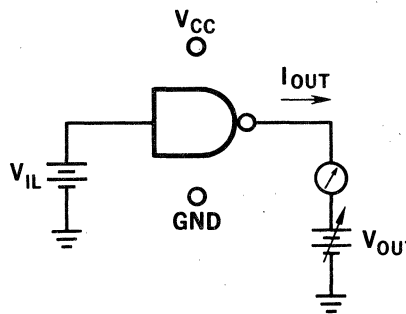
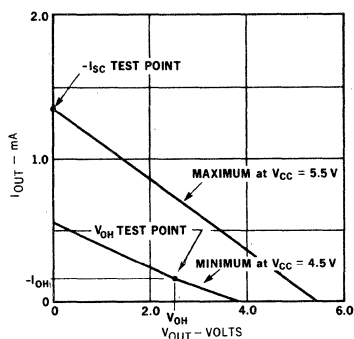
$V_{AGTH}(\min)$  With CP at or above  $V_{AGTH}(\min)$ , the clocked inputs will control the state of the "master" Flip-Flop, with  $V_{CC}$  and clocked inputs worst case.

$V_{CPTH}(\min)$  With CP at or below  $V_{CPTH}(\min)$ , the "master" Flip-Flop will control the output Flip-Flop, with  $V_{CC}$  and outputs worst case.

$V_{CPTH}(\max)$  With CP at or above  $V_{CPTH}(\max)$ , the "master" Flip-Flop will not control the output Flip-Flop, with  $V_{CC}$  and outputs worst case.

**OUTPUT CURRENT VS. OUTPUT VOLTAGE FOR DT  $\mu$ L 930 AND 931 ELEMENTS**

**FIG. 9**



**EXAMPLES OF USES FOR THE MINIMUM-MAXIMUM DC CURVES (Pages 6 & 7)**

**EXAMPLE 1.**

A low DT  $\mu$ L 930 output at  $-55^\circ\text{C}$  fans out to 8 inputs of DT  $\mu$ L 930 or 932.  $V_{CC} = 5\text{V}$ . Positive DC ground noise ( $V_{NG}$ ) of 350 mV is applied to the 1<sup>st</sup> 930. Its output may thus rise to .75 Volt ( $V_{NG} + V_{OI}$ ). 4.65 Volts ( $V_{CC} - V_{NG}$ ) remain from  $V_{CC}$  pin to ground pin; this is above  $V_{CCL} = 4.5\text{V}$ , and test  $I_{OL}$  is conservative. Maximum current flowing in each input of the 8 930/932's is given by Fig. 1 on Page 4 with  $V_F = 0.75\text{V}$  and  $V_{CC} = 5\text{V}$ ; the current ( $I_F$ ) is less than 1.25 mA and total current ( $\leq 8 \times 1.25 = 10\text{mA}$ ) is less than the  $I_{OL}$  test current used at  $-55^\circ\text{C}$  to saturate the low output. Above the 350 mV of  $V_{NG}$  already applied, the difference between the common node voltage ( $\leq .75\text{V}$ ) and the low input threshold ( $V_{IL} = 1.40\text{V}$ ) of the 8 930/932's is still  $\geq 350\text{mV}$ , allowing for signal noise to be superposed above ground noise.

**EXAMPLE 2.**

The  $I_F$  and  $I_{OL}$  curves on Page 6 may be expressed in analytical form, as follows

$$I_F \text{ (930 and 932)} \leq \frac{V_{CC} - V_F - V_{FD}}{3\text{K}\Omega} \quad T_A < 25^\circ\text{C}$$

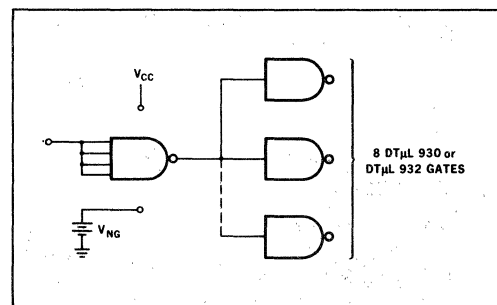
For  $T_A$  greater than  $25^\circ\text{C}$ , the  $3\text{K}\Omega$  rises by  $0.12\%/^\circ\text{C}$  to approximately  $3.36\text{K}\Omega$  at  $+125^\circ\text{C}$ .  $V_{FD}$  is the temperature dependent silicon forward diode drop and is about  $0.70\text{V}$  at  $25^\circ\text{C}$  and  $1\text{mA}$ .  $\Delta V_{FD}/^\circ\text{C}$  is roughly  $1.8\text{mV}/^\circ\text{C}$ .

The ratio of  $I_{OL}$ , on 930 and 931 (Figs. 4, 5, and 6) at  $V_{CC}$  below test  $V_{CC}$ , to  $I_{OL}$  at test  $V_{CC}$  can be given by

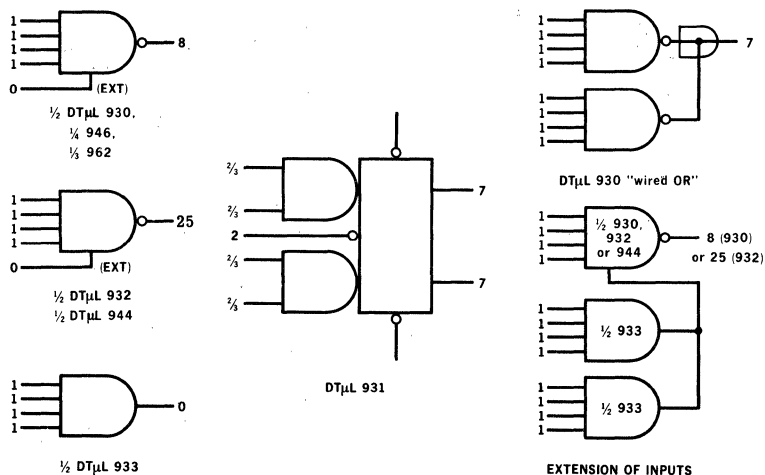
$$\frac{I_{OL} @ -55^\circ\text{C}}{\text{Test } I_{OL} @ V_{CCL} = 4.5\text{V}} \geq \frac{V_{CC} - 3.0\text{V}}{4.5\text{V} - 3.0\text{V}} \quad \text{and by} \quad \frac{I_{OL} @ 25^\circ\text{C}}{\text{Test } I_{OL} @ V_{CCL} = 4.5\text{V}} \geq \frac{V_{CC} - 2.3\text{V}}{4.5\text{V} - 2.3\text{V}}$$

Since, at  $25^\circ\text{C}$ ,  $I_{OL} \geq 12\text{mA}$  at  $V_{CCL} = 4.5\text{V}$  is guaranteed by the Page 2 and 3 specifications,  $I_{OL}$  at  $V_{CC}$  pin to GND pin voltage of  $3.6\text{V}$  is  $\left(\frac{3.6 - 2.3}{4.5 - 2.3}\right) 12\text{mA} = 7.1\text{mA}$ .

The similar expression for the 932 gives a very conservative value due to the phase splitter gain. Above  $V_{CCL}$ ,  $I_{OL}$  is limited by  $V_{OL}$  with an essentially resistive ( $\frac{V_{OL}}{I_{OL}}$  saturation resistance) slope. Fig. 6 at  $+125^\circ\text{C}$  shows this, with  $V_{CC}$  having relatively small effect.



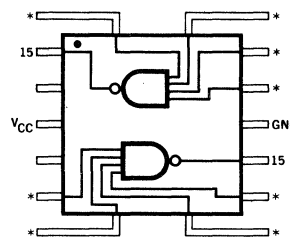
## SUGGESTED INPUT-OUTPUT LOADING FACTORS



The number of elements that may be driven by an output terminal may consist of any combination of elements whose summation of input loading does not exceed the output terminal driving capability.

## RULES FOR USE OF TT $\mu$ L 103 AND 104 WITH DT $\mu$ L

(4V < V<sub>CC</sub> < 6V)



- \* = 2 input loads for fan-in = 1 to DT $\mu$ L output driver.
- \* = 3 input loads for fan-in  $\geq$  2 to DT $\mu$ L output driver.
- \* = 1 input load to TT $\mu$ L output driver.

These input loads are primarily determined by inverse beta leakage at the TT $\mu$ L inputs at +125°C. For special cases where improved loading rules may be required, please consult the Fairchild Sales representative.

The TT $\mu$ L makes an excellent output interface driver for DT $\mu$ L. TT $\mu$ L outputs can be tied thru external loads to 8 or 10 V separate voltage supplies, to obtain output levels up to 6 or 8 volts.

## MISCELLANEOUS RULES

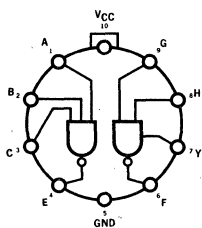
1. Outputs of DT $\mu$ L 930 may be tied together for the "wired OR" function ( $ABCD \cdot GHLJ = ABCD + GHLJ$ ). Subtract 1 unit fanout for each added gate. Subtract 5 fanouts for six added gates.
2. Outputs of DT $\mu$ L 932 may not be tied together for the "wired OR" function.
3. Extension of inputs within the DT $\mu$ L 933 does not affect quiescent loading of the supplemented element (DT $\mu$ L 930 or 932). However, capacitance due to wiring to the DT $\mu$ L 933 will affect noise tolerance and propagation delay, and thus establish a fanin limit for the particular application. Please refer to the typical curves on the DT $\mu$ L 933 Dual Extender Element preliminary specifications.
4. For operation with a nominal supply voltage of 4.0 volts from -55°C to +125°C, reduce element fanout as follows: DT $\mu$ L 930 = 5, DT $\mu$ L 931 = 5,

DT $\mu$ L 932 = 18. If temperature is maintained above -20°C, no fanout reduction is necessary.

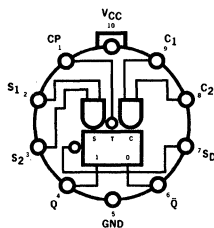
5. For operation with a nominal supply voltage of 6.0 volts from -55°C to +125°C, reduce element fanout as follows: DT $\mu$ L 930 = 6, DT $\mu$ L 931 = 6, DT $\mu$ L 932 = 20. If ambient temperature remains below +100°C or if worst case Noise Threshold is considered to be 250 mV, no fanout reduction is necessary. Except as noted, these rules apply over the entire military temperature range with a supply voltage of 4.5 to 5.5 volts. These rules also permit a 50°C temperature differential between individual elements. These rules guarantee a worst case signal-line or ground Noise Threshold of at least 350 mV. Practical Noise Thresholds exceed 500 mV.

6. All rules for DT $\mu$ L 930 apply to DT $\mu$ L 946 and DT $\mu$ L 962.

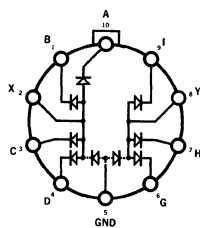
## 10 LEAD TO-5 PACKAGE PIN LOCATIONS



DT $\mu$ L 930 DUAL GATE  
DT $\mu$ L 932 DUAL BUFFER  
DT $\mu$ L 944 DUAL POWER GATE



DT $\mu$ L 931  
CLOCKED FLIP-FLOP



DT $\mu$ L 933  
DUAL EXTENDER

## PURCHASING INFORMATION

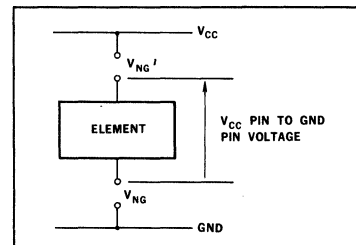
9YXXXSZ

- Y = 1 for 14 pin CERPAC
- Y = 5 for 10 pin TO-5
- XXX = 930
- 931
- 932
- 933
- Z = 1 for -55°C to +125°C operation

(cont'd)

### EXAMPLE 3.

The test sequences on Page 2 and tables of conditions and limits on Page 3 use two values of V<sub>CC</sub>, V<sub>CCL</sub> and V<sub>CCH</sub>. With a nominal 5 volts V<sub>CC</sub>, for example, and assuming  $\Delta V_{CC} = \pm .2V$ , testing at V<sub>CCL</sub> = 4.5 V and V<sub>CCH</sub> = 5.5 V allows simulation of  $\pm 0.3V$  ground noise V<sub>NG</sub> or V<sub>CC</sub> line noise V<sub>NG'</sub>. Since there is gain associated with V<sub>NG</sub> (refer to DT $\mu$ L 930 and 931 specifications), particularly at lower temperatures and V<sub>CC</sub> values; the test guarantees of output low current and voltage are the worst case test conditions to simulate worst case ground noise. Much better numbers could be shown, for example, in the ratio of output current to input current (I<sub>OL</sub>/I<sub>F</sub>) if both I<sub>OL</sub> and I<sub>F</sub> were measured at identical V<sub>CC</sub> values and if input current was sunk into V<sub>F</sub> = V<sub>OL</sub>, the worst case low output level, or even into V<sub>F</sub> = V<sub>IL</sub>, the input threshold value. However, the test values would then guarantee only signal line noise immunity, where there is no gain associated with V<sub>NS</sub>. By use of the Minimum/Maximum DC curves on Page 6 or by the Example 2 equations, limits for the single V<sub>CC</sub> testing approach could be recovered. More important, each design or components engineer can develop the fanout, power, and noise margin tradeoffs for this unique application.



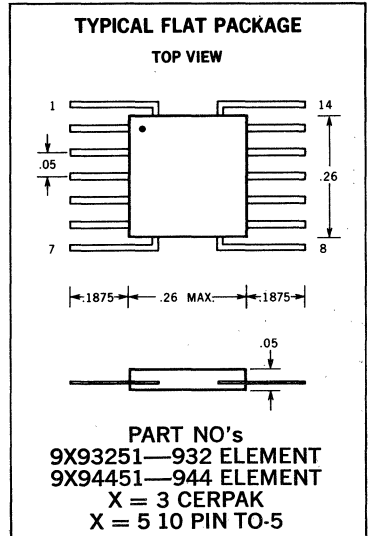
# DT $\mu$ L 932 DUAL BUFFER ELEMENT DT $\mu$ L 944 DUAL POWER GATE ELEMENT DIODE TRANSISTOR MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS

**GENERAL DESCRIPTION** - The DT $\mu$ L 932 Dual Buffer Element and the DT $\mu$ L 944 Dual Power Gate Element are dual 4-input inverting drivers for use with the Fairchild Diode-Transistor Micrologic Family or any similar DTL logic circuits. The fan-in of either element may be extended with the use of the DT $\mu$ L 933 Element. Input thresholds and currents are the same as other DT $\mu$ L gate elements.

Both DT $\mu$ L 932 and DT $\mu$ L 944 Elements have typical saturation resistances of 5 ohms which allow output currents of up to 100 mA. The DT $\mu$ L 932 features an emitter-follower output pull-up, which provides a high fan-out device with superior capacitance-driving capability.

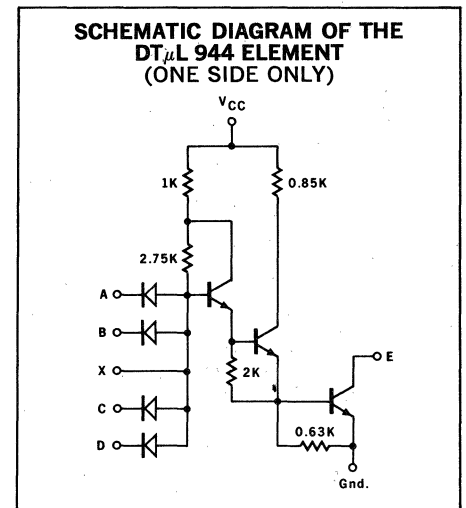
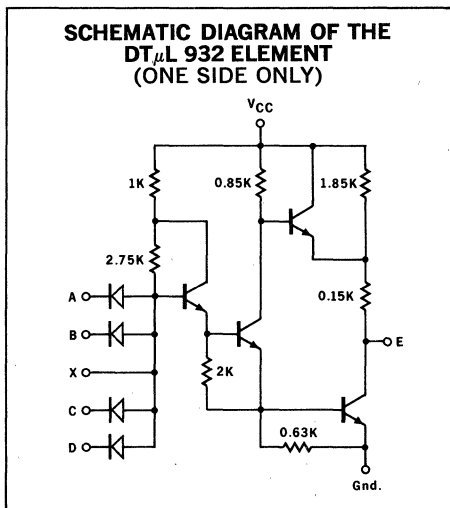
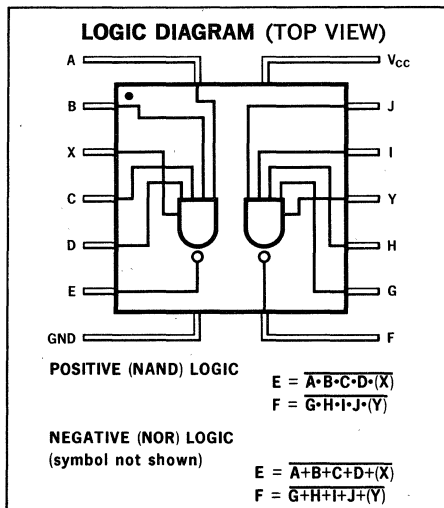
The DT $\mu$ L 944 features an output with no internal pull-up. Thus, 944 outputs may be tied together for the "wired-OR" function, or may drive inputs with logic thresholds of 4 to 6 volts. The 944 is intended as a high fan-out gate interface driver, or low-power lamp driver. An external pull-up resistor may return to the nominal DT $\mu$ L V<sub>CC</sub> supply of 5 volts or to other supplies up to 12 volts. These supplies may be located near the output or at the far end of an open transmission line or twisted pair interconnection.

Complete test specifications, typical and worst-case DC curves, t<sub>pd</sub> curves, and suggested loading rules are included in these specifications.



**ABSOLUTE MAXIMUM RATINGS** (above which useful life may be impaired)

Supply Voltage (V <sub>CC</sub> ), -55°C to +125°C, Continuous	+8.0 Volts	Input Reverse Current	5.0 mA
Supply Voltage (V <sub>CC</sub> ), pulsed, < 1.0 sec.	+12 Volts	Operating Ambient Temperature	-55°C to +125°C
Output Current, into Outputs, Continuous	150 mA	Storage Temperature	-65°C to +150°C
Output Current, into Outputs, pulsed, <30 milliseconds	300 mA	Operating Junction Temperature	+175°C Maximum (See note A on page 2)
Input Forward Current	-10 mA		



# DIODE-TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS

## TEST SEQUENCE DT<sub>μ</sub>L 932 AND DT<sub>μ</sub>L 944 ELEMENTS

**NOTE:** Both elements are dual "NAND" gates; therefore, the test sequences for each are identical. Tests on each side of the dual are identical; therefore, matching test and pin numbers are shown in parentheses.

Test No.	LTPD Group	Notes	Pin A (G)	Pin B (H)	Pin C (I)	Pin D (J)	Pin X (Y)	Pin E (F)	V <sub>CC</sub>	Sense	Limits	
											Min.	Max.
1, (2)	A		V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IH</sub>		I <sub>OL</sub>	V <sub>CCL</sub>	V <sub>E</sub> (V <sub>F</sub> )		V <sub>OL</sub>
3, 4, 5, 6, (7, 8, 9, 10)	B	1, 3	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>		I <sub>OH</sub>	V <sub>CCL</sub>	V <sub>E</sub> (V <sub>F</sub> )	V <sub>OH</sub>	
11, (12)	C		V <sub>R</sub>	GND	GND	GND			V <sub>CCH</sub>	I <sub>A</sub> (I <sub>G</sub> )		I <sub>R</sub>
13, (14)	C		GND	V <sub>R</sub>	GND	GND			V <sub>CCH</sub>	I <sub>B</sub> (I <sub>H</sub> )		I <sub>R</sub>
15, (16)	C		GND	GND	V <sub>R</sub>	GND			V <sub>CCH</sub>	I <sub>C</sub> (I <sub>I</sub> )		I <sub>R</sub>
17, (18)	C		GND	GND	GND	V <sub>R</sub>			V <sub>CCH</sub>	I <sub>D</sub> (I <sub>J</sub> )		I <sub>R</sub>
19, (20)	D		V <sub>F</sub>	V <sub>R</sub>	V <sub>R</sub>	V <sub>R</sub>			V <sub>CCH</sub>	I <sub>A</sub> (I <sub>G</sub> )		I <sub>F</sub>
21, (22)	D		V <sub>R</sub>	V <sub>F</sub>	V <sub>R</sub>	V <sub>R</sub>			V <sub>CCH</sub>	I <sub>B</sub> (I <sub>H</sub> )		I <sub>F</sub>
23, (24)	D		V <sub>R</sub>	V <sub>R</sub>	V <sub>F</sub>	V <sub>R</sub>			V <sub>CCH</sub>	I <sub>C</sub> (I <sub>I</sub> )		I <sub>F</sub>
25, (26)	D		V <sub>R</sub>	V <sub>R</sub>	V <sub>R</sub>	V <sub>F</sub>			V <sub>CCH</sub>	I <sub>D</sub> (I <sub>J</sub> )		I <sub>F</sub>
27, (28)	C	3	GND					V <sub>CEX</sub>	V <sub>CEX</sub>	I <sub>E</sub> (I <sub>F</sub> )		I <sub>CEX</sub>
29, (30)	B	2, 3	GND					GND	V <sub>CCH</sub>	I <sub>E</sub> (I <sub>F</sub> )	I <sub>SC</sub>	
31	E								V <sub>PD</sub>	V <sub>VCC</sub>		I <sub>PDH</sub>
32	E	2	GND						V <sub>(max)</sub>	V <sub>VCC</sub>		I <sub>(max)</sub>
33, (34)	E	3					V <sub>X</sub>	I <sub>OH</sub>	V <sub>CCL</sub>	V <sub>E</sub> (V <sub>F</sub> )	V <sub>OH</sub>	
35, 36	F	t <sub>pd+</sub> , t <sub>pd-</sub>	See Table of test circuit conditions and limits.									
35, 36, 37, 38 (39, 40, 41, 42)	B	1, 4	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>		V <sub>CEX</sub>	V <sub>CCH</sub>	I <sub>E</sub> (I <sub>F</sub> )		I <sub>CEX</sub>
43, (44)	B	4					V <sub>X</sub>	V <sub>CEX</sub>	V <sub>CCH</sub>	I <sub>E</sub> (I <sub>F</sub> )		I <sub>CEX</sub>
45, (46)	B	4	GND					I <sub>CE</sub>	V <sub>CCH</sub>	V <sub>E</sub> (V <sub>F</sub> )	LV <sub>CE</sub>	

- NOTES:**
- (1) V<sub>IL</sub> applied individually to 1 input each test. Other inputs open.
  - (2) Apply GND to both pins A and G.
  - (3) DT<sub>μ</sub>L932 only.
  - (4) DT<sub>μ</sub>L944 only.
  - (5) On 10 Pin TO-5 units, pins D, X, I and J are omitted. Thus tests 6, 9, 10, 16, 17, 18, 24, 25, 26, 33, 38, 41, 42 and 43 do not apply.

### TEST LIMITS—DT<sub>μ</sub>L 932 AND DT<sub>μ</sub>L 944

	Units	-55°C		+25°C		+125°C	
		Min	Max	Min	Max	Min	Max
V <sub>OL</sub>	Volts	0.4	0.4	0.4	0.45		
V <sub>OH</sub>	Volts	2.6	2.5	2.5			
I <sub>R</sub>	μA	2.0	2.0	5.0			
I <sub>F</sub>	mA	-1.6	-1.6	-1.5			
I <sub>CEX</sub> <sup>932</sup>	μA	50					
I <sub>SC</sub> (min) <sup>932</sup>	mA	-16	-18	-16			
I <sub>(max)</sub> <sup>932&amp;944</sup>	mA		6.0				
I <sub>PDH</sub> <sup>944</sup>	mA		20				
I <sub>PDH</sub> <sup>932</sup>	mA		26.6				
I <sub>CEX</sub> <sup>944</sup>	mA	0.05	0.1	0.2			
LV <sub>CE</sub> <sup>944</sup>	Volts		6.0				

### CONDITIONS AND LIMITS, t<sub>pd</sub> TESTS

(V<sub>CC</sub> = 5.0 V, T<sub>A</sub> = 25°C)

		R	C <sub>2</sub>	Limits	
				Min.	Max.
t <sub>pd+</sub>	944	510 Ω	20 pF	15 ns	50 ns
t <sub>pd-</sub>	944	150 Ω	100 pF	10 ns	35 ns
t <sub>pd+</sub>	932	510 Ω	500 pF	25 ns	80 ns
t <sub>pd-</sub>	932	150 Ω	500 pF	15 ns	40 ns
t <sub>pd+</sub>	944	150 Ω	20 pF	10 ns	35 ns (Note 1)
t <sub>pd-</sub>	944	510 Ω	20 pF	5.0 ns	20 ns (Note 1)
t <sub>pd+</sub>	932	150 Ω	500 pF	20 ns	65 ns (Note 1)
t <sub>pd-</sub>	932	510 Ω	200 pF	8.0 ns	30 ns (Note 1)

**NOTE:** Correlating limit provided as design information only.

### FORCING CONDITIONS

	Units	-55°C	+25°C	+125°C
V <sub>(max)</sub>	Volts	--	8.0	--
V <sub>PD</sub>	Volts	--	5.0	--
V <sub>CCH</sub>	Volts	5.5	5.5	5.5
V <sub>CCL</sub>	Volts	4.5	4.5	4.5
V <sub>R</sub>	Volts	4.0	4.0	4.0
V <sub>F</sub>	Volts	0	0	0
V <sub>CEX</sub>	Volts	4.5	4.5	4.5

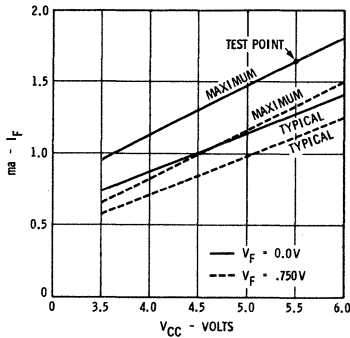
	Units	-55°C	+25°C	+125°C
I <sub>OL</sub> <sup>944</sup>	mA	36	40	36
I <sub>OL</sub> <sup>932</sup>	mA	34	36	32
I <sub>OH</sub> <sup>932</sup>	mA	-2.0	-2.5	-4.0
V <sub>IL</sub>	Volts	1.4	1.1	0.8
V <sub>IH</sub>	Volts	2.1	1.9	1.7
V <sub>X</sub>	Volts		1.8	
I <sub>CE</sub> <sup>944</sup>	mA		5.0	

**NOTE A:** Allow 200°C/Watt θ<sub>J-A</sub> for TO-5; 300°C/Watt θ<sub>J-A</sub> for cerpak. Allow 50°C/Watt θ<sub>J-C</sub> for TO-5; 180°C/Watt θ<sub>J-C</sub> for cerpak. Heat removal in cerpaks is highly dependent upon contact surfaces or air flow and on lead attachment and Thermal paths thru leads, as well as number of soldered leads.

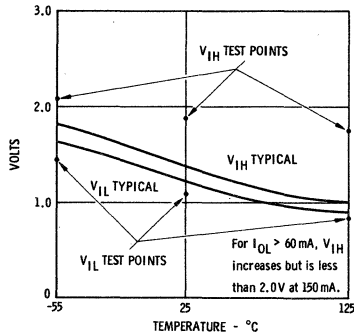
# DIODE-TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS

## MINIMUM/MAXIMUM AND TYPICAL DC CURVES

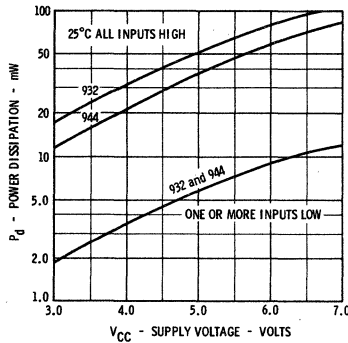
**FIG. 1. -1 I<sub>F</sub> DT<sub>μ</sub>L932, 944  
MAXIMUM VS. TYPICAL  
(T<sub>A</sub> = -55°C & +25°C)**



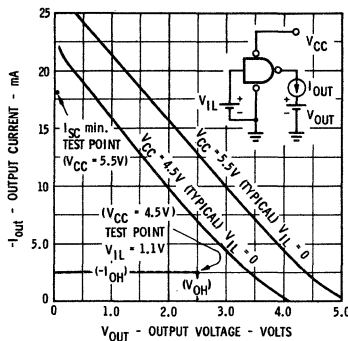
**FIG. 2. DT<sub>μ</sub>L INPUT THRESHOLDS  
VS. TEMPERATURE (932, 944)**



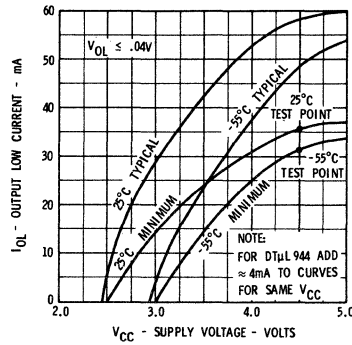
**FIG. 3. TYPICAL POWER DISSIPATION  
PER SIDE VS. SUPPLY VOLTAGE  
(OUTPUT NOT LOADED) (932, 944)**



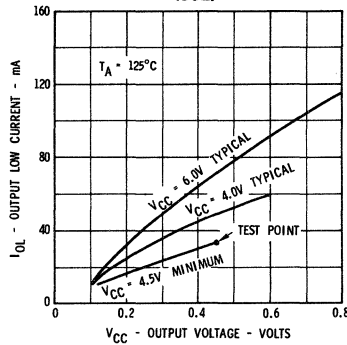
**FIG. 4. TYPICAL OUTPUT CURRENT  
WITH INPUTS LOW (932)**



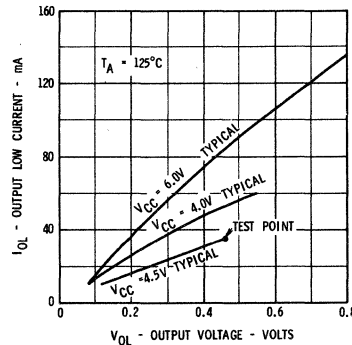
**FIG. 5. TYPICAL OUTPUT LOW  
CURRENT VS. SUPPLY VOLTAGE  
(-55°C and +25°C) (932)**



**FIG. 6. TYPICAL OUTPUT LOW  
CURRENT VS. OUTPUT VOLTAGE  
(932)**

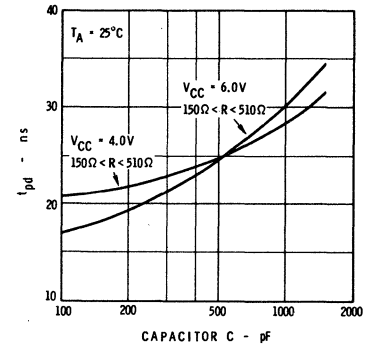


**FIG. 7. TYPICAL OUTPUT LOW  
CURRENT VS. OUTPUT VOLTAGE  
(944)**

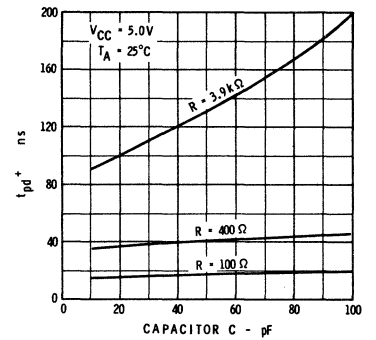


## t<sub>pd</sub> CURVES

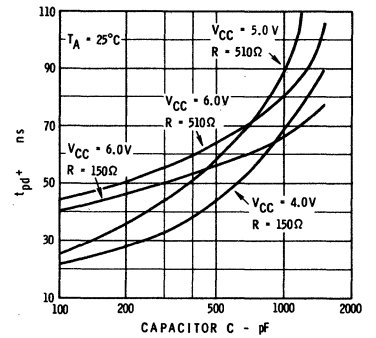
**FIG. 8. TYPICAL t<sub>pd</sub>- VS.  
CAPACITY (932, 944)**



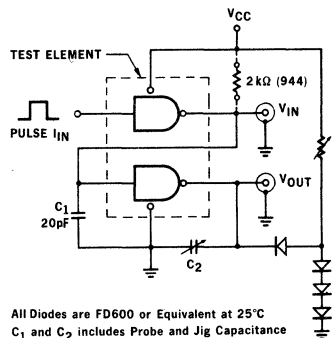
**FIG. 9. TYPICAL t<sub>pd</sub>+ VS.  
CAPACITY (944)**



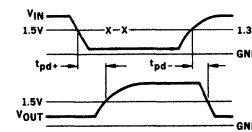
**FIG. 10. TYPICAL t<sub>pd</sub>+ VS.  
CAPACITY (932)**



## t<sub>pd</sub> TEST CIRCUIT FOR DT<sub>μ</sub>L 932 ELEMENT



All Diodes are FD600 or Equivalent at 25°C  
C<sub>1</sub> and C<sub>2</sub> includes Probe and Jig Capacitance

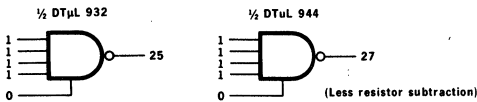


### NOTE:

The same circuit is used on the DT<sub>μ</sub>L 944 element except that all diodes are omitted. The resistor R is tied to capacitor C and the Test Output. A 2 kΩ resistor is used to load the input gate.

# DIODE-TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS

**SUGGESTED INPUT-OUTPUT LOADING FACTORS** (Please refer to DT $\mu$ L Composite Data Sheet for complete family rules).



## INPUT LOAD FACTORS FOR OTHER DT $\mu$ L ELEMENTS

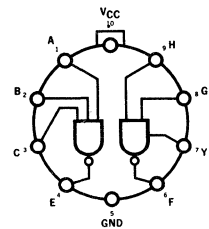
- 1 - DT $\mu$ L 930, 946, 932, 944 inputs
- 2 - DT $\mu$ L 931, 945, 948 CP pin
- 2/3 - DT $\mu$ L 931, 945, 948 S<sub>1</sub> S<sub>2</sub> C<sub>1</sub> C<sub>2</sub>
- 3/4 - DT $\mu$ L 931 S<sub>D</sub> C<sub>D</sub> pins
- 2 - DT $\mu$ L 945, 948 S<sub>D</sub> C<sub>D</sub> pins
- 1 - TT $\mu$ L 103, 104 when driven by DT $\mu$ L 932 or 944 with external resistor  $\leq 510 \Omega$ .

## MISCELLANEOUS RULES

1. DT $\mu$ L 932 may not be output "OR"ed.
2. For increased current, inputs and outputs of 1/2 DT $\mu$ L 932 or 1/2 DT $\mu$ L 944 may be paralleled up to 4 common outputs. Each combined input = 4 loads. Combined output = 100 loads.
3. DT $\mu$ L 944 may be output "OR"ed.
4. An external resistor should be used with DT $\mu$ L 944. With external R to 5 volt V<sub>CC</sub>  $\pm 0.5$  V; subtract output loads as follows:

- R = 2k - 2 loads
- R = 1k - 4 loads
- R = .510k - 8 loads

## 10 LEAD TO-5 PACKAGE

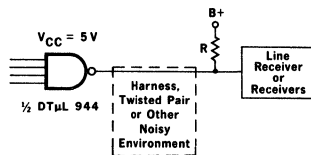


DT $\mu$ L 930 DUAL GATE  
DT $\mu$ L 932 DUAL BUFFER  
DT $\mu$ L 944 DUAL POWER GATE

## MISCELLANEOUS APPLICATIONS

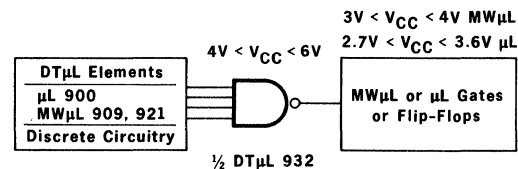
**NOTE:** In some of these applications, use of the elements is made within the design of the element but beyond the guaranteed test limits on page 2. Consult your Fairchild sales representative for additional information and/or selection requirements.

### INTERFACING



B<sup>+</sup> up to 12 volts. Line Receiver may have nominal low level  $\leq 1$  volt; nominal threshold  $\approx 4$  V and nominal high level  $\geq 8$  V, for example. Resistor selected should be as low as possible consistent with required low input level of receiver, number of receivers, and power dissipation of system. For a guaranteed V<sub>OH</sub> level above 6 volts, an LV<sub>CE</sub> selection may be desirable; for use of resistor that requires the 944 to sink more than 40 mA (at V<sub>OL</sub> above .40 volt), a high current I<sub>OL</sub> - V<sub>OL</sub> selection may be desirable.

### DRIVING $\mu$ L AND MW $\mu$ L

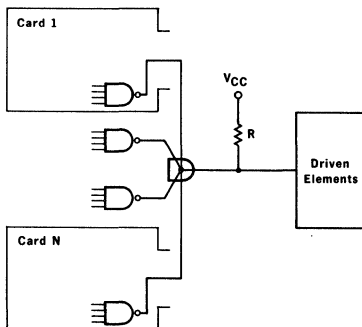


Rules: With V<sub>CC</sub> > 4.5 V a 932 will drive 25-unit  $\mu$ Logic loads or 100 MW $\mu$ L unit loads.

Derate DT $\mu$ L output drive by 25% for DT $\mu$ L 932 V<sub>CC</sub> = 4 V.

Refer to DT $\mu$ L 932 Output Current vs Output Voltage curve, Page 3, for matching to  $\mu$ L-MW $\mu$ L I<sub>AVAILABLE</sub> requirements.

### POWER GATING



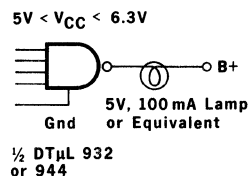
Each output driver is 1/2 DT $\mu$ L 944. Note that the DT $\mu$ L 944 is a direct high fan-out replacement for DT $\mu$ L 930, except that an external resistor must be used.

### LAMP DRIVING

Suggested Ratings T<sub>A</sub>  $\leq 75^\circ$ C

Power Dissipation TO-5 400 mW Maximum

Power Dissipation Cerpak 240 mW Maximum



Maximum "hot" lamp current

120 mA TO-5 one side only ON

100 mA Cerpak one side only ON

90 mA TO-5 both sides ON

75 mA Cerpak both sides ON

"Cold" lamp current is limited by saturation resistance, emitter resistance, and base current to about 200 to 250 mA.

The most significant thermal time constants for 932 and 944:

TO-5 Package 50 ms Cerpak 100 ms

Thermal time constant is measured by forward diode drop in one gate with power pulsed into opposite gate. A high current  $\beta$  selection is desirable in this application.

**FAIRCHILD**  
SEMICONDUCTOR  
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION



# DT $\mu$ L933 DUAL FOUR-INPUT EXTENDER ELEMENT

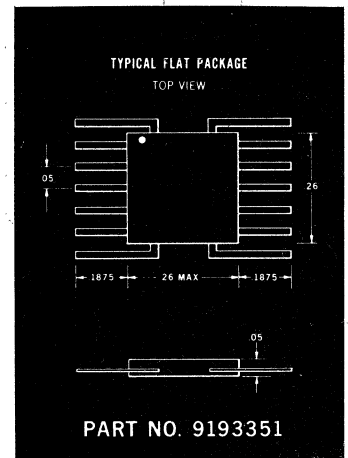
FAIRCHILD DIODE-TRANSISTOR MICROLOGIC

The DT $\mu$ L 933 is a Dual Input-Extender consisting of two independent diode arrays identical in every respect to the input diodes of the DT $\mu$ L Gate and Buffer elements. DT $\mu$ L 933 elements may be used to extend fan-in capability to more than 20 without adversely affecting the noise immunity or load driving capability of the element to which they are connected.

Good practice dictates that extension interconnection paths be as short as possible to minimize the effects of distributed capacitance on circuit performance. The effects of capacitance are summarized on the back page.

Typical input capacitance of DT $\mu$ L 933 is 2 pf and output capacitance is 5 pf.

For complete test sequence and test values, please refer to the composite DT $\mu$ L specification



**SCHEMATIC DIAGRAM**

**FLAT PACKAGE LAYOUT (TOP VIEW)**

**LOGIC EXAMPLE**

POSITIVE LOGIC  $E = A B C D G H I J$   
NEGATIVE LOGIC  $E = A + B + C + D + G + H + I + J$

**FORWARD VOLTAGE VS. FORWARD CURRENT + 25°C**

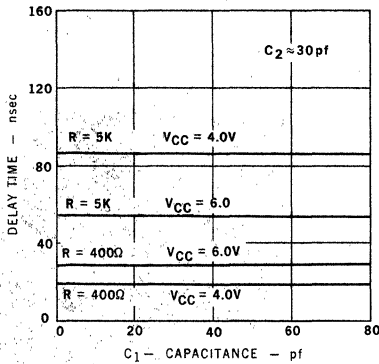
Copyright 1964 by Fairchild Semiconductor, a Division of Fairchild Camera and Instrument Corporation

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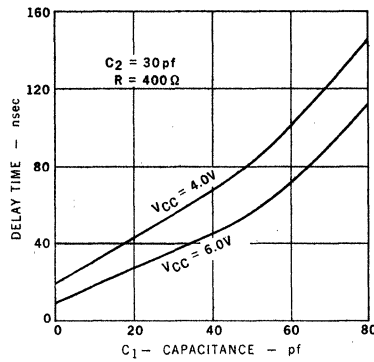
313 FAIRCHILD DRIVE, MOUNTAIN VIEW, CALIFORNIA, (415) 962-5011, TWX: 910-379-6435

Typical Curves to Show the Effects of Extender Pin Capacitance (Resulting From the Use of DT $\mu$ L 933) on Time Delay of DT $\mu$ L 930 Dual Gate and DT $\mu$ L 932 Dual Buffer  
+ 25°C

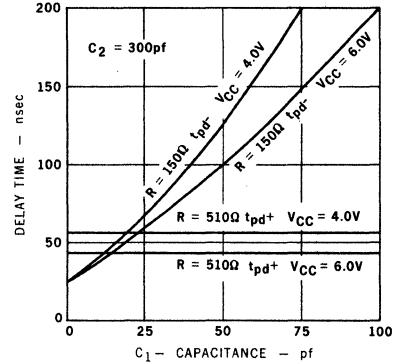
DT $\mu$ L 930  $t_{pd}$  + VS. EXTENDER PIN CAPACITANCE



DT $\mu$ L 930  $t_{pd}$  - VS. EXTENDER PIN CAPACITANCE



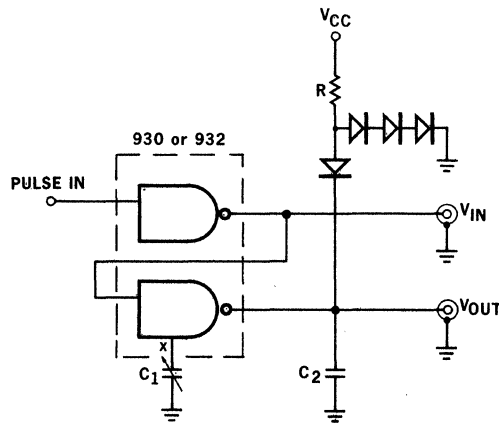
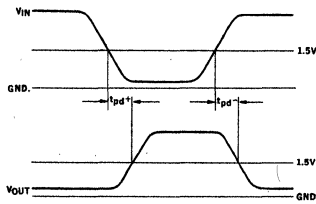
DT $\mu$ L 932 TIME DELAY VS. EXTENDER PIN CAPACITANCE



$t_{pd}$  - at R = 5 K $\Omega$  is slightly lower.

TEST CONDITIONS

WAVESHAPES

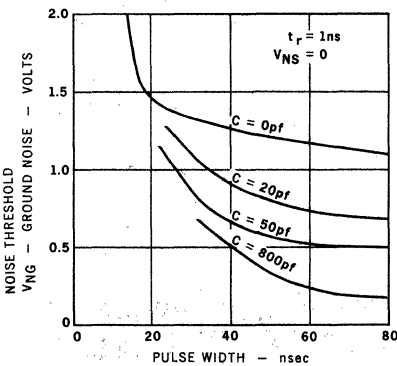


Diodes are FD600

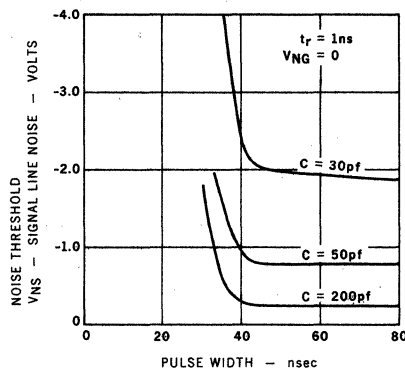
$C_1$  represents the summation of the DT $\mu$ L 933 Dual Extender Element output capacitances (~5 pf per output) and associated board, connector and wiring capacitances.

Typical Curves to Show the Effects of Extender Pin Capacitance on Noise Threshold of DT $\mu$ L 930 Dual Gate  
+ 25°C

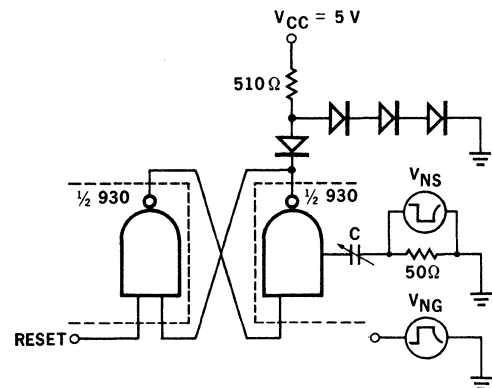
PULSED GROUND NOISE THRESHOLD AS A FUNCTION OF EXTENDER PIN CAPACITANCE



PULSED SIGNAL LINE NOISE THRESHOLD AS A FUNCTION OF EXTENDER PIN CAPACITANCE



TEST CONDITIONS



Diodes are FD600

# 4501

## CCSL MICROMATRIX™ QUARTER-CELL

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The 4501 consists of a single 4-input DT $\mu$ L gate designed for use in breadboarding the 4500 Micromatrix™. It corresponds to one of the 32 quarter-cells available in the 4500 Micromatrix array. Logic flexibility is offered with pin options for interconnections of four independent elements. These elements are a) 4-diode cluster, b) non-inverting amplifier, c) common emitter inverting amplifier and d) load resistor.

### FEATURES

- Offers 4500 Micromatrix breadboarding capability
- Compatible with all CCSL devices

### ABSOLUTE MAXIMUM RATINGS

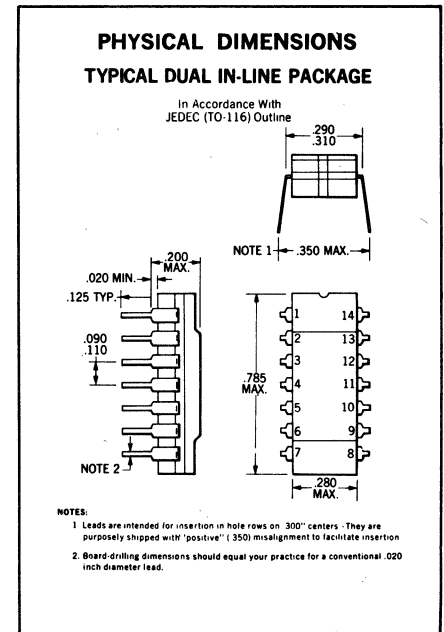
$V_{CC}$  Pin Potential to Ground Pin  
Input Voltage  
Voltage Applied to Outputs  
Storage Temperature  
Temperature (ambient) under Bias

–.5 V to +7 V  
–.5 V to +5.5 V  
–.5 V to + $V_{CC}$  Value  
–65°C to +150°C  
–55°C to +125°C

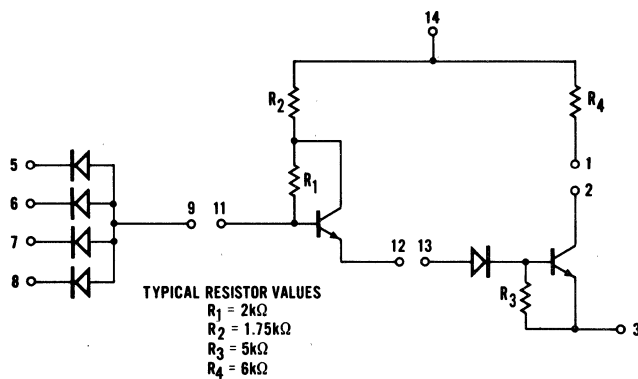
### ORDER INFORMATION

Specify A6A45015XX, where 5XX is 51X for –55°C to +125°C temperature range or 59X for the 0°C to +75°C temperature range.

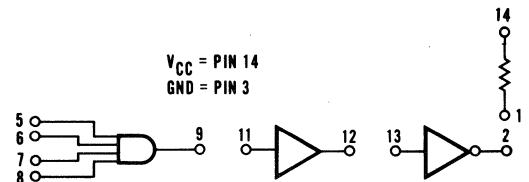
To order 4500 design kit, specify A6A4501KTX



### CIRCUIT SCHEMATIC (PIN NUMBERS)



### LOGIC DIAGRAM (PIN NUMBERS)



# FAIRCHILD 4500 MICROMATRIX™ • 4501 QUARTER-CELL

**ELECTRICAL CHARACTERISTICS** ( $T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} = 10\%$ ) Connected as NAND gate with pull-up resistor  
**MILITARY TEMPERATURE RANGE**

SYMBOL	CHARACTERISTIC	LIMITS						UNITS	CONDITIONS
		-55°C MIN. MAX.		+25°C MIN. TYP. MAX.		+125°C MIN. MAX.			
$V_{OH}$	Output High Voltage	2.6		2.6	3.4	2.5		Volts	$V_{CC} = 4.5\text{V}$ $V_{IL}$ on any input $I_{OH} = -180\ \mu\text{A}$
$V_{OL}$	Output Low Voltage	0.4		0.22	0.4	0.4		Volts	$V_{CC} = 5.5\text{V}$ $V_{CC} = 4.5\text{V}$ $I_{OL} = 8\text{mA}$ $I_{OL} = 6.2\text{mA}$
$V_{IH}$	Input High Voltage	2.1		1.9		1.7		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage	1.3		1.0		0.7		Volts	Guaranteed input low threshold for all inputs
$I_F$	Input Load Current	1.6		1.18	1.6	1.6		mA	$V_{CC} = 5.5\text{V}$ $V_F = 0.4\text{V}$
		1.24		0.91	1.24	1.24		mA	$V_{CC} = 4.5\text{V}$ $V_F = 0.4\text{V}$
$I_R$	Input Leakage Current			2		10		$\mu\text{A}$	$V_R = 4\text{V}$ , GND on other inputs
$P_D$	Power Dissipation			15.5				mW	$V_{CC} = 5\text{V}$ Inputs open, pull-up connected
				8.8				mW	$V_{CC} = 5\text{V}$ Any input grounded

**ELECTRICAL CHARACTERISTICS** ( $T_A = 0^\circ\text{C}$  to  $+75^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} = 5\%$ ) Connected as NAND gate with pull-up resistor  
**INDUSTRIAL TEMPERATURE RANGE**

SYMBOL	CHARACTERISTIC	LIMITS						UNITS	CONDITIONS
		0°C MIN. MAX.		+25°C MIN. TYP. MAX.		+75°C MIN. MAX.			
$V_{OH}$	Output High Voltage	2.6		2.6	3.65	2.5		Volts	$V_{CC} = 4.75\text{V}$ $V_{IL}$ on any input $I_{OH} = -180\ \mu\text{A}$
$V_{OL}$	Output Low Voltage	0.45		0.22	0.45	0.45		Volts	$V_{CC} = 5.25\text{V}$ $V_{CC} = 4.75\text{V}$ $I_{OL} = 9.6\text{mA}$ $I_{OL} = 8.5\text{mA}$
$V_{IH}$	Input High Voltage	2.0		1.9		1.8		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage	1.1		1.0		0.8		Volts	Guaranteed input low threshold for all inputs
$I_F$	Input Load Current	1.6		1.09	1.6	1.6		mA	$V_{CC} = 5.25\text{V}$ $V_F = 0.45\text{V}$
		1.41		0.96	1.41	1.41		mA	$V_{CC} = 4.75\text{V}$ $V_F = 0.45\text{V}$
$I_R$	Input Leakage Current			5		10		$\mu\text{A}$	$V_R = 4\text{V}$ , GND on other inputs
$P_D$	Power Dissipation			16.5				mW	$V_{CC} = 5\text{V}$ Inputs open, pull-up connected
				9				mW	$V_{CC} = 5\text{V}$ Any input grounded

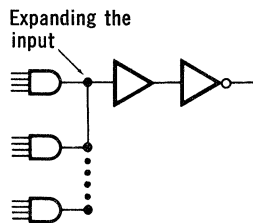
Loading and interconnections for 4501 are identical to 4500 Micromatrix array except for Note 3.

### LOADING RULES

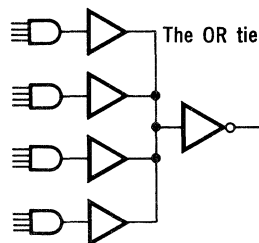
Connected as NAND gate with pull-up resistor

Load	Fan-out	
	51X	59X
DTL	5	6
TTL	3	3

### INTERCONNECTION RULES



Maximum fan-in — 20 inputs corresponding to 5 diode clusters.  
 Fan-out — same as NAND gate.



If OR tie is utilized, 4501 fan-out is restricted to 3 unit loads for 51X temperature range operation (4 unit loads for 59X temperature range.) (Note 3.)

Maximum of 4 OR ties allowed.

Note 3: Fan-out of 5 (6 for 59X temperature range) with OR tie used, can be maintained if temperature range of operation is limited to  $+15^\circ\text{C}$  to  $+125^\circ\text{C}$  ( $+15^\circ\text{C}$  to  $+75^\circ\text{C}$  for 59X temperature range.)

# 4510

## CCSL MICROMATRIX™ DUAL 4-BIT COMPARATOR

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The 4510 consists of two independent 4-bit comparators useful in many decision making control applications, such as digital printers. Each comparator is capable of accepting two 4-bit inputs and provides a high level output signal when they are identical. An output latch stores the compared output when the strobe pin is high. Outputs may be "Wire ANDed" to expand comparison capability. The circuit is produced with two layer metal interconnections using the Fairchild 4500 Bipolar Micromatrix™ Array.

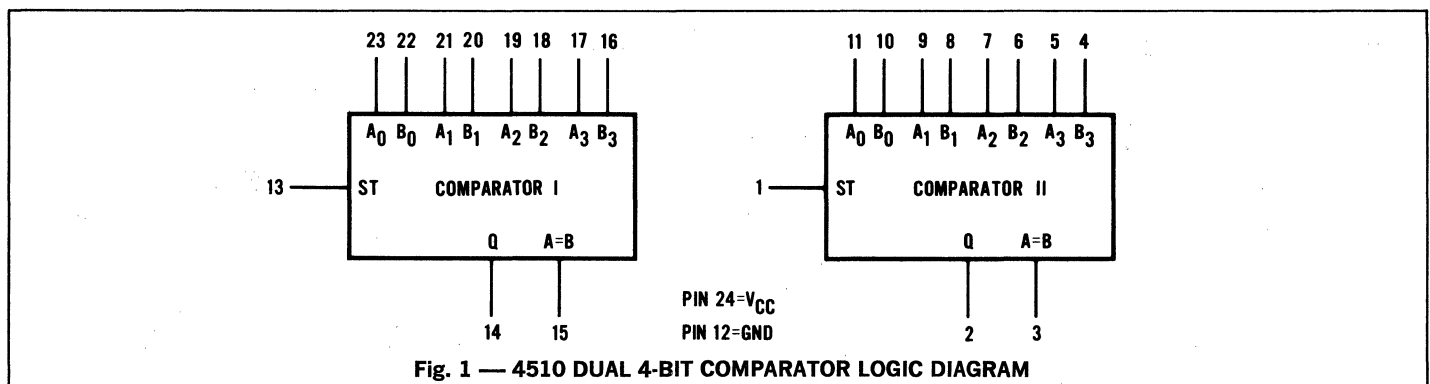
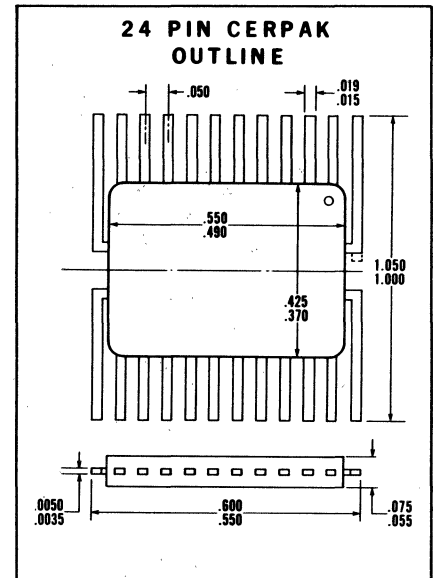
### FEATURES

- ASYNCHRONOUS AND SYNCHRONOUS OUTPUTS
- OPTIONAL LATCH STORAGE OF OUTPUT
- EXPANDABLE IN GROUPS OF 4 BITS
- TYPICAL POWER DISSIPATION OF 250 mW
- CCSL COMPATIBLE
- ALL CERAMIC "HERMETIC" 24 PIN CERPAK
- MEMBER OF 4500 MICROMATRIX™ ARRAY FAMILY
- TWO LAYER METAL INTERCONNECTIONS

### ABSOLUTE MAXIMUM RATINGS (above which the useful life may be impaired)

Storage Temperature	−65°C to +150°C
Temperature (Ambient) Under Bias	−55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground Pin	−0.5 V to +7.0 V
Voltage Applied to Output for High Output State	−0.5 V to +V <sub>CC</sub> Value
Output Current Into Low Output State	20 mA
Input Voltage (D.C.)	−0.5 V to +5.5 V

**ORDER INFORMATION** — Specify A3M45105XX for flat package, where 5XX is 51X for −55°C to +125°C temperature range or 59X for the 0°C to +75°C temperature range.



# FAIRCHILD 4510 MICROMATRIX™ CIRCUIT

## ELECTRICAL CHARACTERISTICS ( $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ , $V_{CC} = 5.0\text{ V} = 10\%$ ) MILITARY TEMPERATURE RANGE

SYMBOL	CHARACTERISTIC	LIMITS				UNITS	CONDITIONS
		$-55^\circ\text{C}$ MIN. MAX.		$+25^\circ\text{C}$ MIN. TYP. MAX.			
$V_{OH}$	Q Output High Voltage	2.6	2.6	3.4	2.5	Volts	$I_{OH} = -180\ \mu\text{A}$ } $V_{IL}$ on any two inputs $I_{OH} = -240\ \mu\text{A}$ } $V_{CC} = 4.5\text{ V}$
	A = B Output High Voltage	2.6	2.6	3.4	2.5	Volts	
$V_{OL}$	Output Low Voltage Q and A = B Output	0.4	0.22	0.4	0.4	Volts	$V_{CC} = 5.5\text{ V}$ } $I_{OL} = 6.4\text{ mA}$ } $V_{ST} = \text{GND}$ for $V_{CC} = 4.5\text{ V}$ } $I_{OL} = 5.0\text{ mA}$ } A = B output only
	Output Low Voltage A = B Output Only	0.4	0.22	0.4	0.4	Volts	
$V_{IH}$	Input High Voltage	2.1	1.9		1.7	Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage	1.3		1.0	0.7	Volts	Guaranteed input low threshold for all inputs
$2 I_F$	Input Load Current	3.2	2.36	3.2	3.2	mA	$V_{CC} = 5.5\text{ V}$ } $V_F = 0.4\text{ V}$
		2.43	1.82	2.48	2.48	mA	$V_{CC} = 4.5\text{ V}$ } $V_F = 0.4\text{ V}$
$1.5 I_F$	A = B Output Load Current	2.4	1.77	2.4	2.4	mA	$V_{CC} = 5.5\text{ V}$ } } $V_F = 0.4\text{ V}$
		1.86	1.37	1.86	1.86	mA	$V_{CC} = 4.5\text{ V}$ } } $V_{ST} = \text{GND}$
$2.5 I_F$	For "Wired AND"	4.0	2.95	4.0	4.0	mA	$V_{CC} = 5.5\text{ V}$ } } $V_F = 0.4\text{ V}$
		3.1	2.28	3.1	3.1	mA	$V_{CC} = 4.5\text{ V}$ } } $V_{ST} = 4\text{ V}$
$I_R$	Input Leakage Current			20	20	$\mu\text{A}$	$V_R = 4\text{ V}$ , GND on other inputs
t23+ 15+	Comparison Switching Speed			50		ns	$V_{CC} = 5\text{ V}$
t23- 15-	A <sub>O</sub> to A = B			50		ns	$C_L = 15\text{ pF}$ @ Pin 15

## ELECTRICAL CHARACTERISTICS ( $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$ , $V_{CC} = 5.0\text{ V} = 5\%$ ) INDUSTRIAL TEMPERATURE RANGE

SYMBOL	CHARACTERISTIC	LIMITS				UNITS	CONDITIONS
		$0^\circ\text{C}$ MIN. MAX.		$+25^\circ\text{C}$ MIN. TYP. MAX.			
$V_{OH}$	Q Output High Voltage	2.6	2.6	3.65	2.5	Volts	$I_{OH} = -180\ \mu\text{A}$ } $V_{IL}$ on any two inputs $I_{OH} = -300\ \mu\text{A}$ } $V_{CC} = 4.75\text{ V}$
	A = B Output High Voltage	2.6	2.6	3.65	2.5	Volts	
$V_{OL}$	Output Low Voltage Q and A = B Output	0.45	0.22	0.45	0.45	Volts	$V_{CC} = 5.25\text{ V}$ } $I_{OL} = 8.0\text{ mA}$ } $V_{ST} = \text{GND}$ for $V_{CC} = 4.75\text{ V}$ } $I_{OL} = 6.25\text{ mA}$ } A = B output only
	Output Low Voltage A = B Output Only	0.45	0.22	0.45	0.45	Volts	
$V_{IH}$	Input High Voltage	2.0	1.9		1.8	Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage	1.1		1.0	0.8	Volts	Guaranteed input low threshold for all inputs
$2 I_F$	Input Load Current	3.2	2.18	3.2	3.2	mA	$V_{CC} = 5.25\text{ V}$ } $V_F = 0.45\text{ V}$
		2.82	1.92	2.82	2.82	mA	$V_{CC} = 4.75\text{ V}$ } $V_F = 0.45\text{ V}$
$1.5 I_F$	A = B Output Load Current	2.4	1.65	2.4	2.4	mA	$V_{CC} = 5.25\text{ V}$ } } $V_F = 0.4\text{ V}$
		2.11	1.44	2.11	2.11	mA	$V_{CC} = 4.75\text{ V}$ } } $V_{ST} = \text{GND}$
$2.5 I_F$	For "Wired AND"	4.0	2.64	4.0	4.0	mA	$V_{CC} = 5.25\text{ V}$ } } $V_F = 0.4\text{ V}$
		3.52	2.4	3.52	3.52	mA	$V_{CC} = 4.75\text{ V}$ } } $V_{ST} = 4\text{ V}$
$I_R$	Input Leakage Current			20	20	$\mu\text{A}$	$V_R = 4\text{ V}$ , GND on other inputs
t23+ 15+	Comparison Switching Speed			50		ns	$V_{CC} = 5\text{ V}$
t23- 15-	A <sub>O</sub> to A = B			50		ns	$C_L = 15\text{ pF}$ @ Pin 15

# FAIRCHILD 4510 MICROMATRIX™ CIRCUIT

## FUNCTIONAL DESCRIPTION

**ASYNCHRONOUS** — Fig. 2 shows the detailed logic representation of the comparator and latch (½ 4510). Whenever the 4-bit data word on lines A is identical to the 4-bit data word on lines B the A=B output is high. If data word A is not equal to data word B the A=B output is low.

**SYNCHRONOUS** — The strobe (ST) and the latch output (Q) provide storage capability of the A=B output. This function is shown in Table 1. When ST is high,  $Q_N$  equals the A=B output. When ST is low,  $Q_N = Q_{N-1}$ .

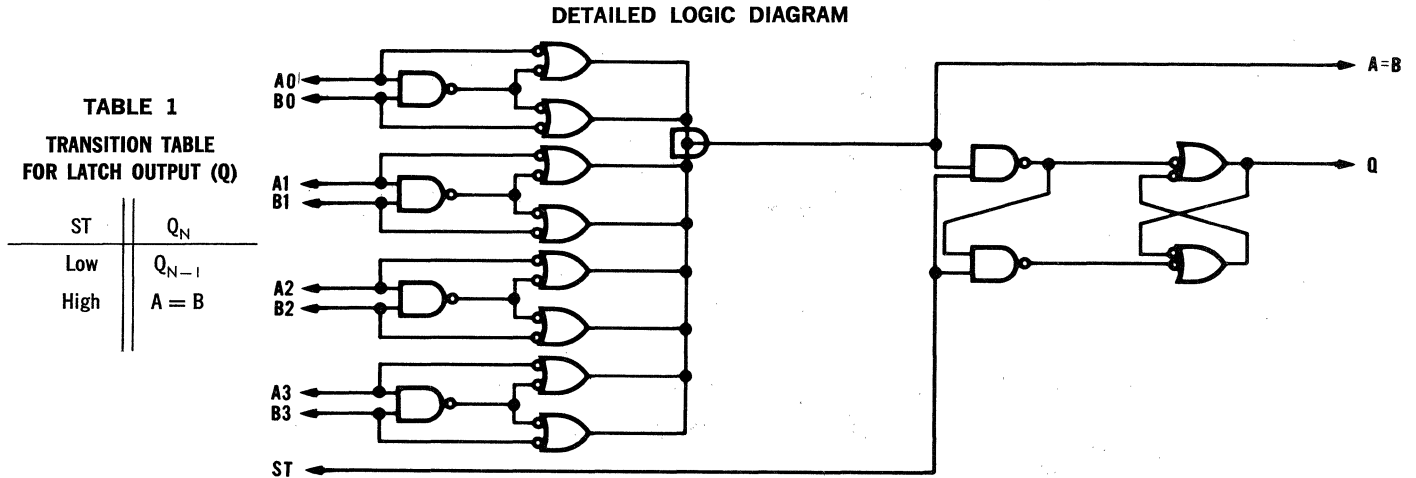


Fig. 2

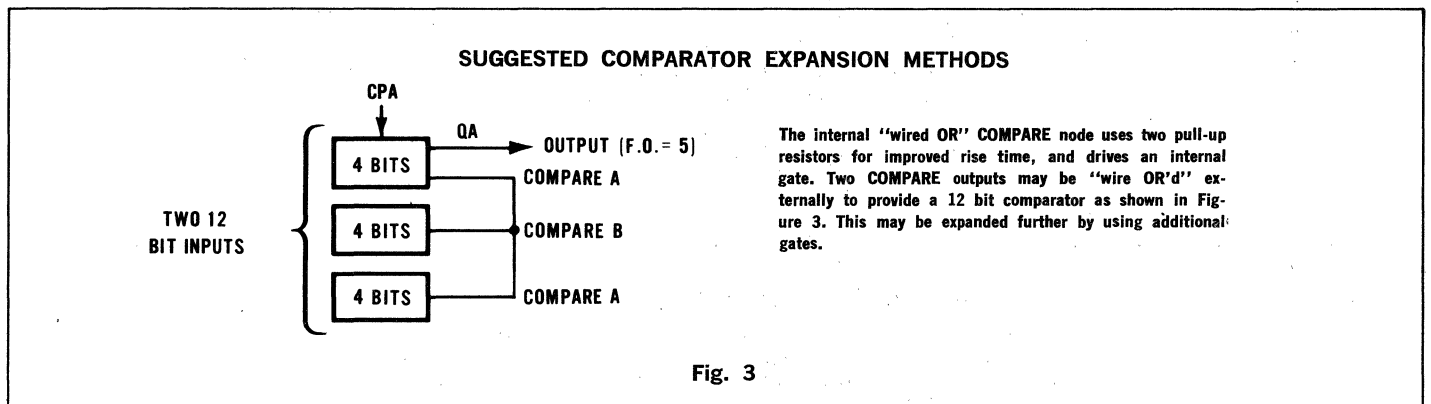


Fig. 3

## 4510 EQUIVALENT CIRCUITS

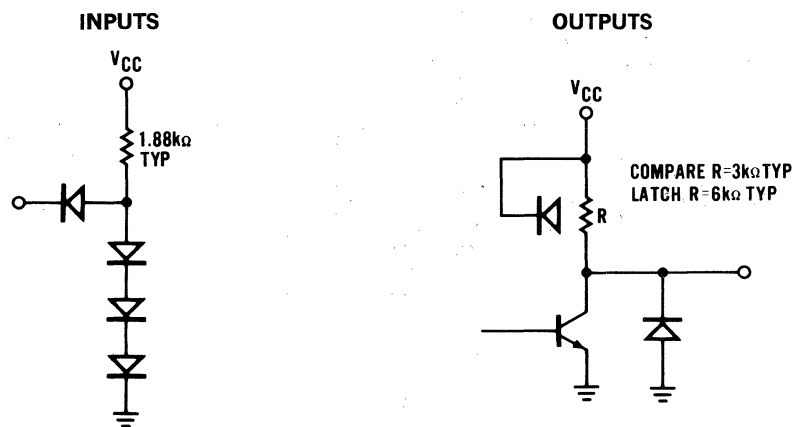


Fig. 4

# FAIRCHILD 4510 MICROMATRIX™ CIRCUIT

## LOADING RULES

### INPUT LOADING RULES (FAN-IN) DT $\mu$ L UNIT LOADS

	51X	59X
Data Inputs	2.0	2.0
Strobe Inputs	2.0	2.0
“Wired AND” A = B Outputs (ST GND)	1.5	1.5
A = B Outputs (ST High)	2.5	2.5

### OUTPUT DRIVE CAPABILITY (FAN-OUT)

	DT $\mu$ L LOADS				TT $\mu$ L LOADS			
	ST = GND		ST = HIGH		ST = GND		ST = HIGH	
	51X	59X	51X	59X	51X	59X	51X	59X
Q OUTPUT	4.0	5.0	4.0	5.0	3.0	3.0	3.0	3.0
A = B Outputs	4.0	5.0	3.0	4.0	4.0	5.0	3.0	4.0
(1) “Wired AND” 2	2.5	3.5	1.5	2.5	2.5	3.5	1.5	2.5
(1) “Wired AND” 3	1.0	2.0	0	1.0	1.0	2.0	0	1.0

(1) “Wired AND” 2 and 3 means the number of compare outputs (A = B) that are connected together. The result of this “Wired AND” connection, logically, is a high level true “AND” gate.

### 4-BIT COMPARATOR AND LAMP/RELAY DRIVER

One-half of a 4510 dual comparator drives a discrete driver so that when  $A_0 = B_0$ ,  $A_1 = B_1$ ,  $A_2 = B_2$ , and  $A_3 = B_3$  the lamp will light or the relay operate. This circuit might also be used for a digital printer solenoid driver. The ST input is connected through a 2 k $\Omega$  resistor to  $V_{CC}$  so that Q and A = B may be paralleled for additional driver base current.

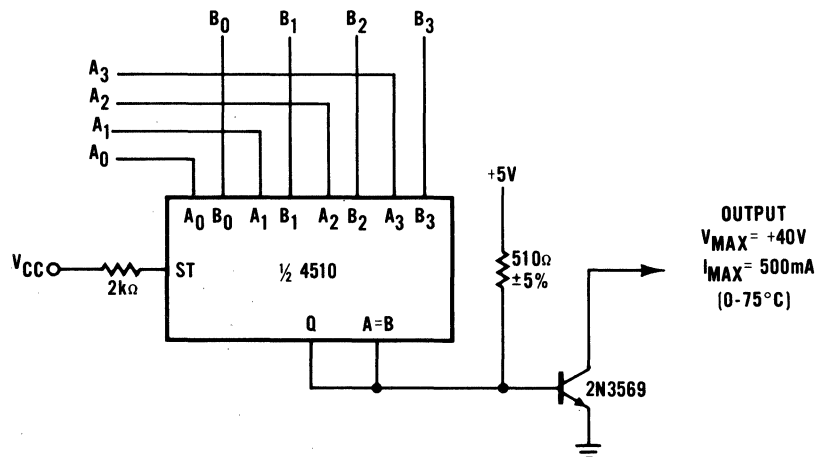


Fig. 5



# 4601

## TTL MICROMATRIX™ ARRAY INTERNAL QUARTER-CELL A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The 4601 is a single 4-4 AND-OR-INVERT (AOI) TTL gate to be used for breadboarding logic designs planned for the 4600 or 4700 Micromatrix™ arrays. The 4601 corresponds to one of the quarter-cell gate elements that are intended for internal (on-chip) usage on the 4600 or 4700 arrays. Standard family TTL gates such as the 9002 through 9008 may be used to breadboard the quarter-cells having external drive capability. The TTL 9006 may be used to extend the 4601 at the OR tie points.

### FEATURES

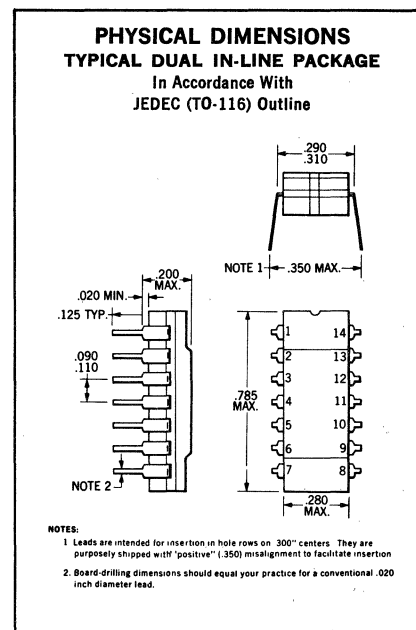
- "INTERNAL" TYPE LOGIC GATES FOR BREADBOARDING 4600 OR 4700 MICROMATRIX ARRAY DESIGNS
- CCSL COMPATIBLE
- OR EXTENDABLE WITH TTL 9006
- FANOUT = 7 INTERNAL LOADS OR 4.5 EXTERNAL LOADS
- "WIRED-AND" OUTPUT CAPABILITY
- INPUT CLAMP DIODES FOR RINGING ATTENUATION

### ABSOLUTE MAXIMUM RATINGS (above which useful life may be impaired)

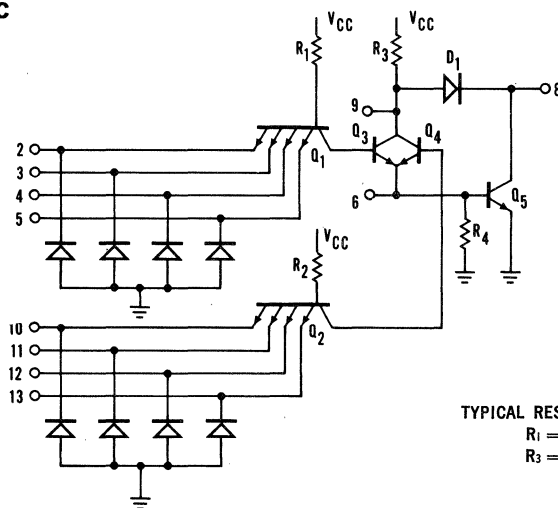
Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
V <sub>CC</sub> Pin Potential Referenced to Ground	-0.5 V to 7 V
Input Voltage Applied to Input	-0.5 V to 5.5 V
Voltage Applied to Output When Output is High	V <sub>CC</sub>
Input Current Into Inputs	5 mA
Current Into Output When Output is Low	30 mA
Lead Temperature (soldering, 60 seconds)	300°C

**ORDER INFORMATION** — Specify A6A46015XX where 5XX is 51X for -55°C to +125°C temperature range and V<sub>CC</sub> = 5 V ±10%; and 59X for 0°C to 75°C temperature range and V<sub>CC</sub> = 5 V ±5%.

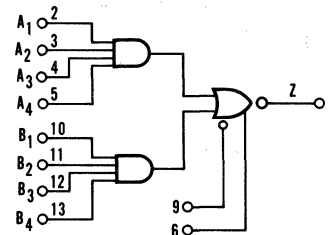
To order the 4600 Design Kit, specify A6A4600KTX. For the 4700 Design Kit, specify A6A4700KTX.



### CIRCUIT SCHEMATIC



### LOGIC DIAGRAM



PIN 14 = V<sub>CC</sub>  
PIN 7 = GND  
PIN 1 = NOT USED

Logic Equation:  $Z = \overline{A_1 A_2 A_3 A_4 + B_1 B_2 B_3 B_4 + \dots}$   
\* More terms are provided with OR extension

# TTL MICROMATRIX™ ARRAY INTERNAL QUARTER-CELL 4601

## ELECTRICAL CHARACTERISTICS:

Temperature Range: 0°C to +75°C  
Supply Voltage Range: 5 V ±5%

SYMBOL	CHARACTERISTIC	LIMITS						UNITS	CONDITIONS	
		0°C		25°C		75°C				
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.			MAX.
V <sub>OH</sub>	Output High Voltage	2.3		2.3	2.8		2.3		V V <sub>CC</sub> = 4.75 V, I <sub>OH</sub> = -600 μA V <sub>IL</sub> On Inputs	
V <sub>OL</sub>	Output Low Voltage Internal Loading		0.6		0.42	0.6		0.6	V V <sub>CC</sub> = 5.25 V, I <sub>OL</sub> = 10.7 mA	
	Output Low Voltage External CCSL Loading		0.4		0.3	0.4		0.4	V V <sub>CC</sub> = 4.75 V, I <sub>OL</sub> = 9.3 mA V <sub>CC</sub> = 5.25 V, I <sub>OL</sub> = 7.3 mA V <sub>CC</sub> = 4.75 V, I <sub>OL</sub> = 6.4 mA	
V <sub>IH</sub>	Input High Voltage	1.9		1.8			1.6		V Guaranteed Input High Threshold For All Inputs	
V <sub>IL</sub>	Input Low Voltage		0.8			0.8		0.8	V Guaranteed Input Low Threshold For All Inputs	
I <sub>F</sub>	Input Load Current Internal V <sub>F</sub> Level		-1.52		-1.00	-1.52		-1.52	mA V <sub>CC</sub> = 5.25 V	V <sub>F</sub> = 0.6 V
			-1.33		-0.87	-1.33		-1.33	mA V <sub>CC</sub> = 4.75 V	
	Input Load Current External CCSL V <sub>F</sub> Level		-1.60		-1.08	-1.60		-1.60	mA V <sub>CC</sub> = 5.25 V	V <sub>F</sub> = 0.45 V
			-1.41		-0.91	-1.41		-1.41	mA V <sub>CC</sub> = 4.75 V	
I <sub>R</sub>	Input Leakage Current				5.0	60		60	μA V <sub>CC</sub> = 5.25 V, V <sub>R</sub> = 4.5 V	
P <sub>D</sub>	Power Dissipation				21	30			mW Inputs Open	V <sub>CC</sub> = 5.0 V
					11	16			mW Inputs Grounded	

## ELECTRICAL CHARACTERISTICS:

Temperature Range: -55°C to +125°C  
Supply Voltage Range: 5 V ±10%

SYMBOL	CHARACTERISTIC	LIMITS						UNITS	CONDITIONS	
		-55°C		25°C		125°C				
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.			MAX.
V <sub>OH</sub>	Output High Voltage	2.3		2.3	2.55		2.3		V V <sub>CC</sub> = 4.5 V, I <sub>OH</sub> = -600 μA V <sub>IL</sub> On Inputs	
V <sub>OL</sub>	Output Low Voltage Internal Loading		0.55		0.42	0.55		0.55	V V <sub>CC</sub> = 5.5 V, I <sub>OL</sub> = 10.7 mA V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 8.2 mA	
	Output Low Voltage External CCSL Loading		0.4		0.3	0.4		0.4	V V <sub>CC</sub> = 5.5 V, I <sub>OL</sub> = 7.3 mA V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 5.6 mA	
V <sub>IH</sub>	Input High Voltage	2.0		1.7			1.4		V Guaranteed Input High Threshold For All Inputs	
V <sub>IL</sub>	Input Low Voltage		0.8			0.8		0.7	V Guaranteed Input Low Threshold For All Inputs	
I <sub>F</sub>	Input Load Current Internal V <sub>F</sub> Level		-1.52		-1.04	-1.52		-1.52	mA V <sub>CC</sub> = 5.5 V	V <sub>F</sub> = 0.55 V
			-1.17		-0.8	-1.17		-1.17	mA V <sub>CC</sub> = 4.5 V	
	Input Load Current External CCSL V <sub>F</sub> Level		-1.60		-1.1	-1.60		-1.60	mA V <sub>CC</sub> = 5.5 V	V <sub>F</sub> = 0.4 V
			-1.24		-0.85	-1.24		-1.24	mA V <sub>CC</sub> = 4.5 V	
I <sub>R</sub>	Input Leakage Current				5.0	60		60	μA V <sub>CC</sub> = 5.5 V, V <sub>R</sub> = 4.5 V	
P <sub>D</sub>	Power Dissipation				21	30			mW Inputs Open	V <sub>CC</sub> = 5.0 V
					11	16			mW Inputs Grounded	

## LOADING RULES

### FAN-OUT (See table):

The internal or "on-chip" fan-out of the 4601 is specified with reduced noise margins since on-chip noise is low. If the 4601 is used specifically for off-chip driving, the maximum fan-out must be reduced to maintain CCSL noise margins.

### EXTENSION:

Extension at the 4601 OR extender pins 9 and 6 may be accomplished with TTμL 9006 dual 4 input extender elements. A maximum of 10 extenders (5-9006's) may be tied to the 4601 pins. (See Fig. 1)

### WIRED "AND":

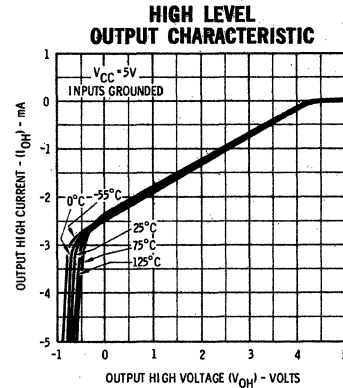
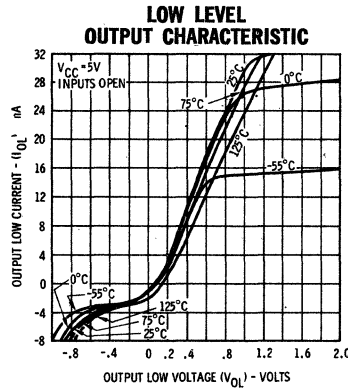
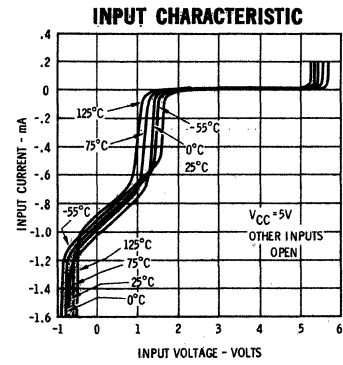
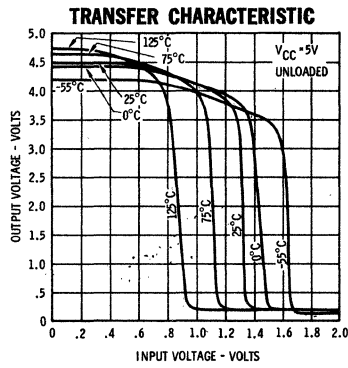
Since the 4601 internal gates have resistive pull-ups, the AND tie of outputs is allowed. (See Fig. 4).  
Breadboarding of the combined outputs is:  
FAN-OUT = 7 - (3) (number of outputs tied together - 1)  
For "on array" usage optional pull-up resistors allow fan-out as summarized below:

### FAN-OUT TABLE

LOADING TYPE	FAN-OUT
INTERNAL	7
TTμL	4.5
DTμL	4.5
LPDTμL	45

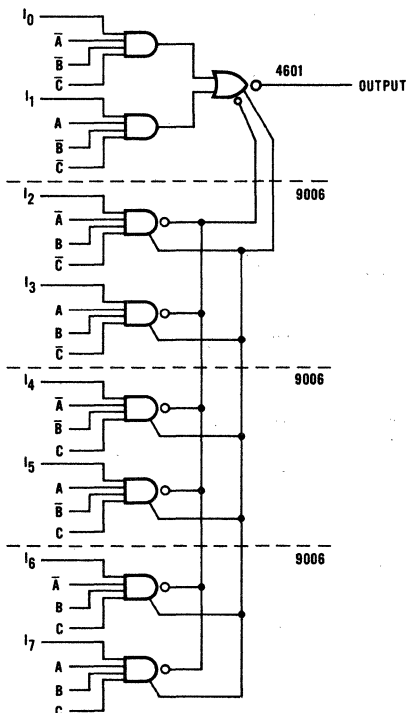
# TTL MICROMATRIX™ ARRAY INTERNAL QUARTER-CELL 4601

## TYPICAL INPUT-OUTPUT CHARACTERISTICS



## TYPICAL APPLICATIONS

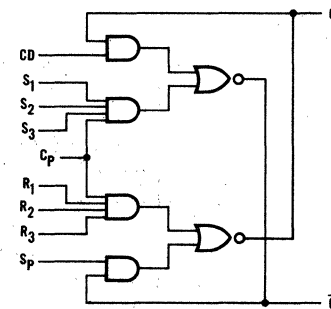
**EIGHT INPUT DIGITAL MULTIPLEXER USING "OR" EXTENSION**



**Fig. 1**

Three bit address ABC selects an input ( $I_0, I_1, \dots, I_7$ ) which is presented at the output in inverted form. The 4601 is OR-expanded using 3-9006 extender elements.

**GATED LATCH USING TWO 4601**



**Fig. 2**

# 4610

## DUAL TWO-VARIABLE FUNCTION GENERATOR TTL MICROMATRIX™ ARRAY CIRCUIT

### A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION**—The 4610 is a Dual Two-Variable Function Generator useful for non-arithmetic operations and variable decision making control in central processor units. Each circuit, controlled by a common 4-bit word, can select one of 16 possible Boolean functions performed on the two variable inputs. An alternate input select configuration increases circuit flexibility and allows simultaneous generation of two separate output functions from a single pair of variables. The circuit is produced with two layer metal interconnection using the Fairchild 4600 TTL Micromatrix™ Array.

**FEATURES**

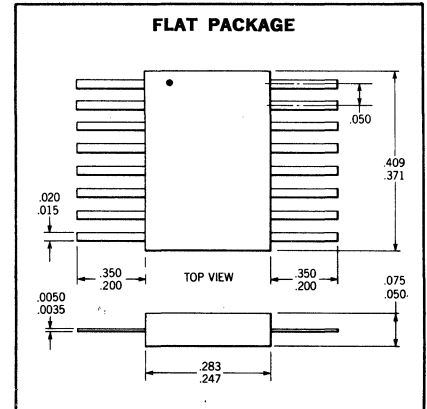
- EXPANDABLE IN GROUPS OF 2 BITS
- MEMBER OF 4600 MICROMATRIX ARRAY FAMILY
- CCSL COMPATIBLE
- ALL CERAMIC "HERMETIC" 16-PIN FLAT PACK
- TWO LAYER METAL INTERCONNECTIONS
- SIMULTANEOUS FUNCTIONS OF 1 PAIR OF VARIABLES

**ABSOLUTE MAXIMUM RATINGS** (above which the useful life may be impaired)

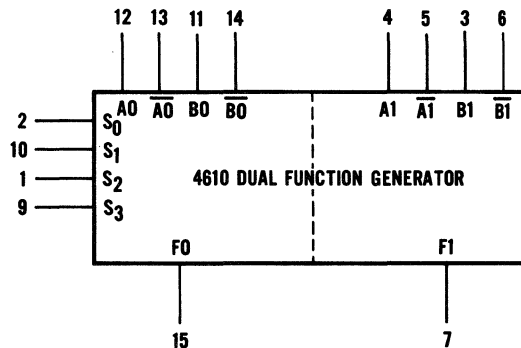
Storage Temperature	-65°C to +150°C
Temperature (Case) Under Bias	-55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5 V to +7 V
Voltage Applied to Outputs (Output high)	Gnd to +V <sub>CC</sub> value
Input Voltage (DC) (See Note 1)	-0.5 V to +5.5 V
Input Current (DC) (See Note 1)	-30 mA to +5 mA
Current into Output (Output low)	+30 mA

Note 1—either Input Voltage limit or Input Current limit is sufficient to protect the inputs.

**ORDER INFORMATION** — Specify A3L46105XX for Flat package, where 51X is for -55°C to +125°C (Case) temperature range or 59X for the 0°C to +75°C (Case) temperature range.



**FIG. 1 — 4610 DUAL TWO-VARIABLE FUNCTION GENERATOR**



Pin 16 = V<sub>CC</sub>  
Pin 8 = Gnd

# FAIRCHILD 4610 MICROMATRIX™ ARRAY CIRCUIT

## ELECTRICAL CHARACTERISTICS ( $T_C = -55^\circ\text{C}$ to $+125^\circ\text{C}$ , $V_{CC} = 5.0\text{ V} \pm 10\%$ )

SYMBOL	CHARACTERISTIC	LIMITS			UNITS	CONDITIONS
		-55°C MIN. MAX.	+25°C MIN. TYP. MAX.	+125°C MIN. MAX.		
$V_{OH}$	Output High Voltage	2.4	2.4	2.4	Volts	$V_{CC} = 4.5\text{ V}$ , $I_{OH} = -1.2\text{ mA}$
$V_{OL}$	Output Low Voltage	0.45	0.45	0.45	Volts	$V_{CC} = 5.5\text{ V}$ , $I_{OL} = 12.8\text{ mA}$ $V_{CC} = 4.5\text{ V}$ , $I_{OL} = 9.92\text{ mA}$
$V_{IH}$	Input High Voltage	2.0	1.7	1.4	Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage	0.8	0.9	.75	Volts	Guaranteed input low threshold for all inputs
$I_F$ (See Loading Rules Note 1)	Input Load Current	-1.60	-1.1 -1.60	-1.60	mA	$V_{CC} = 5.5\text{ V}$ $V_F = 0.45\text{ V}$
	One Low Level Unit Load	-1.24	-0.85 -1.24	-1.24	mA	$V_{CC} = 4.5\text{ V}$
$I_R$ (See Loading Rules Note 2)	Input Leakage Current		5.0 60	60	$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ , $V_R = 4.5\text{ V}$
$P_D$	Power Dissipation		375 500		mW	$V_{CC} = 5.0\text{ V}$ , Inputs open
$t_{12}$	Avg. Propagation Delay		20		ns	$V_{CC} = 5.0\text{ V}$ $C_L = 20\text{ pf}$ , $R_L = 1\text{ k}$

## ELECTRICAL CHARACTERISTICS ( $T_C = 0^\circ\text{C}$ to $+75^\circ\text{C}$ , $V_{CC} = 5.0\text{ V} \pm 5\%$ )

SYMBOL	CHARACTERISTIC	LIMITS			UNITS	CONDITIONS
		0°C MIN. MAX.	+25°C MIN. TYP. MAX.	+75°C MIN. MAX.		
$V_{OH}$	Q Output High Voltage	2.4	2.4	2.4	Volts	$V_{CC} = 4.75\text{ V}$ , $I_{OH} = -1.2\text{ mA}$
$V_{OL}$	Output Low Voltage	0.45	0.45	0.45	Volts	$V_{CC} = 5.25\text{ V}$ , $I_{OL} = 12.8\text{ mA}$ $V_{CC} = 4.75\text{ V}$ , $I_{OL} = 11.3\text{ mA}$
$V_{IH}$	Input High Voltage	1.9	1.8	1.6	Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage	0.85	0.85	0.85	Volts	Guaranteed input low threshold for all inputs
$I_F$ (See Loading Rules Note 1)	Input Load Current	-1.60	-1.08 -1.60	-1.60	mA	$V_{CC} = 5.25\text{ V}$ $V_F = 0.45\text{ V}$
	One Low Level Unit Load	-1.41	-0.91 -1.41	-1.41	mA	$V_{CC} = 4.75\text{ V}$
$I_R$ (See Loading Rules Note 2)	Input Leakage Current		60	60	$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ , $V_R = 4.5\text{ V}$
$P_D$	Power Dissipation		375 500		mW	$V_{CC} = 5.0\text{ V}$ , Inputs open
$t_{12}$	Avg. Propagation Delay		20		ns	$V_{CC} = 5.0\text{ V}$ $C_L = 20\text{ pf}$ , $R_L = 1\text{ k}$

# FAIRCHILD 4610 MICROMATRIX™ ARRAY CIRCUIT

## FUNCTION GENERATOR DESCRIPTION

A detailed logic representation of the common control ( $S_0, S_1, S_2, S_3$ ) and one of the two output function blocks is shown in Figure 2. The Truth Table implemented by the function generator shows the functions of input variables A and B with the 16 possible combinations of  $S_0, S_1, S_2,$  and  $S_3$  (refer to Table 1). Note that any desired output function may be chosen active level high or active level low.

**FUNCTION GENERATOR  
TRUTH TABLE  
WITH INPUT VARIABLES  
ACTIVE HIGH**

$S_0$	$S_1$	$S_2$	$S_3$	FUNCTION (ACTIVE LOW)	FUNCTION (ACTIVE HIGH)
L	L	L	L	$A + B$	$\bar{A} \cdot \bar{B}$
L	H	L	L	$A + \bar{B}$	$\bar{A} \cdot B$
H	L	L	L	$\bar{A} + B$	$A \cdot \bar{B}$
H	H	L	L	$\bar{A} + \bar{B}$	$A \cdot B$
L	L	L	H	$\bar{A} \cdot \bar{B}$	$A + B$
L	H	L	H	$\bar{A} \cdot B$	$A + \bar{B}$
H	L	L	H	$A \cdot \bar{B}$	$\bar{A} + B$
H	H	L	H	$A \cdot B$	$\bar{A} + \bar{B}$
L	L	H	L	$A \oplus B$	$A \oplus \bar{B}$
L	H	H	L	$A \oplus \bar{B}$	$A \oplus B$
H	L	H	L	1	0
H	H	H	L	0	1
L	L	H	H	A	$\bar{A}$
L	H	H	H	B	$\bar{B}$
H	L	H	H	$\bar{A}$	A
H	H	H	H	$\bar{B}$	B

TABLE 1

**DETAILED LOGIC DIAGRAM**

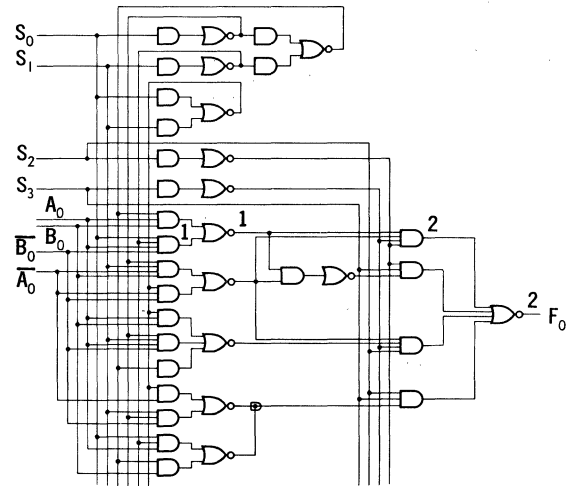


FIG. 2

Circuit flexibility can be increased by using  $S_2, S_3, A$  and  $B$  inputs as controls and  $S_0, S_1$  as the input variables. In this mode of operation two separate output functions are performed simultaneously on a single pair of variables  $S_0$  and  $S_1$ . Refer to Table 2 below for complete truth table.

For example, if it is desired to obtain the active high functions  $\bar{S}_0 \cdot S_1$  and  $S_0 \cdot \bar{S}_1$  simultaneously,  $S_2, S_3$  are set low,  $A_0$  low,  $B_0$  high,  $A_1$  high, and  $B_1$  low. The function  $\bar{S}_0 \cdot S_1$  will appear at the  $F_0$  output; likewise function  $S_0 \cdot \bar{S}_1$  will appear at the  $F_1$  output.

**FUNCTION GENERATOR TRUTH TABLE WITH INPUT VARIABLES ACTIVE HIGH  
WHERE A, B,  $S_2, S_3$  ARE USED AS CONTROL INPUTS AND  $S_0, S_1$  ARE INPUT  
VARIABLES ON WHICH THE FUNCTIONS ARE PERFORMED.**

$S_2$	$S_3$	A	B	FUNCTION (ACTIVE LOW)	FUNCTION (ACTIVE HIGH)
L	L	L	L	$S_0 + S_1$	$\bar{S}_0 \cdot \bar{S}_1$
L	L	L	H	$S_0 + \bar{S}_1$	$\bar{S}_0 \cdot S_1$
L	L	H	L	$\bar{S}_0 + S_1$	$S_0 \cdot \bar{S}_1$
L	L	H	H	$\bar{S}_0 + \bar{S}_1$	$S_0 \cdot S_1$
L	H	L	L	$\bar{S}_0 \cdot \bar{S}_1$	$S_0 + S_1$
L	H	L	H	$\bar{S}_0 \cdot S_1$	$S_0 + \bar{S}_1$
L	H	H	L	$S_0 \cdot \bar{S}_1$	$\bar{S}_0 + S_1$
L	H	H	H	$S_0 \cdot S_1$	$\bar{S}_0 + \bar{S}_1$
H	L	L	L	$S_0 \oplus S_1$	$S_0 \oplus \bar{S}_1$
H	L	L	H	$\bar{S}_1$	$S_1$
H	L	H	L	$S_1$	$\bar{S}_1$
H	L	H	H	$S_0 \oplus S_1$	$S_0 \oplus \bar{S}_1$
H	H	L	L	$S_0$	$\bar{S}_0$
H	H	L	H	$S_0 \oplus S_1$	$S_0 \oplus \bar{S}_1$
H	H	H	L	$S_0 \oplus \bar{S}_1$	$S_0 \oplus S_1$
H	H	H	H	$\bar{S}_0$	$S_0$

TABLE 2

Note that by varying control lines  $S_2, S_3, A$  and  $B$  that any pair of  $S_0$  and  $S_1$  min terms, max terms, or symmetric function can be generated.

# FAIRCHILD 4610 MICROMATRIX™ ARRAY CIRCUIT

## LOADING RULES

### Input Loading Rules (Fan-in)

1.  $I_L$  is defined as one low level unit load. The multipliers to determine low level unit loads for individual inputs are:

INPUT	MULTIPLIER
$S_1$	8
$S_0$	6
$S_2, S_3$	5
$A_0, A_1, B_0, B_1$ $\overline{B_0}, \overline{B_1}$	4
$\overline{A_0}, \overline{A_1}$	3

2.  $I_H$  is defined as one unit high level load. The multipliers to determine high level unit loads for individual inputs are:

INPUT	MULTIPLIER
$S_1$	8
$S_0$	6
$A_0, A_1, S_2, S_3$	5
$\overline{B_0}, \overline{B_1}, B_0, B_1$	4
$\overline{A_0}, \overline{A_1}$	3

### FAN OUT

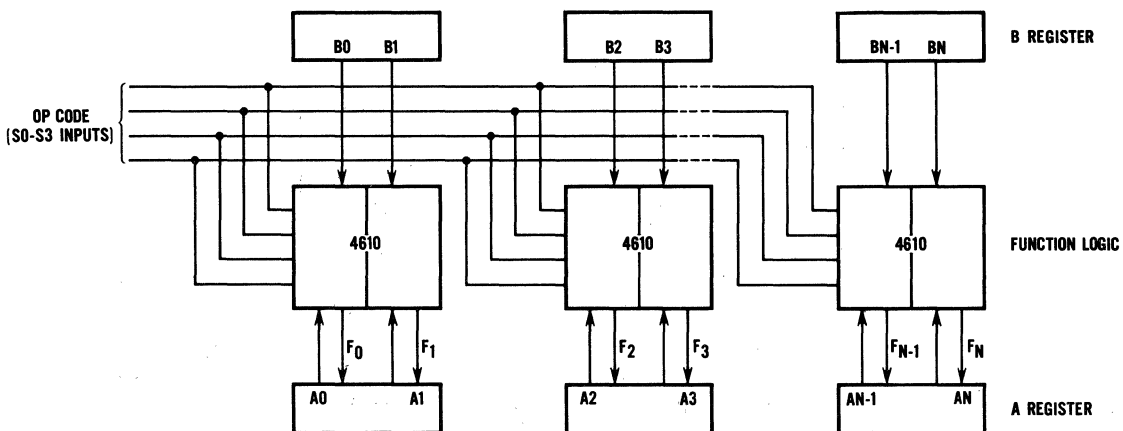
OUTPUT	LEVEL	
	HIGH	LOW
$F_0$	20	8
$F_1$	20	8

## APPLICATIONS

A Typical Processor Application is the transfer and logical operation control between two registers (A and B). The function generators are controlled by a 4-bit operation code field,  $S_0, S_1, S_2,$  and  $S_3$ . The operation code repertoire includes the 16 operations listed below.

AND $\overline{A}$ and $\overline{B}$ to A AND $\overline{A}$ and B to A AND A and $\overline{B}$ to A AND A and B to A	OR A and B to A OR A and $\overline{B}$ to A OR $\overline{A}$ and B to A OR $\overline{A}$ and $\overline{B}$ to A
Exclusive OR A and $\overline{B}$ to A Exclusive OR A and B to A Reset A Set A	Complement A Transfer $\overline{B}$ to A No Operation Transfer B to A

FIG. 3



# TRANSISTOR-TRANSISTOR MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

MILITARY TEMPERATURE RANGE:  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$

## GENERAL DESCRIPTION

The Fairchild Transistor-Transistor Micrologic<sup>®</sup> Integrated Circuit family ( $\text{TT}\mu\text{L}$ ) combines a high fanout, high noise immunity, low power dissipation and good capacitive load driving capability with low propagation delay times.

The circuits are fabricated within a silicon monolithic substrate using standard Fairchild Planar<sup>†</sup> Epitaxial processes.

$\text{TT}\mu\text{L}$  elements are available in two hermetically sealed ceramic packages; the Dual In-Line Package (DIP), designed for automated and low cost insertion techniques, and the 14 lead CERPAK<sup>®</sup> flat package.

Worst case curves of important device characteristics are offered to assist the designer in achieving maximum system reliability. For additional information refer to Application note No. 131.

## FEATURES

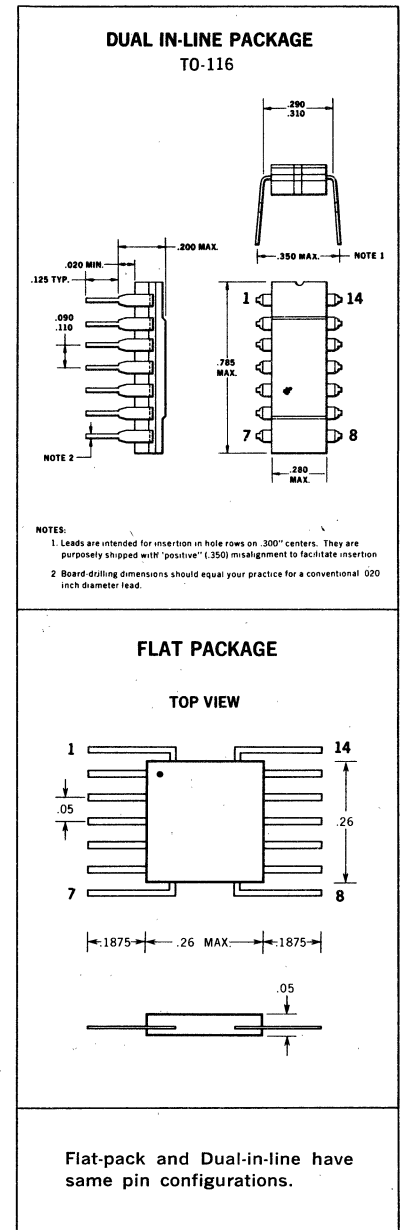
- Single power supply requirement; 5 volts optimum, 4.5 to 5.5 volt range.
- Reliable operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ .
- Guaranteed fanout of 10  $\text{TT}\mu\text{L}$  loads over the full temperature and supply voltage range.
- Guaranteed minimum of 0.4 volt noise immunity at the temperature extremes.
- Typical "one" level noise immunity of 1.3 volts and "zero" level noise immunity of 0.8 volt.
- Typical power dissipation of 11 mW per gate at a 50% duty cycle.
- Typical logic gate propagation delays of 6 ns for 15 pF, 11 ns for 150 pF of capacitance.
- The unique output pull-up circuitry gives a higher output "one" level and can provide more output high current at low temperatures than conventional pull-ups.
- The input threshold of 1.5 volts and  $V_{\text{CC}}$  of 5 volts provides easy interfacing with the Fairchild  $\text{DT}\mu\text{L}$  family, and other DTL and TTL circuits.
- Nand gate pin configurations are compatible with  $\text{DT}\mu\text{L}$ .

## ABSOLUTE MAXIMUM RATINGS (above which the useful life may be impaired)

Storage Temperature	$-65^{\circ}\text{C}$ to $+150^{\circ}\text{C}$
Temperature (Ambient) Under Bias	$-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$
$V_{\text{CC}}$ pin potential to ground	$-.5$ to $+8\text{ V}$
Input Voltage	$-1.5$ to $+5.5\text{ V}$
Gate Output Voltage, Inputs Low	$-.5$ to $+V_{\text{CC}}$ value
Gate Current Into Output Terminal, Inputs High (except 9009)	50 mA
Gate Current Into Output Terminal, Inputs High 9009	100 mA
Flip-Flop Output Voltage when output is normally high	$-.5$ to $+V_{\text{CC}}$ value
Flip-Flop Current Into Output Terminal when output is normally low	50 mA

## ORDER INFORMATION

To order Transistor-Transistor Micrologic elements specify U31XXXX-51X for Flat package and U6AXXX51X for Dual In-Line package where XXXX is the four-digit number denoting the specific element desired.



<sup>†</sup> Planar is a patented Fairchild process.

**FAIRCHILD**  
SEMICONDUCTOR  
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION

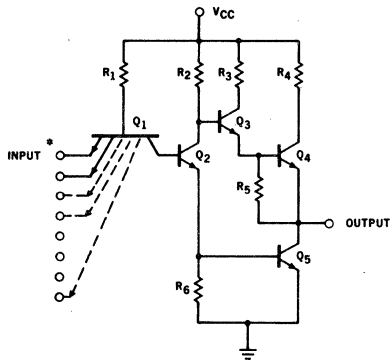


# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## GATE ELEMENTS — 9002, 9003, 9004, 9007

All TT $\mu$ L gates are positive logic NAND gates and negative logic NOR gates. A variety of gate combinations is available which provides the system designer the utmost in logic flexibility and reduces package requirements to a minimum.

### BASIC GATE CIRCUIT

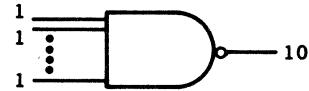


#### TYPICAL RESISTOR VALUES

- $R_1 = R_5 = 4 \text{ k}\Omega$
- $R_2 = 1.5 \text{ k}\Omega$
- $R_3 = 150 \Omega$
- $R_4 = 80 \Omega$
- $R_6 = 1.25 \text{ k}\Omega$

\*Number of inputs depends on the gate.

### LOADING RULES



The outputs CANNOT be tied together for the "wired OR" function.

Figure 1

Figure 2

### PIN CONFIGURATION

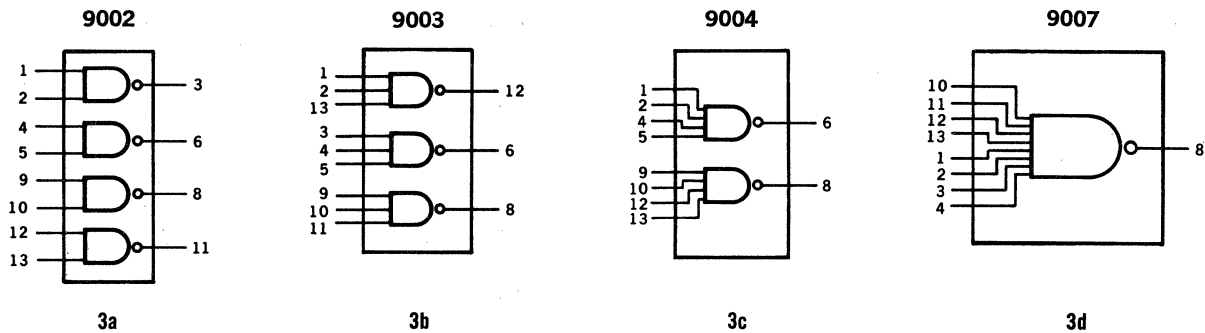


Figure 3

$V_{CC} = \text{PIN } 14$      $\text{GND} = \text{PIN } 7$

### ELECTRICAL CHARACTERISTICS

SYMBOL	CHARACTERISTIC	LIMITS						UNITS	CONDITIONS & COMMENTS	
		-55°C		25°C		125°C				
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.			MAX.
$V_{OH}$	Output High Voltage	2.4		2.4	2.7		2.4	Volts	$V_{CC} = 4.5 \text{ V}$ , $I_{OH} = 1.0 \text{ mA}$ $V_{IL} = \text{value indicated below on this table.}$	
$V_{OL}$	Output Low Voltage		0.4		0.2	0.4		0.4	$V_{CC} = 5.5 \text{ V}$ , $I_{OL} = 17.6 \text{ mA}$ $V_{CC} = 4.5 \text{ V}$ , $I_{OL} = 14.5 \text{ mA}$	
$V_{IH}$	Input High Voltage	2.0		1.7			1.4	Volts	Guaranteed input high threshold for all inputs.	
$V_{IL}$	Input Low Voltage		0.8			0.9		0.8	Volts	Guaranteed input low threshold for all inputs.
$I_F$	Input Load Current		-1.76		-1.10	-1.76		-1.76	mA	$V_{CC} = 5.5 \text{ V}$
$I_F$	Input Load Current		-1.45		-0.97	-1.45		-1.45	mA	$V_{CC} = 4.5 \text{ V}$
$I_R$	Input Leakage Current				20	60		100	$\mu\text{A}$	$V_{CC} = 5.5 \text{ V}$ , $V_R = 4.5 \text{ V}$ , Gnd. on other inputs
$t_{pd+}$	Turn Off Delay			4.0		12			ns	$V_{CC} = 5.0 \text{ V}$ , $C_L = 15 \text{ pF}$ (see fig. 5b)
$t_{pd-}$	Turn On Delay			3.0		10			ns	$V_{CC} = 5.0 \text{ V}$ , $C_L = 15 \text{ pF}$ (see fig. 5b)

# FAIRCHILD $TT\mu L$ INTEGRATED CIRCUITS

## GATE ELEMENTS — 9002, 9003, 9004, 9007 (continued)

**WORST CASE LOGIC LEVELS  
VERSUS TEMPERATURE**

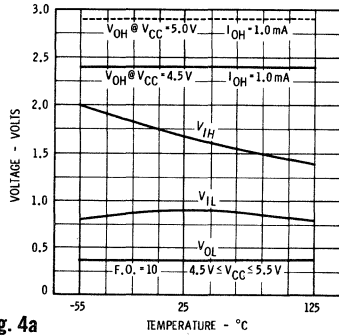


Fig. 4a

**WORST CASE  
HIGH LEVEL NOISE IMMUNITY  
VERSUS TEMPERATURE**

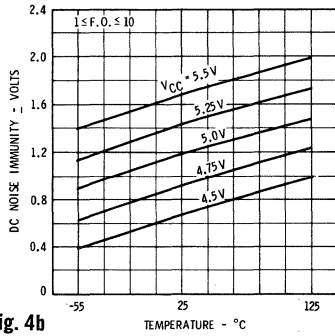


Fig. 4b

**WORST CASE  
LOW LEVEL NOISE IMMUNITY  
VERSUS TEMPERATURE**

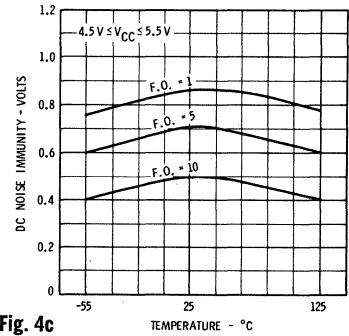


Fig. 4c

**WORST CASE POWER DISSIPATION  
VERSUS SUPPLY VOLTAGE  
(PER GATE)**

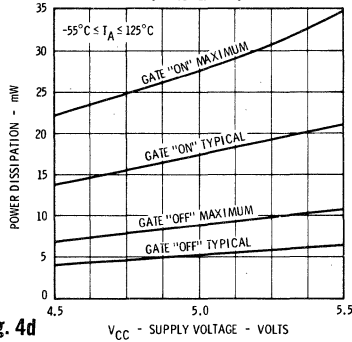


Fig. 4d

**WORST CASE POWER DISSIPATION  
VERSUS FREQUENCY (PER GATE)**

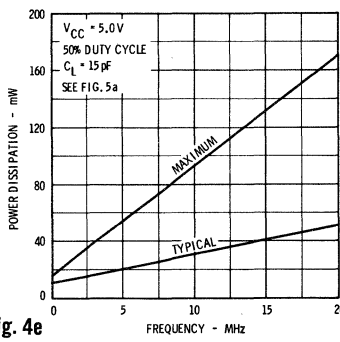


Fig. 4e

**WORST CASE TURN OFF DELAY  
VERSUS TEMPERATURE**

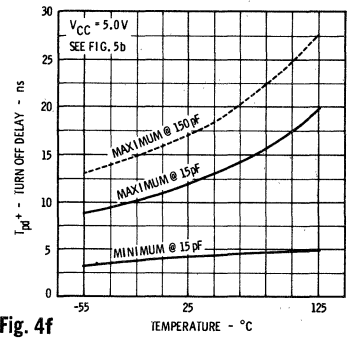


Fig. 4f

**WORST CASE TURN ON DELAY  
VERSUS TEMPERATURE**

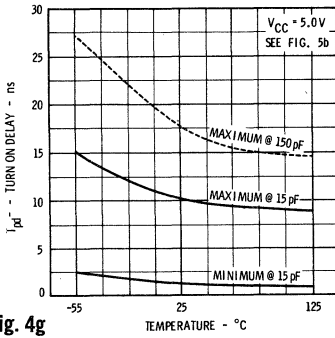


Fig. 4g

FIGURE 4

**AC POWER TEST CIRCUIT**

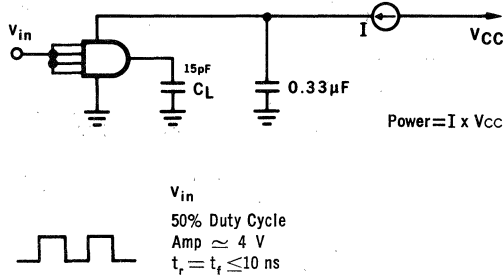


FIGURE 5a

NOTE: Capacitance includes probe and jig capacity.  
All inputs are to be tied together.

**tpd TEST CIRCUIT**

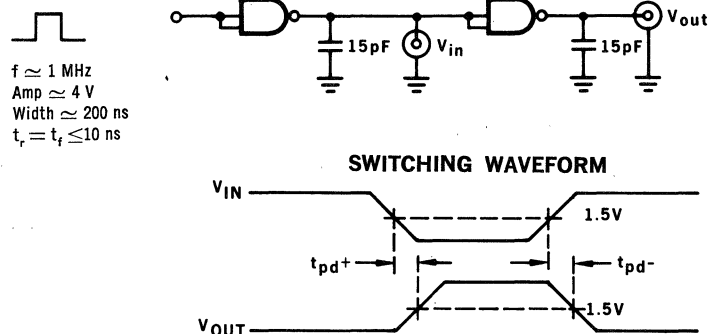


FIGURE 5b

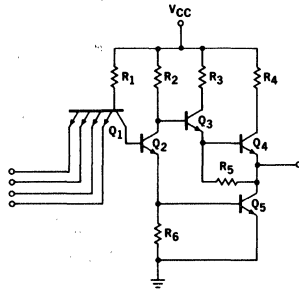
NOTE: Capacitance includes probe and jig capacity.  
All inputs are to be tied together.

# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## POWER GATE ELEMENT — 9009

The TT $\mu$ L 9009 element is a NAND power gate capable of driving and sinking large currents for high fan-out applications.

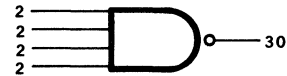
For noise immunity and operating level curves, refer to the gate section.



### TYPICAL RESISTOR VALUES

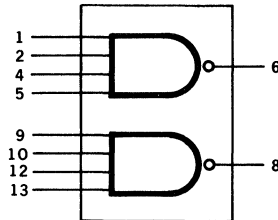
$R_1 = 2.2k\Omega$	$R_4 = 50\Omega$
$R_2 = 450\Omega$	$R_5 = 4k\Omega$
$R_3 = 150\Omega$	$R_6 = 400\Omega$

### LOADING RULES:



The outputs **CANNOT** be tied together for the "wired OR" function.

### PIN CONFIGURATION



$V_{CC} = \text{PIN } 14$      $\text{GND} = \text{PIN } 7$

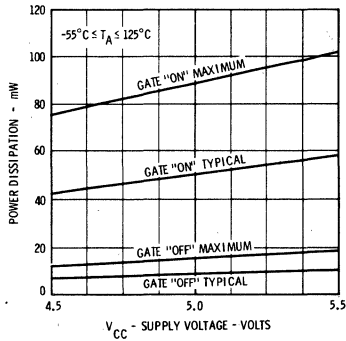
### ELECTRICAL CHARACTERISTICS

SYMBOL	CHARACTERISTIC	LIMITS						UNITS	CONDITIONS & COMMENTS
		-55°C		25°C		125°C			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.		
$V_{OH}$	Output High Voltage	2.4		2.4	2.7		2.4	Volts	$V_{CC} = 4.5 \text{ V}$ , $I_{OH} = 3.0 \text{ mA}$ $V_{IL} =$ value indicated below on this table.
$V_{OL}$	Output Low Voltage		0.4		0.2	0.4	0.4	Volts	$V_{CC} = 5.5 \text{ V}$ , $I_{OL} = 52.8 \text{ mA}$ $V_{CC} = 4.5 \text{ V}$ , $I_{OL} = 42.9 \text{ mA}$
$V_{IH}$	Input High Voltage	2.0		1.7			1.4	Volts	Guaranteed input high threshold for all inputs.
$V_{IL}$	Input Low Voltage		0.8		0.9		0.8	Volts	Guaranteed input low threshold for all inputs.
$I_F$	Input Load Current	-3.52		-1.95	-3.52		-3.52	mA	$V_{CC} = 5.5 \text{ V}$
$I_F$	Input Load Current	-2.9		-1.6	-2.9		-2.9	mA	$V_{CC} = 4.5 \text{ V}$
$I_R$	Input Leakage Current			35	120		200	$\mu\text{A}$	$V_{CC} = 5.5 \text{ V}$ , $V_R = 4.5 \text{ V}$ , Gnd. on other inputs.
$t_{pd+}$	Turn Off Delay			4.0		17		ns	$V_{CC} = 5.0 \text{ V}$ , $C_L = 15 \text{ pF}$ (see fig. 2a)
$t_{pd-}$	Turn On Delay			3.0		10		ns	$V_{CC} = 5.0 \text{ V}$ , $C_L = 15 \text{ pF}$ (see fig. 2a)

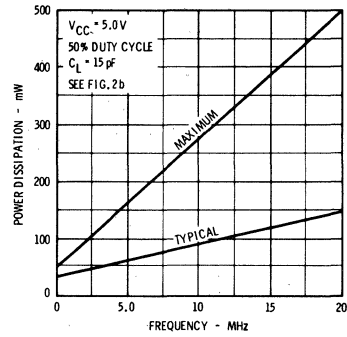
# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## POWER GATE ELEMENT — 9009 (continued)

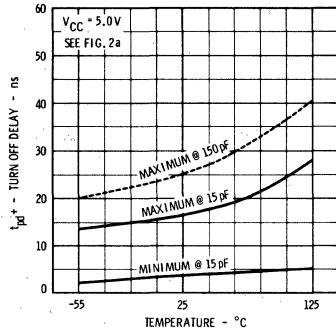
**WORST CASE POWER DISSIPATION  
VERSUS COLLECTOR SUPPLY  
VOLTAGE (PER GATE)**



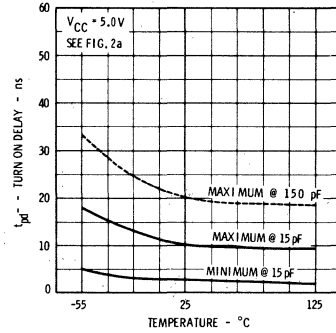
**WORST CASE POWER DISSIPATION  
VERSUS FREQUENCY (PER GATE)**



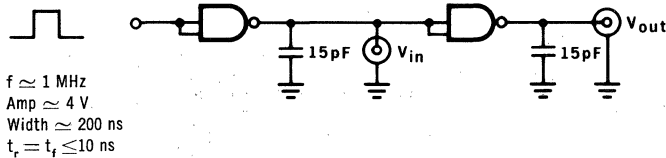
**WORST CASE TURNOFF DELAY  
VERSUS TEMPERATURE**



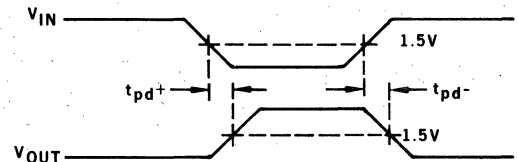
**WORST CASE TURN ON DELAY  
VERSUS TEMPERATURE**



**tpd TEST CIRCUIT**



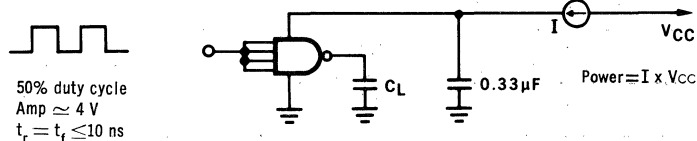
**SWITCHING WAVEFORM**



**NOTE:** Capacitance includes probe and jig capacity.  
All inputs are to be tied together.

**FIGURE 2a**

**AC POWER TEST CIRCUIT**



**NOTE:** Capacitance includes probe and jig capacity.  
All inputs are to be tied together.

**FIGURE 2b**

# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## EXPANDABLE GATES — 9005, 9006, 9008

The TT $\mu$ L 9005 and 9008 are AND-NOR gates which may be NOR expanded with the use of the 9006 element. For noise immunity and operating level curves, refer to the gate section.

**9005**

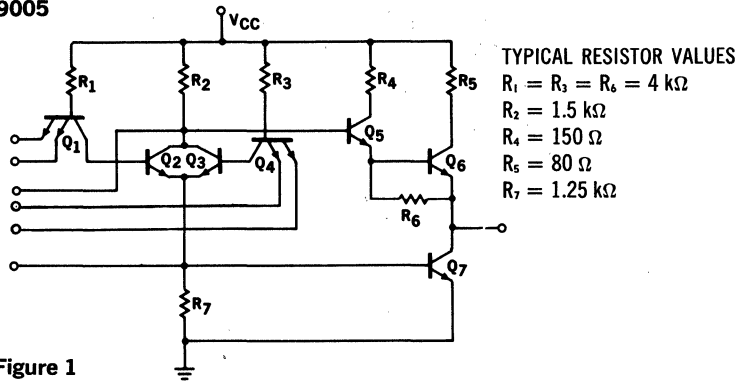
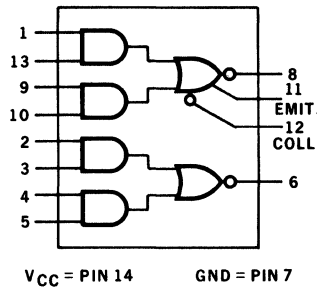
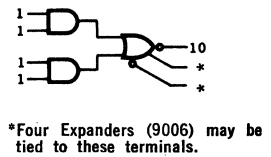


Figure 1

**PIN CONFIGURATION**



**LOADING RULES:**



**9006**

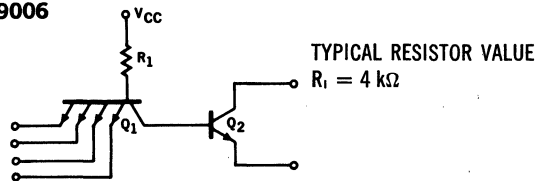
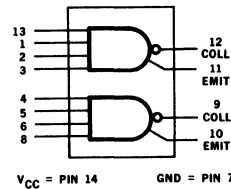
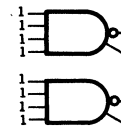


Figure 2

**PIN CONFIGURATION**



**LOADING RULES:**



**9008**

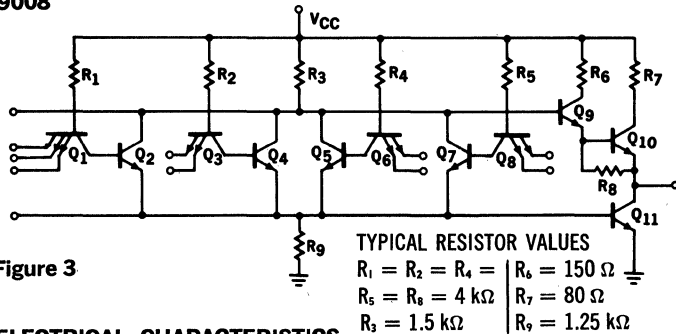
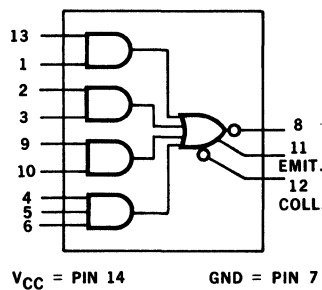
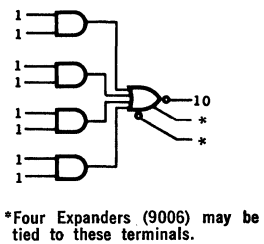


Figure 3

**PIN CONFIGURATION**



**LOADING RULES:**

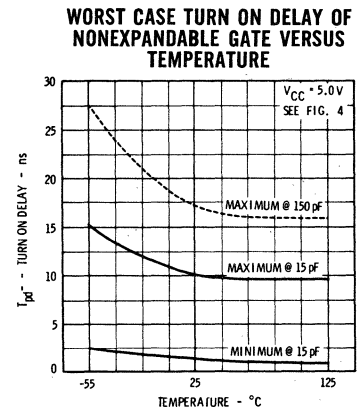
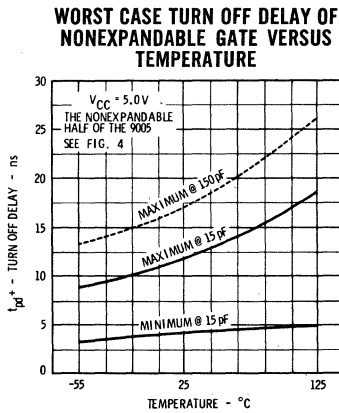
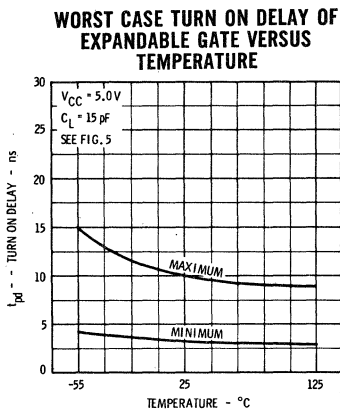
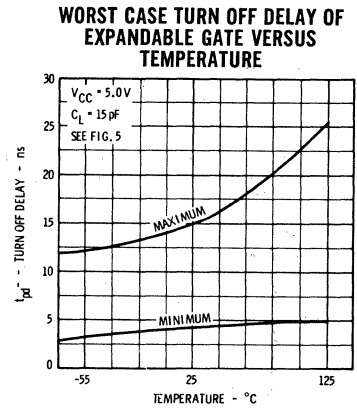
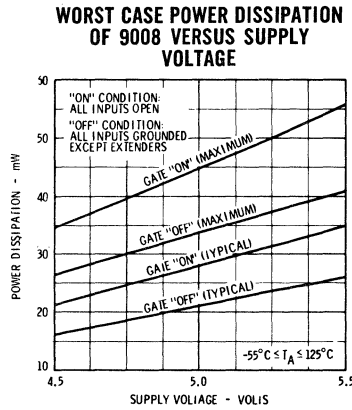
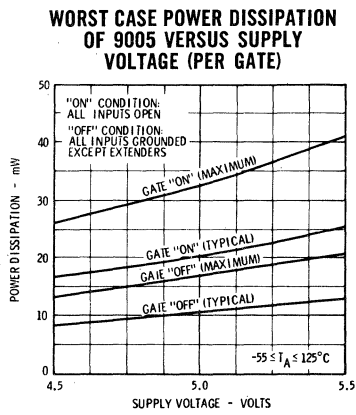


### ELECTRICAL CHARACTERISTICS

SYMBOL	CHARACTERISTIC	LIMITS						UNITS	CONDITIONS & COMMENTS
		-55°C		25°C		125°C			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.		
$V_{OH}$	Output High Voltage	2.4		2.4	2.7		2.4	Volts	$V_{CC} = 4.5\text{ V}$ , $I_{OH} = 1.0\text{ mA}$ $V_{IL} = \text{value indicated below on this table}$
$V_{OL}$	Output Low Voltage		0.4		0.2	0.4	0.4	Volts	$V_{CC} = 5.5\text{ V}$ , $I_{OL} = 17.6\text{ mA}$ $V_{CC} = 4.5\text{ V}$ , $I_{OL} = 14.5\text{ mA}$
$V_{IH}$	Input High Voltage	2.0		1.7			1.4	Volts	Guaranteed input high threshold for all inputs.
$V_{IL}$	Input Low Voltage		0.8		0.9		0.8	Volts	Guaranteed input low threshold for all inputs.
$I_F$	Input Load Current		-1.76		-1.10	-1.76	-1.76	mA	$V_{CC} = 5.5\text{ V}$
$I_F$	Input Load Current		-1.45		-0.97	-1.45	-1.45	mA	$V_{CC} = 4.5\text{ V}$
$I_R$	Input Leakage Current				20	60	100	$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ , $V_R = 4.5\text{ V}$ , Gnd. on other inputs
$t_{pd+}$	Defined in Test Circuit			4		12		ns	$V_{CC} = 5.0\text{ V}$ , $C_L = 15\text{ pF}$ Applies to 9005 nonexpandable Gate only
$t_{pd-}$	Defined in Test Circuit			3		12		ns	$V_{CC} = 5.0\text{ V}$ , $C_L = 15\text{ pF}$ Applies to 9005 nonexpandable Gate only
$t_{pd+}$	Defined in Test Circuit			4		15		ns	$V_{CC} = 5.0\text{ V}$ , $C_L = 15\text{ pF}$ , $C_N = 5.0\text{ pF}$ Applies to 9008 and 9005 Expandable Gate
$t_{pd-}$	Defined in Test Circuit			3		10		ns	$V_{CC} = 5.0\text{ V}$ , $C_L = 15\text{ pF}$ , $C_N = 5.0\text{ pF}$ Applies to 9008 and 9005 Expandable Gate
$\Delta t_{pd+}$	See Comment			0		4		ns	9006 only
$\Delta t_{pd-}$	See Comment			0		4		ns	The 9006 shall be tested by measuring its propagation time through the 9005. The $t_{pd}$ reading shall not exceed the 9005 reading by the specified amount.

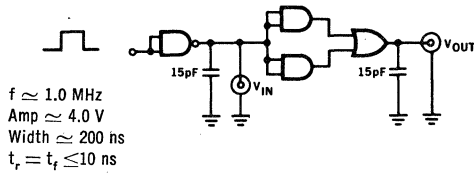
# FAIRCHILD T $\mu$ L INTEGRATED CIRCUITS

## EXPANDABLE GATES — 9005, 9006, 9008 (continued)

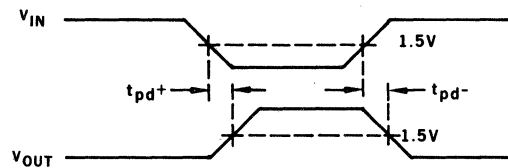


### tpd TEST CIRCUIT

#### 9005 NONEXPANDABLE GATE ONLY



### SWITCHING WAVEFORM

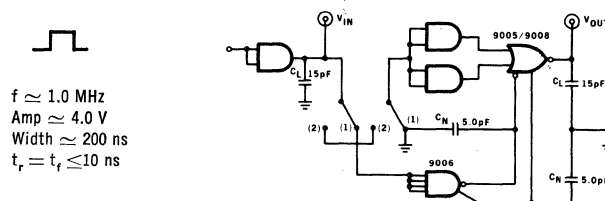


NOTE: Capacitance includes probe and jig capacity.  
All inputs are to be tied together.

Figure 4

### tpd TEST CIRCUIT

#### 9005/9008 EXPANDABLE GATE AND 9006 EXPANDER



NOTE: Position (2) is used to test 9005/9008.  
Position (1) is used to test 9006.  
Capacitance includes probe and jig capacity.

Figure 5

# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## J-K FLIP-FLOPS — 9000, 9001

**GENERAL DESCRIPTION** — The TT $\mu$ L family includes the 9000 and 9001 flip-flops to satisfy the storage element needs of a logic system. Each is a master-slave JK flip-flop with the same multi-emitter inputs and low impedance active pull-up outputs common to the gate elements.

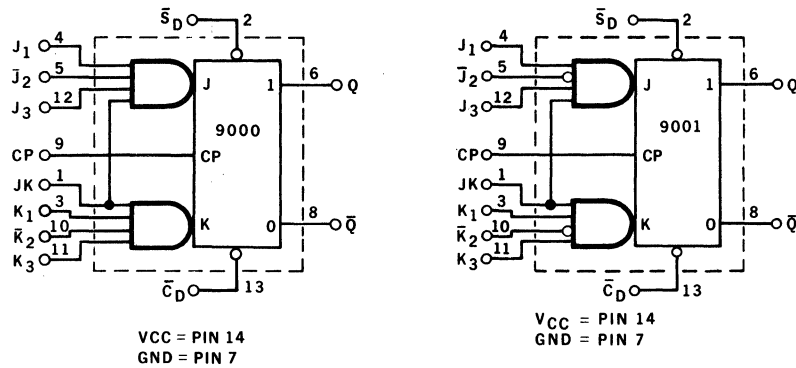
The internal JK connections assure the user of non-ambiguous operation for all input states. The master-slave design with buffered clock input offers high noise immunity, low clock loading and eliminates the need for careful control of clock pulse rise or fall times. Data is accepted by the master when the clock is in the low logic state. Transfer from master to slave occurs when the clock goes from the low to the high logic level. When the clock is in the high logic level both J and K inputs are inhibited. For this reason it is desirable to maintain the clock pulse in the high level most of the duty cycle. Direct set and reset inputs provide true asynchronous control of both master and slave flip-flops independent of logic and clock input levels.

A common J-K input is provided which is useful in the physical layout of most logic configurations.

The two circuits are identical with a few exceptions. The 9000 has capacitors at the outputs of the J and K data input gates in the master flip-flop. The capacitors serve to lengthen the time requirements between J or K data and the low-to-high clock transition. This feature makes the 9000 particularly attractive for applications where clock skew is an important consideration.

The 9001 provides one  $\bar{J}$  and one  $\bar{K}$  input for additional logic flexibility. It has no master flip-flop capacitors to extend the set-up time and therefore has a higher toggling rate.

The important characteristics of the two flip-flops are illustrated in the following curves and specifications. Noise immunity and operating level curves shown in the gate section of the data sheet are applicable to the flip-flops as well.



### LOADING RULES

FLIP-FLOP INPUTS	LOADING*
CP, J <sub>1</sub> , J <sub>2</sub> , J <sub>3</sub> , K <sub>1</sub> , K <sub>2</sub> , K <sub>3</sub> , $\bar{J}_2$ , $\bar{K}_2$ ,	1
JK	2
$\bar{S}_D$ , $\bar{C}_D$	2.7
OUTPUTS	
Q, $\bar{Q}$	10

\*1 load = 1 TT $\mu$ L Gate Input Load

### TRUTH TABLES

#### SYNCHRONOUS ENTRY J-K MODE OPERATION

JK	INPUTS @ t <sub>n</sub>			OUTPUTS @ t <sub>n+1</sub>	
	(5) J <sub>1</sub> · J <sub>2</sub> · J <sub>3</sub>	(5) K <sub>1</sub> · K <sub>2</sub> · K <sub>3</sub>		Q	$\bar{Q}$
1	4 5 12	3 10 11		6	8
L	X	X		No Change (4)	
H	L	L		No Change (4)	
H	L	H		L	H
H	H	L		H	L
H	H	H		Toggles	

#### ASYNCHRONOUS ENTRY

Independent of Clock and Synchronous Input

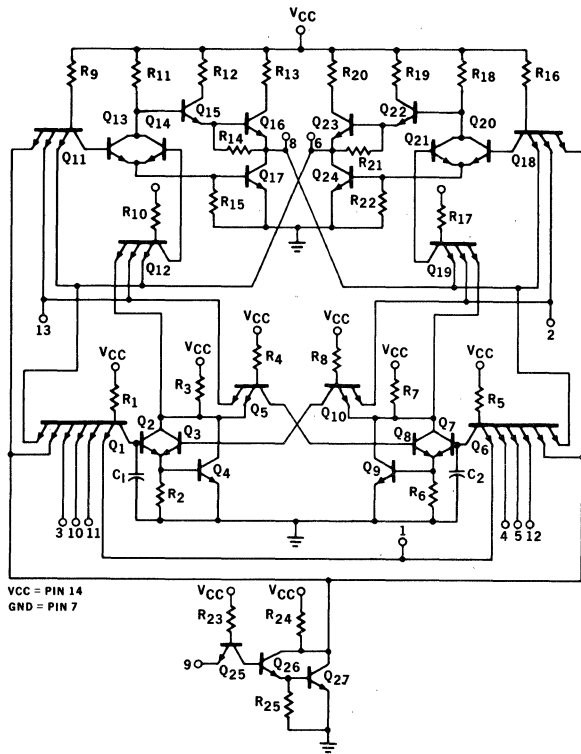
INPUTS		OUTPUTS	
$\bar{S}_D$	$\bar{C}_D$	Q	$\bar{Q}$
2	13	6	8
L	L	H	H
L	H	H	L
H	L	L	H
H	H	No Change	

#### NOTES:

- (1.) H = Most positive logic level.
- (2.) L = Most negative voltage level.
- (3.) X = Could be high or low.
- (4.) For no change of outputs, the J and K inputs or the common JK input must remain low from the time the clock goes low to the time the clock goes high again.
- (5.) The 9001 has inverted J<sub>2</sub> (Pin 5) and K<sub>2</sub> (Pin 10) inputs. When not in use, they must be grounded.

# FAIRCHILD T $\mu$ L INTEGRATED CIRCUITS

## 9000 SCHEMATIC DIAGRAM

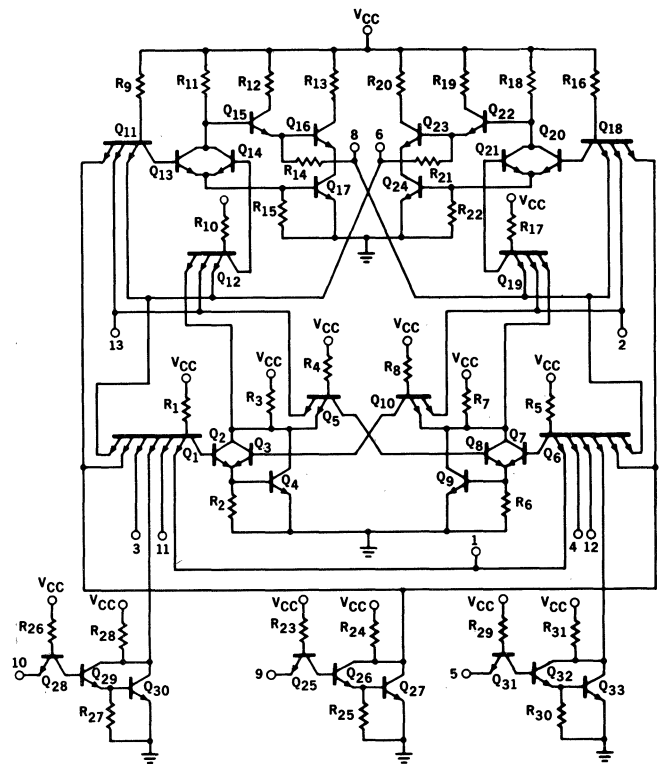


### TYPICAL COMPONENT VALUES

- $R_1, R_4, R_5, R_6, R_{10},$
- $R_{14}, R_{17}, R_{21}, R_{22}, R_{23}, R_{24} = 4 \text{ k}\Omega$
- $R_2, R_3, R_6, R_7 = 2 \text{ k}\Omega$
- $R_9, R_{16} = 6 \text{ k}\Omega$
- $R_{11}, R_{18} = 1.5 \text{ k}\Omega$
- $R_{12}, R_{19} = 150 \Omega$
- $R_{13}, R_{20} = 80 \Omega$
- $R_{15}, R_{22}, R_{25} = 1.25 \text{ k}\Omega$
- $C_1, C_2 = 10 \text{ pF}$

Figure 6

## 9001 SCHEMATIC DIAGRAM



### TYPICAL COMPONENT VALUES

- $R_1, R_4, R_5, R_6, R_{10}, R_{14}, R_{17}, R_{21},$
- $R_{22}, R_{23}, R_{24}, R_{26}, R_{29} = 4 \text{ k}\Omega$
- $R_2, R_3, R_6, R_7 = 2 \text{ k}\Omega$
- $R_9, R_{16}, R_{28}, R_{31} = 6 \text{ k}\Omega$
- $R_{11}, R_{18} = 1.5 \text{ k}\Omega$
- $R_{12}, R_{19} = 150 \Omega$
- $R_{13}, R_{20} = 80 \Omega$
- $R_{15}, R_{22}, R_{25}, R_{27}, R_{30} = 1.25 \text{ k}\Omega$

Figure 7

## 9000 AND 9001 FUNCTIONAL LOGIC DIAGRAM

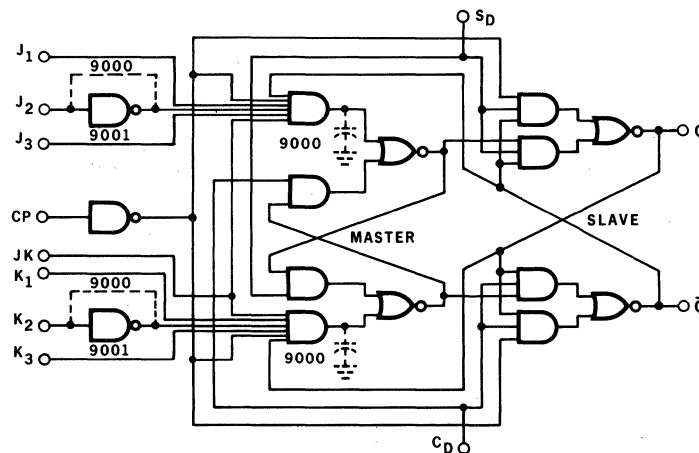


Figure 8



# FAIRCHILD TTL INTEGRATED CIRCUITS

## J-K FLIP-FLOPS — 9000, 9001 (continued)

### ELECTRICAL CHARACTERISTICS

SYMBOL	CHARACTERISTIC	LIMITS						UNITS	CONDITIONS & COMMENTS	
		-55°C		25°C		125°C				
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.			
$V_{OH}$	Output High Voltage	2.4		2.4	2.7		2.4		Volts	$V_{CC} = 4.5\text{ V}$ , $I_{OH} = 1.0\text{ mA}$ , $V_{IL}$ on asynchronous input
$V_{OL}$	Output Low Voltage		0.4		0.2	0.4		0.4	Volts	$V_{CC} = 4.5\text{ V}$ , $I_{OL} = 14.5\text{ mA}$ $V_{CC} = 5.5\text{ V}$ , $I_{OL} = 17.7\text{ mA}$
$V_{IH}$	Input High Voltage	2.0		1.7			1.4		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.8			0.9		0.8	Volts	Guaranteed input low threshold for all inputs
$I_R$ $2 I_R$ $I_{RS}$	Input Leakage Current J, K, J, K & Clock Inputs J-K Input Asynchronous Inputs				20 40 55	60 120 162		100 200 270	$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ , $V_R = 4.5\text{ V}$ , Gnd. on other inputs
$I_F$ $2 I_F$ $I_{FSI}$	Input Load Current J, K, J, K & Clock Inputs J-K Input Asynchronous Inputs	-1.76 -3.52 -4.75		-1.1 -2.2 -3.0	-1.76 -3.52 -4.75			-1.76 -3.52 -4.75	mA	$V_{CC} = 5.5\text{ V}$ $V_{CC} = 5.5\text{ V}$ $V_{CC} = 5.5\text{ V}$
$I_F$ $2 I_F$ $I_{FSI}$	Input Load Current J, K, J, K & Clock Inputs J-K Input Asynchronous Inputs	-1.45 -2.9 -3.92		-0.91 -1.82 -2.48	-1.45 -2.9 -3.92			-1.45 -2.9 -3.92	mA	$V_{CC} = 4.5\text{ V}$ $V_{CC} = 4.5\text{ V}$ $V_{CC} = 4.5\text{ V}$
$t_{pd+}$				—	12	20			ns	9000 or 9001
$t_{pd-}$				—	18	30			ns	9000 or 9001
$t_{release}$	See Fig. 8				5	1			ns	9001 only
$t_{set-up}$	See Fig. 8			10	6				ns	9001 only
	Negative Clock pulse width			15	10				ns	9001 only Toggle condition

$V_{CC} = 5.0\text{ V}$   
 $C_L = 15\text{ pF}$   
See test circuits and curves.

**WORST CASE POWER DISSIPATION VERSUS CLOCK INPUT FREQUENCY**

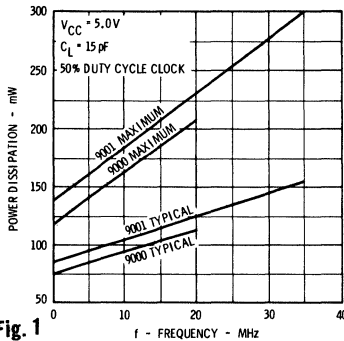


Fig. 1

**9000 & 9001 WORST CASE MAX. & MIN.  $t_{pd+}$  &  $t_{pd-}$  PROPAGATION DELAYS — CP TO OUTPUTS**

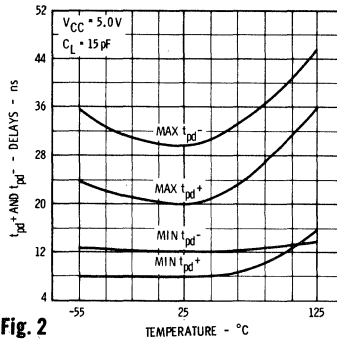


Fig. 2

**9000 & 9001 WORST CASE MAX. & MIN.  $t_{pd+}$  &  $t_{pd-}$  PROPAGATION DELAYS — ASYNCHRONOUS INPUTS TO OUTPUTS**

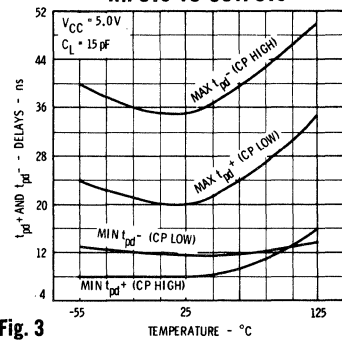


Fig. 3

**INCREASE IN ASYNCHRONOUS OR CLOCK INPUT  $t_{pd+}$  AND  $t_{pd-}$  DUE TO OUTPUT CAPACITANCE**

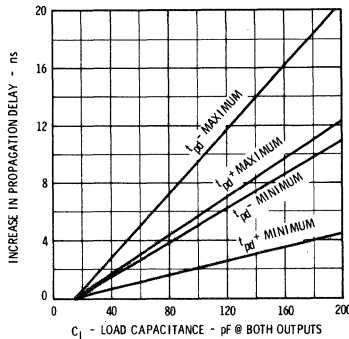


Fig. 4

**9001 WORST CASE SET-UP/RELEASE TIME & NEG. CLOCK PULSE WIDTH**

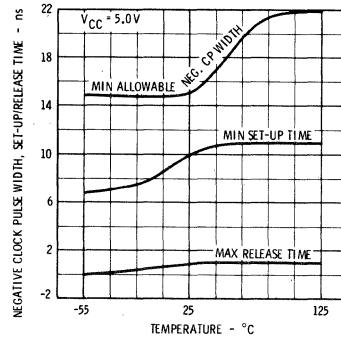


Fig. 5

# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## J-K FLIP-FLOPS — 9000, 9001 (continued)

### SWITCHING TIME TEST CIRCUITS

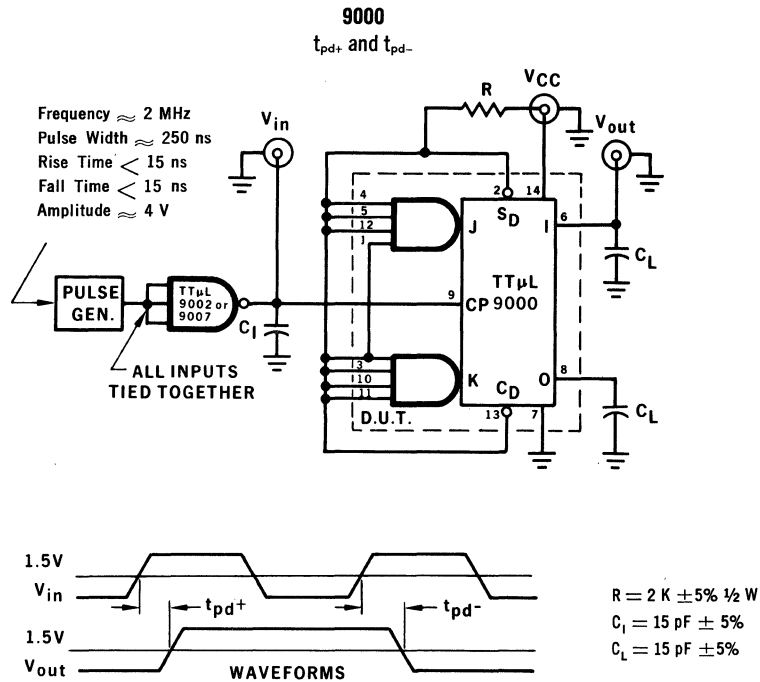


Figure 9

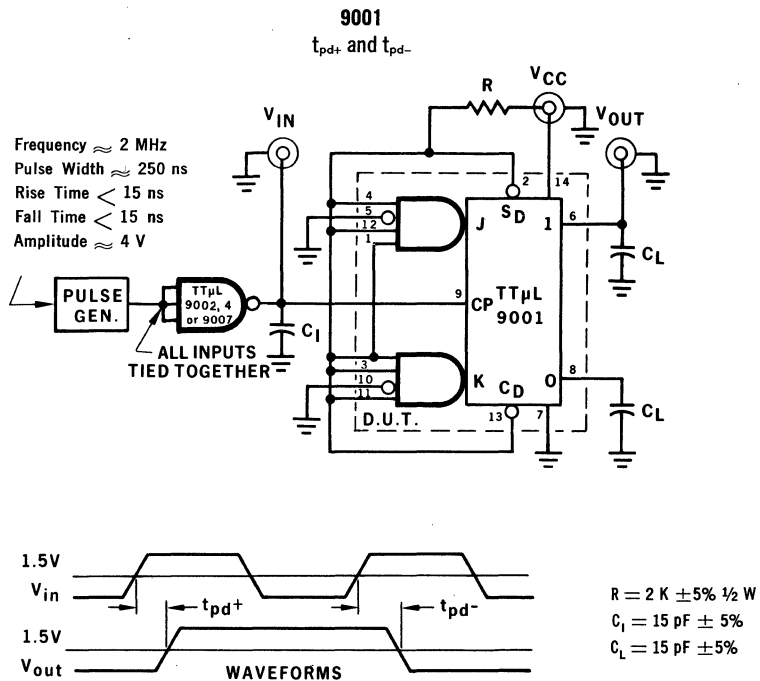


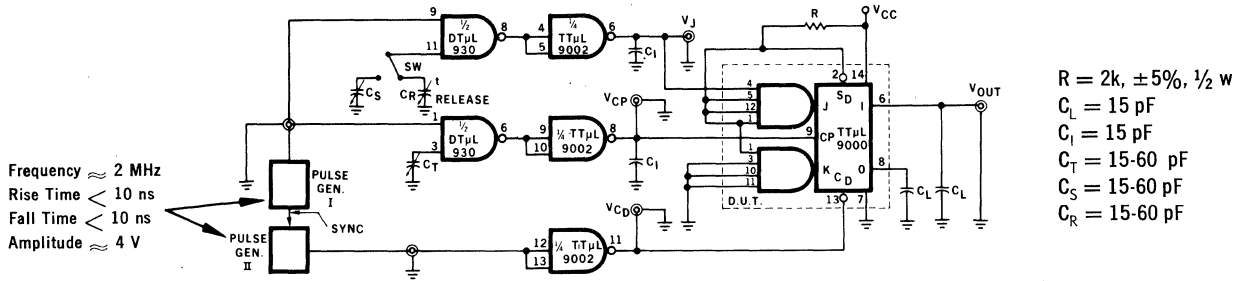
Figure 10

#### SWITCHING NOTES

- (1) The load capacitance indicated in test circuits includes the capacitance of probe and jig.
- (2) All curves represent worst case composites of the behavior of limit devices. A typical device will not necessarily follow the temperature trend indicated by the curve, but should always be better than the worst case curve at any temperature in the range.
- (3) Sensitivity of all switching parameters to supply voltage change (within range of 5 V  $\pm$  10%) and D.C. loading is very small.
- (4) Figure 4 should be used with Figs. 2 and 3 to determine worst case delays with capacitive loading greater than 15 pF.
- (5) Allowable clock skew  $\leq t_{pd+}(\text{min.}) + t_{\text{release}}(\text{max.})$

# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## J-K FLIP-FLOPS — 9000, 9001 (continued) 9000 $t_{set-up}$ and $t_{release}$ TEST CIRCUIT



### INITIAL ADJUSTMENT

1. With switch in  $t_{release}$  position adjust pulse generators,  $C_T$  &  $C_R$  for proper  $V_{CP}$ ,  $V_J$  &  $V_D$  waveforms and  $t_{release}$  limit value.
2. With switch in  $t_{set-up}$  position adjust  $C_S$  for  $t_{set-up}$  limit value

$t_{set-up}$  is defined as the minimum time required for a ONE to be present at the logic input prior to the clock transition from low to high in order for the flip flop to respond.

$t_{release}$  is defined as the maximum time allowed for a ONE to be present at the logic inputs prior to the clock transition from low to high in order for the flip flop **not** to respond.

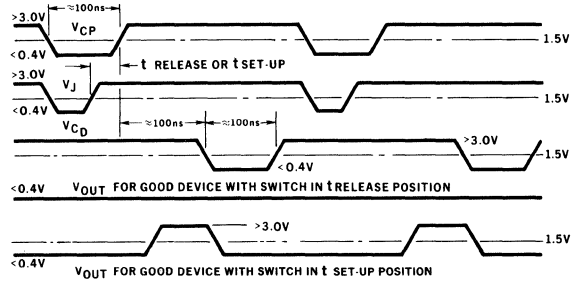
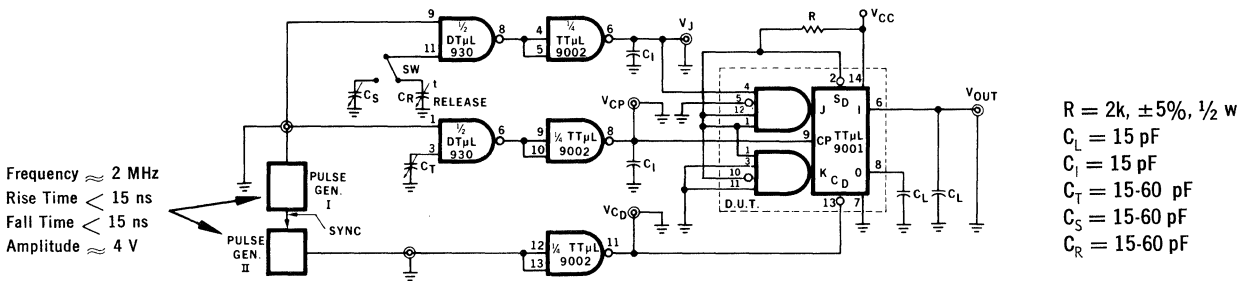


Figure 11

## 9001 $t_{set-up}$ and $t_{release}$ TEST CIRCUIT



### INITIAL ADJUSTMENT

1. With switch in  $t_{release}$  position adjust pulse generators,  $C_T$  &  $C_R$  for proper  $V_{CP}$ ,  $V_J$  &  $V_D$  waveforms and  $t_{release}$  limit value.
2. With switch in  $t_{set-up}$  position adjust  $C_S$  for  $t_{set-up}$  limit value

$t_{set-up}$  is defined as the minimum time required for a ONE to be present at the logic input prior to the clock transition from low to high in order for the flip flop to respond.

$t_{release}$  is defined as the maximum time allowed for a ONE to be present at the logic inputs prior to the clock transition from low to high in order for the flip flop **not** to respond.

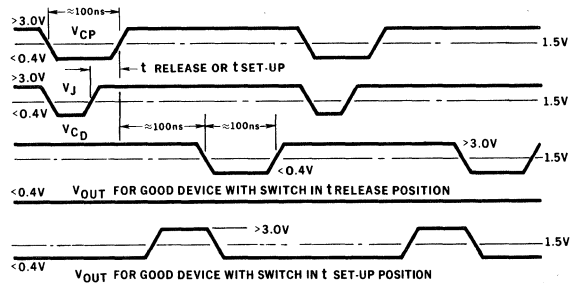


Figure 12

# CCSL COMPOSITE DATA SHEET

## COMPATIBLE CURRENT SINKING LOGIC

-55°C TO +125°C TEMPERATURE RANGE

### CCSL LOADING RULES

The first step towards realization of a compatible logic family is to establish optimized input-output logic levels. These levels determine the noise immunity for all the elements, as well as the basis for system interfacing.

Fairchild CCSL loading rules guarantee the optimum logic levels over the full military temperature range of -55°C to +125°C with  $V_{CC}$  supply within the range of  $5V \pm 0.5V$ . These same logic levels, as well as the input load and output drive factors are also guaranteed over the temperature range of -20°C to +100°C, for all CCSL elements. These guaranteed levels are:

Low level output voltage ( $V_{OL}$ ) = 0.4V

High level output voltage ( $V_{OH}$ ) = 2.5V

Low level input voltage ( $V_{IL}$ ) = 0.7V

High level input voltage ( $V_{IH}$ ) = 2.1V

Noise immunity is derived from the above numbers according to the following equations.

1. High level noise immunity =  $V_{OH} - V_{IH}$

2. Low level noise immunity =  $V_{IL} - V_{OL}$

Once the logic levels and DC noise margins are established, interfacing rules can be resolved. To simplify input loading and output drive capability, load factors and drive factors were assigned to each element.

These factors are written as a ratio, but are not defined as an arithmetic ratio. The numerator can be added or subtracted independent of the denominator and vice versa. This ratio form was chosen for convenient loading rule analysis.

$$\text{Load Factor} \equiv \frac{\text{High Level Load Factor}}{\text{Low Level Load Factor}} \quad (\text{Shown as ratio on inputs to circuits})$$

$$\text{Drive Factor} \equiv \frac{\text{High Level Drive Factor}}{\text{Low Level Drive Factor}} \quad (\text{Shown as ratio on outputs of circuits})$$

Where:

High Level Load Factor = Input current drawn into the inputs, during the High Input Level State.

Low Level Load Factor = Input current drawn out of the input during the Low Input Level State.

High Level Drive Factor = Ability of the output to supply current out of the output during the High Output Level State.

Low Level Drive Factor = Ability of the output to sink current into the output during the Low Output Level State.

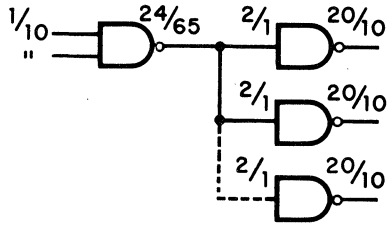
A necessary condition is that the High Level Drive Factor must be equal to or greater than the sum of the Driven High Level Load Factors and the Low Level Drive Factor must be equal to or greater than the sum of the Driven Low Level Load Factors. Both High Level Drive and Load factors and Low Level Drive and Load factors must be considered if efficient interfacing is to be accomplished.

## CCSL COMPOSITE DATA SHEET

The load factors given are based on worst case conditions at both  $-55^{\circ}\text{C}$  and  $+125^{\circ}\text{C}$ . Input Low Level Load Factors are guaranteed with the Low Level Output Voltage ( $V_{OL}$ ) applied to the inputs. Input High Level Load Factors are tested with arbitrarily selected voltages much higher than the  $V_{OH}$  value.

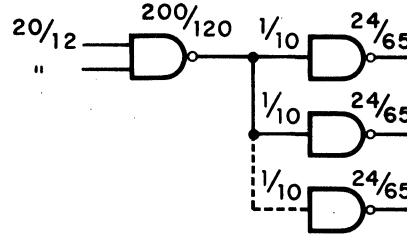
If the temperature range is restricted to  $-40^{\circ}\text{C}$  to  $+110^{\circ}\text{C}$  or the  $V_{CC}$  range to 4.75 to 5.25V, a 10% increase in drive factors may be used.

Examples: A.



(1) DTuL Gate (6K pullup) driving LPDTL Gates

B.



(2) TTL gate driving DTL Gates

### Example A

Maximum load = 12 LPDTL gates. Limited by the high level drive capabilities. In this case the Low Level Load is only 12, and the drive capability is 65. Reference to the curves shown in Figure 1, will show this node to have a maximum  $V_{OL} = 100\text{mV}$  and therefore a worst case Low level noise immunity of 0.6 volts.

### Example B

Maximum load - 12 DTL gates, limited by low level drive capabilities. Here the high level load = 12 and the drive capability is 200.

## LIMITED LOADING APPLICATIONS

The curves shown in Figures 1, and 2 show improvements in the low level noise margin for TTL and  $\text{DT}\mu\text{L}$ .  $\text{DT}\mu\text{L}$  is shown with 6K or 2K pullup resistors.

Example: A TTL gate type output can drive a maximum of 120 low level loads and meet a guaranteed  $V_{OL}$  of 0.40 volts. If, however, this same output is only driving 50 low level loads, the worst case  $V_{OL}$  at that output would be 0.20 volts and the worst case low level noise immunity would be 0.50 volts.

Figure 2 shows similar low level curves for the TTL and  $\text{DT}\mu\text{L}$  Buffers.

Figure 3 shows the increase of  $V_{OH}$  of a  $\text{DT}\mu\text{L}$  output high level if the high level loads are less than the maximum specified in the CCSL loading rules. This drive is determined by using a -30% tolerance resistor and is guaranteed by D.C. testing.

Figure 4 shows changes in  $V_{OH}$  for  $\text{DT}\mu\text{L}$  devices which have 2K pullup resistor. The test point guarantees a  $V_{OH}$  4.0 volts with 24 high level loads being driven. The increased number of loads which can be driven and still meet the CCSL  $V_{OH}$  of 2.5 volts is based on a worst case maximum tolerance pullup resistor as determined by D.C. testing. If less than 24 high level loads are driven, the increase in  $V_{OH}$  is determined by the worst case minimum tolerance pullup resistor.

TTL and  $\text{LPDT}\mu\text{L}$  devices having active pullups are relatively immune to changes in the high level loads. Their  $V_{OH}$  level is primarily set by being  $2V_{BE}$ 's below  $V_{CC}$ .

## CCSL COMPOSITE DATA SHEET

### SPECIAL APPLICATIONS

When using the DT $\mu$ L 9944 element, the following currents represent unit loads, and must be considered when choosing different external collector resistors.

		-55 C	+25 C	-125 C
$V_{CC} = 4.5V$	High Level	3 $\mu$ A	3 $\mu$ A	5 $\mu$ A
	Low Level	.121mA	Not worst case	Not worst case
$V_{CC} = 5.5V$	High Level	Not worst case	Not worst case	Not worst case
	Lower Level	.151mA	.154mA	.146mA

### "WIRED OR" APPLICATIONS

For elements 9930, 9962, 9946 and 9936 add 24 to the High Level Drive Factor and subtract 9 from the Low Level Drive Factor for each added gate.

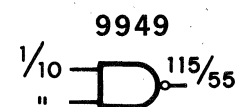
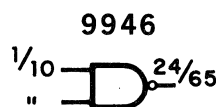
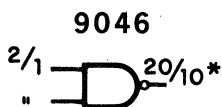
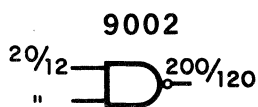
For elements 9041, 9043, 9046 and 9048 using one internal 15 $\Omega$  pull-up resistor the High Level Drive Factor becomes 14 and the Low Level Drive Factor becomes 7. Subtract 2 from the High Level Drive Factor for each added gate.

Note 1

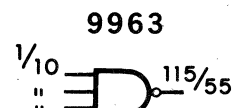
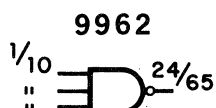
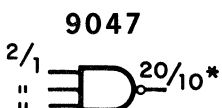
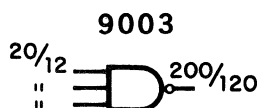
If the minimum temperature is limited to -30°C, the Low Level Drive Factor is 12.

### CCSL INPUT LOAD & DRIVE FACTORS

#### QUAD 2-INPUT NAND GATES



#### TRIPLE 3-INPUT NAND GATES

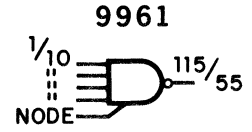
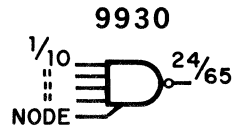
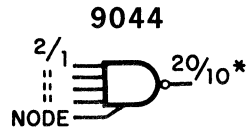
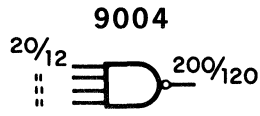


\*See Note 1

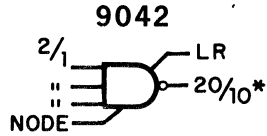
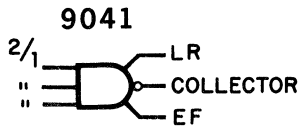
# CCSL COMPOSITE DATA SHEET

## CCSL INPUT LOAD & DRIVE FACTORS

### DUAL 4-INPUT NAND GATES

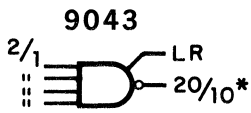


### DUAL 3-INPUT NAND GATES



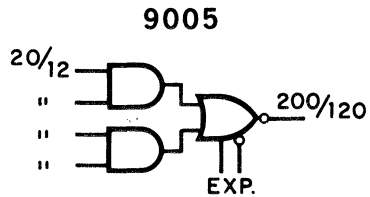
LR=LOAD RESISTOR OUTPUT, EF=EMITTER FOLLOWER OUTPUT

### 3 & 4-INPUT NAND GATES

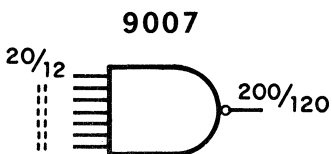


LR=LOAD RESISTOR OUTPUT

### DUAL AND/NOR FUNCTION



### EIGHT-INPUT NAND GATE

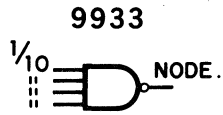
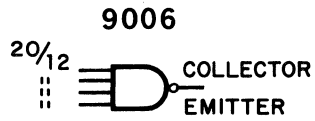


\*See Note 1

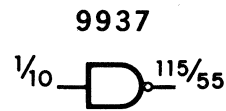
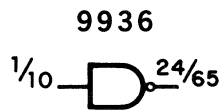
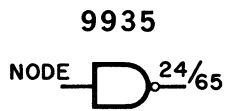
# CCSL COMPOSITE DATA SHEET

## CCSL INPUT LOAD & DRIVE FACTORS

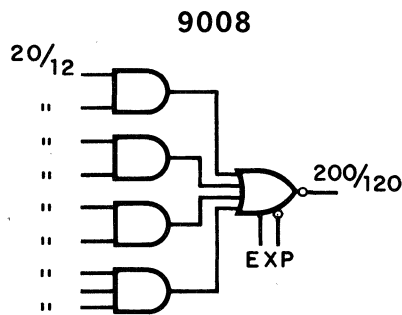
### DUAL 4-INPUT EXPANDERS



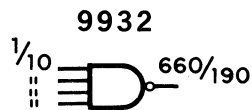
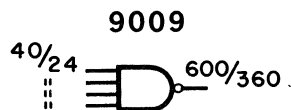
### HEX INVERTERS



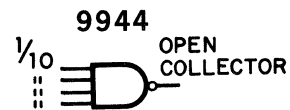
### 2-2-2-3-INPUT AND/NOR FUNCTION



### DUAL 4-INPUT BUFFERS



### DUAL 4-INPUT DRIVER



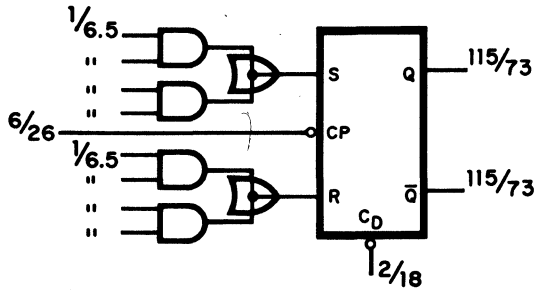


# CCSL COMPOSITE DATA SHEET

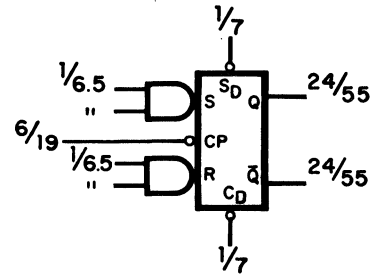
## CCSL INPUT LOAD & DRIVE FACTORS

### R-S FLIP-FLOPS

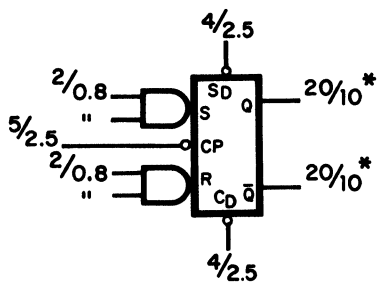
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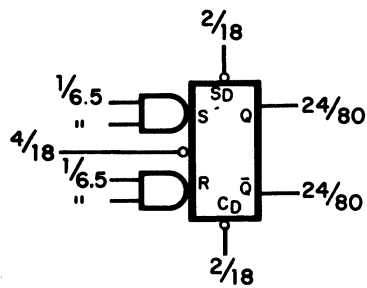
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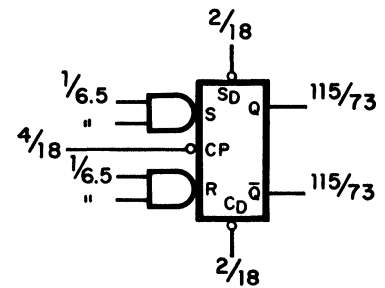
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9945

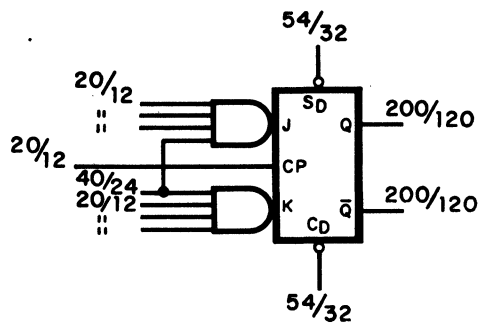


9948

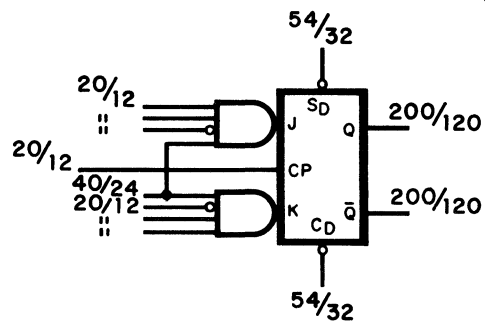


### J-K FLIP-FLOPS

9000



9001



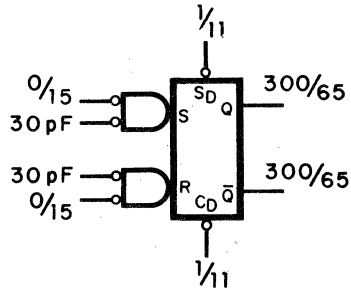
\* See Note 1

# CCSL COMPOSITE DATA SHEET

## CCSL INPUT LOAD & DRIVE FACTORS

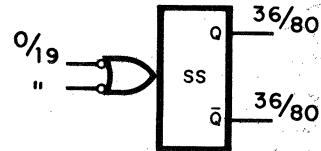
### BINARY

9950

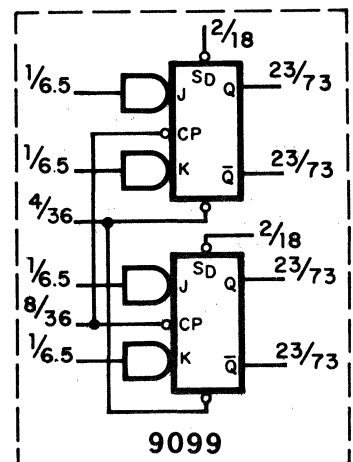
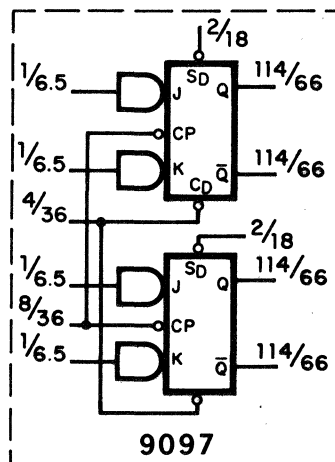
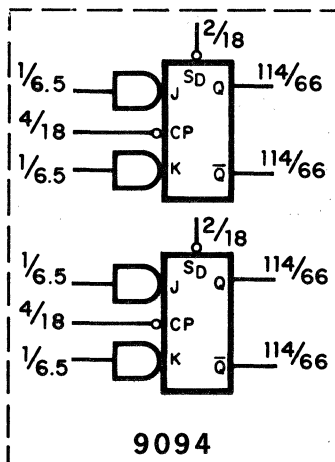
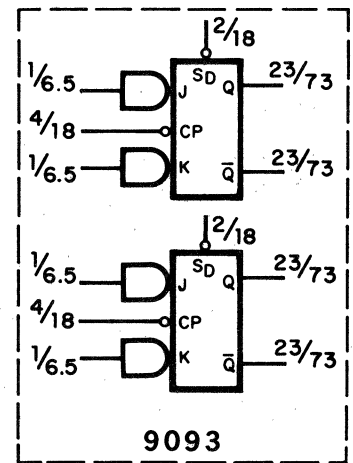
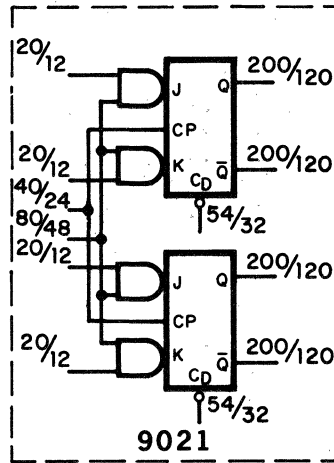
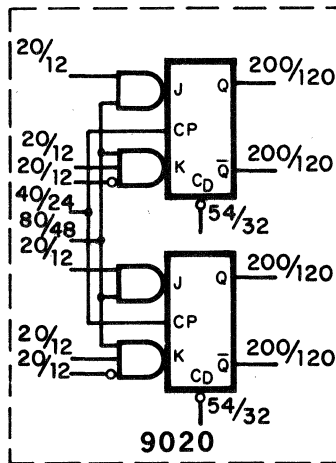


### ONE-SHOTS (MONOSTABLE)

9941 & 9951



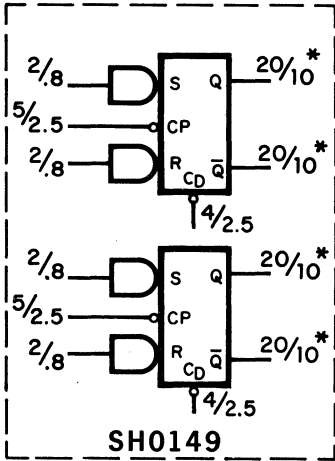
### DUAL FLIP-FLOPS



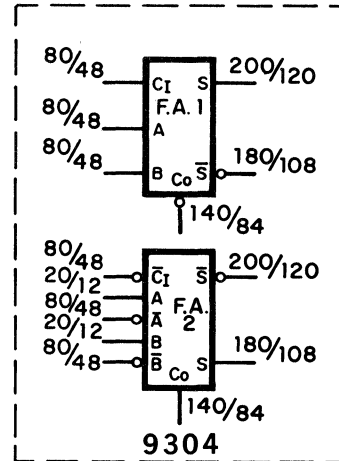
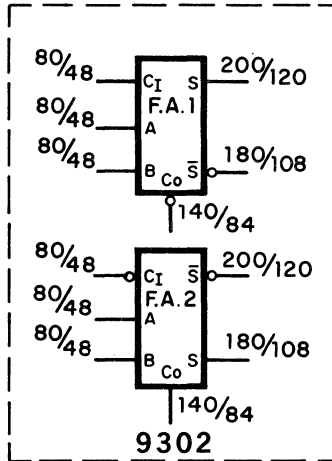
# CCSL COMPOSITE DATA SHEET

## CCSL INPUT LOAD & DRIVE FACTORS

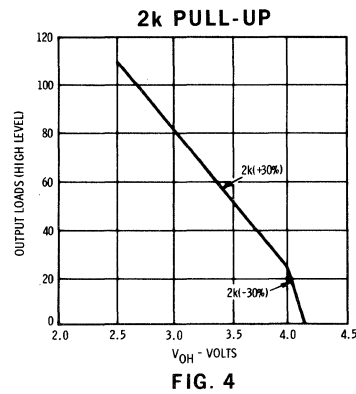
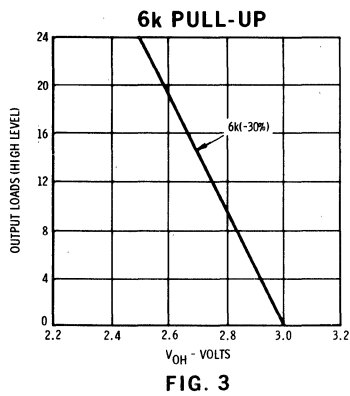
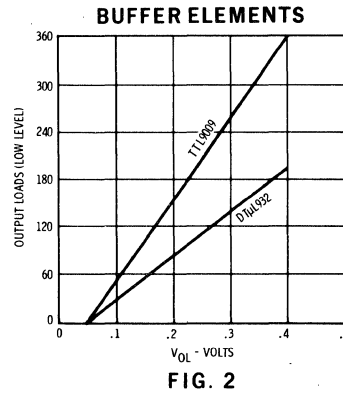
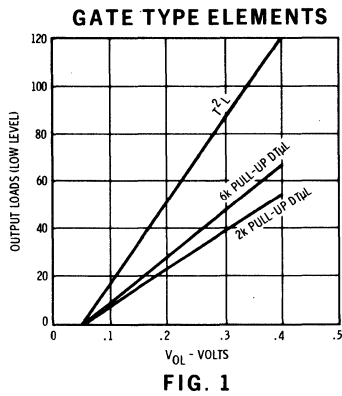
### DUAL FLIP-FLOPS (continued)



### DUAL FULL-ADDERS



## OUTPUT LEVELS VERSUS LOADING



\* See Note 1

# TT $\mu$ L9016

## HEX INVERTER

TRANSISTOR-TRANSISTOR MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS  
 A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

### GENERAL DESCRIPTION

The 9016 consists of six TT $\mu$ L gates where each gate performs a single inversion function. Designed for high speed operation, the 9016 is very useful where a number of complement signals are desired simultaneously.

### FEATURES

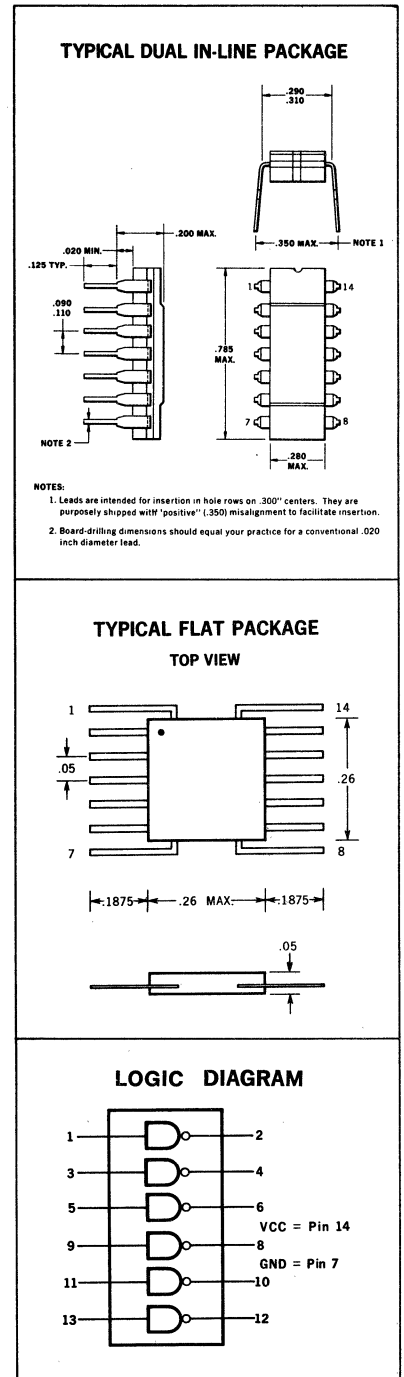
- High Speed Operation
- Input Diode Clamping
- High Capacitive Drive Capability
- The input/output characteristics provide easy interfacing with Fairchild DT $\mu$ L, LPDT $\mu$ L, TT $\mu$ L and MSI families (CCSL.)
- All ceramic "HERMETIC" packages

### ABSOLUTE MAXIMUM RATINGS (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +8V
Input Voltage	-0.5V to +5.5V
Voltage Applied to Outputs	-0.5V to +V <sub>CC</sub> value

### ORDER INFORMATION

Specify U3I90165XX for flat package and U6A90165XX for Dual-In-Line package, where 5XX is 51X for -55°C to +125°C temperature range or 59X for the 0°C to +75°C temperature range.



# TRANSISTOR-TRANSISTOR MICROLOGIC® I. C.

## ELECTRICAL CHARACTERISTICS 0°C to +75°C, V<sub>CC</sub>=5.0V ±5%

SYMBOL	CHARACTERISTICS	LIMITS			UNITS	CONDITIONS & COMMENTS
		0°C MIN. MAX.	+25°C MIN. TYP. MAX.	+75°C MIN. MAX.		
V <sub>OH</sub>	Output High Voltage	2.4	2.4 3.0	2.4	Volts	V <sub>CC</sub> = 4.75V, I <sub>OH</sub> = -1.2 mA V <sub>IL</sub> = VALUE INDICATED BELOW
V <sub>OL</sub>	Output Low Voltage	0.45	0.2 0.45	0.45	Volts	V <sub>CC</sub> = 4.75V, I <sub>OL</sub> = 14.1 mA V <sub>CC</sub> = 5.25V, I <sub>OL</sub> = 16.0 mA
V <sub>IH</sub>	Input High Voltage	1.9	1.8	1.6	Volts	Guaranteed input high threshold for all inputs.
V <sub>IL</sub>	Input Low Voltage	0.85	0.85	0.85	Volts	* Guaranteed input low threshold for all inputs.
I <sub>F</sub>	Input Load Current	-1.6	-1.0 -1.6	-1.6	mA	V <sub>CC</sub> = 5.25V, V <sub>F</sub> = 0.45V
I <sub>F</sub>	Input Load Current	-1.24	-0.97 -1.24	-1.24	mA	V <sub>CC</sub> = 4.75V, V <sub>F</sub> = 0.45V
I <sub>R</sub>	Input Leakage Current		15 60	60	μA	V <sub>CC</sub> = 5.25V, V <sub>R</sub> = 4.5V
t <sub>pd+</sub>	Turn Off Delay		3 8 15		ns	V <sub>CC</sub> = 5.0V C <sub>L</sub> = 15pF
t <sub>pd-</sub>	Turn On Delay		3 7 13		ns	

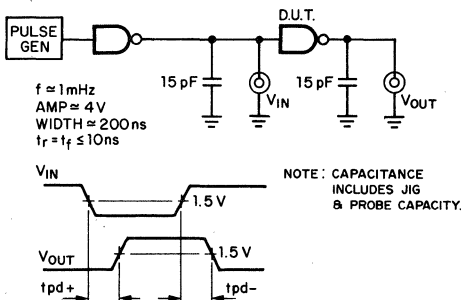
\* Pulse Tested (pulse duration = 50 msec.)

## ELECTRICAL CHARACTERISTICS -55°C to +125°C, V<sub>CC</sub>=5.0V ±10%

SYMBOL	CHARACTERISTICS	LIMITS			UNITS	CONDITIONS & COMMENTS
		0°C MIN. MAX.	+25°C MIN. TYP. MAX.	+75°C MIN. MAX.		
V <sub>OH</sub>	Output High Voltage	2.4	2.4 2.7	2.4	Volts	V <sub>CC</sub> = 4.5V, I <sub>OH</sub> = -1.32 mA V <sub>IL</sub> = VALUE INDICATED BELOW
V <sub>OL</sub>	Output Low Voltage	0.4	0.2 0.4	0.4	Volts	V <sub>CC</sub> = 4.5V, I <sub>OL</sub> = 13.6 mA V <sub>CC</sub> = 5.5V, I <sub>OL</sub> = 17.6 mA
V <sub>IH</sub>	Input High Voltage	2.0	1.7	1.4	Volts	Guaranteed input high threshold for all inputs.
V <sub>IL</sub>	Input Low Voltage	0.8	0.9	0.8	Volts	*Guaranteed input low threshold for all inputs.
I <sub>F</sub>	Input Load Current	-1.6	-1.10 -1.6	-1.6	mA	V <sub>CC</sub> = 5.5V, V <sub>F</sub> = 0.4V
I <sub>F</sub>	Input Load Current	-1.24	-0.97 -1.24	-1.24	mA	V <sub>CC</sub> = 4.5V, V <sub>F</sub> = 0.4V
I <sub>R</sub>	Input Leakage Current		15 60	60	μA	V <sub>CC</sub> = 5.5V, V <sub>R</sub> = 4.5V
t <sub>pd+</sub>	Turn Off Delay		3 8 12		ns	V <sub>CC</sub> = 5.0V C <sub>L</sub> = 15pF
t <sub>pd-</sub>	Turn On Delay		3 7 10		ns	

\* Pulse Tested (pulse duration = 50 msec.)

### tpd TEST CIRCUIT

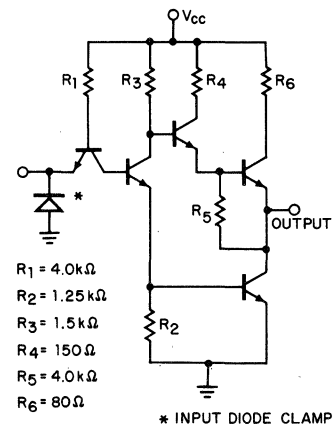


### LOADING RULES

INPUT LEVEL	LOAD FACTOR	
HIGH	1	
LOW	1	
OUTPUT STATE	FANOUT	
HIGH	22	20
LOW	11	10

1 HIGH LEVEL LOAD = I<sub>R</sub>  
1 LOW LEVEL LOAD = I<sub>F</sub>

### SCHEMATIC DIAGRAM



# TT $\mu$ L 9020

## DUAL JK $\bar{K}$ FLIP-FLOP

### A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

#### GENERAL DESCRIPTION

The 9020 consists of two JK flip-flops with a common clock, separate J, K, and  $\bar{K}$  inputs and a common JK input. The JK $\bar{K}$  design allows the 9020 to be operated as a D type flip-flop or as a standard J-K flip-flop. Incorporated in the element is a single clock buffer which reduces clock loading.

The joint (JK) input to the flip-flops can be used to advantage for gating information into the flip-flops. This common input removes the necessity of gating clock waveforms and can result in an improved logic design requiring fewer circuits. It also minimizes clock skew problems if a single clock line is used and all the clock drivers are tied together.

#### FEATURES

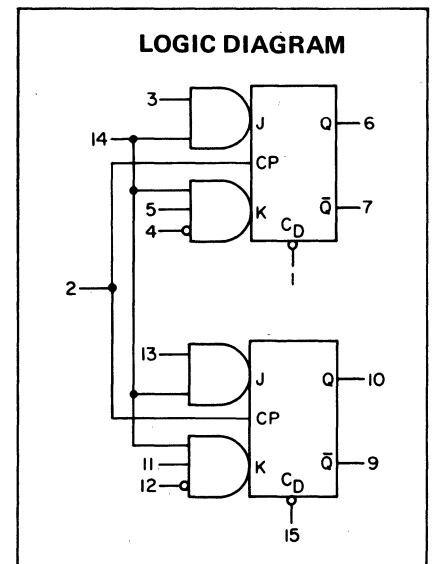
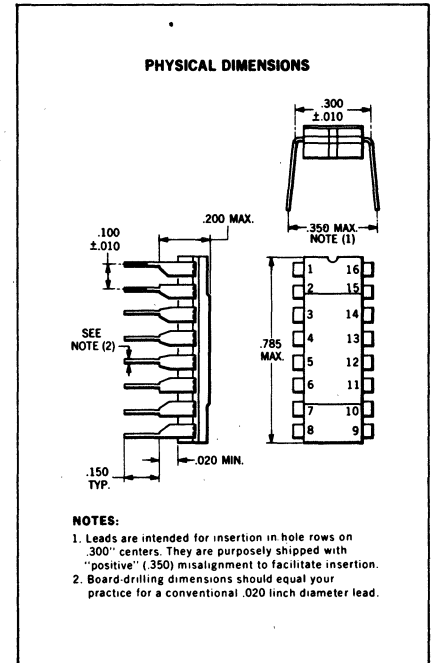
- 50 MHz operation
- Master-slave circuit
- Common buffered clock input
- Separate JK $\bar{K}$  inputs
- Common Input Enable logic
- Separate Direct Clear inputs
- The input/output characteristics provide easy interfacing with Fairchild DT $\mu$ L, LPDT $\mu$ L, and MSI families (CCSL).
- All ceramic "HERMETIC" 16-pin Dual In-Line package
- Input Diode Clamping

#### ABSOLUTE MAXIMUM RATINGS (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +8V
Input Voltage	-1.5V to +5.5V
Voltage Applied to Outputs	-0.5V to V <sub>CC</sub> Value
Current Into Output When Output is Low	50 mA

#### ORDER INFORMATION

Specify U6B9020XXX for 16 pin Dual In-Line package where XXX is 51X for the -55°C to +125°C temperature range, or 59X for the 0°C to +75°C temperature range.



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# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## TRUTH TABLE

### SYNCHRONOUS ENTRY J-K MODE OPERATION

INPUTS @ $t_n$			OUTPUTS @ $t_{n+1}$	
JK 14	J 3(13)	$K \cdot \bar{K}$ 5(11) · 4(12)	Q 6(10)	$\bar{Q}$ 7(9)
L	X	X	(1)	No Change
H	L	L	(1)	No Change
H	L	H	L	H
H	H	L	H	L
H	H	H	Toggles	

### ASYNCHRONOUS ENTRY INDEPENDENT OF CLOCK & SYNCHRONOUS INPUTS

INPUTS	OUTPUTS	
$C_D$ 1(15)	Q 6(10)	$\bar{Q}$ 7(9)
L	L	H
H	No Change	

H = Most positive logic level  
L = Most negative logic level  
X = Could be high or low

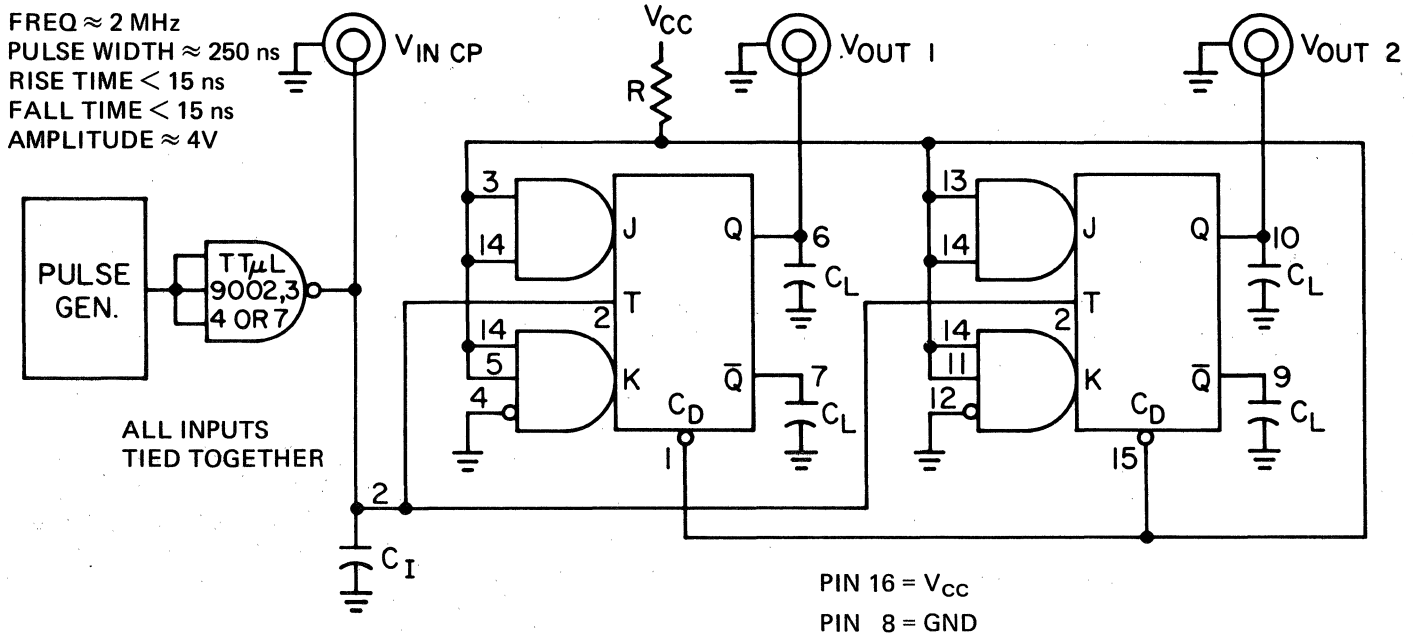
### NOTES:

- (1) For no change of outputs, the J and K inputs or the common JK input must remain low for the entire period in which the clock pulse is at low logic level.
- (2)  $\bar{K}$  inputs should be grounded when not in use.

### LOADING RULES

INPUTS	LOADING
J, K, $\bar{K}$	1
CP	2
JK	4
CD	2.7
OUTPUTS	FANOUT
Q, $\bar{Q}$	10

### SWITCHING TIME TEST CIRCUITS:



# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## ELECTRICAL CHARACTERISTICS

INDUSTRIAL TEMPERATURE RANGE 0°C to 75°C,  $V_{CC}$  5.0V  $\pm$ 5%

SYMBOL	CHARACTERISTIC	LIMITS							UNITS	CONDITIONS & COMMENTS
		0°C		25°C			75°C			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	3.0		2.4		Volts	$V_{CC} = 4.75V, I_{OH} = 1.2 mA$
$V_{OL}$	Output Low Voltage		0.45		0.21	0.45		0.45	Volts	$V_{CC} = 4.75V, I_{OL} = 14.1 mA$ $V_{CC} = 5.25V, I_{OL} = 16 mA$
$V_{IH}$	Input High Voltage	1.9		1.8				1.6	Volts	Guaranteed input high threshold for all inputs.
$V_{IL}$	Input Low Voltage		0.85			0.85		0.85	Volts	Guaranteed input low threshold for all inputs.
$I_R$ 2 $I_R$ 4 $I_R$ $I_{RS}$	J, K, $\bar{K}$ Leakage Current Clock Input J-K Input Asynchronous Inputs				5 10 20 14	60 120 240 160		60 120 240 160	$\mu A$	$V_{CC} = 5.25V, V_R = 4.5V$ Gnd. on other inputs.
$I_F$ 2 $I_F$ 4 $I_F$ $I_{FSI}$	J, K, $\bar{K}$ Input Current Clock Input J-K Input Asynchronous Inputs		-1.60 -3.20 -6.40 -4.32		-1.0 -2.0 -4.0 -2.7	-1.60 -3.20 -6.40 -4.32		-1.60 -3.20 -6.40 -4.32	mA	$V_{CC} = 5.25V$ $V_F = 0.45V$ $V_R = 4.5V$ on other inputs.
$I_F$ 2 $I_F$ 4 $I_F$ $I_{FSI}$	J, K, $\bar{K}$ Input Current Clock Input J-K Input Asynchronous Inputs		-1.41 -2.82 -5.64 -3.78		-0.94 -1.88 -3.76 -2.54	-1.41 -2.82 -5.64 -3.78		-1.41 -2.82 -5.64 -3.78	mA	$V_{CC} = 4.75V$
$t_{pd+}$					13	22			ns	$V_{CC} = 5.0V$ $C_L = 15 pF$
$t_{pd-}$					21	35			ns	
$t_{release}$					6	1			ns	
$t_{set-up}$				12	7				ns	
	Negative Clock pulse width			16	11				ns	

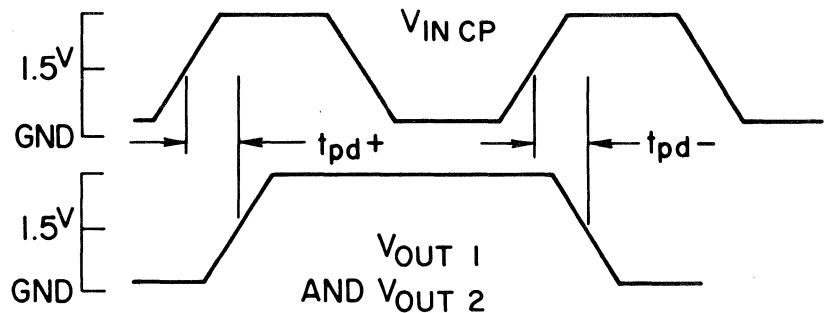
## SWITCHING TIME TEST CIRCUITS (Continued)

### NOTES:

$R = 2K, \pm 5\%, \frac{1}{2}W$   
 $C_I = 15 pF \pm 5\%$   
 $C_L = 15 pF \pm 5\%$

$C_I$  &  $C_L$  include all probe and jig capacity. Very short stranded or printed wire should be used for all interconnections. Probes should be connected directly to the input & output pins.

### WAVEFORMS





## FAIRCHILD TT<sub>μ</sub>L INTEGRATED CIRCUITS

### ELECTRICAL CHARACTERISTICS

**MILITARY TEMPERATURE RANGE -55°C to +125°C, V<sub>CC</sub> 5.0V ±10%**

SYMBOL	CHARACTERISTIC	LIMITS						UNITS	CONDITIONS & COMMENTS		
		-55°C		25°C			125°C				
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.				MAX.
V <sub>OH</sub>	Output High Voltage	2.4		2.4	2.7		2.4		Volts	V <sub>CC</sub> = 4.5V, I <sub>OH</sub> = 1.2 mA	
V <sub>OL</sub>	Output Low Voltage		0.4		0.21	0.4		0.4	Volts	V <sub>CC</sub> = 4.5V, I <sub>OL</sub> = 12.4 mA V <sub>CC</sub> = 5.5V, I <sub>OL</sub> = 16 mA	
V <sub>IH</sub>	Input High Voltage	2.0		1.7				1.4	Volts	Guaranteed input high threshold for all inputs.	
V <sub>IL</sub>	Input Low Voltage		0.8			0.9		0.8	Volts	Guaranteed input low threshold for all inputs.	
I <sub>R</sub> 2 I <sub>R</sub> 4 I <sub>R</sub> I <sub>RS</sub>	J, K, $\bar{K}$ Leakage Current Clock Input J-K Input Asynchronous Inputs				5 10 20 14	60 120 240 160		60 120 240 160	μA	V <sub>CC</sub> = 5.5V, V <sub>R</sub> = 4.5V Gnd. on other inputs.	
I <sub>F</sub> 2 I <sub>F</sub> 4 I <sub>F</sub> I <sub>FSI</sub>	J, K, $\bar{K}$ Input Current Clock Input J-K Input Asynchronous Inputs		-1.60 -3.20 -6.40 -4.32		-1.1 -2.2 -4.4 -3.0	-1.60 -3.2 -6.40 -4.32		-1.60 -3.2 -6.40 -4.32	mA	V <sub>CC</sub> = 5.5V V <sub>F</sub> = 0.4V V <sub>R</sub> = 4.5V	
I <sub>F</sub> 2 I <sub>F</sub> 4 I <sub>F</sub> I <sub>FSI</sub>	J, K, $\bar{K}$ Input Current Clock Input J-K Input Asynchronous		-1.24 -2.48 -4.86 -3.29		-0.91 -1.82 -3.64 -2.48	-1.24 -2.48 -4.96 -3.29		-1.24 -2.48 -4.96 -3.29	mA	V <sub>CC</sub> = 4.5V on other inputs	
t <sub>pd+</sub>					13	22			ns	Each Flip-Flop V <sub>CC</sub> = 5.0V C <sub>L</sub> = 15 pF	
t <sub>pd-</sub>					21	35			ns		
t <sub>release</sub>					6	1			ns		
t <sub>set-up</sub>				12	7				ns		
	Negative Clock pulse width			16	11				ns	Toggle Condition	

# TT $\mu$ L 9022

## DUAL JK FLIP-FLOP

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

### GENERAL DESCRIPTION

The 9022 consists of two JK flip-flops with a common clock, separate J and  $\bar{K}$  inputs and a common JK input. The JK design allows the 9022 to be operated as a D type flip-flop or as a standard J-K flip-flop. Incorporated in the element is a single clock buffer which reduces clock loading.

The joint (JK) input to the flip-flops can be used to advantage for gating information into the flip-flops. It also minimizes clock skew by allowing separate enable control of flip-flops when they are connected to a common clock buss.

### FEATURES

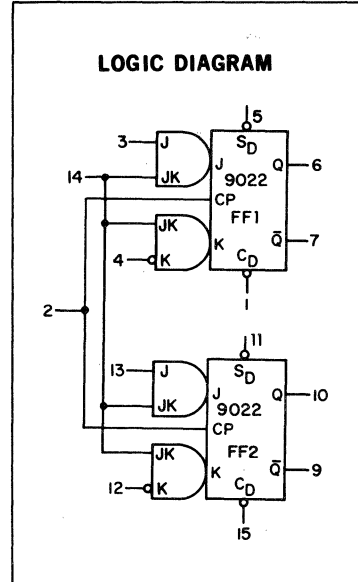
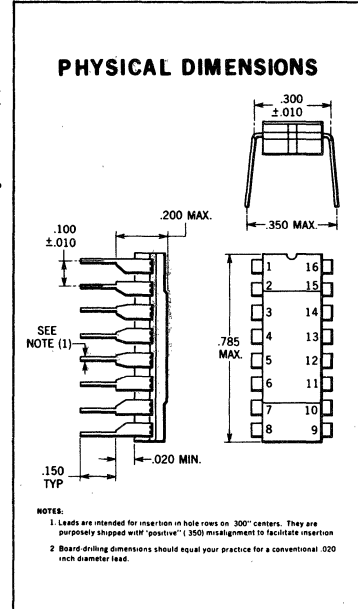
- 35 MHz operation
- Master-slave circuit
- Common buffered clock input
- Separate JK inputs
- Common Input Enable logic
- Separate Direct Clear and Direct set inputs
- The input/output characteristics provide easy interfacing with Fairchild DT $\mu$ L, LPDT $\mu$ L, and MSI families (CCSL).
- All ceramic "HERMETIC" 16-pin Dual In-Line package
- Input Diode Clamping

### ABSOLUTE MAXIMUM RATINGS (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +8V
Input Voltage	-0.5V to +5.5V
Voltage Applied to Outputs	-0.5V to V <sub>CC</sub> Value
Current Into Output When Output is Low	50 mA

### ORDER INFORMATION

Specify U6B9022XXX for 16 pin Dual In-Line package where XXX is 51X for the -55°C to +125°C temperature range, or 59X for the 0°C to +75°C temperature range.



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# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## TRUTH TABLE

### SYNCHRONOUS ENTRY J-K MODE OPERATION

INPUTS @ $t_n$			OUTPUTS @ $t_{n+1}$	
JK 14	J 3(13)	$\bar{K}$ 4(12)	Q 6(10)	$\bar{Q}$ 7(9)
L	X	X	(1)	No Change
H	L	H	(1)	No Change
H	L	L	L	H
H	H	H	H	L
H	H	L	Toggles	

### ASYNCHRONOUS ENTRY INDEPENDENT OF CLOCK & SYNCHRONOUS INPUTS

INPUTS		OUTPUTS	
$S_D$ 5(11)	$C_D$ 1(15)	Q 6(10)	$\bar{Q}$ 7(9)
L	L	H	H
L	H	H	L
H	L	L	H
H	H	No Change	

H = Most positive logic level

L = Most negative logic level

X = Could be high or low

### NOTES:

- (1) For no change of outputs, the J and  $\bar{K}$  inputs or the common JK input must remain low ( $\bar{K}$  = High) for the entire period in which the clock pulse is at low logic level.
- (2)  $\bar{K}$  inputs should be grounded when not in use.

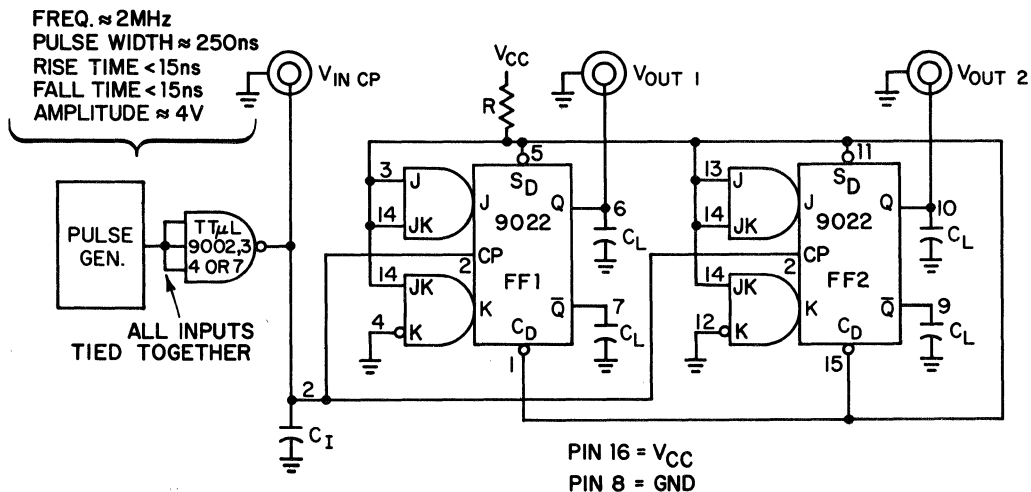
### LOADING RULES

INPUTS	LOADING
J, $\bar{K}$	1
CP	2
JK	4
$C_D$ & $S_D$	2.7

OUTPUTS	FANOUT
Q, $\bar{Q}$	10

### SWITCHING TIME TEST CIRCUITS



# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## ELECTRICAL CHARACTERISTICS

**INDUSTRIAL TEMPERATURE RANGE** 0°C to 75°C,  $V_{CC}$  5.0V  $\pm$ 5%

SYMBOL	CHARACTERISTIC	LIMITS						UNITS	CONDITIONS & COMMENTS		
		0°C		25°C			75°C				
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.				MAX.
$V_{OH}$	Output High Voltage	2.4		2.4	3.0		2.4		Volts	$V_{CC} = 4.75V$ $I_{OH} = -1.2mA$	
$V_{OL}$	Output Low Voltage		0.45		0.21	0.45		0.45	Volts	$V_{CC} = 4.75V$ , $I_{OL} = 14.1mA$ $V_{CC} = 5.25V$ , $I_{OL} = 16mA$	
$V_{IH}$	Input High Voltage	1.9		1.8			1.6		Volts	Guaranteed input high threshold for all inputs.	
$V_{IL}$	Input Low Voltage		0.85			0.85		0.85	Volts	Guaranteed input low threshold for all inputs.	
$I_R$ $2I_R$ $4I_R$ $I_{RS}$	J, $\bar{K}$ Leakage Current Clock Input J-K Input Asynchronous Inputs				5 10 20 14	60 120 240 160		60 120 240 160	$\mu A$	$V_{CC} = 5.25V$ , $V_R = 4.5V$ Gnd. on other inputs.	
$I_F$ $2I_F$ $4I_F$ $I_{FSI}$	J, $\bar{K}$ Input Current Clock Input J-K Input Asynchronous Inputs		-1.60 -3.20 -6.40 -4.32		-1.0 -2.0 -4.0 -2.7	-1.60 -3.20 -6.40 -4.32		-1.60 -3.20 -6.40 -4.32	mA	$V_{CC} = 5.25V$  $V_F = 0.45V$ $V_R = 4.5V$ on other inputs.	
$I_F$ $2I_F$ $4I_F$ $I_{FSI}$	J, $\bar{K}$ Input Current Clock Input J-K Input Asynchronous Inputs		-1.41 -2.82 -5.64 -3.78		-0.94 -1.88 -3.76 -2.54	-1.41 -2.82 -5.64 -3.78		-1.41 -2.82 -5.64 -3.78	mA	$V_{CC} = 4.75V$	
$t_{pd+}$					12	22			ns	$V_{CC} = 5.0V$ $C_L = 15pF$	
$t_{pd-}$					21	35			ns		
$t_{release}$					6	1			ns		
$t_{set-up}$				12	7				ns		
	Negative Clock pulse width			16	11				Toggle Condition		

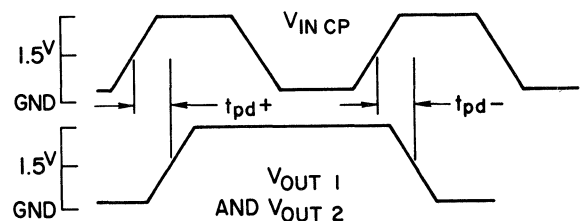
### SWITCHING TIME TEST CIRCUITS (Continued)

#### NOTES:

- $R = 2K, \pm 5\%, 1/2W$
- $C_I = 15 pF \pm 5\%$
- $C_L = 15 pF \pm 5\%$

$C_I$  &  $C_L$  include all probe and jig capacity. Very short stranded or printed wire should be used for all interconnections. Probes should be connected directly to the input & output pins.

#### WAVEFORMS



# FAIRCHILD TT $\mu$ L INTEGRATED CIRCUITS

## ELECTRICAL CHARACTERISTICS

**MILITARY TEMPERATURE RANGE** -55°C to +125°C, V<sub>CC</sub> 5.0V ±10%

SYMBOL	CHARACTERISTICS	LIMITS							UNITS	CONDITIONS & COMMENTS	
		-55°C		25°C			125°C				
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.			
V <sub>OH</sub>	Output High Voltage	2.4		2.4	2.7		2.4		Volts	V <sub>CC</sub> = 4.5 V, I <sub>OH</sub> = -1.2 mA	
V <sub>OL</sub>	Output Low Voltage		0.4		0.21	0.4		0.4	Volts	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 12.4 mA V <sub>CC</sub> = 5.5 V, I <sub>OL</sub> = 16 mA	
V <sub>IH</sub>	Input High Voltage	2.0		1.7			1.4		Volts	Guaranteed input high threshold for all inputs.	
V <sub>IL</sub>	Input Low Voltage		0.8			0.9		0.8	Volts	Guaranteed input low threshold for all inputs.	
I <sub>R</sub> 2I <sub>R</sub> 4I <sub>R</sub> I <sub>RS</sub>	J, $\bar{K}$ Leakage Current Clock Input J-K Input Asynchronous Inputs				5 10 20 14	60 120 240 160		60	$\mu$ A	V <sub>CC</sub> = 5.5 V, V <sub>R</sub> = 4.5 V Gnd. on other inputs.	
I <sub>F</sub> 2I <sub>F</sub> 4I <sub>F</sub> I <sub>FSI</sub>	J, $\bar{K}$ Input Current Clock input J-K Input Asynchronous Inputs		-1.60 -3.20 -6.40 -4.32		-1.1 -2.2 -4.4 -3.0	-1.60 -3.2 -6.40 -4.32		-1.60	mA	V <sub>CC</sub> = 5.5 V	V <sub>F</sub> = 0.4 V  V <sub>R</sub> = 4.5 V on other inputs
I <sub>F</sub> 2I <sub>F</sub> 4I <sub>F</sub> I <sub>FSI</sub>	J, $\bar{K}$ Input Current Clock Input J-K Input Asynchronous		-1.24 -2.48 -4.86 -3.29		-0.91 -1.82 -3.96 -2.48	-1.24 -2.48 -4.96 -3.29		-1.24	mA	V <sub>CC</sub> = 4.5 V	
t <sub>pd+</sub>					12	22			ns	Each Flip-Flop	V <sub>CC</sub> = 5.0 V C <sub>L</sub> = 15 pF
t <sub>pd</sub>					21	35			ns		
t <sub>release</sub>					6	1			ns		
t <sub>set-up</sub>				12	7				ns		
	Negative Clock pulse width			16	11				ns		

# M $\mu$ L9033

## 16-BIT MEMORY CELL

MEMORY MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS  
A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The M $\mu$ L9033 is a Planar\* epitaxial integrated 16-bit, bit-oriented, non-destructive readout memory cell, compatible with Fairchild Transistor-Transistor Micrologic<sup>®</sup> (TT $\mu$ L) and other Compatible Current-Sinking Logic (CCSL) integrated circuits. This memory cell, organized as 16 words by one bit, is designed for high-speed scratch-pad memory applications.

**OPERATION** — The memory cell consists of 16 R-S flip-flops arranged in an addressable four-by-four matrix. The desired bit location is selected by raising the coincident X-Y address lines to a logic "H" level (>2.1 volts) and holding the non-selected address lines at logic "L" level (<0.7 volts). As many as four locations may be addressed simultaneously without destroying stored information. The stored data and its complement at the addressed bit location may be read at the output terminals. If the addressed bit location contains a "1", the S<sub>1</sub> output will be low and the S<sub>0</sub> output will be high. If the addressed bit location contains a "0", the S<sub>1</sub> output will be high and the S<sub>0</sub> output will be low.

Writing is accomplished by activating one of the write amplifiers. To write a "1", the desired bit location is addressed and the input of the "write one" (W<sub>1</sub>) amplifier is raised to a High level. To write a "0", the input of the "write zero" (W<sub>0</sub>) amplifier is raised to a High level.

The outputs are open-collector, which may be wire "OR"ed for word expansion. (The output transistors are off when none of the bits are selected.) An external resistor should be returned to V<sub>CC</sub> to pull-up the wire "OR"ed outputs.

### FEATURES

- CCSL COMPATIBLE
- OUTPUT WIRED-OR CAPABILITY
- TRUE AND COMPLEMENTARY OUTPUTS ARE PROVIDED
- NON DESTRUCTIVE READ OUT

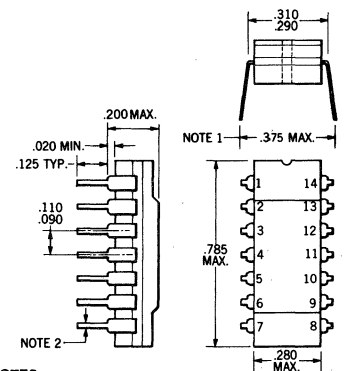
### ABSOLUTE MAXIMUM RATINGS (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground	-0.5 V to +8.0 V
Input Pin Voltage	-1.5 V to +5.5 V
Current Into Output Terminal	100 mA
Output Voltage	-0.5 V to +8.0 V

**ORDER INFORMATION** — Specify A319033XXX for Flat Package or A6A9033XXX for Dual In-Line (TO-116) package where XXX is 51X for -55°C to 125°C temperature range or 59X for the 0°C to 75°C range. The last digit in the order code is 1 for 40 mA Fanout and 2 for 20 mA Fanout.

### PHYSICAL DIMENSIONS

In Accordance With  
JEDEC (TO-116) Outline  
Dual In-Line Package

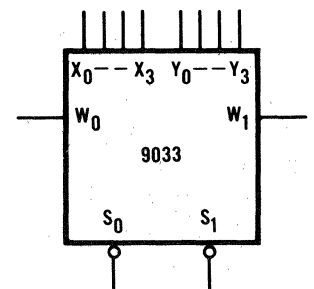
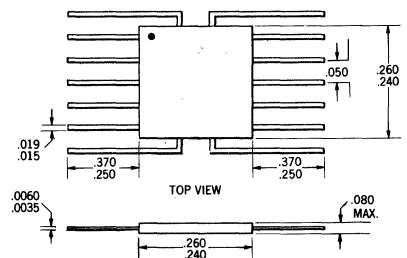


#### NOTES:

1. Leads are intended for insertion in hole rows on .300" centers. They are purposely shipped with "positive" (.350) misalignment to facilitate insertion.
2. Board drilling dimensions should equal your practice for a conventional .020 inch diameter lead.

### PHYSICAL DIMENSIONS

In Accordance With  
JEDEC (TO-86) Outline  
CERPAK I 14 lead



\*Planar is a patented Fairchild process.

**FAIRCHILD**  
SEMICONDUCTOR  
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION

# FAIRCHILD MEMORY MICROLOGIC® INTEGRATED CIRCUIT • M $\mu$ L9033

## ELECTRICAL CHARACTERISTICS ( $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ , $V_{CC} = 5.0\text{ V} \pm 10\%$ )

SYMBOL	TEST	LIMITS		UNITS	TEST CONDITIONS
		MIN.	MAX.		
$I_{FX}$	X Address Input Load Current		11	mA	$V_{CC} = 5.5\text{ V}$ , $V_X = 0\text{ V}$ , $V_Y = 4.5\text{ V}$ , other X inputs grounded
$I_{FY}$	Y Address Input Load Current		11	mA	$V_{CC} = 5.5\text{ V}$ , $V_Y = 0\text{ V}$ , $V_X = 4.5\text{ V}$ , other Y inputs grounded
$I_{RX}$	X Address Input Leakage Current		400	$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ , $V_X = 4.5\text{ V}$ , other X and Y inputs grounded
$I_{RY}$	Y Address Input Leakage Current		400	$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ , $V_Y = 4.5\text{ V}$ , other X and Y inputs grounded
$I_{FW}$	Write Input Load Current		1.5	mA	$V_{CC} = 5.5\text{ V}$ , $V_W = 0\text{ V}$
$I_{RW}$	Write Input Leakage Current		100	$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ , $V_W = 4.5\text{ V}$
$I_{CC}$	Power Supply Current		65	mA	$V_{CC} = 5.5\text{ V}$ , All Inputs Grounded
$I_{BV}$	Power Supply Current at $V_{CC} = 7\text{ V}$		84	mA	$V_{CC} = 7.0\text{ V}$ , All Inputs Grounded
$I_{CEX}$	Output Leakage Current		250	$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ , $V_{CEX} = 5.5\text{ V}$ , all inputs grounded
$V_{OL}$	Output Low Voltage		0.45	V	$V_{CC} = 4.5\text{ V}$ , One Bit Selected $I_{OL} = 20\text{ mA}$ (A6A9033512 - A3F9033512)
$V_{XY(W)}$	Address Input Threshold to Prevent Writing		0.75	V*	$V_{CC} = 5.0\text{ V}$ , other X and Y grounded. Alternately pulse $W_0$ and $W_1$ , cell must not change state.
$V_{XY(W)}$	Address Input Threshold to insure Writing	2.1		V*	$V_{CC} = 5.0\text{ V}$ , other X and Y grounded. Alternately pulse $W_0$ and $W_1$ , cell state must alternate.
$V_{XY(R)}$	Address Input Threshold to Prevent Reading		0.8	V	$V_{CC} = 5.0\text{ V}$ , other inputs grounded. Both outputs must be on "high" state.
$V_{XY(R)}$	Address Input Threshold to Insure Reading	2.1		V*	$V_{CC} = 5.0\text{ V}$ , other X and Y grounded. Alternately pulse $W_0$ and $W_1$ , cell state must alternate.
$V_{W(W)}$	Write Input Threshold to Prevent Writing		0.8	V*	$V_{CC} = 5.0\text{ V}$ , one X and one Y to 4.5 V, other X and Y grounded. One write input to $V_{W(W)}$ , pulse the other write input. If $W_0$ is pulsed, $S_0$ will assume low state. If $W_1$ is pulsed, $S_1$ will assume low state.
$V_{W(W)}$	Write Input Threshold to Insure Writing	2.1		V*	$V_{CC} = 5.0\text{ V}$ , one X and one Y to 4.5 V, other X and Y grounded. One write input to $V_{W(W)}$ , pulse the other write input. If $W_0$ is pulsed, $S_1$ will assume low state. If $W_1$ is pulsed, $S_0$ will assume low state.

## ELECTRICAL CHARACTERISTICS ( $T_A = 0^\circ\text{C}$ to $75^\circ\text{C}$ , $V_{CC} = 5.0\text{ V} \pm 5\%$ )

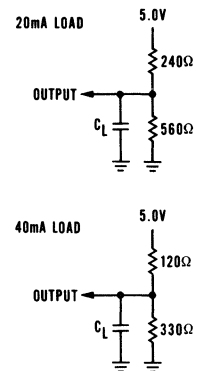
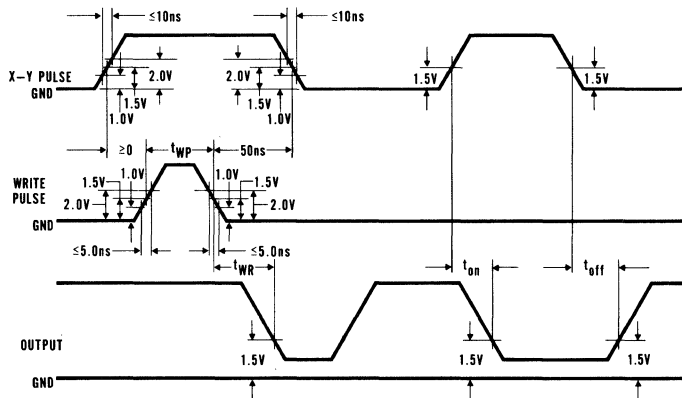
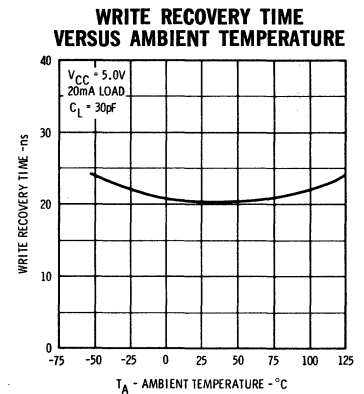
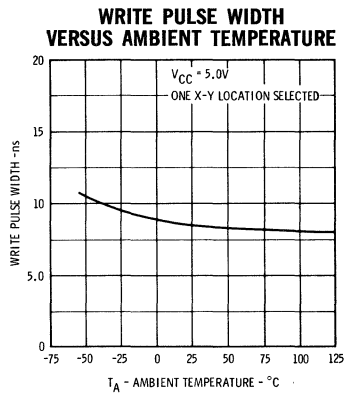
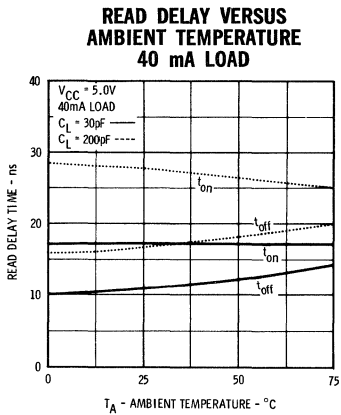
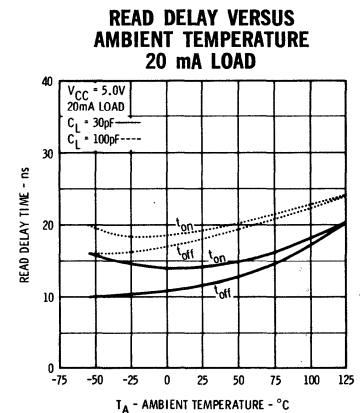
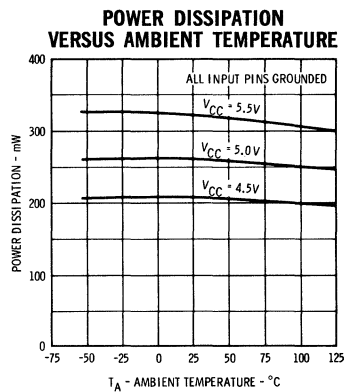
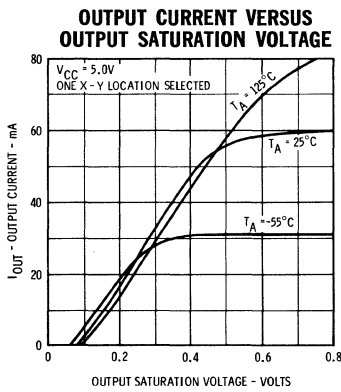
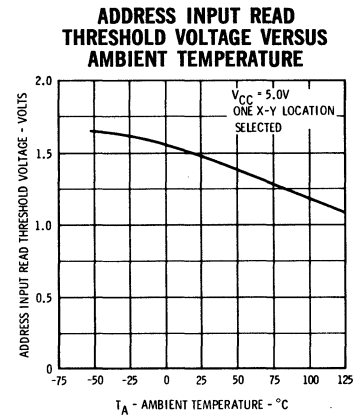
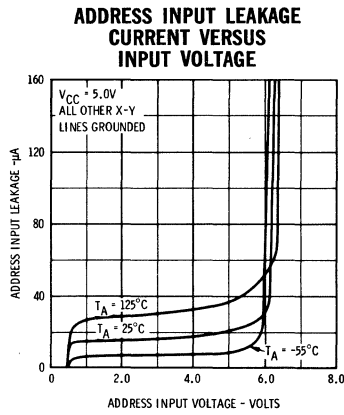
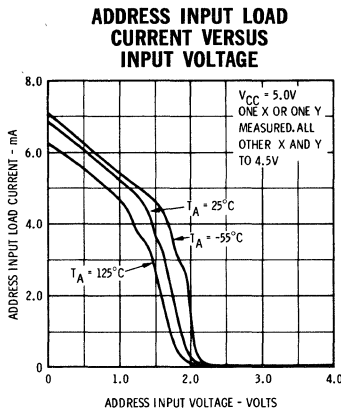
SYMBOL	TEST	LIMITS		UNITS	TEST CONDITIONS
		MIN.	MAX.		
$I_{FX}$	X Address Input Load Current		11	mA	$V_{CC} = 5.25\text{ V}$ , $V_X = 0\text{ V}$ , $V_Y = 4.5\text{ V}$ , other X inputs grounded
$I_{FY}$	Y Address Input Load Current		11	mA	$V_{CC} = 5.25\text{ V}$ , $V_Y = 0\text{ V}$ , $V_X = 4.5\text{ V}$ , other X inputs grounded
$I_{RX}$	X Address Input Leakage Current		400	$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ , $V_X = 4.5\text{ V}$ , other X and Y inputs grounded
$I_{RY}$	Y Address Input Leakage Current		400	$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ , $V_Y = 4.5\text{ V}$ , other X and Y inputs grounded
$I_{FW}$	Write Input Load Current		1.5	mA	$V_{CC} = 5.25\text{ V}$ , $V_W = 0\text{ V}$
$I_{RW}$	Write Input Leakage Current		100	$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ , $V_W = 4.5\text{ V}$
$I_{CC}$	Power Supply Current		65	mA	$V_{CC} = 5.25\text{ V}$ , All Inputs Grounded
$I_{BV}$	Power Supply Current at $V_{CC} = 7\text{ V}$		95	mA	$V_{CC} = 7.0\text{ V}$ , All Inputs Grounded
$I_{CEX}$	Output Leakage Current		250	$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ , $V_{CEX} = 5.5\text{ V}$ , all inputs grounded
$V_{OL}$	Output Low Voltage		0.45	V	$V_{CC} = 4.75\text{ V}$ , One bit selected $I_{OL} = 20\text{ mA}$ (A6A9033592 - A3F9033592) $I_{OL} = 40\text{ mA}$ (A6A9033591 - A3F9033591)
$V_{XY(W)}$	Address Input Threshold to Prevent Writing		0.8	V*	$V_{CC} = 5.0\text{ V}$ , other X and Y grounded. Alternately pulse $W_0$ and $W_1$ , cell must not change state.
$V_{XY(W)}$	Address Input Threshold to insure Writing	2.0		V*	$V_{CC} = 5.0\text{ V}$ , other X and Y grounded. Alternately pulse $W_0$ and $W_1$ , cell state must alternate.
$V_{XY(R)}$	Address Input Threshold to Prevent Reading		1.0	V	$V_{CC} = 5.0\text{ V}$ , other inputs grounded. Both outputs must be on "high" state.
$V_{XY(R)}$	Address Input Threshold to Insure Reading	2.0		V*	$V_{CC} = 5.0\text{ V}$ , other X and Y grounded. Alternately pulse $W_0$ and $W_1$ , cell state must alternate.
$V_{W(W)}$	Write Input Threshold to Prevent Writing		1.0	V*	$V_{CC} = 5.0\text{ V}$ , one X and one Y to 4.5 V, other X and Y grounded. One write input to $V_{W(W)}$ , pulse the other write input. If $W_0$ is pulsed, $S_0$ will assume low state. If $W_1$ is pulsed, $S_1$ will assume low state.
$V_{W(W)}$	Write Input Threshold to Insure Writing	2.0		V*	$V_{CC} = 5.0\text{ V}$ , one X and one Y to 4.5 V, other X and Y grounded. One write input to $V_{W(W)}$ , pulse the other write input. If $W_0$ is pulsed, $S_1$ will assume low state. If $W_1$ is pulsed, $S_0$ will assume low state.

\* Amplitude of the pulse  $\geq 2.5\text{ V}$ , pulse width  $\geq 100\text{ ns}$ . The cell state is determined 35 ns after pulse disappears.

## SWITCHING CHARACTERISTICS

SYMBOL	CHARACTERISTICS	9033511			9033591		9033592		UNITS	CONDITIONS		
		-55°C to 125°C		0°C to 75°C		0°C to 75°C		LOAD		$C_L$	INPUT	
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	(mA)	(pF)			
$t_{WP}$	Write Pulse Width	25		25		25		20		$V_{CC} = 5.0\text{ V}$ , One X-Y Location Selected		
$t_{WR}$	Write Recovery Time		40		35		35	40	30			
$t_{on}$	Turn On Delay		25		20		20	40	30			
			35		30		30	20	100	$V_{CC} = 5.0\text{ V}$ , One X-Y Location Switched		
							20	40	30			
							30	40	200			
$t_{off}$	Turn Off Read Delay		25		20		20	20	30			
			35		30		30	40	100			
							20	40	30			
							30	40	200			

TYPICAL ELECTRICAL CHARACTERISTICS





**APPLICATION:**

A memory utilizing 9033 memory cells may have any desired word length. The number of words in the memory is a multiple of four words. The following example of a 64 word memory illustrates how a number of 16 bit memory cells 9033 may be used to construct a typical memory.

The 64 word memory as shown in Figure A consists of groups of four 9033 memory cells. Each of the groups of four 9033 memory cells supplies one bit for each of the 64 words stored in the memory. All bits belonging to one word are stored in the same address location. Therefore, the address of a word in the memory is the address of each of the bits of the addressed word in the groups of four 9033 memory cells. The equal outputs of the four memory cells are tied together so that each group of four memory cells has one high and one low level output.

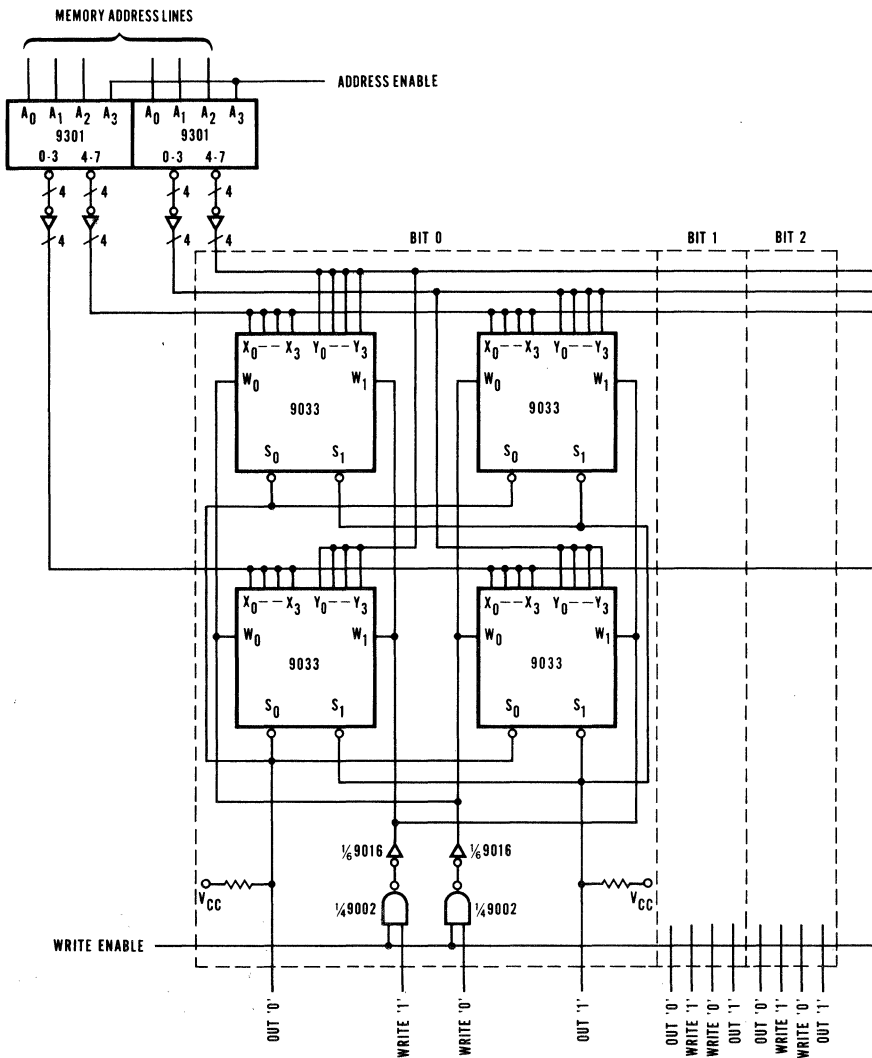
The six memory address lines from an external source are decoded at the first level with two 9301 decoders. The fourth input to each of the two decoders can be used as an enable control input to the 64 word memory. If the address enable is at a low logic level, one and only one of the eight outputs, 0 to 7, in the illustration assumes a low logic level. If the address enable is at a high logic level, the outputs 0 to 7 of the two decoders assume a high logic level, thus none of the 64 words stored in the memory is addressed. The outputs, 0 to 7, of the two decoders serve as X-and-Y address lines. The output signals of the decoders are connected to driving transistors which provide the necessary current to address the memory cells.

The example given above is only one of the many organizations and is presented as an illustration. Obviously many address decoding schemes may be utilized depending on memory size, driver fan-out, decoder fan-out, wiring, heat dissipation, etc.

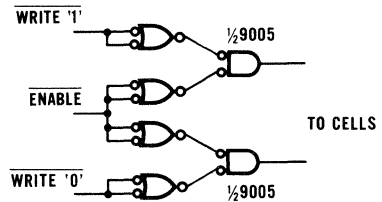
Figures B through D show alternative schemes to enter data into the memory cell.

**LOGIC DIAGRAM**

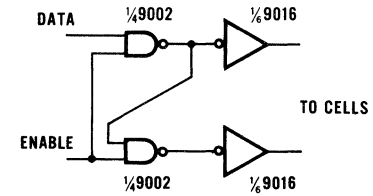
**Fig. A**



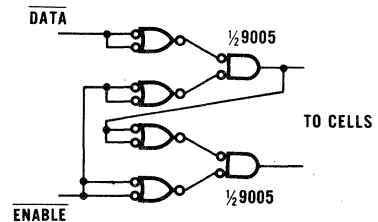
**Fig. B**  
**DOUBLE RAIL ACTIVE LOW INPUTS AND ENABLE**



**Fig. C**  
**SINGLE RAIL ACTIVE HIGH INPUT AND ENABLE**



**Fig. D**  
**SINGLE RAIL ACTIVE LOW INPUT AND ENABLE**



# M $\mu$ L9034

## 256-BIT READ ONLY MEMORY

### MEMORY MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS

#### A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION**—The Fairchild M $\mu$ L9034 is a 256-bit bipolar transistor read only memory. The memory is organized as 32 words of 8-bits each. The words are selected through 5 address lines. The 8 outputs of the words are uncommitted collectors which may be wired-or'd with the outputs of other ROM's. An Enable input is provided for additional decoding flexibility. A low Enable forces all outputs to be high.

The contents of the memory are permanently programmed on customer request.

**FEATURES:**

- CCSL COMPATIBLE
- OUTPUT WIRED-OR'D ABLE WITH OTHER OUTPUTS
- SINGLE TTL LOAD INPUTS

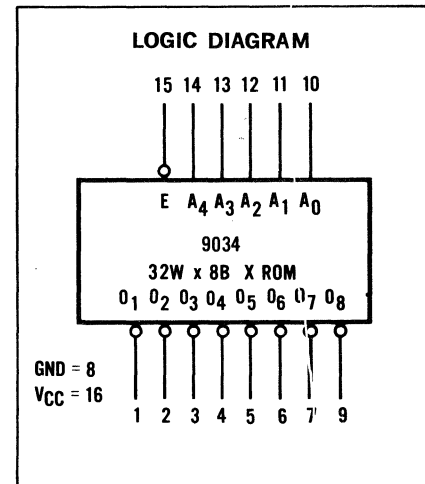
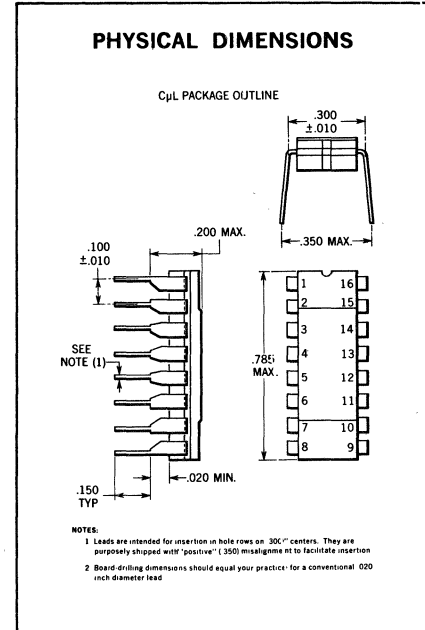
**ABSOLUTE MAXIMUM RATINGS**

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground	-0.5 V to +8.0 V
Input Pin Voltage	-1.5 V to 5.5 V
Current Into Output Terminal	100 mA
Output Voltages	-0.5 to V <sub>CC</sub> Value

**ORDER INFORMATION**

**Custom Code**—Specify A6B9034XXX where X1X is for -55°C to +125°C temperature range or X9X is for 0°C to +75°C temperature range. Remaining X's are to be assigned alphabet letters to customer code.

**Standard Code Available**—Specify A6B9034A1A or A6B9034A9A for figures 1 thru 6 code. Specify A6B9034A1B or A6B9034A9B for figures 7 thru 0, comma and period code. For additional information on these two codes refer to individual data sheets.



# FAIRCHILD MEMORY MICROLOGIC® INTEGRATED CIRCUIT M $\mu$ L9034

## ELECTRICAL CHARACTERISTICS ( $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ , $V_{CC} = 5.0\text{ V} \pm 10\%$ )

SYMBOL	TEST	LIMITS						UNITS	TEST CONDITIONS
		$-55^\circ\text{C}$		$+25^\circ\text{C}$		$+125^\circ\text{C}$			
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
$I_{FA}$	Address Input Load Current		1.6	1.6	1.6		mA	$V_{CC} = 5.5\text{ V}$ $V_A = 0$	
$I_{FI}$	Enable Input Load Current		1.6	1.6	1.6		mA	$V_{CC} = 5.5\text{ V}$ $V_E = 0$	
$I_{RA}$	Address Input Leakage Current		100	100	100		$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ $V_A = 4.5\text{ V}$	
$I_{RI}$	Enable Input Leakage Current		100	100	100		$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ $V_I = 4.5\text{ V}$	
$I_{CEX}$	Output Leakage Current		100	100	100		$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ $V_{CEX} = 5.5\text{ V}$ Enable Input to 2.0 V	
$V_{OL}$	Output Low Voltage		0.45	0.45	0.45		V	$V_{CC} = 4.5\text{ V}$ $I_{OUT} = 10\text{ mA}$ The word containing a "1" bit is selected when performing this test.	
$V_{IL}$	Input Low Voltage		0.8	0.9	0.8		V	$V_{CC} = 5.5\text{ V}$ Enable input grounded. Monitor appropriate output to guarantee this test.	
$V_{IH}$	Input High Voltage	2.1		2.0		2.0	V	$V_{CC} = 4.5\text{ V}$ Enable input grounded. Monitor appropriate output to guarantee this test.	

## ELECTRICAL CHARACTERISTICS ( $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$ , $V_{CC} = 5.0\text{ V} \pm 5\%$ )

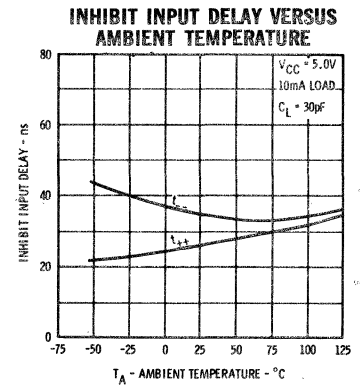
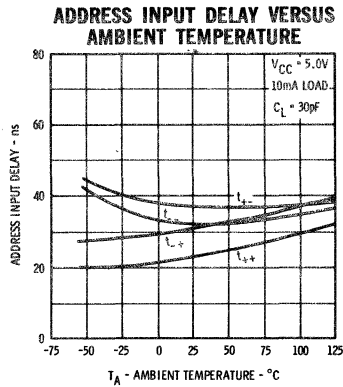
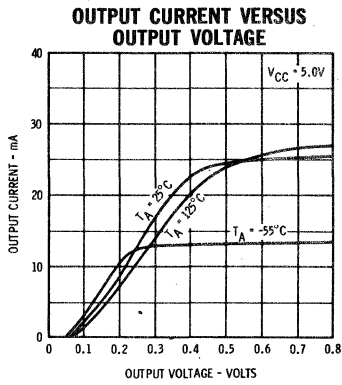
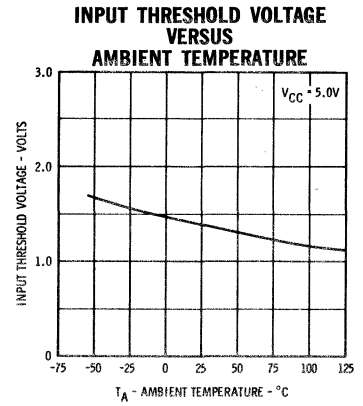
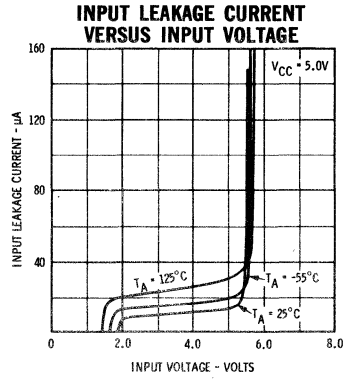
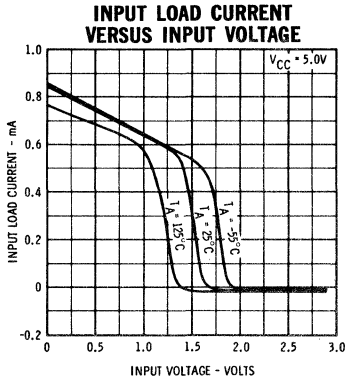
SYMBOL	TEST	LIMITS						UNITS	TEST CONDITIONS
		$0^\circ\text{C}$		$+25^\circ\text{C}$		$+75^\circ\text{C}$			
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
$I_{FA}$	Address Input Load Current		1.6	1.6	1.6		mA	$V_{CC} = 5.25\text{ V}$ $V_A = 0$	
$I_{FI}$	Enable Input Load Current		1.6	1.6	1.6		mA	$V_{CC} = 5.25\text{ V}$ $V_E = 0$	
$I_{RA}$	Address Input Leakage Current		100	100	100		$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ $V_A = 4.5\text{ V}$	
$I_{RI}$	Enable Input Leakage Current		100	100	100		$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ $V_I = 4.5\text{ V}$	
$I_{CEX}$	Output Leakage Current		100	100	100		$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ $V_{CEX} = 5.25\text{ V}$ Enable Input to 2.0 V	
$V_{OL}$	Output Low Voltage		0.45	0.45	0.45		V	$V_{CC} = 4.75\text{ V}$ $I_{OUT} = 10\text{ mA}$ The word containing a "1" bit is selected when performing this test.	
$V_{IL}$	Input Low Voltage		0.85	0.9	0.85		V	$V_{CC} = 5.25\text{ V}$ Enable input grounded. Monitor appropriate output to guarantee this test.	
$V_{IH}$	Input High Voltage	2.0		2.0		2.0	V	$V_{CC} = 4.75\text{ V}$ Enable input grounded. Monitor appropriate output to guarantee this test.	

## SWITCHING CHARACTERISTICS ( $T_A = +25^\circ\text{C}$ , $V_{CC} = 5.0\text{ V}$ )

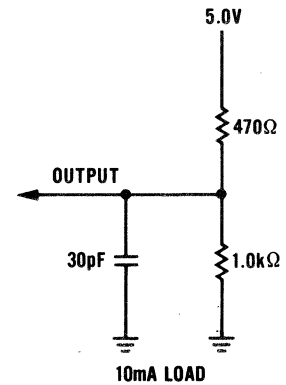
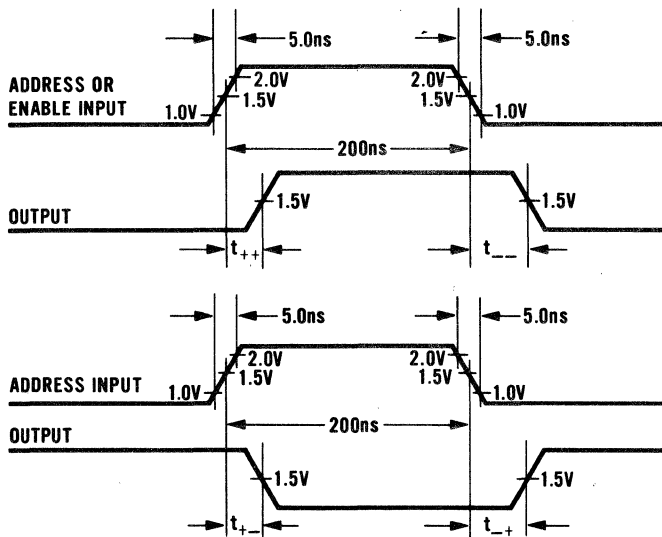
SYMBOL	LIMIT (Max.)	NOTE	CONDITION		$C_L$	NOTES:
			LOAD			
$t_{++}$	50 ns	1	10 mA		30 pF	(1) To test enable delay, apply input pulse to enable input. The word selected must contain a "1" in the bit under test. To test address delay, apply input pulse to the address input under test. The words selected must contain a "1" when input pulse is low and a "0" when input pulse is high in the bit under test. (2) To test address delay, apply input pulse to the address input under test. The words selected must contain a "0" when input pulse is low and a "1" when input pulse is high in the bit under test.
$t_{--}$	50 ns	1	10 mA		30 pF	
$t_{+-}$	50 ns	2	10 mA		30 pF	
$t_{-+}$	50 ns	2	10 mA		30 pF	

# FAIRCHILD MEMORY MICROLOGIC® INTEGRATED CIRCUIT M $\mu$ L9034

## TYPICAL ELECTRICAL CHARACTERISTICS



## SWITCHING TIME TEST CONDITIONS AND WAVEFORMS



# FAIRCHILD MEMORY MICROLOGIC® INTEGRATED CIRCUIT M $\mu$ L9034

## APPLICATIONS:

The Fairchild M $\mu$ L9034 Read-Only Memory has many storage and display applications. Two main uses of the memory are for 1) microprogrammed subroutines (core replacements) and 2) character generator display systems.

## APPLICATION OF THE 9034 READ-ONLY MEMORY IN DIFFERENT TYPES OF DISPLAY SYSTEMS.

In the application of this ROM as display storage, the enable input is the most important control, since every display system requires a number of ROM's organized in parallel to each other. The effectiveness of such a character storage system depends on the flexibility in addressing a desired character. Most of the character storage systems will be character code oriented.

### 16 SEGMENT DECODER

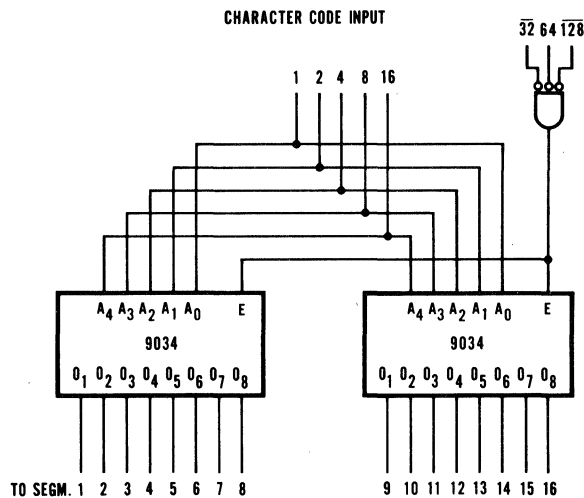
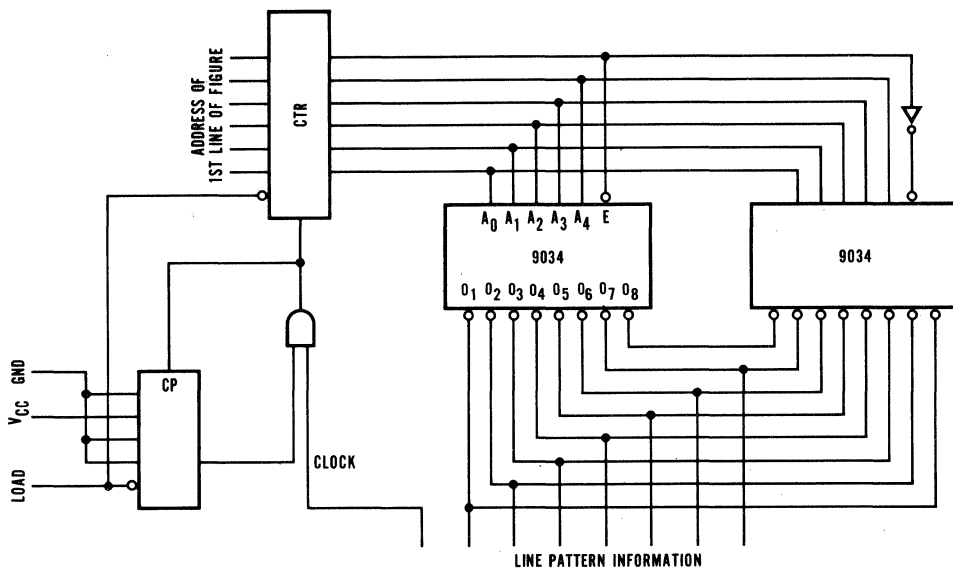


Figure 1a illustrates the use of two 9034 ROM's for driving a 16 segment decoder. The character code is used directly as a control for both ROM's. One additional 3-input gate controlling the enable inputs of the 2 ROM's is required for selecting the group of codes within the ASCII system which refer to the characters. For uninterrupted control, 2 ROM's are required for each of the 16 segment display units.

### DISPLAY GENERATOR 5 x 8 DOT MATRIX



The four 8-bit words representing the 5 x 8 dot pattern of a figure are stored in sequence. The external source which calls for a figure has to supply the address of the first 8-bit word of this figure. The clock will increment this address by one each time the generated pattern has been displayed until all five 8-bit patterns have been used. The mod. 5 counter calls for the first line address of the next figure automatically.

If these data are used to control a CRT display the outputs of the 2 9034 ROM's may be connected to an 8-channel multiplexer (3705) which serves as an interface to the Z modulation input of the display unit. The 8 channels are selected in sequence by a mod. 8 counter of which the eight output generates the control pulses for the mod. 5 and the address counter.

# M $\mu$ L9034AXA

## 256-BIT READ-ONLY MEMORY

### MEMORY MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS

#### GENERAL DESCRIPTION

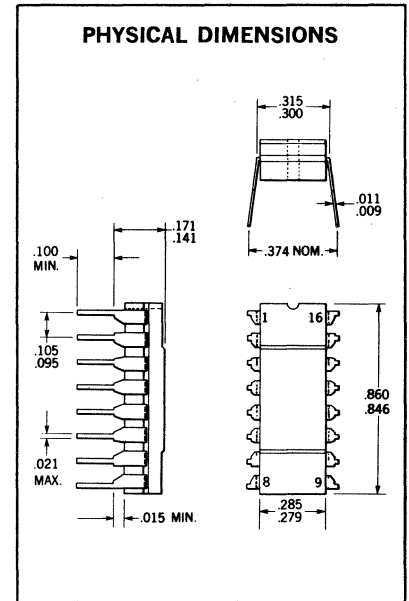
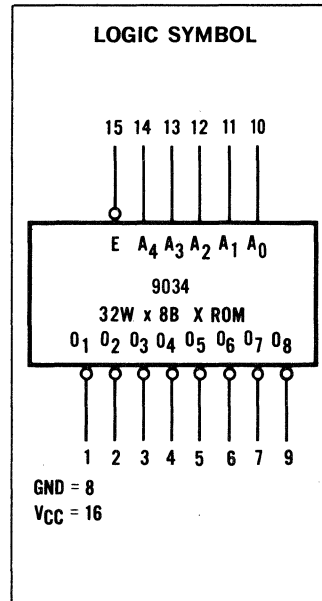
The 9034 Read-Only Memory code AXA (9034AXA) is programmed to store information for generating Figures 1 thru 6 on a 5 by 8 dot pattern display. The memory stores the information by using 5 consecutive words of 8 bits for each figure or symbol.

#### OPERATION AND ELECTRICAL CHARACTERISTICS

Refer to 9034 Data Sheet

#### ORDER INFORMATION

Specify A6B9034AXA where A1A is for -55°C to +125°C temperature range or A9A for the 0°C to +75°C temperature range.



#### 9034AXA TRUTH TABLE

O U T P U T S	O <sub>1</sub>	H	H	L	H	H	H	L	L	L	H	H	L	L	L	H	H	H	H	L	H	L	L	L	L	L	H	L	L	L	H	H	H					
	O <sub>2</sub>	H	L	L	H	H	L	H	H	H	L	L	H	H	L	L	L	H	H	L	H	L	H	H	H	H	H	L	H	H	H	H	H	H				
O <sub>3</sub>	H	H	L	H	H	H	H	L	H	H	H	H	L	L	H	L	H	H	L	H	L	L	L	L	L	H	L	L	L	L	H	H	H	H				
O <sub>4</sub>	H	H	L	H	H	H	L	H	H	H	H	H	L	L	H	L	H	H	L	H	L	L	L	L	L	H	L	L	L	L	L	H	H	H	H			
O <sub>5</sub>	H	H	L	H	H	H	L	H	H	H	H	H	H	L	L	H	H	L	H	H	H	H	H	H	H	L	L	H	H	H	H	H	H	H	H			
O <sub>6</sub>	H	H	L	H	H	L	H	H	H	H	H	H	H	L	L	L	L	L	L	H	H	H	H	H	H	L	L	H	H	H	H	H	H	H	H			
O <sub>7</sub>	H	H	L	H	H	L	H	H	H	H	H	H	H	L	L	H	H	L	H	H	H	H	H	H	H	L	L	L	L	H	H	H	H	H	H	H		
O <sub>8</sub>	H	L	L	L	H	L	L	L	L	L	H	L	L	L	L	H	H	H	H	L	H	L	L	L	L	L	L	L	L	L	L	L	L	L	L	H	H	
I N P U T S	A <sub>0</sub>	L	H	L	H	L	H	L	H	L	H	L	H	L	H	L	H	L	H	L	H	L	H	L	H	L	H	L	H	L	H	L	H	L	H	L	H	
	A <sub>1</sub>	L	L	H	H	L	L	H	H	L	L	H	H	L	L	H	H	L	L	H	H	L	L	H	H	L	L	H	H	L	L	H	H	L	L	H	H	
A <sub>2</sub>	L	L	L	L	H	H	H	H	L	L	L	L	H	H	H	H	L	L	L	L	H	H	H	H	L	L	L	L	H	H	H	H	H	H	H	H	H	
A <sub>3</sub>	L	L	L	L	L	L	L	L	L	H	H	H	H	H	H	H	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L
A <sub>4</sub>	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L
O U T P U T S	O <sub>1</sub>	[Dot pattern for O1]																																				
	O <sub>2</sub>	[Dot pattern for O2]																																				
O <sub>3</sub>	[Dot pattern for O3]																																					
O <sub>4</sub>	[Dot pattern for O4]																																					
O <sub>5</sub>	[Dot pattern for O5]																																					
O <sub>6</sub>	[Dot pattern for O6]																																					
O <sub>7</sub>	[Dot pattern for O7]																																					
O <sub>8</sub>	[Dot pattern for O8]																																					
W O R D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32						
	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32							

L — Low Voltage    H — High Voltage

313 FAIRCHILD DRIVE, MOUNTAIN VIEW, CALIFORNIA, (415) 962-5011, TWX: 910-379-6435





# M $\mu$ L9035

## 64-BIT READ/WRITE MEMORY CELL MEMORY MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS

### A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The 9035 is a high speed 64-bit read/write memory cell designed for use in high speed scratch pad memories. It is organized in a linear select 16 word by 4-bit array. The 9035 is made with TT $\mu$ L circuitry making it CCSL compatible.

The 9035 is available in the hermetically sealed 36-pin ceramic dual in-line package and will operate over the temperature range from  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ .

**OPERATION** — In addition to 16 address lines, 4 data outputs, and 4 data inputs, the 9035 has a chip select and a write enable. When the chip select is high, a word may be addressed by a high on the address input. Data is written into the addressed word only when the write enable is held low. While the address is present, the outputs continuously show the contents of the word selected. Readout is non-destructive.

Up to four words may be addressed and read simultaneously with the OR function of the words appearing at the output. Data can be written into two locations simultaneously.

Uncommitted collector outputs are provided on the 9035 to allow maximum flexibility in output connection. In many applications such as word expansion, the outputs of many 9035's are wire-OR'd together. In other applications the wire-OR is not used. In either case an external pullup resistor of value R must be used to provide a high at the output when it is off. Any value of R within the range specified below may be used.

$$\frac{5.1}{10 - \text{F.O. (1.6)}} \leq R \leq \frac{2.1}{N(0.1) + \text{F.O. (0.06)}}$$

R is in K $\Omega$   
 N = number of  
 outputs wire-OR'd  
 F.O. = number of  
 TT $\mu$ L loads driven

The minimum value of R is limited by output current sinking ability. The maximum value of R is determined by the output and input leakage current ( $I_{\text{CEX}}$  and  $I_{\text{R}}$ ) which must be supplied to hold the output at 2.4 V.

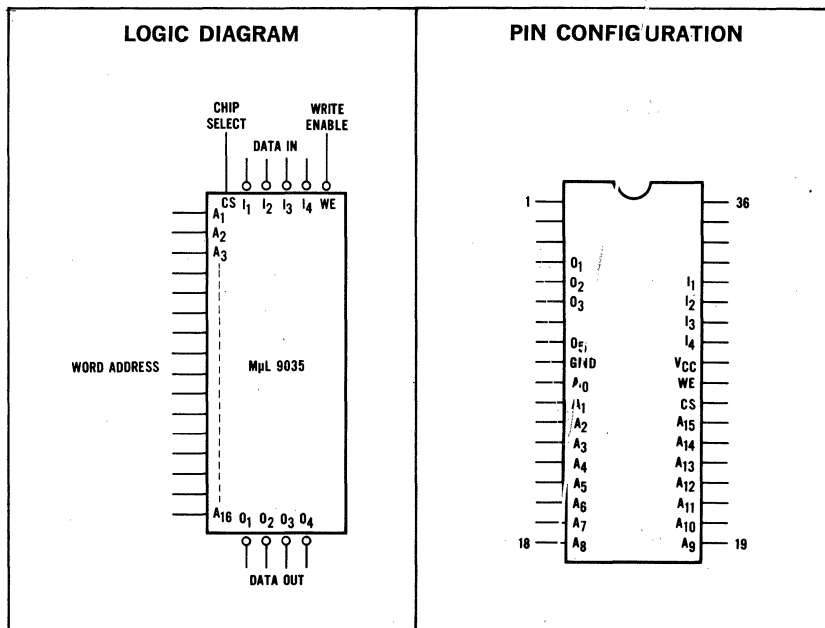
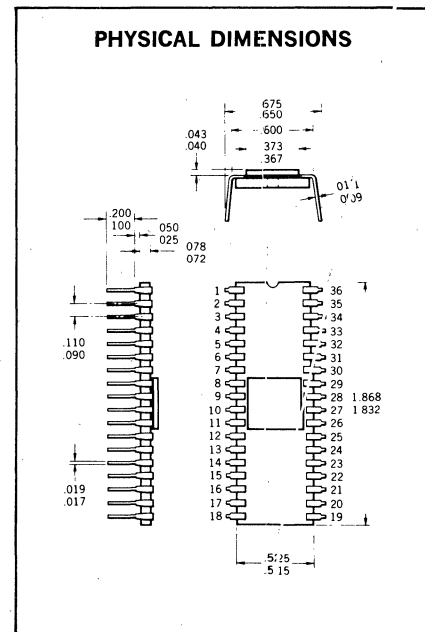
**FEATURES:**

- 35 ns READ ACCESS TIME
- CHIP SELECT AND WRITE ENABLES
- UNCOMMITTED COLLECTOR OUTPUTS FOR WIRE OR CAPABILITY
- LINEAR SELECT
- ON CHIP ADDRESS LINE BUFFERING
- CCSL COMPATIBLE

**ABSOLUTE MAXIMUM RATINGS**

Storage Temperature	$-65^{\circ}\text{C}$ to $+150^{\circ}\text{C}$ .
Temperature (Ambient) Under Bias	$-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$
V <sub>CC</sub> Pin Potential to Ground	$-0.5$ V to $+8.0$ V
Input Pin Voltage	$-1.5$ V to $+5.5$ V
Current into Output Terminal	100 mA
Output Voltage	$-0.5$ V to $+8.0$ V

**ORDER INFORMATION** — Specify A6H\*9035XXX where XXX is 51X for the  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$  temperature range or 59X for the  $0^{\circ}\text{C}$  to  $75^{\circ}\text{C}$  temperature range.





# FAIRCHILD MEMORY MICROLOGIC® INTEGRATED CIRCUIT M $\mu$ L9035

## LOADING RULES

	HIGH LEVEL (TT $\mu$ L Unit Loads)	LOW LEVEL (TT $\mu$ L Unit Loads)
Address	1.67	1
Chip Select	26.7	1 (see note 1)
Write Enable	1.67	1
Data Input	3.34	2
Data Output	Open Collector	6.2

1 Low Level TT $\mu$ L Unit Load = 60  $\mu$ A

1 High Level TT $\mu$ L Unit Load = -1.6 mA

## ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = -55°C to 125°C, V<sub>CC</sub> = 5.0 V $\pm$ 10%)

SYMBOL	TEST	LIMITS						UNITS	CONDITIONS
		-55°C		+25°C		+125°C			
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
I <sub>FA</sub>	Address Input Load Current		-1.6		-1.6		-1.6	mA	V <sub>CC</sub> = 5.5 V, V <sub>A</sub> = 0.4 V
I <sub>FS</sub>	Chip Select Load Current		-1.6		-1.6		-1.6	mA	V <sub>CC</sub> = 5.5 V, V <sub>CS</sub> = 0.4 V See Note 1
I <sub>FW</sub>	Write Enable Load Current		-1.6		-1.6		-1.6	mA	V <sub>CC</sub> = 5.5 V, V <sub>W</sub> = 0.4 V
I <sub>FD</sub>	Data Input Load Current		-3.2		-3.2		-3.2	mA	V <sub>CC</sub> = 5.5 V, V <sub>D</sub> = 0.4 V
I <sub>RA</sub>	Address Input Leakage Current		100		100		100	$\mu$ A	V <sub>CC</sub> = 5.5 V, V <sub>A</sub> = 4.5 V
I <sub>RS</sub>	Chip Select Input Leakage Current		1.6		1.6		1.6	mA	V <sub>CC</sub> = 5.5 V, V <sub>CS</sub> = 4.5 V
I <sub>RW</sub>	Write Enable Leakage Current		100		100		100	$\mu$ A	V <sub>CC</sub> = 5.5 V, V <sub>W</sub> = 4.5 V
I <sub>RD</sub>	Data Input Leakage Current		200		200		200	$\mu$ A	V <sub>CC</sub> = 5.5 V, V <sub>D</sub> = 4.5 V
I <sub>CEX</sub>	Output Leakage Current		200		200		200	$\mu$ A	V <sub>CC</sub> = 5.5 V, V <sub>CEX</sub> = 5.5 V Enable Input Grounded
V <sub>OL</sub>	Output "Low" Voltage		0.4		0.4		0.4	V	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 10 mA One Word Selected
V <sub>IL</sub>	Input "Low" Voltage		0.8		0.8		0.8	V	V <sub>CC</sub> = 5.0 V, Monitor Appropriate Output To Guarantee This Test Limit
V <sub>IH</sub>	Input "High" Voltage	2.1		2.0		2.0		V	V <sub>CC</sub> = 5.0 V, Monitor Appropriate Output To Guarantee This Test Limit
I <sub>PD</sub>	Supply Current		118		118		118	mA	V <sub>CC</sub> = 5.5 V, One Word Selected

NOTE 1: I<sub>FE</sub> increases by 1.6 mA for each address enable held at a logical 1.

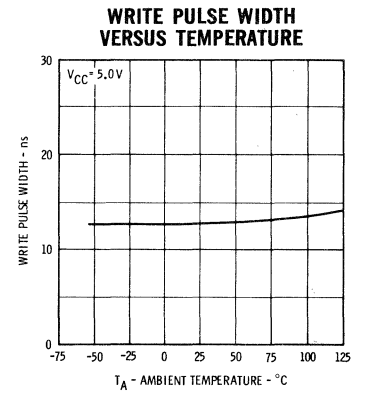
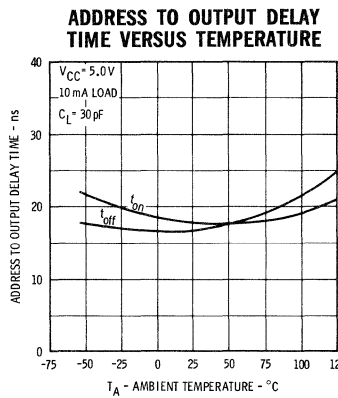
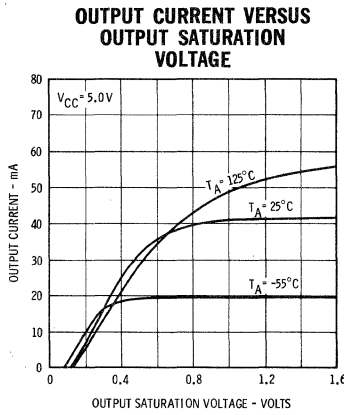
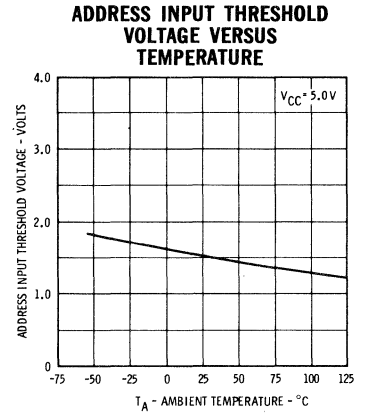
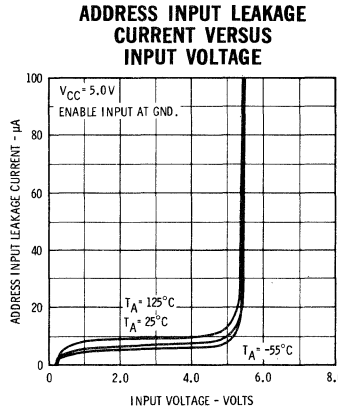
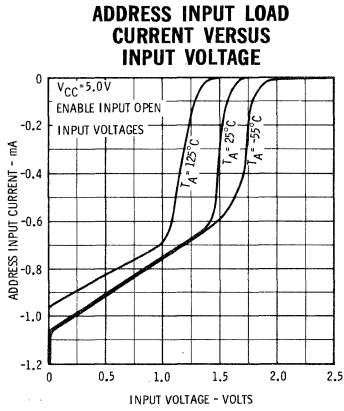
## ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 0°C to 75°C, V<sub>CC</sub> = 5.0 V $\pm$ 5%)

SYMBOL	TEST	LIMITS						UNITS	CONDITIONS
		0°C		+25°C		+75°C			
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
I <sub>FA</sub>	Address Input Load Current		-1.6		-1.6		-1.6	mA	V <sub>CC</sub> = 5.25 V, V <sub>A</sub> = 0.45 V
I <sub>FS</sub>	Chip Select Load Current		-1.6		-1.6		-1.6	mA	V <sub>CC</sub> = 5.25 V, V <sub>CS</sub> = 0.45 V See Note 1
I <sub>FW</sub>	Write Enable Load Current		-1.6		-1.6		-1.6	mA	V <sub>CC</sub> = 5.25 V, V <sub>W</sub> = 0.45 V
I <sub>FD</sub>	Data Input Load Current		-3.2		-3.2		-3.2	mA	V <sub>CC</sub> = 5.25 V, V <sub>D</sub> = 0.45 V
I <sub>RA</sub>	Address Input Leakage Current		100		100		100	$\mu$ A	V <sub>CC</sub> = 5.25 V, V <sub>A</sub> = 4.5 V
I <sub>RE</sub>	Chip Select Leakage Current		1.6		1.6		1.6	mA	V <sub>CC</sub> = 5.25 V, V <sub>CS</sub> = 4.5 V
I <sub>RW</sub>	Write Enable Leakage Current		100		100		100	$\mu$ A	V <sub>CC</sub> = 5.25 V, V <sub>W</sub> = 4.5 V
I <sub>RD</sub>	Data Input Leakage Current		200		200		200	$\mu$ A	V <sub>CC</sub> = 5.25 V, V <sub>D</sub> = 4.5 V
I <sub>CEX</sub>	Output Leakage Current		200		200		200	$\mu$ A	V <sub>CC</sub> = 5.25 V, V <sub>CEX</sub> = 5.25 V Enable Input Grounded
V <sub>OL</sub>	Output "Low" Voltage		0.45		0.45		0.45	V	V <sub>CC</sub> = 4.75 V, I <sub>OL</sub> = 10 mA One Word Selected
V <sub>IL</sub>	Input "Low" Voltage		0.85		0.85		0.85	V	V <sub>CC</sub> = 5.0 V, Monitor Appropriate Output To Guarantee This Test Limit
V <sub>IH</sub>	Input "High" Voltage	2.0		2.0		2.0		V	V <sub>CC</sub> = 5.0 V, Monitor Appropriate Output To Guarantee This Test Limit
I <sub>PD</sub>	Supply Current		124		124		124	mA	V <sub>CC</sub> = 5.25 V, One Word Selected

NOTE 1: I<sub>FE</sub> increases by 1.6 mA for each address enable held at a logical 1.

# FAIRCHILD MEMORY MICROLOGIC® INTEGRATED CIRCUIT M<sub>μ</sub>L9035

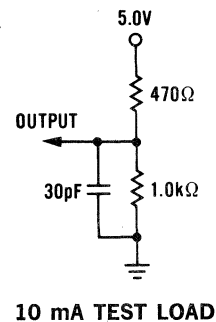
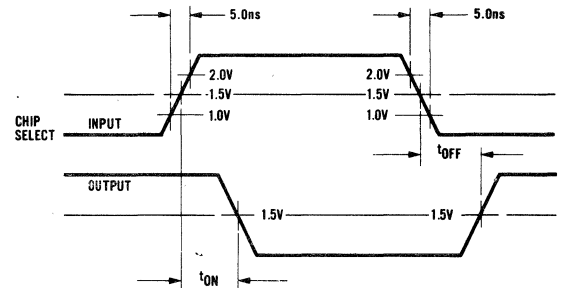
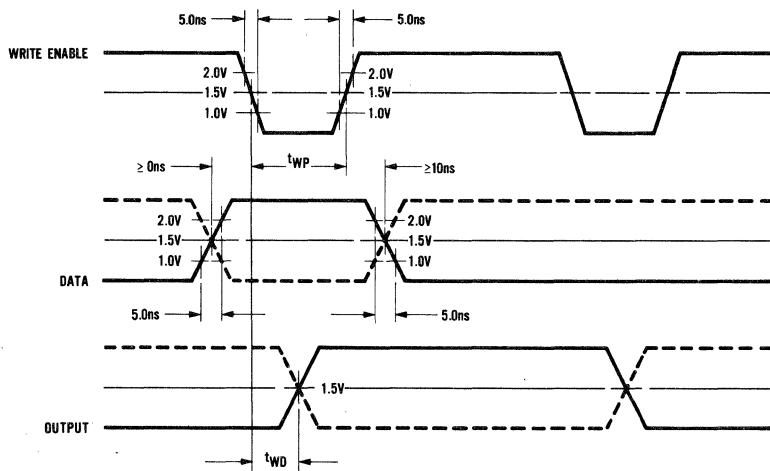
## TYPICAL ELECTRICAL CHARACTERISTICS



### SWITCHING CHARACTERISTICS (T<sub>A</sub> = 25°C, V<sub>CC</sub> = 5.0 V)

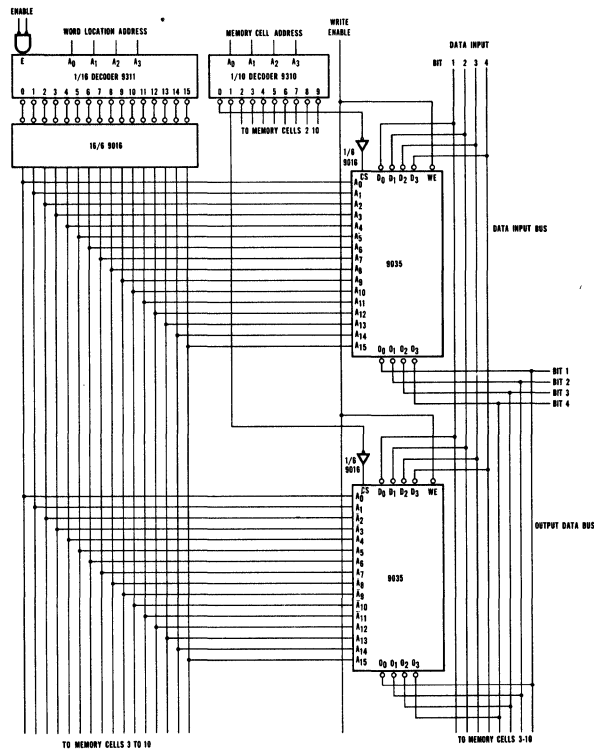
SYMBOL	TEST	LIMIT (ns)			CONDITION		
		MIN.	TYP.	MAX.	LOAD	C	NOTE
t <sub>on</sub>	Address to Output Turn-On Delay		16	35	10 mA	30 pF	1
t <sub>off</sub>	Address to Output Turn-Off Delay		18	35	10 mA	30 pF	1
t <sub>WP</sub>	Write Pulse Width Required to Write	25	15		10 mA	30 pF	2
t <sub>WD</sub>	Write Delay		30	50	10 mA	30 pF	2

NOTE 1: To test t<sub>on</sub> and t<sub>off</sub>, a "Low" must be stored in the cell under test.  
 NOTE 2: One word is selected during the test.



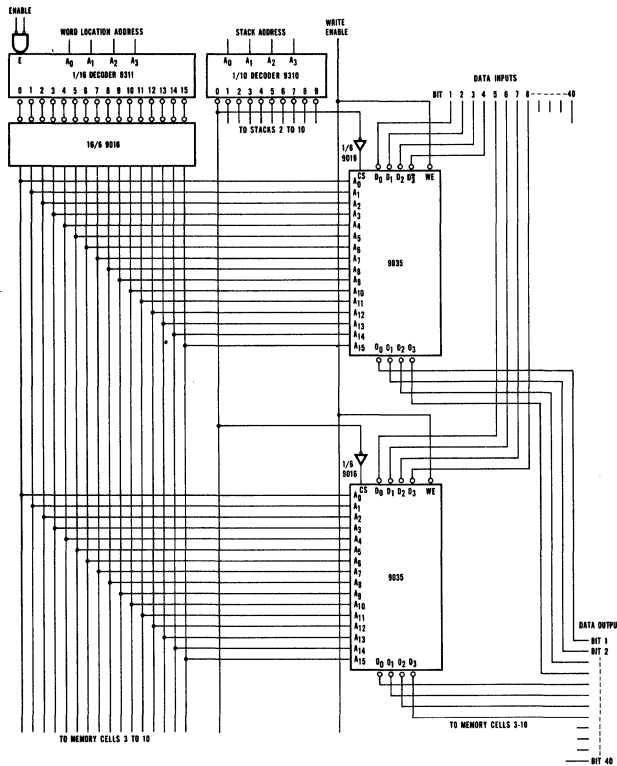
APPLICATIONS

MEMORY EXPANSIONS: N16 WORDS BY 4-BITS



In this application the 9035 memory cells are connected in parallel and two levels of decoding are performed. One of the cells is selected by the 9310 decoder and then a word is addressed by the 9316.

MEMORY STACK 160 WORDS OF 40-BITS



There are 16 words by 40 bits for each stack. The outputs and inputs of all stacks are tied together. Stack 1 contains words 1-16, stack 2, 17-32, and so on through 144-160 for the 10th stack. The stack address decoder tells which word group (1-16 or 17-32, etc.) is addressed while the word location decoder addresses one of the 16 words of the stack addressed. The entire memory has 40 data input lines, 40 data output lines, 8 address lines, and a write enable line.

# LPDT $\mu$ L 9040, 9041 AND 9042

## LOW POWER DIODE TRANSISTOR MICROLOGIC<sup>®</sup>

### INTEGRATED CIRCUITS

#### GENERAL DESCRIPTION

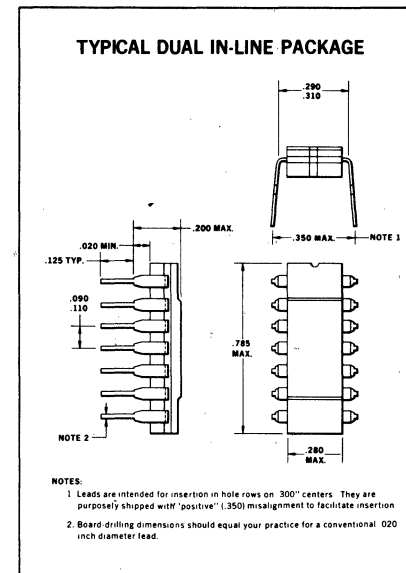
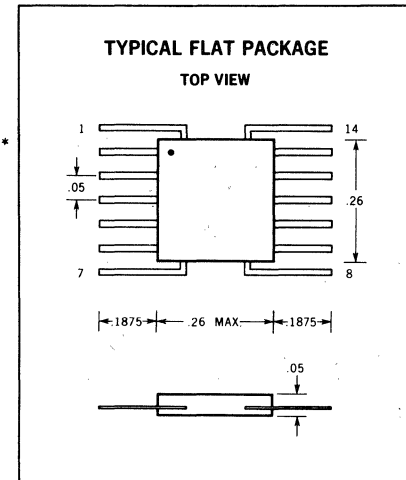
The Fairchild LPDT $\mu$ L Micrologic<sup>®</sup> Integrated Circuit Family consists of a set of compatible, integrated logic circuits specifically designed for low power, medium speed applications.

The circuits are fabricated with a silicon monolithic substrate using standard Fairchild Planar\* epitaxial processes.

Packaging options include the Flat package and the Dual In-Line package.

Important features of the LPDT $\mu$ L Micrologic<sup>®</sup> integrated circuits include the following:

- Reliable operation over the full military temperature range of -55°C to +125°C
- Typical power drains of less than 1 mW per gate (50% duty cycle) for the logic gate elements and less than 4 mW for the clocked flip-flop.
- Single power supply requirement—5 volts optimum, 4.5 to 5.5 volts range.
- Guaranteed fan-out of 10 LPDT $\mu$ L unit loads or 1 standard Fairchild DT $\mu$ L unit load, over the full temperature and supply voltage range.
- Guaranteed minimum of 450 mV noise immunity at the temperature extremes.
- Typical logic gate propagation delays of 60 ns and binary clock rate of 2.5 MHz.
- Emitter follower outputs providing good capacitive drive capability.



\*Planar is a patented Fairchild process.

#### ORDER INFORMATION

To order Low Power Diode Transistor Micrologic<sup>®</sup> integrated circuit elements specify U31XXXX51X for flat package and U6AXXX51X for Dual In-Line package where XXXX is 9040, 9041 or 9042.

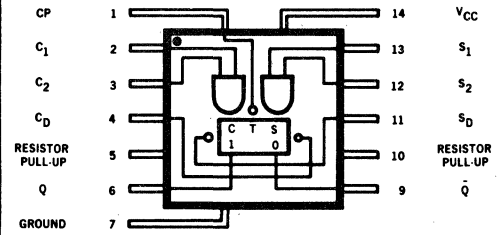
# FAIRCHILD MICROLOGIC® LOW POWER DIODE TRANSISTOR INTEGRATED CIRCUITS

## LPDT $\mu$ L 9040 CLOCKED FLIP-FLOP

### DESCRIPTION

The LPDT $\mu$ L 9040 element is a directly coupled, dual-rank flip-flop suitable for use in counters, shift registers and other storage applications. Either R-S or J-K mode operation is possible. Direct set and clear inputs are provided which override all other data inputs.

### LOGIC DIAGRAM SHOWING FLAT OR DUAL-IN LINE PACKAGE PIN ASSIGNMENT



### SYNCHRONOUS ENTRY TRUTH TABLES

#### R-S MODE OPERATION

#### J-K MODE OPERATION

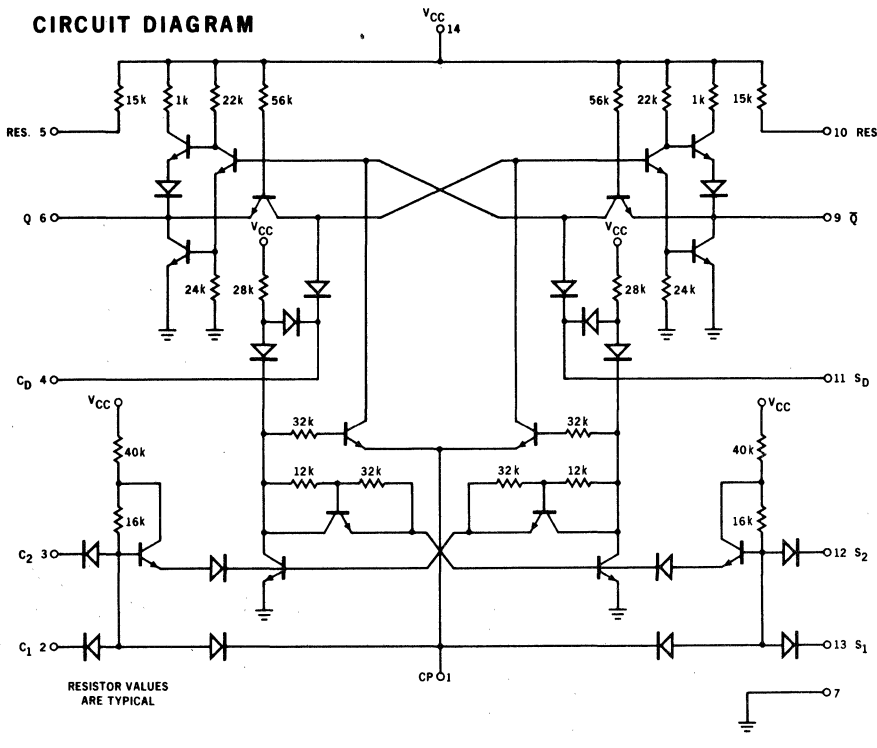
### ASYNCHRONOUS ENTRY TRUTH TABLE

R-S MODE OPERATION						J-K MODE OPERATION				ASYNCHRONOUS ENTRY TRUTH TABLE			
INPUTS @ $t_n$				OUTPUTS @ $t_{n+1}$		INPUTS @ $t_n$		OUTPUTS @ $t_{n+1}$		INPUTS		OUTPUTS	
$S_1$	$S_2$	$C_1$	$C_2$	Q	$\bar{Q}$	$S_1$	$C_1$	Q	$\bar{Q}$	$S_D$	$C_D$	Q	$\bar{Q}$
13	12	2	3	6	9	13	2	6	9	11	4	6	9
L	X	L	X	NC	NC	L	L	NC	NC	H	H	NC	NC
L	X	X	L	NC	NC	L	H	L	H	H	L	L	H
X	L	L	X	NC	NC	H	L	H	L	L	H	H	L
X	L	X	L	NC	NC	H	H	TOGGLES		L	L	H	H
L	X	H	H	L	H	<b>Symbols</b> H - Most positive logic level L - Most negative logic level X - Either H or L can be present NC - No change in state							
X	L	H	H	L	H								
H	H	L	X	H	L								
H	H	X	L	H	L								
H	H	H	H	AMBIGUOUS									

#### NOTES:

- For J-K mode operation connect Pin 6 to Pin 3 and Pin 9 to Pin 12.
- Asynchronous entries override all synchronous entries.

### CIRCUIT DIAGRAM



### LOADING RULES

INPUT	*NORMALIZED UNIT LOADS (U.L.)
$S_1$ $S_2$ $C_1$ $C_2$	0.75 U.L.
$S_D$ $C_D$	2.5 U.L.
CP	2.5 U.L.
OUTPUT	FAN-OUT
$Q, \bar{Q}$	10 U.L. 7 U.L. WITH RESISTOR PULL-UP CONNECTED

\*1 UNIT LOAD EQUALS 1-LPDT $\mu$ L 9041 OR 9042 INPUT LOAD

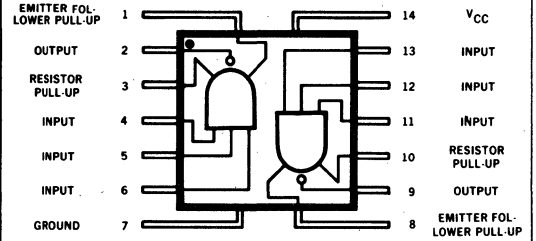
# FAIRCHILD MICROLOGIC® LOW POWER DIODE TRANSISTOR INTEGRATED CIRCUITS

## LPDT $\mu$ L 9041 – DUAL 3 INPUT NAND GATE

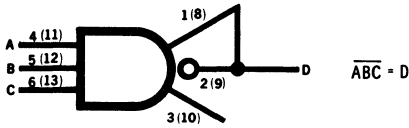
### DESCRIPTION

The LPDT $\mu$ L 9041 element consists of two, 3-input positive logic NAND gates suitable for general logic gate and inverter applications. The unique feature of this gate is that the output transistor collector and the emitter follower pull-up are not internally connected. This allows the user to tie collectors to a common node for the wired "OR" logic function.

### LOGIC DIAGRAM SHOWING FLAT OR DUAL-IN-LINE PACKAGE PIN ASSIGNMENT



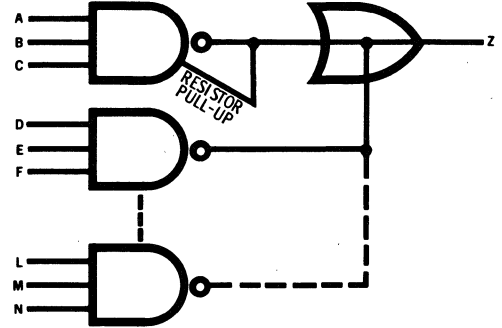
### POSITIVE LOGIC NAND GATE



EACH INPUT = 1 UNIT LOAD  
 OUTPUT FAN-OUT = 10 UNIT LOADS  
 = 7 U.L. WITH RESISTOR PULL-UP CONNECTED

EITHER THE EMITTER FOLLOWER OR RESISTOR PULL-UP MUST BE CONNECTED TO THE OUTPUT TO ESTABLISH THE HIGH LEVEL.

### WIRED 'OR' APPLICATION

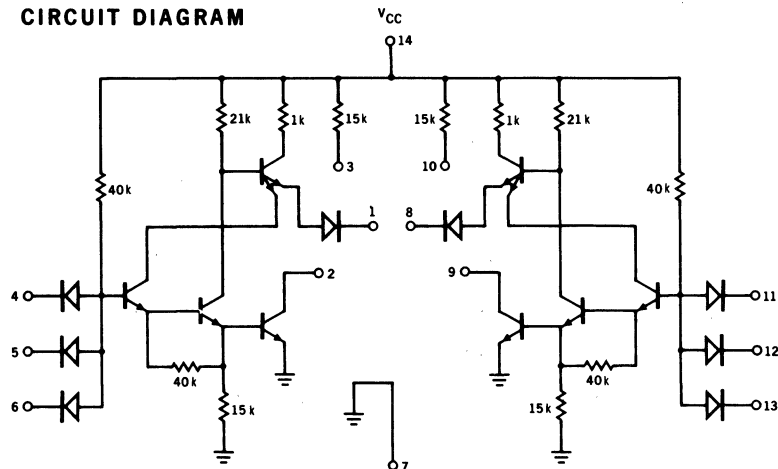


$$ABC + DEF + \dots + LMN = Z$$

OUTPUT FAN-OUT = 10 - 3 (NO. OF RESISTOR PULL-UPS)

ONE PULL-UP RESISTOR IS REQUIRED FOR EVERY 8 GATES CONNECTED TO THE COMMON "OR" NODE.

### CIRCUIT DIAGRAM



RESISTOR VALUES ARE TYPICAL

# FAIRCHILD MICROLOGIC® LOW POWER DIODE TRANSISTOR INTEGRATED CIRCUITS

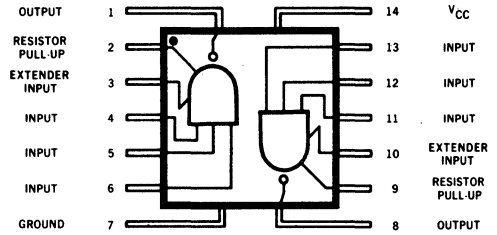
## LPDT $\mu$ L 9042 – DUAL 3 INPUT NAND GATE WITH EXTENDER INPUTS

### DESCRIPTION

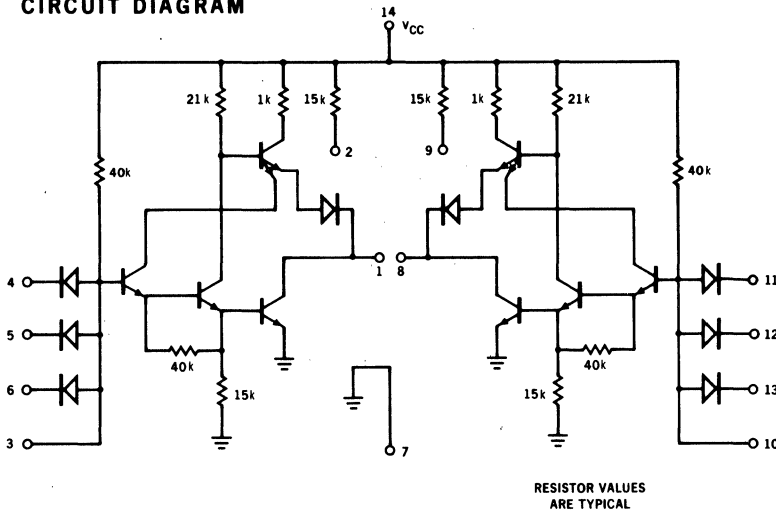
The LPDT $\mu$ L 9042 element consists of two 3-input positive logic NAND gates with extender inputs. This element in the family allows the user to implement logic applications requiring a gate fan-in exceeding three.

The DT $\mu$ L 9933 4-input extender element or equivalent—may be used to provide additional diode inputs. Any capacitance added to the extender input will increase the turn-on delay of the LPDT $\mu$ L 9042 gate. Typically, the increase is 10 ns/picofarad. Turn-off delay is not affected.

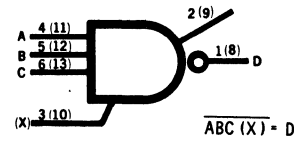
### LOGIC DIAGRAM SHOWING FLAT OR DUAL-IN-LINE PACKAGE PIN ASSIGNMENT



### CIRCUIT DIAGRAM



### POSITIVE LOGIC NAND GATE



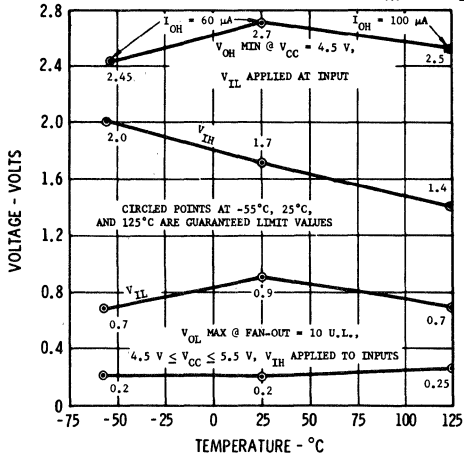
EACH INPUT = 1 UNIT LOAD  
 OUTPUT FAN-OUT = 10 UNIT LOADS  
 = 7 UNIT LOADS WITH RESISTOR PULL-UP CONNECTED

## BUFFER ELEMENT

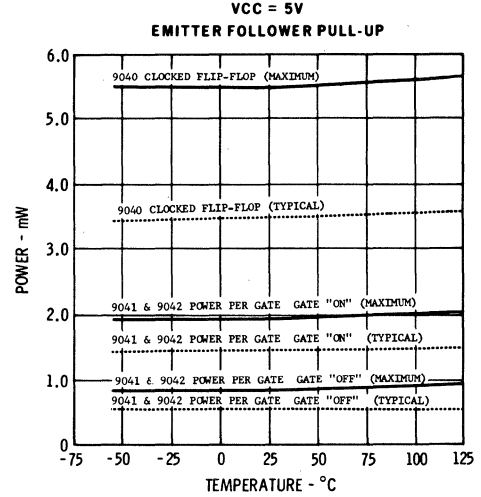
For applications requiring a fan-out exceeding ten, the Fairchild DT $\mu$ L 9930 Dual 4-Input Gate may be used. The DT $\mu$ L 9930 will drive 44 LPDT $\mu$ L unit loads, while maintaining the same output logic levels as the low power circuits.

The input of a DT $\mu$ L 9930 requires the equivalent of 10 LPDT $\mu$ L unit loads. Therefore, a low power circuit can drive only one DT $\mu$ L 9930 input.

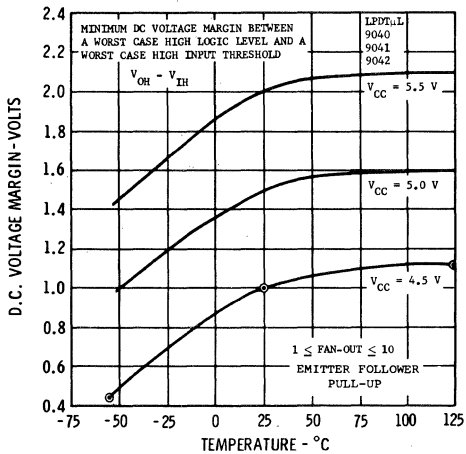
**OPERATING VOLTAGE CHARACTERISTICS**  
**OUTPUT LOGIC LEVELS -  $V_{OH}$  AND  $V_{OL}$**   
**WORST CASE**  
**INPUT THRESHOLD LEVELS -  $V_{IH}$  AND  $V_{IL}$**



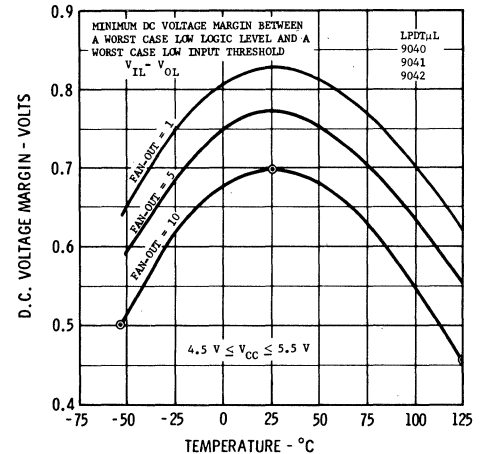
**POWER CHARACTERISTICS**



**HIGH LEVEL NOISE IMMUNITY**



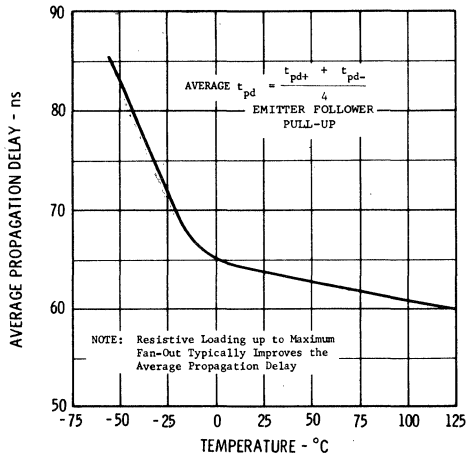
**LOW LEVEL NOISE IMMUNITY**



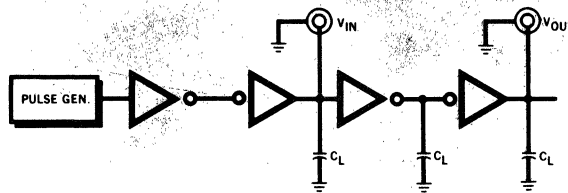


# FAIRCHILD MICROLOGIC® LOW POWER DIODE TRANSISTOR INTEGRATED CIRCUITS

**TYPICAL  
AVERAGE PROPAGATION DELAY  
LPDTμL 9041 • 9042**



## TEST CIRCUIT



## CONDITIONS

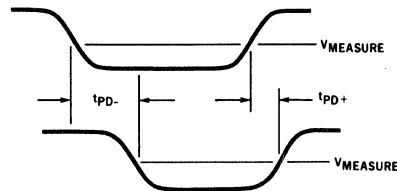
$V_{CC} = 5.0V$ ,  $C_L = 50pF$  (INCLUDING PROBE AND JIG CAPACITANCE)

$V_{MEASURE} = 1.6V @ -55^{\circ}C$

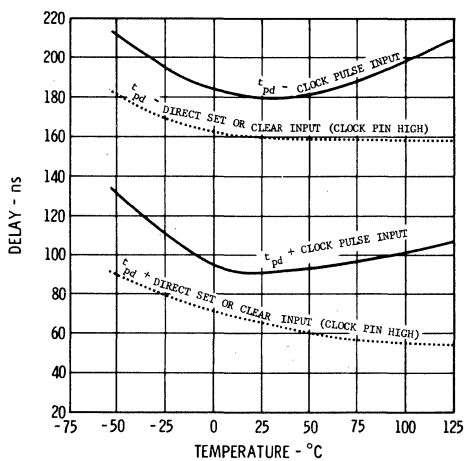
(GND. REF.)  $1.3V @ 25^{\circ}C$

$0.9V @ 125^{\circ}C$

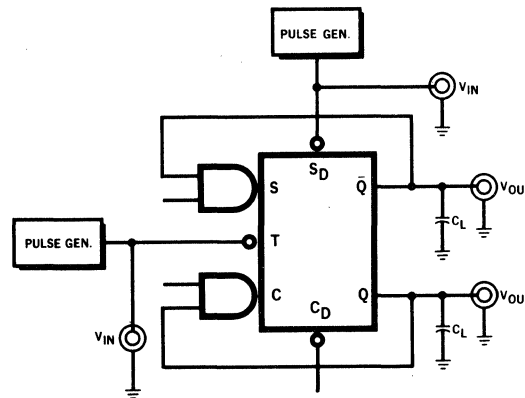
## WAVE FORMS



**TYPICAL DELAY CHARACTERISTICS  
LPDTμL 9040**



## TEST CIRCUIT



## CONDITIONS

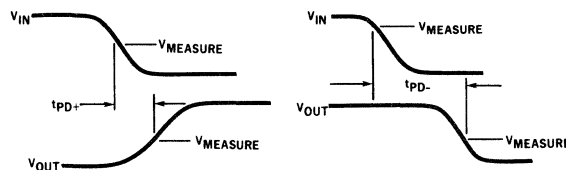
$V_{CC} = 5.0V$ ,  $C_L = 50pF$  (INCLUDING PROBE AND JIG CAPACITY)

$V_{MEASURE} = 1.6V @ -55^{\circ}C$

(GND. REF.)  $1.3V @ 25^{\circ}C$

$0.9V @ 125^{\circ}C$

## WAVE FORMS



# DT $\mu$ L 9093 • 9094 • 9097 • 9099

## DUAL MONOLITHIC, CLOCKED J-K FLIP-FLOPS

### DIODE TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS

TEMPERATURE RANGE: -55°C to +125°C, -20°C to +100°C, 0°C to +75°C

#### General Description:

- The 9093 and 9094 devices are Dual Monolithic, internally connected J-K flip-flops of the 9945 and 9948 DT $\mu$ L type respectively. These devices have separate clocks, separate J and K inputs, separate Direct Set inputs and no Direct Clear input (refer to logic diagram).
- The 9097 and 9099 devices are also Dual Monolithic, internally connected J-K flip-flops of the 9948 and 9945 DT $\mu$ L type respectively. These devices have separate J and K inputs, separate Direct Set inputs, a common clock input pin and a common Direct Clear input pin (refer to logic diagram).

#### Typical Applications:

- Shift Registers
- Two individually operated flip-flops
- Counters

#### Features:

- Compatible with all DT $\mu$ L 930 series
- Compatible with TT $\mu$ L
- Reduced can count
- Greater logic flexibility

#### ABSOLUTE MAXIMUM RATINGS

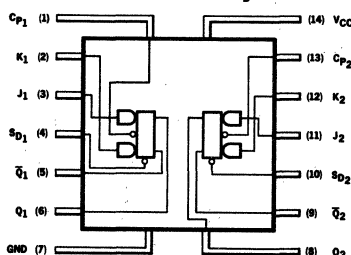
Supply Voltage (V <sub>CC</sub> ) Continuous	+8.0 Volts
Supply Voltage (V <sub>CC</sub> ) Pulsed <1.0 second	+12.0 Volts
Internal Power Dissipation 25°C Ambient	500 mW
Typical Power Dissipation 5 V (V <sub>CC</sub> )	100 mW
Operating Temperature Range	-55°C to +125°C
Storage Temperature Range	+65°C to +150°C
Lead Temperature (Soldering 60 second)	300°C

#### LOADING RULES

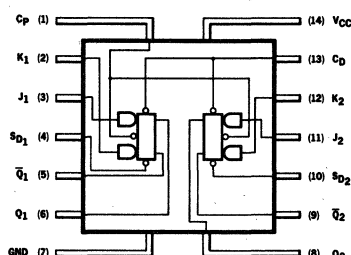
	9093/9094	9097/9099	FANOUT	-55°C to +125°C -20°C to +100°C	0°C to 75°C
• INPUTS					
C <sub>P1</sub> or C <sub>P2</sub> = 2		C <sub>P</sub> = 4	9093 — Q <sub>1</sub> = Q <sub>2</sub> = $\bar{Q}_1$ = $\bar{Q}_2$ =	12	10
K <sub>1</sub> or K <sub>2</sub> = 2/3		K <sub>1</sub> or K <sub>2</sub> = 2/3	9094 — Q <sub>1</sub> = Q <sub>2</sub> = $\bar{Q}_1$ = $\bar{Q}_2$ =	11	9
J <sub>1</sub> or J <sub>2</sub> = 2/3		J <sub>1</sub> or J <sub>2</sub> = 2/3	9097 — Q <sub>1</sub> = Q <sub>2</sub> = $\bar{Q}_1$ = $\bar{Q}_2$ =	11	9
S <sub>D1</sub> or S <sub>D2</sub> = 2		S <sub>D1</sub> or S <sub>D2</sub> = 2 C <sub>D</sub> = 4	9099 — Q <sub>1</sub> = Q <sub>2</sub> = $\bar{Q}_1$ = $\bar{Q}_2$ =	12	10

**PIN CONFIGURATION:** Identical for dual-in-line and flat packages.

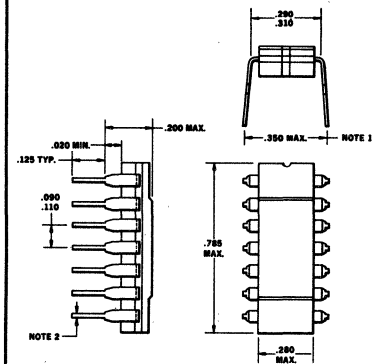
**9093/9094**  
(DUAL 9945/9948 SEPARATE S<sub>D</sub>; SEPARATE C<sub>P</sub>)



**9097/9099**  
(DUAL 9948/9945 COMMON C<sub>P</sub>; COMMON C<sub>D</sub>)

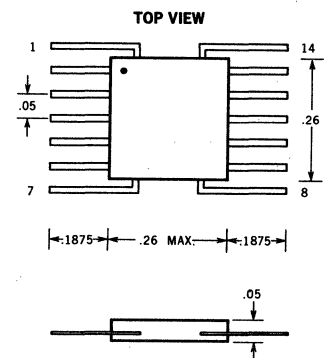


#### TYPICAL DUAL IN-LINE PACKAGE



**NOTES:**  
1. Leads are intended for insertion in hole rows on .300" centers. They are purposely shipped with "positive" (.350) misalignment to facilitate insertion.  
2. Board-drilling dimensions should equal your practice for a conventional .020 inch diameter lead.

#### TYPICAL FLAT PACKAGE



#### PURCHASING INFORMATION:

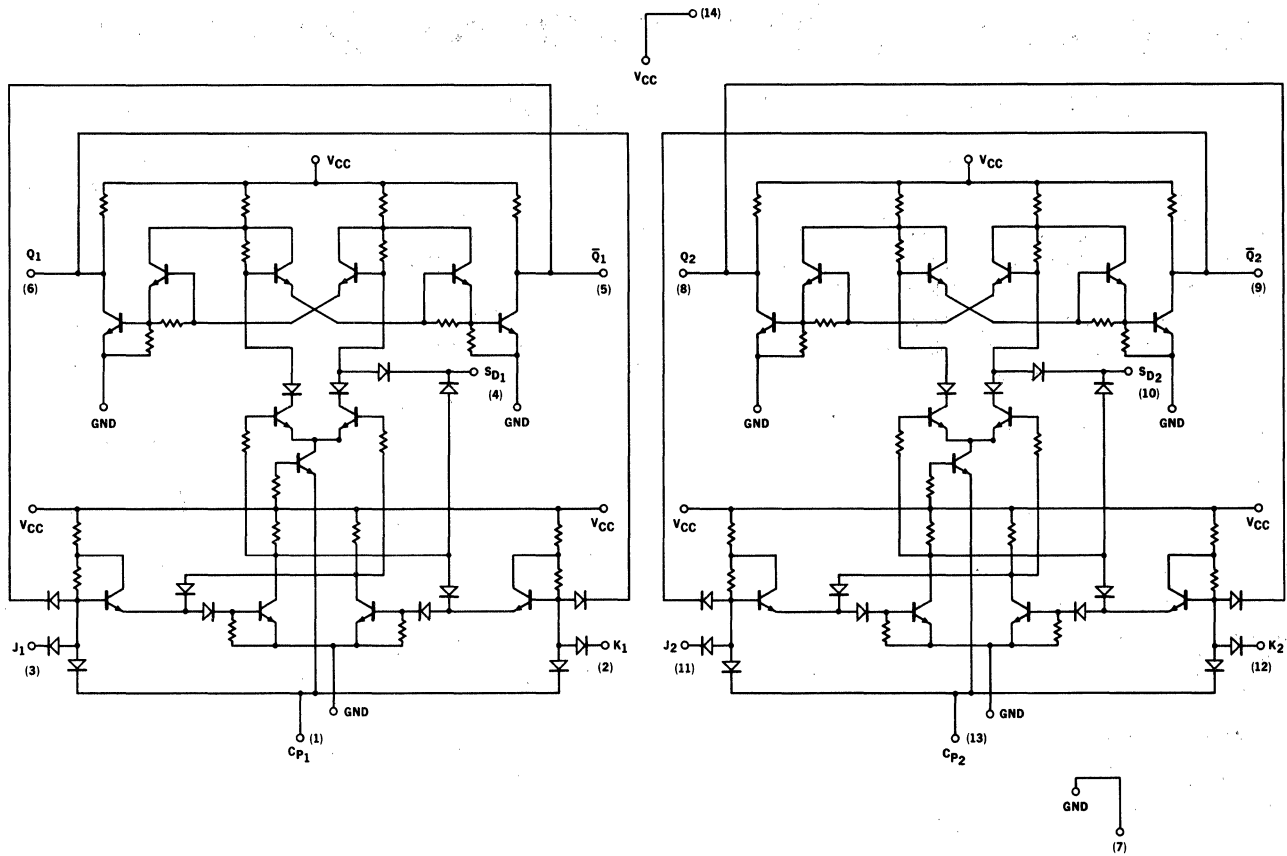
To order Diode Transistor Micrologic Integrated Circuit elements specify U31XXXX5XX for flat package and U6A-XXXX5XX for Dual In-line package, where XXXX is 9093, 9094, 9097, or 9099, and 5X is 51 for the -55°C to +125°C temperature range, 56 for the -20°C to +100°C temperature range or 59 for the 0°C to 75°C temperature range.

\* Fairchild patent Pending

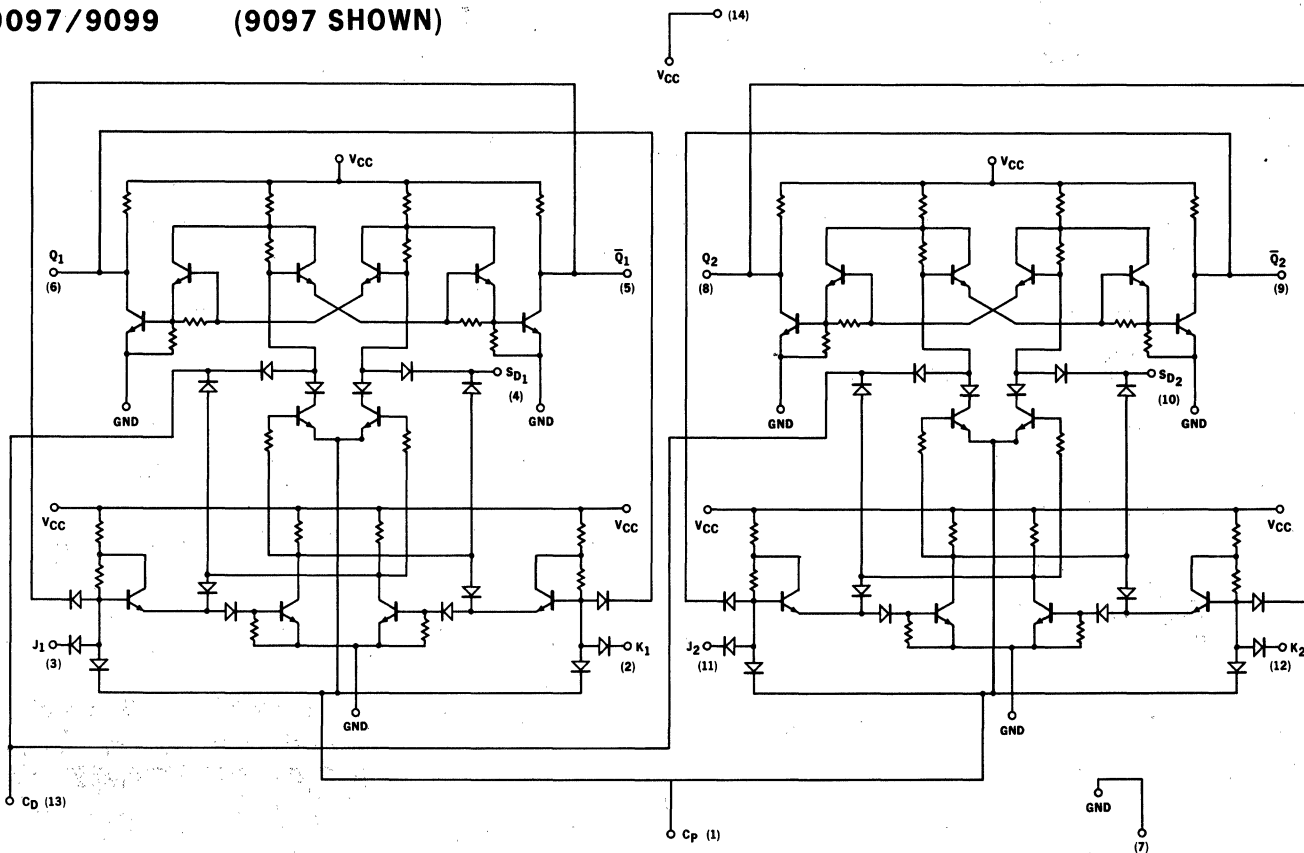
**FAIRCHILD**  
SEMICONDUCTOR  
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION

# FAIRCHILD TRANSISTORS DT $\mu$ L 9093•9094•9097•9099

## 9093/9094 (9093 SHOWN)



## 9097/9099 (9097 SHOWN)



# HIGH LEVEL LOGIC DIODE-TRANSISTOR MICROLOGIC®

## INTEGRATED CIRCUITS COMPOSITE DATA SHEET

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

0°C TO 75°C TEMPERATURE RANGE

**GENERAL DESCRIPTION** — The Fairchild High Level Logic Diode-Transistor Micrologic® Integrated Circuit family (HLLDT $\mu$ L) consists of three high voltage, high threshold hex inverters which offer extremely good D.C. and A.C. Noise Immunity. These circuits are useful in applications involving a high noise environment or high voltage supply which prohibits the use of CCSL.

Interfacing from CCSL to HLLDT $\mu$ L is accomplished with the 9112, shifting from HLLDT $\mu$ L to CCSL is accomplished with the 9109. The 9112 can also be used to drive the  $\mu$ M3700 MOS Multiplexer.

The circuits are fabricated within a silicon monolithic substrate using standard Fairchild Planar\* and Epitaxial processes.

HLLDT $\mu$ L elements are available in the hermetically sealed ceramic Dual In-Line Package (DIP), designed for automated and low cost insertion techniques.

### FEATURES

- High Voltage Operation . . .  $V_{CC}$  Range 12 to 20 V.
- Utilizes inexpensive external input diodes to facilitate a high density building block approach and very high Logic Fan-In where desired.
- High D.C. Noise Immunity . . . 6.5 V minimum
- High A.C. Noise Immunity . . . 10 V at 150 ns
- Interfaces with CCSL

### ABSOLUTE MAXIMUM RATINGS (above which the reliability of the device may be impaired)

Storage Temperature	-65°C to +150°C
Operating Temperature	0°C to +75°C
$V_{CC}$ Pin Potential to Gnd Pin	-0.5 V to +25 V
Output Current when output is low	40 mA
Input Current (9109, 9110)	10 mA
Output Voltage	25 V
Input Voltage (9112)	5.5 V

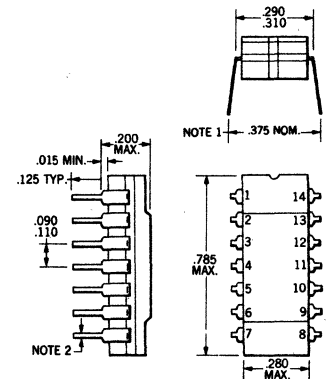
### ORDERING INFORMATION

To order HLLDT $\mu$ L elements specify U6AXXXX59X, where XXXX is the four-digit number denoting the specific element desired.

\*Planar is a patented Fairchild process.

### TYPICAL DUAL IN-LINE PACKAGE

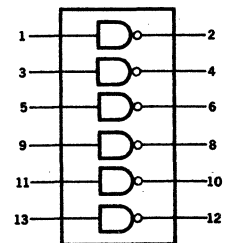
similar to  
JEDEC (TO-116) Outline



#### NOTES:

1. Leads are intended for insertion in hole rows on .300" centers. They are purposely shipped with "positive" (.375) misalignment to facilitate insertion.
2. Board-drilling dimensions should equal your practice for a conventional .020 inch diameter lead.

### LOGIC DIAGRAM



$V_{CC}$  = Pin 14  
GND = Pin 7

**FAIRCHILD**  
**SEMICONDUCTOR**  
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION

# FAIRCHILD HLLDT $\mu$ L INTEGRATED CIRCUITS

## ELECTRICAL CHARACTERISTICS

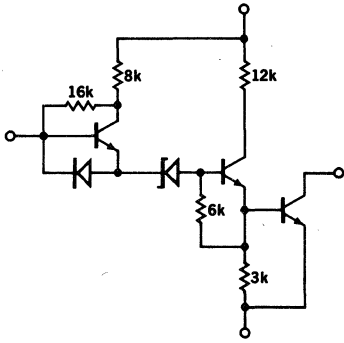
SYMBOL	CHARACTERISTIC	DEVICE	LIMITS						UNITS	CONDITIONS AND COMMENTS	
			0°C		+25°C			+75°C			
			MIN.	MAX.	MIN.	TYP.	MAX.	MIN.			MAX.
$V_{OH}$	Output High Voltage	9110 9112	Note 2		Note 2			Note 2		Volts	$V_{CC} = 12\text{ V to }20\text{ V}$ $I_{OH} = -0.1\text{ mA}$ @ $V_{IL}$
$I_{CEX}^1$	Output Leakage Current	9109	75		1.0	75	75		$\mu\text{A}$	$V_{CC} = 20\text{ V}$ $V_{OH} = 20\text{ V}$ @ $V_{IL}$	
$V_{OL1}$	Output Low Voltage	9109 9110 9112	0.5		0.25	0.5	0.5		Volts	$V_{CC} = 12\text{ V}$ $I_{OL} = 10\text{ mA}$ @ $V_{IH}$	
$V_{OL2}$	Output Low Voltage	9109 9110 9112	1.0		0.5	1.0	1.0		Volts	$V_{CC} = 20\text{ V}$ $I_{OL} = 20\text{ mA}$ @ $V_{IH}$	
$V_{IL}$	Input Low Voltage	9109	7.05		7.0			6.8		Volts	Input Low Threshold @ $V_{OH}$
		9110	7.05		7.0			6.8			
		9112	1.05		1.0			0.8			
$V_{IH}$	Input High Voltage	9109	8.6		8.5			8.4		Volts	Input High Threshold @ $V_{OL}$
		9110	8.6		8.5			8.4			
		9112	2.1		2.0			1.9			
$I_F$	Input Load Current	9109 9110 9112	-1.20		-0.80	-1.12	-1.12		mA	$V_{CC} = 20\text{ V}$ , $V_F = 0.5\text{ V}$	
$I_{SC}$	Output Short Circuit Current	9110	-17		-9.0	-16.3	-15.6		mA	$V_{CC} = 20\text{ V}$ , $V_{IN} = 0\text{ V}$ $V_{OUT} = 0\text{ V}$	
		9112	-2.4		-1.65	-2.3	-2.3				
$I_{CEX}$	Output Leakage Current	9110 9112	75		1.0	75	75		$\mu\text{A}$	$V_{CC} = 20\text{ V}$ , $V_{OUT} = 20\text{ V}$ $V_{IN} = 0\text{ V}$	
$I_{PDH}$	Input High Supply Current	9109			19	28			mA	$V_{CC} = 20\text{ V}$ , Input Open	
		9110			19	28					
		9112			22	34					
$I_R$	Input Leakage Current	9112			5.0			10	$\mu\text{A}$	$V_{CC} = 20\text{ V}$ , $V_R = 4.0\text{ V}$	
$I_{max}$	Ground Current	9109								mA	$V_{CC} = V_{OUT} = 25\text{ V}$ , Inputs @ GND
		9110			15						
		9112									
$t_{pd+}$	Turn Off Delay	9109								ns	See Fig. 4
		9110			145	300					
		9112									
$t_{pd-}$	Turn On Delay	9109								ns	See Fig. 4
		9110			95	200					
		9112			30	125					
$V_{TN}$	"0" Level A.C. Noise Immunity	9110			7.0					Volts	See Fig. 5
$V_{TP}$	"1" Level A.C. Noise Immunity	9110			8.5					Volts	See Fig. 5

### NOTES:

- (1) Tests on 9109, 9110 are performed with FDH6 input diodes.
- (2) MIN =  $V_{CC} - 2.0\text{ V}$  for all temperature  
TYP =  $V_{CC} - 1.5\text{ V}$  for 25°C

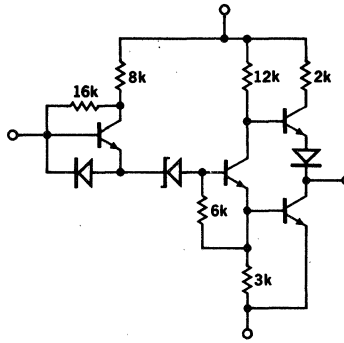
# FAIRCHILD HLLDT $\mu$ L INTEGRATED CIRCUITS

**Fig. 1a**



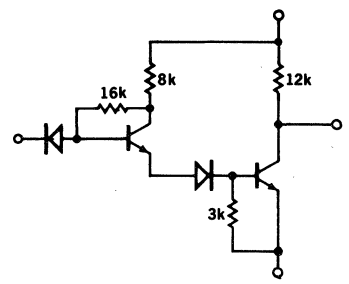
**1/6 HLLDTL 9109  
HLL  $\rightarrow$  CCSL**

**Fig. 1b**



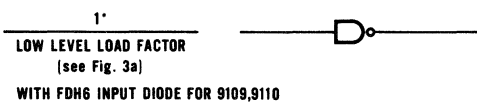
**1/6 HLLDTL 9110  
HLL  $\rightarrow$  HLL**

**Fig. 1c**



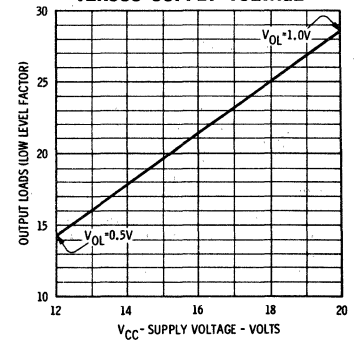
**1/6 HLLDTL 9112  
CCSL  $\rightarrow$  HLL**

**Fig. 2a**



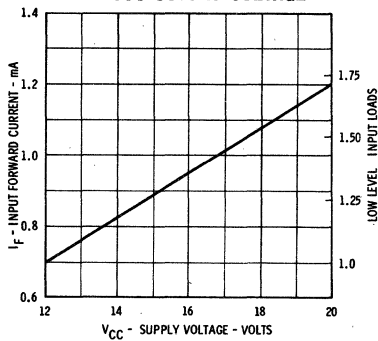
9109: OPEN COLLECTOR  
9110,9112: 20  
LOW LEVEL DRIVE FACTOR  
(see Fig. 2b)

**Fig. 2b  
OUTPUT LOADS  
(LOW LEVEL DRIVE FACTOR)  
VERSUS SUPPLY VOLTAGE**



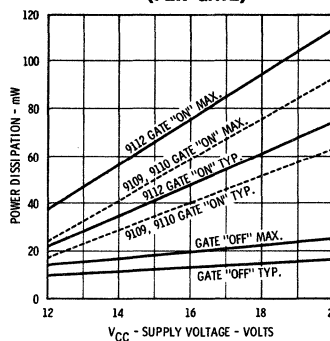
**Fig. 3a**

**WORST CASE INPUT FORWARD CURRENT AND INPUT LOADS VERSUS SUPPLY VOLTAGE**



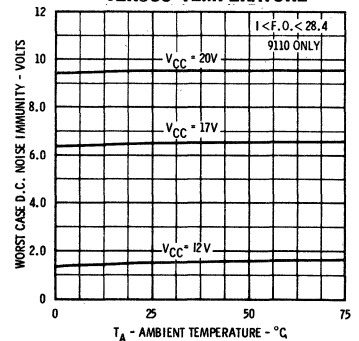
**Fig. 3b**

**WORST CASE POWER DISSIPATION VERSUS SUPPLY VOLTAGE (PER GATE)**



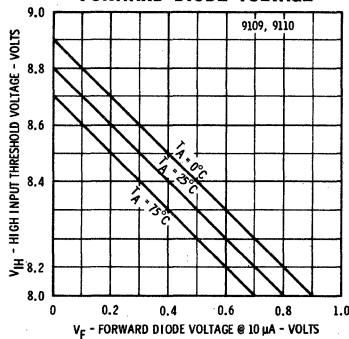
**Fig. 3c**

**WORST CASE HIGH LEVEL D.C. NOISE IMMUNITY VERSUS TEMPERATURE**



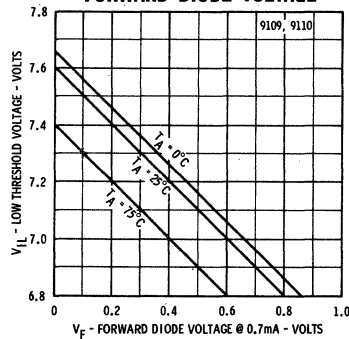
**Fig. 3d**

**WORST CASE HIGH INPUT THRESHOLD VOLTAGE VERSUS FORWARD DIODE VOLTAGE**



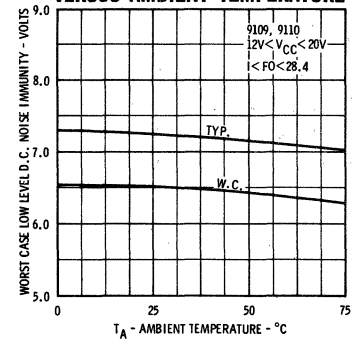
**Fig. 3e**

**WORST CASE LOW THRESHOLD VOLTAGE VERSUS FORWARD DIODE VOLTAGE**



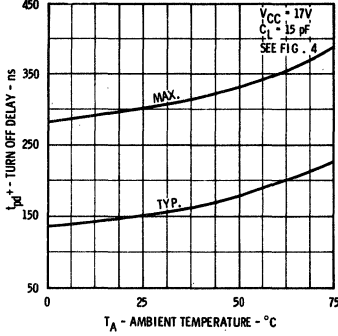
**Fig. 3f**

**WORST CASE LOW LEVEL D.C. NOISE IMMUNITY VERSUS AMBIENT TEMPERATURE**

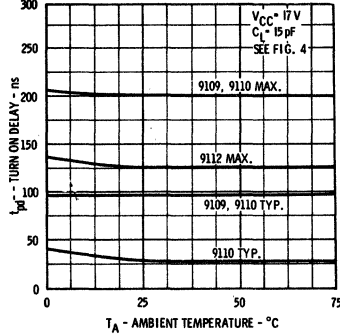


# FAIRCHILD HLLDT $\mu$ L INTEGRATED CIRCUITS

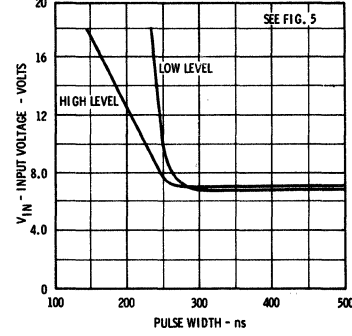
**Fig. 3g**  
**TURN OFF DELAY**  
**VERSUS AMBIENT TEMPERATURE**



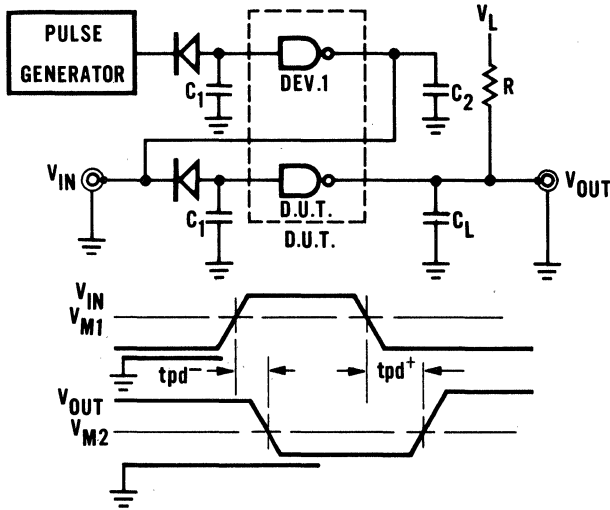
**Fig. 3h**  
**TURN ON DELAY**  
**VERSUS AMBIENT TEMPERATURE**



**Fig. 3i**  
**TYPICAL A.C. NOISE IMMUNITY**  
**INPUT VOLTAGE VERSUS**  
**PULSE WIDTH**



**Fig. 4**  
**SWITCHING TIME TEST CIRCUIT**  
**AND WAVEFORMS**



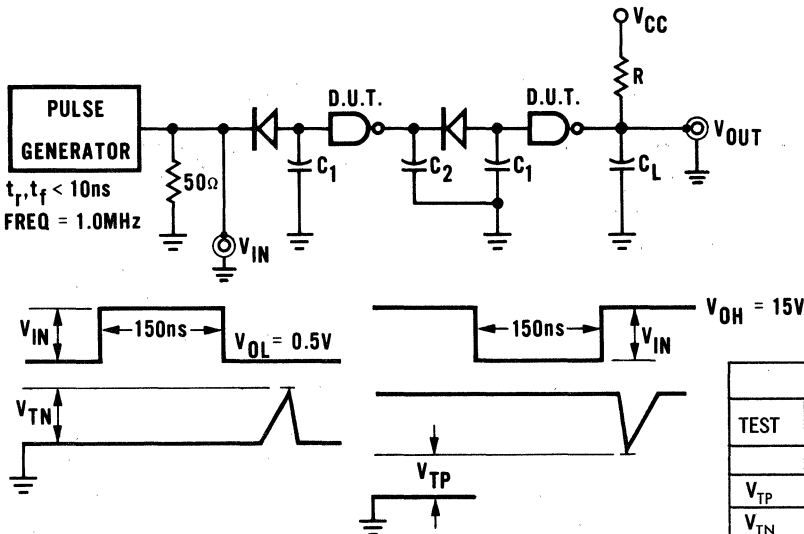
$C_1 = 5.0 \text{ pF}$  Includes all probe  
 $C_2 = 10 \text{ pF}$  and jig capacitance  
 $C_L = 15 \text{ pF}$

FDH6 Input Diodes are used on 9109, 9110

**TEST CONDITIONS**

D.U.T.	DEV. 1	$V_{m1}$ (V)	$V_{m2}$ (V)	$V_L$ (V)	$R_{tpd-}$	$R_{tpd+}$
9109	9110	7.5	1.5	5.0	510 $\Omega$	3.6 k
9110	9110	7.5	7.5	17.0	2.4 k	24 k
9112	932	1.5	7.5	17.0	2.4 k	24 k

**Fig. 5**  
**A.C. NOISE IMMUNITY TEST CIRCUIT**



Unused inputs grounded  
diodes are FDH6  
 $C_1 = 5.0 \text{ pF}$  Includes jig and  
 $C_2 = 10 \text{ pF}$  all probe capacitance  
 $C_L = 15 \text{ pF}$

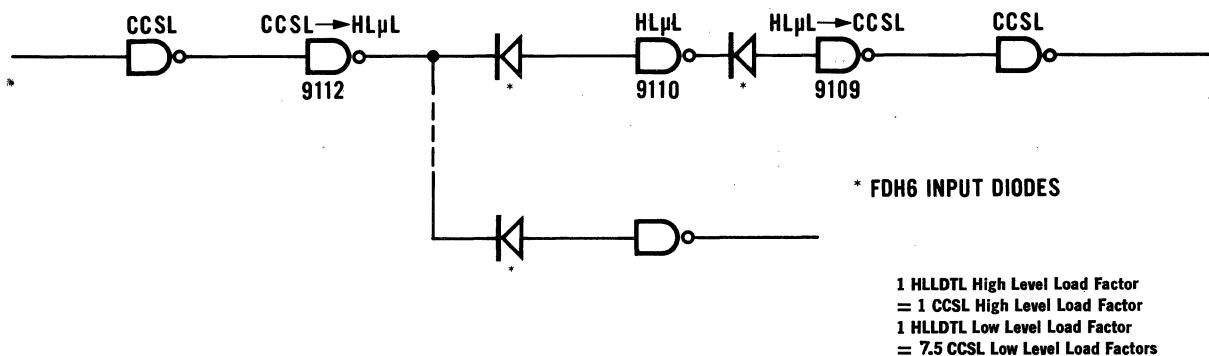
**TEST CONDITIONS AND LIMITS**

TEST	LIMIT		$V_{CC}$ (Volts)	R (k $\Omega$ )	$T_A$ ( $^{\circ}$ C)	$V_{IN}$ (Volts)
	MIN.	MAX.				
$V_{TP}$	8.5 V		17	24	25	10
$V_{TN}$		7.0 V	17	2.4	25	10

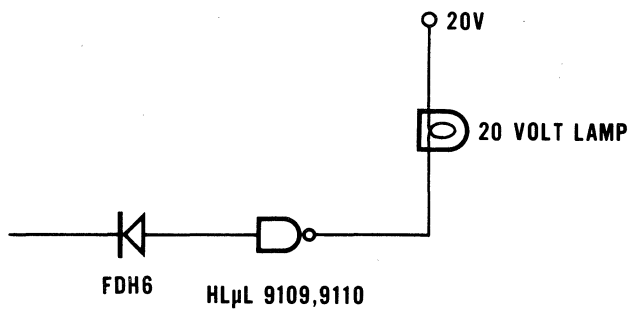
# FAIRCHILD HLLDT $\mu$ L INTEGRATED CIRCUITS

**APPLICATIONS:**

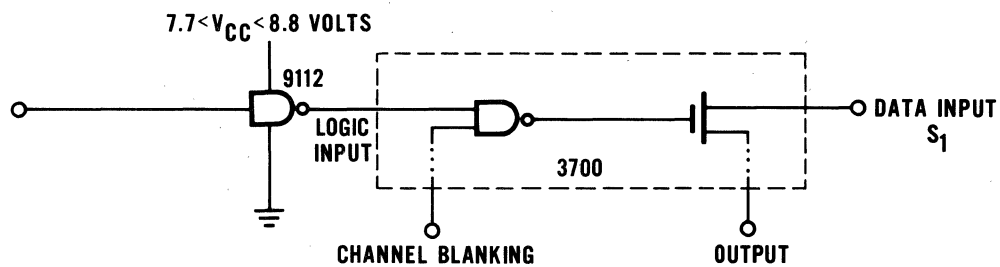
**Fig. 6—CCSL INTERFACING**



**Fig. 7—LAMP DRIVER**



**FIG. 8—DRIVING MOS3700 MULTIPLEXER OR EQUIVALENT**



Output Levels : min "1" level =  $V_{CC} - 1.5 V$   
 : max "0" level = 0.2 V



# FAIRCHILD HLLDT $\mu$ L INTEGRATED CIRCUITS

Fig. 9—SEQUENTIAL COUNTER

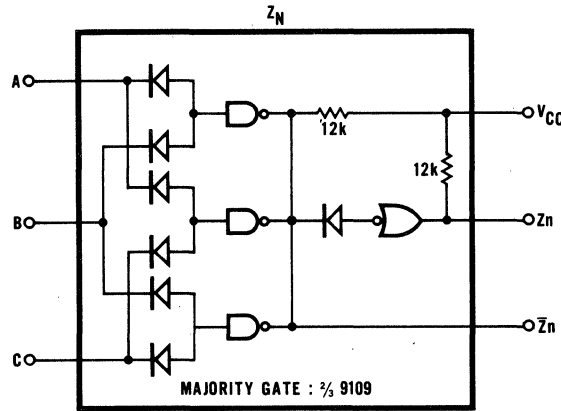
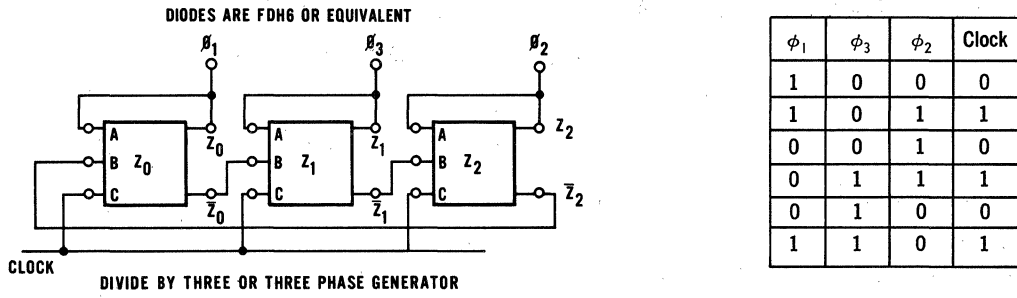
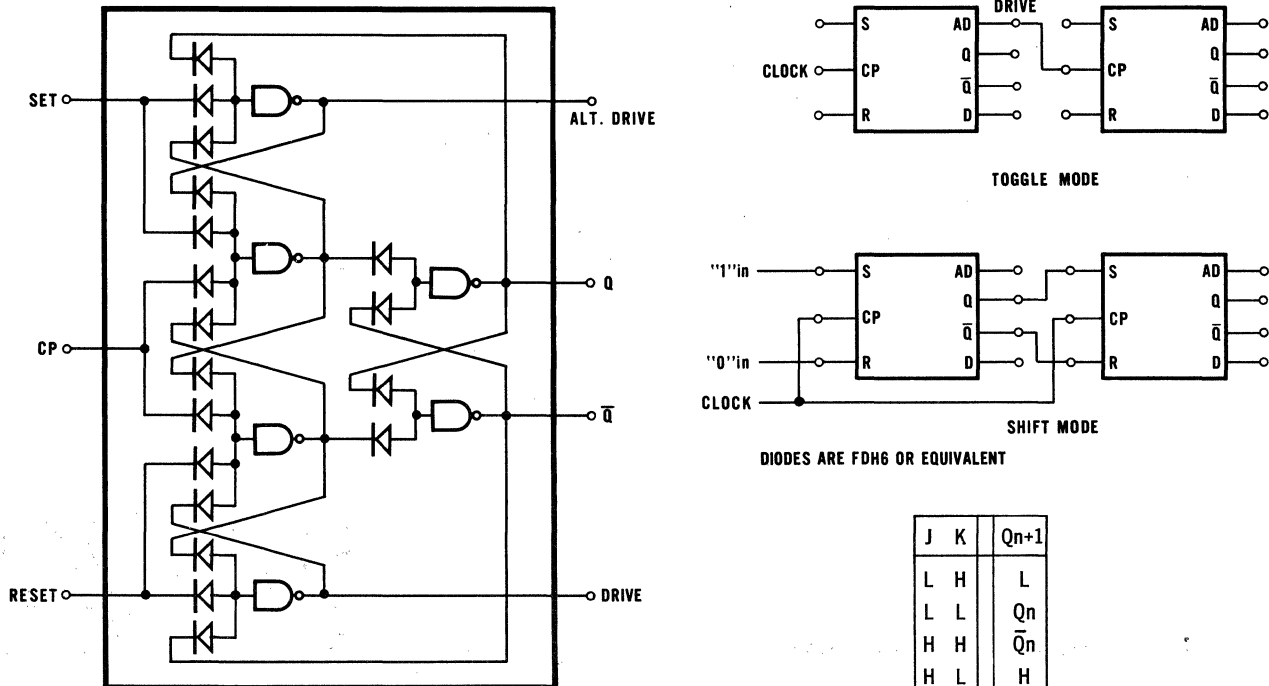


Fig. 10—JK FLIP FLOP



# HLLDT $\mu$ L 9109

## HIGH VOLTAGE HEX INVERTER

### HIGH LEVEL LOGIC DIODE-TRANSISTOR MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

#### GENERAL DESCRIPTION

The HLLDT $\mu$ L9109 is a high voltage, high threshold hex inverter designed for the conversion of high level logic to any logic level from 4V to 20V. The unit is characterized by a 6.5V(min.) DC Noise Immunity and a 20V/100 nsec AC Noise Immunity. The input diode has been left off the circuit so that the input can be expanded to any number of inputs which allows maximum flexibility in use.

The 9109 is available in ceramic Dual In-Line\* Package.

#### FEATURES

CCSL Compatibility

High Voltage Operation 12 to 20 V

Utilizes external input diodes to facilitate high density building block approach

F.O. = 7 CCSL

D.C. Noise Immunity of 6.5V

#### APPLICATIONS

Interfacing from HLL to CCSL levels.

Line receiver.

General purpose logic level converter

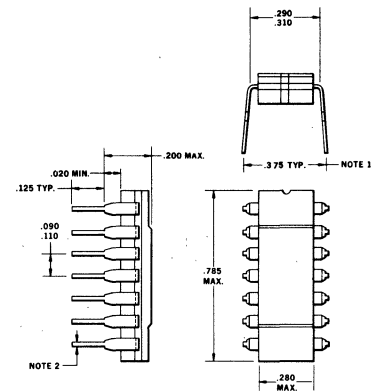
#### ABSOLUTE MAXIMUM RATINGS

Storage Temperature	-65°C to 150°C
Operating temperature	0°C to 75°C
V <sub>CC</sub>	25 V
Output Voltage	25 V
Output low current	40 mA

\*Fairchild patent pending

#### TYPICAL DUAL IN-LINE PACKAGE

(In accordance with JEDEC TO-116)

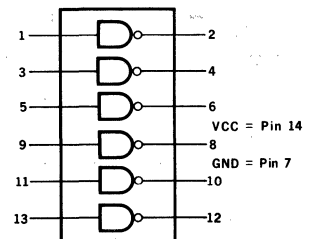


#### NOTES:

- 1 Leads are intended for insertion in hole rows on .300" centers. They are purposely shipped with "positive" (.375) misalignment to facilitate insertion.
- 2 Board-drilling dimensions should equal your practice for a conventional .020 inch diameter lead.

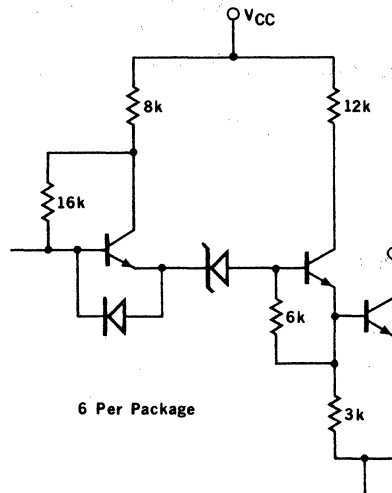
**ORDER PART NO. U6A910959X**

#### LOGIC DIAGRAM



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# FAIRCHILD HLLDT $\mu$ L INTEGRATED CIRCUITS 9109



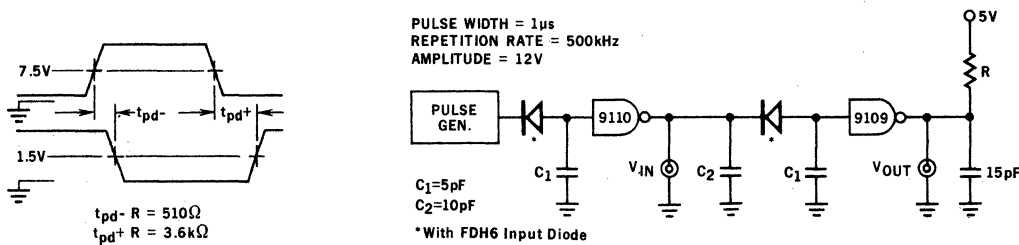
6 Per Package

**CIRCUIT DIAGRAM**

**ELECTRICAL CHARACTERISTICS**

SYMBOL	LIMITS				UNITS	CONDITIONS AND COMMENTS		
	0°C		25°C				75°C	
	MIN.	MAX.	MIN.	TYP. MAX.			MIN.	MAX.
$I_{OH}$	75		0.2	75	75	$\mu A$	$V_{CC} = 20V, V_{OH} = 20V$	
$V_{IL}$			7.0		6.8	Volts		
$V_{OL1}$	0.5		0.25	0.5	0.5	Volts	$V_{CC} = 12V, I_{OL} = 10mA$ $V_{IH}$ = Value indicated on this table.	
$V_{OL2}$	1.0		0.5	1.0	1.0		$V_{CC} = 20V, I_{OL} = 20mA$	
$V_{IH}$	8.6	8.5				Volts		
$I_F$	-1.24		-0.81	-1.16		mA	$V_{CC} = 20V, V_F = 0.5V$	
$I_{PDH}$	30		19	28		mA	$V_{CC} = 20V$ , Inputs open	
$I_{PDL}$	9.5		6.0	9.0		mA	$V_{CC} = 25V$ , Inputs GND $V_{OUT} = 25V$	
$t_{pd}^+$			145	400		ns	See switching time test circuit	
$t_{pd}^-$			85	200		ns		

NOTE: Tests are performed with FDH6 input diode.



**CIRCUIT AND WAVEFORMS FOR SWITCHING TESTS**

# HLLDT $\mu$ L 9110

## HIGH VOLTAGE HEX INVERTER

HIGH LEVEL LOGIC DIODE-TRANSISTOR MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS  
A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

### GENERAL DESCRIPTION

The HLLDT $\mu$ L 9110 is a high voltage, high threshold hex inverter with extremely good D.C. and A.C. Noise Immunity. The circuit is useful in applications involving a high noise environment or high voltage supplies which prohibit the use of DT $\mu$ L.

The 9110 contains six basic logic building blocks from which more complex functions (Flip-Flop, Shift Registers, etc.) can easily be built.

The 9110 is available in the hermetically sealed ceramic Dual-In-Line Package (DIP), designed for automated and low cost insertion techniques.

### FEATURES

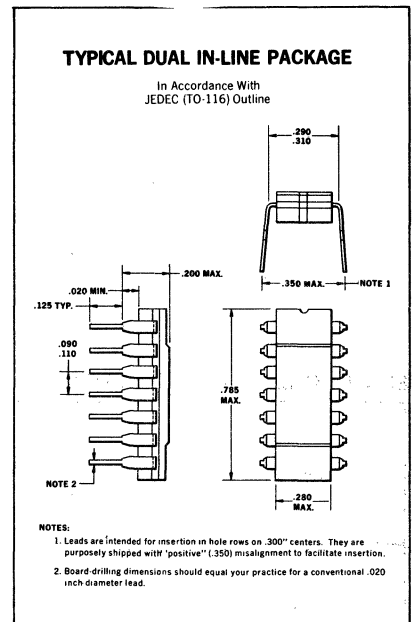
- High Voltage Operation  $V_{CC}$  Range 12 to 20 V.
- Utilizes inexpensive external input diodes to facilitate a high density building block approach and a very high logic Fan-In where desired.
- High D.C. Noise Immunity 6.5 V minimum
- High A.C. Noise Immunity 10 V at 150 ns.

### APPLICATIONS

Industrial Control Logic, Automotive Logic, Lamp Driver, Relay Driver

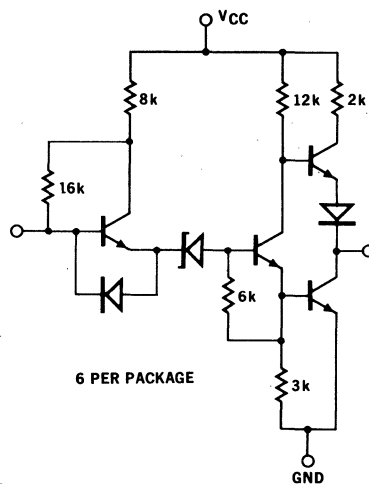
### ABSOLUTE MAXIMUM RATINGS

Storage Temperature	-65°C to 150°C
Operating Temperature	0°C to 75°C
$V_{CC}$	25 V
Output Voltage	25 V
Output low current	40 mA

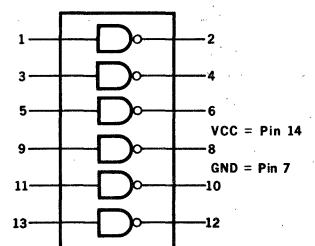


ORDER PART NO. U6A911059X

### CIRCUIT DIAGRAM



### LOGIC DIAGRAM



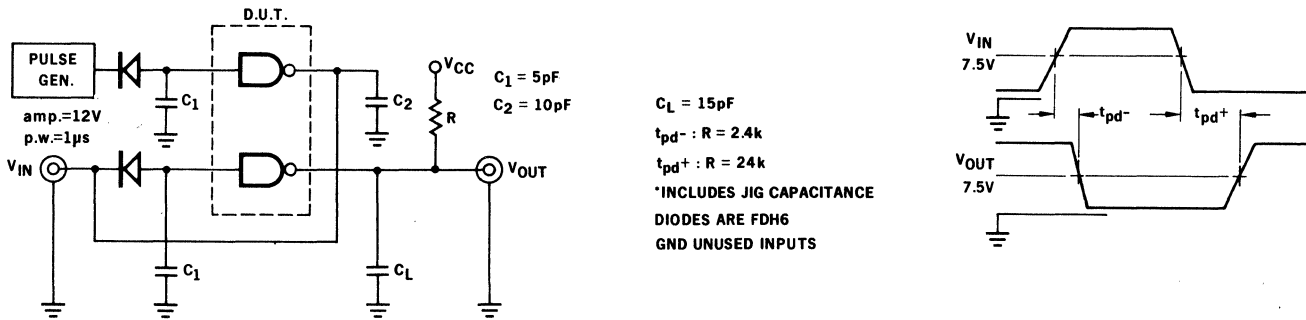
\* Fairchild patent pending

# FAIRCHILD HLLDT $\mu$ L INTEGRATED CIRCUITS 9110

## ELECTRICAL CHARACTERISTICS

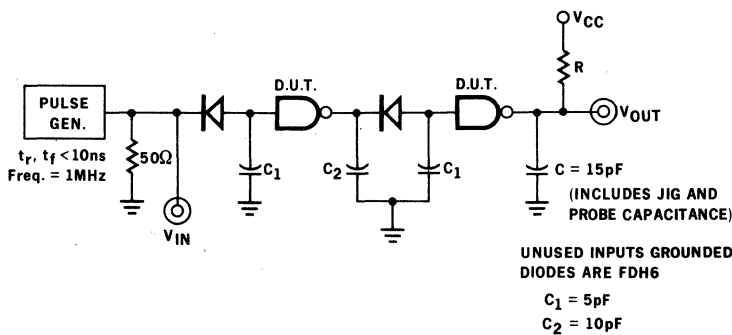
SYMBOL	0°C		LIMITS			UNITS	CONDITIONS AND COMMENTS
	MIN.	MAX.	25°C		75°C		
			MIN.	TYP.	MAX.	MIN.	MAX.
$V_{OH}$			$V_{OH}(\text{min.}) = (V_{CC} - 2.0\text{V})$ $V_{OH}(\text{typ.}) = (V_{CC} - 1.5\text{V})$			Volts	$V_{CC} = 12$ to $20\text{V}$ $I_{OH} = -0.1\text{mA}$ @ $V_{IL}$
$V_{IL}$					7.0	6.8	$V_{CC} = 12$ to $20\text{V}$
$V_{OL1}$	0.5		0.25	0.5		0.5	$V_{CC} = 12\text{V}$ $I_{OL} = 10\text{mA}$ @ $V_{IH}$
$V_{OL2}$	1.0		0.5	1.0		1.0	$V_{CC} = 20\text{V}$ $I_{OL} = 20\text{mA}$ @ $V_{IH}$
$V_{IH}$	8.6		8.5				$V_{CC} = 12$ to $20\text{V}$
$I_F$	-1.24		-0.81	-1.16		-1.16	$V_{CC} = 20\text{V}$ $V_F = 0.5\text{V}$
$I_{SC}$	17.0		9.0	16.3		15.6	$V_{CC} = 20\text{V}$ $V_{out} = 0\text{V}$
$I_{PDH}$	30		19	28		28	$V_{CC} = 20\text{V}$ Inputs open.
$I_{PDL}$	9.5		6.0	9.0		9.0	$V_{CC} = 25\text{V}$ Inputs GND Outputs = $25\text{V}$
$t_{pd+}$			145	400		ns	See switching test circuit.
$t_{pd-}$			100	200		ns	

### SWITCHING TIME TEST CIRCUIT

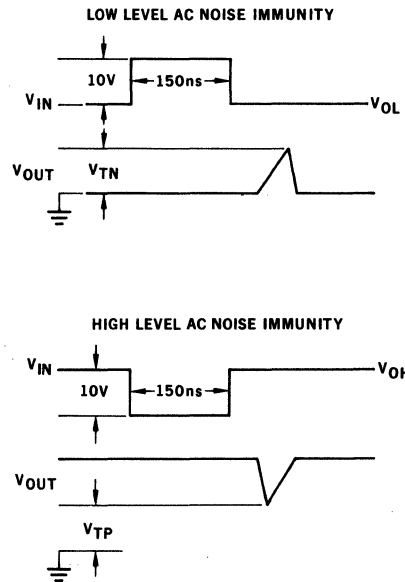


NOTE: TESTS ARE PERFORMED WITH FDH6 INPUT DIODE

### A.C. NOISE IMMUNITY TEST CIRCUIT



TEST CONDITIONS AND LIMITS					
TEST	LIMIT		$V_{CC}$ (Volts)	R k $\Omega$	$T_A$ °C
	MIN.	MAX.			
$V_{TP}$	8.5V		17	24k	25
$V_{TN}$		7.0V	17	2.4	25



# DT $\mu$ L 9111

## PARALLEL GATED-CLOCKED FLIP-FLOP

FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS  
 INDUSTRIAL MICROCIRCUITS - 0°C TO +75°C TEMPERATURE RANGE

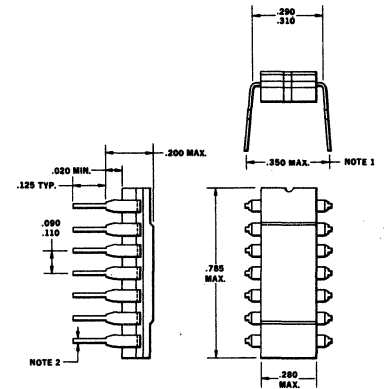
**GENERAL DESCRIPTION** - The DT $\mu$ L9111 is a Parallel Gated, Clocked Flip-Flop. It features directly coupled units operating on the "master-slave" principle. Operation is logically and electrically identical to the DT $\mu$ L9948 with the addition of another pair of two-input gates at the inputs of the flip-flop. This feature enhances the Logic design of some counters and shift-registers and can significantly reduce can count.

A direct clear input is provided which allows asynchronous entry irrespective of signals applied to any other inputs.

Output buffers provide isolation between the "slave" and the output load, thereby enhancing immunity to signal line noise.

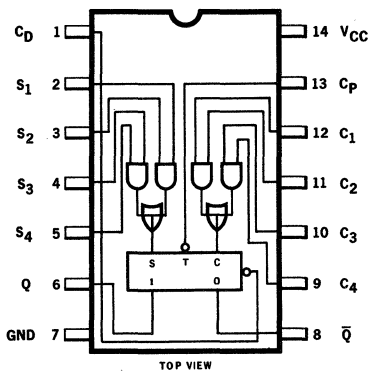
The DT $\mu$ L9111 is completely compatible with all of the Fairchild 9930 Series Diode-Transistor Micrologic® integrated circuits.

### TYPICAL DUAL IN-LINE PACKAGE



**NOTES:**  
 1. Leads are intended for insertion in hole rows on .300" centers. They are purposely shipped with "positive" (.350) misalignment to facilitate insertion.  
 2. Board-drilling dimensions should equal your practice for a conventional .020 inch diameter lead.

### LOGIC DIAGRAM



$$f_s = (S_1 \cdot S_2 + S_3 \cdot S_4) C_p$$

$$f_c = (C_1 \cdot C_2 + C_3 \cdot C_4) C_p + C_D$$

### INPUT-OUTPUT LOADING FACTORS

$$(V_{CC} = 5.0 \text{ V})$$

#### Output Drive

$$\text{Pins 6 \& 8} = 11$$

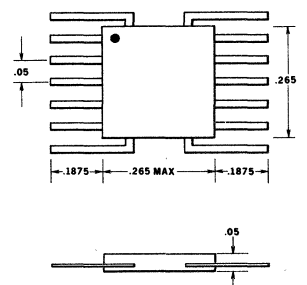
#### Input Loading

$$\text{Pins 2, 3, 4, 5, 9, 10, 11, 12} = 2/3$$

$$\text{Pin 1} = 2$$

$$\text{Pin 13} = 3$$

### TYPICAL FLAT PACKAGE TOP VIEW

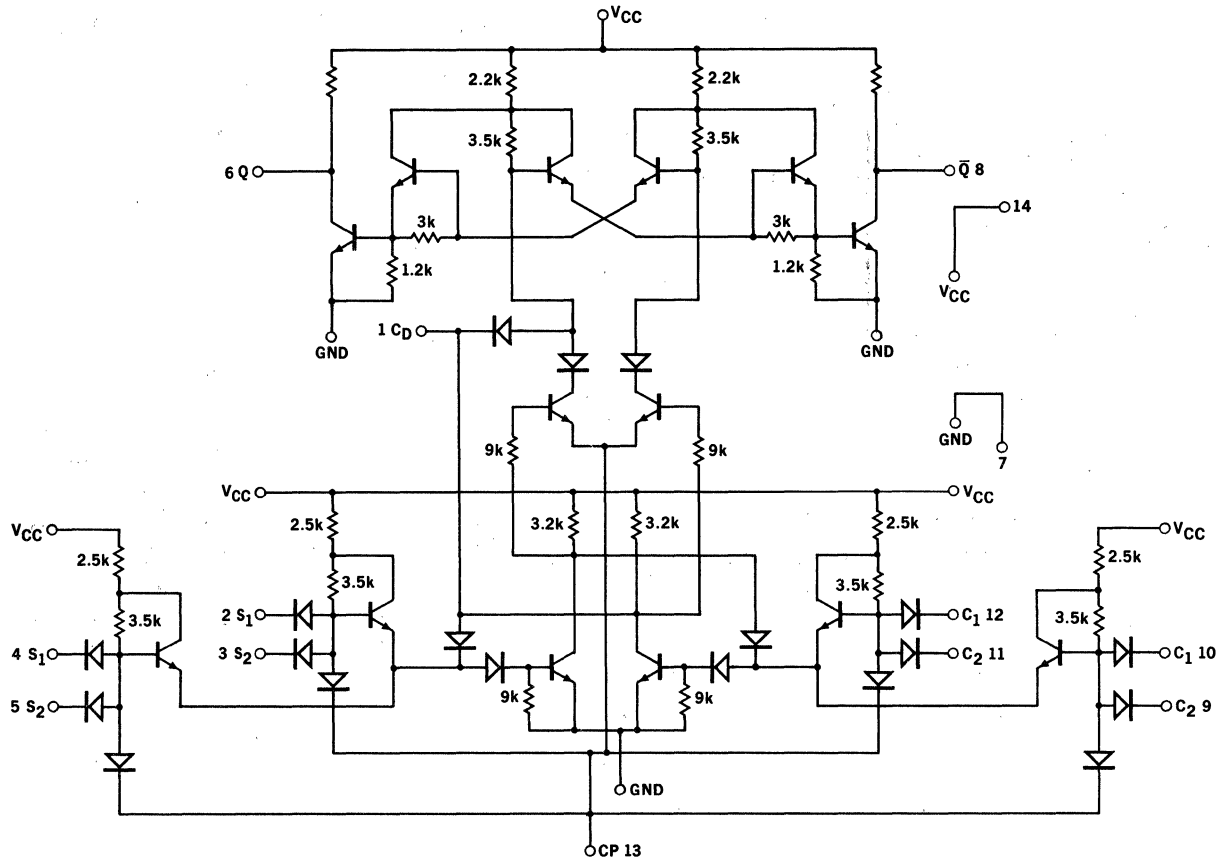


### ORDER INFORMATION:

To order the DT $\mu$ L9111 element, specify the following Part Number:  
 U31911159X for Flat Pkg.  
 U6A911159X for Dual In-Line Pkg.

# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® I.C.

## SCHEMATIC DIAGRAM



## TRUTH TABLE

SYNCHRONOUS ENTRY									OUTPUTS	
INPUTS									$t_{n+1}$	
Pin	2	3	4	5	9	10	11	12	6	8
	L	X	L	X	L	X	L	X	NC	NC
	X	L	X	L	X	L	X	L	NC	NC
	H	H	X	X	L	X	X	L	H	L
	X	X	H	H	X	L	L	X	H	L
	L	X	X	X	H	H	X	X	L	H
	X	L	L	X	X	X	H	H	L	H
	H	H	X	X	H	H	X	X	Undetermined	
	X	X	H	H	X	X	H	H	Undetermined	

ASYNCHRONOUS ENTRY*			
INPUT		OUTPUTS	
Pin	1	6	8
	H	NC	NC
	L	L	H

\*Asynchronous entry is independent of all other inputs and overrides synchronous entry.

### NOTES:

- (1) Pin numbers refer to flat package or dual in-line package.
- (2) Abbreviations used in the body of tables:

L = low, the more negative voltage level

H = high, the more positive voltage level

(In all cases, unused pins have the same effect as high.)

X = immaterial, either H or L has equal effect

NC = no change, the trigger-pulse has no effect on outputs

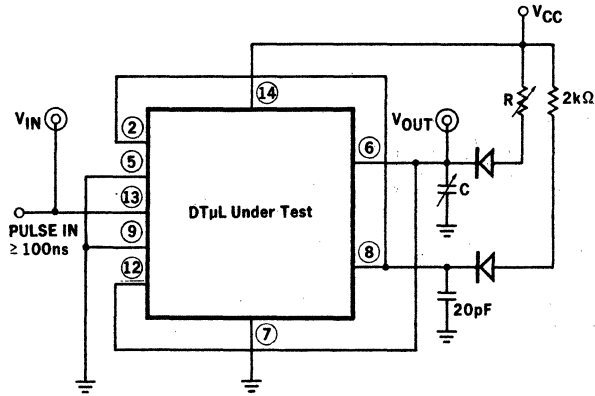
This is a partial table showing significant input-output conditions. Other conditions are similar combinations. Operation is best defined by the set and clear functions shown on Page 1.

For J-K Mode operation:

Connect 6 to 11 and 9; 8 to 3 and 5.

# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® I.C.

## t<sub>pd</sub> TEST CIRCUIT

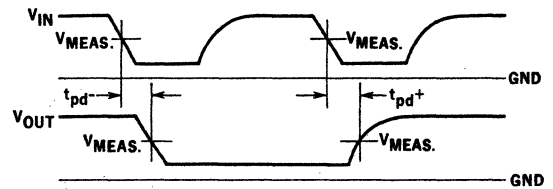


(V<sub>CC</sub> = 5.0 V, T = 25°C)

	R	C	Min.	Max.
t <sub>pd+</sub>	2.0 k	30 pF	30 ns	65 ns
t <sub>pd-</sub>	330 Ω	50 pF	30 ns	75 ns

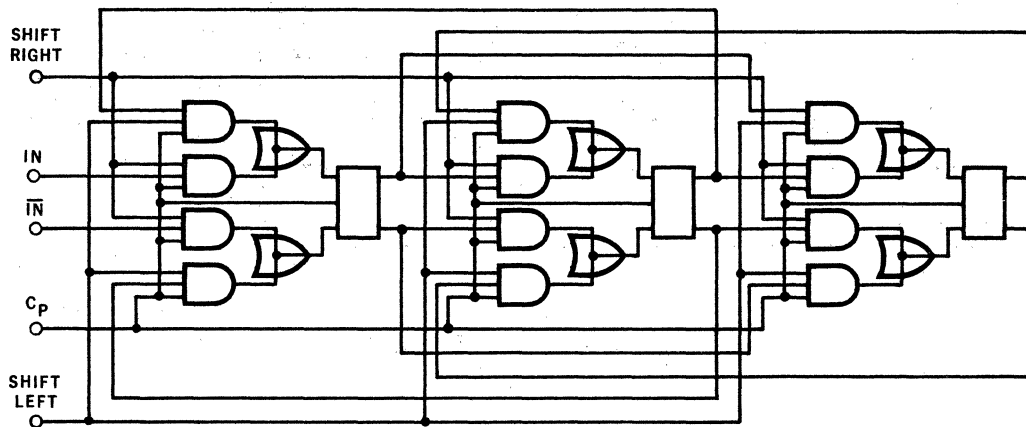
DIODES ARE FD600 OR EQUIVALENT.  
ALL C's INCLUDE JIG & PROBE.

## WAVE FORMS



V<sub>meas.</sub> = 1.5 V at +25°C

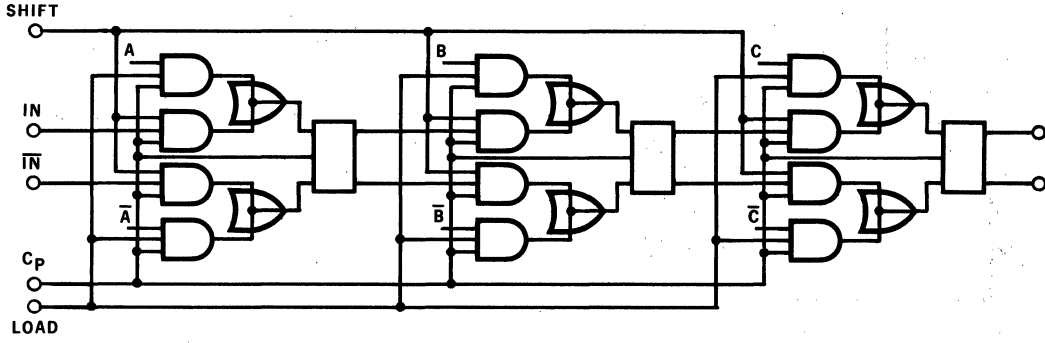
## TYPICAL APPLICATIONS



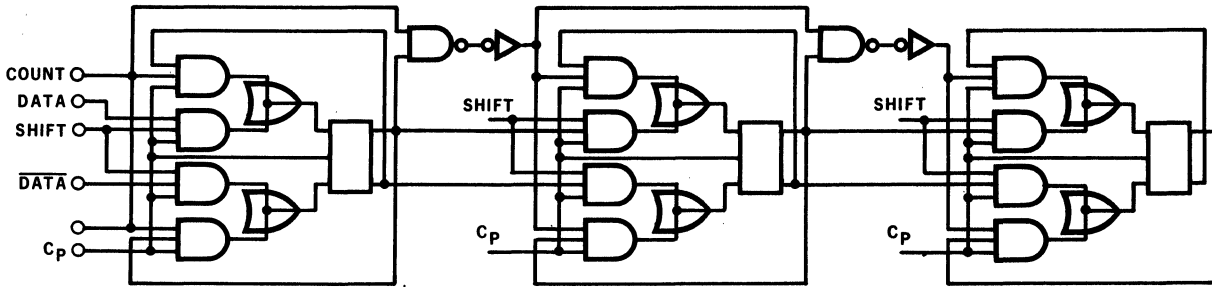
SHIFT RIGHT / SHIFT LEFT SHIFT REGISTER



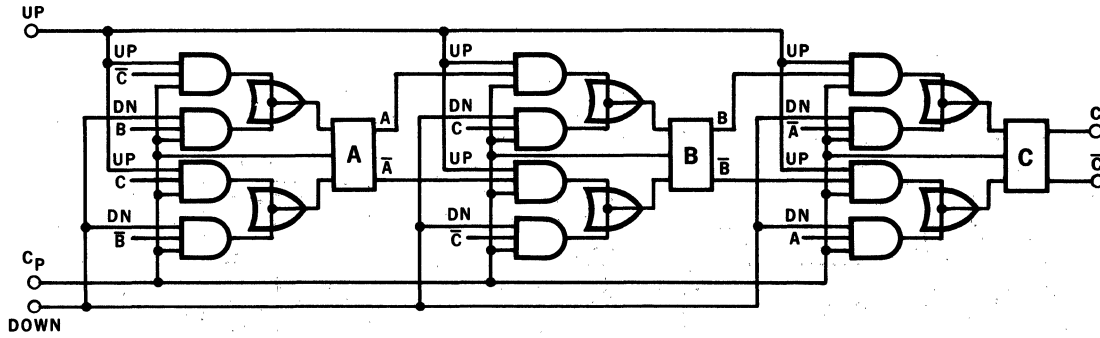
TYPICAL APPLICATIONS



SHIFT REGISTER WITH PARALLEL INPUT LOADING



SERIAL ENTRY - BINARY COUNTER



THREE STAGE MOIBUS COUNTER

# HLLDT $\mu$ L 9112

## HIGH VOLTAGE HEX INVERTER

### HIGH LEVEL LOGIC DIODE-TRANSISTOR MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

#### GENERAL DESCRIPTION

The HLLDT $\mu$ L9112 is a CCSL to high level hex interface element, The 9112 consists of six gates suitable for converting from CCSL levels up to high logic levels (10V to 18V.) The 9112 is ideal for driving MOS devices such as the  $\mu$ M3700 element (6 Channel Multiplexer.)

The 9112 is available in ceramic Dual In-Line\* Package.

#### FEATURES

- CCSL Compatibility
- High Voltage Operation  $V_{CC}$  Range 12 to 20 V
- F.O. = 10 HL
- Wired-OR Capability
- Good AC Noise Immunity

#### APPLICATIONS

- CCSL  $\rightarrow$  HL interface element
- MOS driver

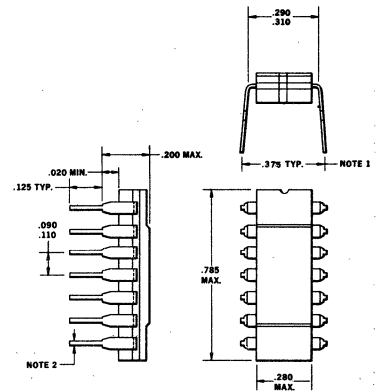
#### ABSOLUTE MAXIMUM RATINGS

Storage temperature	-65°C to 150°C
Operating temperature	0°C to 75°C
$V_{CC}$	25 V
Output Voltage	25 V
Output low current	40 mA

\*Fairchild patent pending

#### TYPICAL DUAL IN-LINE PACKAGE

(In accordance with JEDEC TO-116)

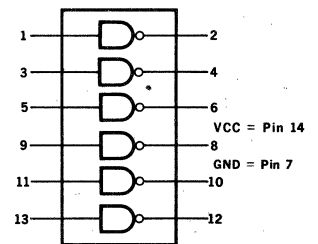


#### NOTES:

1. Leads are intended for insertion in hole rows on .300" centers. They are purposely shipped with ".375" misalignment to facilitate insertion.
2. Board-drilling dimensions should equal your practice for a conventional .020 inch diameter lead

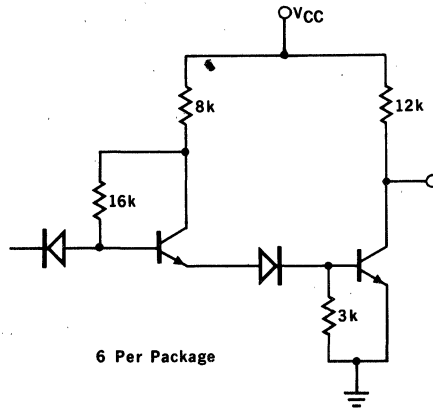
**ORDER PART NO. U6A911259X**

#### LOGIC DIAGRAM



**FAIRCHILD**  
SEMICONDUCTOR  
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION

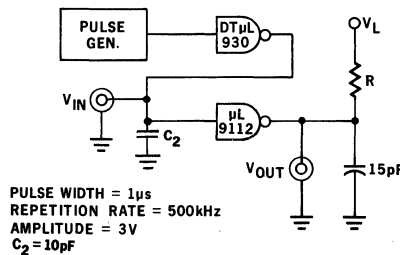
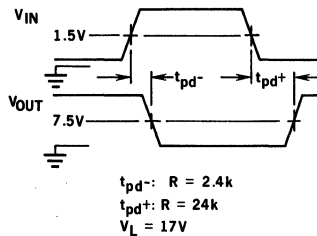
# FAIRCHILD HLLDT $\mu$ L INTEGRATED CIRCUITS 9112



CIRCUIT DIAGRAM

**ELECTRICAL CHARACTERISTICS**

SYMBOL	LIMITS						UNITS	CONDITIONS AND COMMENTS
	0°C		25°C		75°C			
	MIN.	MAX.	MIN.	TYP.	MAX.	MIN.		
$V_{OH}$ (Output High)			18	18.5			Volts	$V_{CC} = 20V, I_{OH} = 0.1mA$ $V_{IL} =$ Value indicated in this table.
$V_{IL}$					1.0		Volts	
$I_{CEX}$ (Output Leakage)		75		0.2	75		$\mu A$	$V_{CC} = 20V, V_{OH} = 20. V$ $V_{IN} = 0V$
$V_{OL1}$ (Output Low)		0.5		0.25	0.5		Volts	$V_{CC} = 12V, I_{OL} = 10mA$ $V_{IH} =$ Value indicated in this table.
$V_{IH}$		2.1		2.0			Volts	
$V_{OL2}$		1.0		0.5	1.0		Volts	$V_{CC} = 20V, I_{OL} = 20mA$
$I_F$ (Input Low)		-1.20		-0.8	-1.12		mA	$V_{CC} = 20V, V_F = 0.45V$
$I_{SC}$ (Output Shorted)		-2.4		-1.65	-2.3		mA	$V_{CC} = 20V, V_{IN} = 0V$ $V_{OUT} = 0V$
$I_{PDH}$ (Power Diss.)		36		22	34		mA	$V_{CC} = 20V, \text{Input open}$
$I_{PDL}$ (Power Diss.)		9.5		6.0	9.0		mA	$V_{CC} = 25V, \text{Input GND}$ $V_{OUT} = 25V$
$t_{pd+}$ (Turn Off)				145	400		ns	See switching time test circuit
$t_{pd-}$ (Turn On)				25	200		ns	



CIRCUIT AND WAVEFORMS FOR SWITCHING TESTS

# 9300

## MSI 4-BIT SHIFT REGISTER

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The 9300 Four Bit Shift Register is a high speed multi-functional sequential logic block which is useful in a wide variety of register and counter applications. As a register it may be used in serial-serial, shift left, shift right, serial-parallel, parallel-serial, and parallel-parallel data transfers. The circuit uses  $TT\mu L$  for high speed and high fanout capability, and is compatible with all devices in the CCSL group of digital integrated circuits.

- 15 MHz shift frequency
- Synchronous parallel entry
- J,  $\bar{K}$  inputs to first stage
- Asynchronous common reset
- Typical power dissipation of 300 mW
- The input/output characteristics provide easy interfacing with Fairchild  $DT\mu L$ ,  $LPDT\mu L$ , and  $TT\mu L$  families (CCSL).
- All ceramic "HERMETIC" 16 pin Dual In-Line package.
- Input diode clamping

**ABSOLUTE MAXIMUM RATINGS** (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
$V_{CC}$ Pin Potential to Ground Pin	-0.5 V to +7 V
Voltage Applied to Outputs for high output state	-0.5 V to + $V_{CC}$ value
Input Voltage (D.C.)	-0.5 V to +5.5 V

**ORDER INFORMATION**

Specify U6B9300XXX for 16 pin Dual In-Line package where XXX is 51X for the -55°C to +125°C temperature range, or 59X for the 0°C to +75°C temperature range.

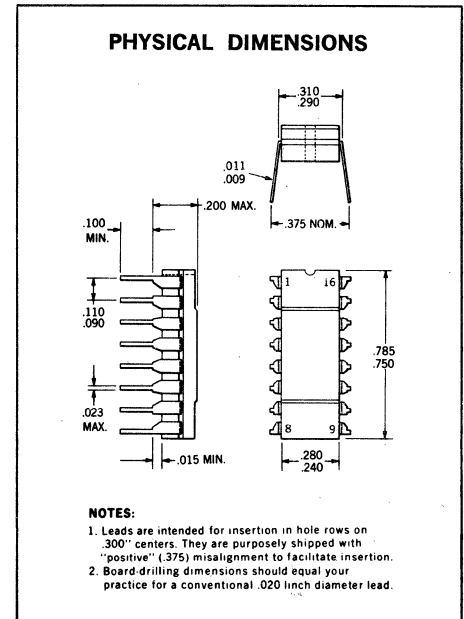


Figure 1

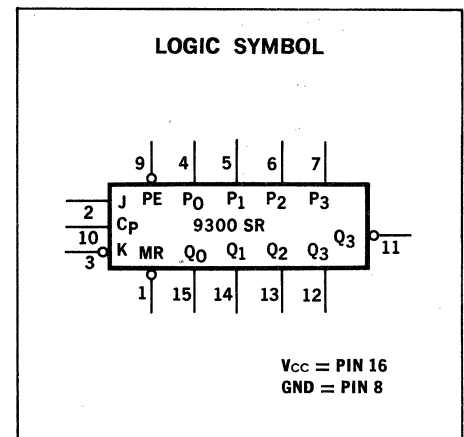


Figure 2

# FAIRCHILD MEDIUM SCALE INTEGRATION • 9300

## FUNCTIONAL DESCRIPTION

The logic symbol of Figure 2 provides an indication of the functional characteristics of the 9300 four bit shift register. Several special logical features of the 9300 design which provide a high degree of general usefulness are described below:

1. A  $\overline{JK}$  input is provided to the first flip flop in the register. This type of input is the same as the more common JK input except that the low voltage level activates the  $\overline{K}$  input. This provides the greater power of the JK type input for more general applications and at the same time the simple D type input that is most appropriate for a shift register can be easily obtained by simply tying the two inputs together.
2. There is no restriction on the activity of the J or  $\overline{K}$  inputs for logical operation — except for the set up and release time requirements.
3. Parallel inputs for all four stages are provided. These will determine the next condition of the shift register synchronous with the clock input, whenever the Parallel Enable input is low. With the Parallel Enable input low the element appears as four common clocked D flip flops. When the Parallel Enable is high, or not connected, the shift register performs a one bit shift for each clock input. In both cases the next state of the flip flops occurs after the low to high transition of the clock input.
4. An internal clock buffer provides both reduced clock input loading, and the ability to gate the clock with only a single NAND gate.
5. The active high output is provided for all four stages and an active low output is provided for the last stage.
6. A master asynchronous clear input allows the setting to zero of all stages, independent of the condition of any other inputs.

**TABLE I — TRUTH TABLE FOR SERIAL ENTRY**

(PE = HIGH, MR = HIGH, (n + 1) indicates state after next clock)

J	$\overline{K}$	$Q_0$ at $t_{n+1}$
L	L	L
L	H	$Q_0$ at $t_n$ (no change)
H	L	$\overline{Q_0}$ at $t_n$ (toggles)
H	H	H

**TABLE II — LOADING RULES (1 U.L. = 1 TT $\mu$ L Gate Input Load)**

INPUTS	LOADING
J, $\overline{K}$ , $\overline{MR}$ , $P_0$ , $P_1$ , $P_2$ & $P_3$	1 U.L.
$\overline{PE}$	2.3 U.L.
$C_p$	4 U.L.
OUTPUTS	FANOUT
$Q_0$ , $Q_1$ , $Q_2$ , $Q_3$ & $\overline{Q_3}$	6 U.L.

**TABLE III**  
ELECTRICAL CHARACTERISTICS ( $T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 10\%$ ) (Part #U6B930051X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS & COMMENTS
		$-55^\circ\text{C}$		$+25^\circ\text{C}$			$+125^\circ\text{C}$		
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	
$V_{OH}$	Output High Voltage	2.2		2.4	2.7		2.4		Volts $V_{CC} = 4.5\text{ V}$ , $I_{OH} = -0.36\text{ mA}$
$V_{OL}$	Output Low Voltage		0.4		0.2	0.4		0.4	Volts $V_{CC} = 5.5\text{ V}$ , $I_{OL} = 9.6\text{ mA}$ $V_{CC} = 4.5\text{ V}$ , $I_{OL} = 7.44\text{ mA}$
$V_{IH}$	Input High Voltage	2.0		1.7			1.4		Volts Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.8			0.9		0.8	Volts Guaranteed input low threshold for all inputs
$I_F$	Input Load Current* J, $\overline{K}$ , $\overline{MR}$ , $P_0$ , $P_1$ , $P_2$ & $P_3$		-1.6		-1.10	-1.6		-1.6	mA $V_{CC} = 5.5\text{ V}$ mA $V_{CC} = 4.5\text{ V}$ $V_F = 0.4\text{ V}$
			-1.24		-0.97	-1.24		-1.24	
$I_R$	Input Leakage Current* J, $\overline{K}$ , $\overline{MR}$ , $P_0$ , $P_1$ , $P_2$ & $P_3$			15	60		60		$\mu\text{A}$ $V_{CC} = 5.5\text{ V}$ , $V_R = 4.5\text{ V}$

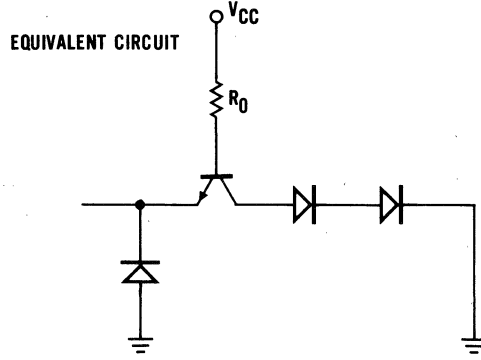
**TABLE IV**  
ELECTRICAL CHARACTERISTICS ( $T_A = 0^\circ\text{C}$  to  $+75^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 5\%$ ) (Part #U6B930059X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS
		$0^\circ\text{C}$		$+25^\circ\text{C}$			$+75^\circ\text{C}$		
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	
$V_{OH}$	Output High Voltage	2.4		2.4	3.0		2.4		Volts $V_{CC} = 4.75\text{ V}$ , $I_{OH} = -0.36\text{ mA}$
$V_{OL}$	Output Low Voltage		0.45		0.2	0.45		0.45	Volts $V_{CC} = 5.25\text{ V}$ , $I_{OL} = 9.6\text{ mA}$
$V_{IH}$	Input High Voltage	1.9		1.8			1.6		Volts $V_{CC} = 4.75\text{ V}$ , $I_{OL} = 8.5\text{ mA}$ Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.85			0.85		0.85	Volts Guaranteed input low threshold for all inputs
$I_F$	Input Load Current* J, $\overline{K}$ , $\overline{MR}$ , $P_0$ , $P_1$ , $P_2$ & $P_3$		-1.6		-1.0	-1.6		-1.6	mA $V_{CC} = 5.25\text{ V}$ mA $V_{CC} = 4.75\text{ V}$ , $V_F = 0.45\text{ V}$
			-1.41		-0.9	-1.41		-1.41	
$I_R$	Input Leakage Current* J, $\overline{K}$ , $\overline{MR}$ , $P_0$ , $P_1$ , $P_2$ & $P_3$			15	60		60		$\mu\text{A}$ $V_{CC} = 5.25\text{ V}$ , $V_R = 4.5\text{ V}$

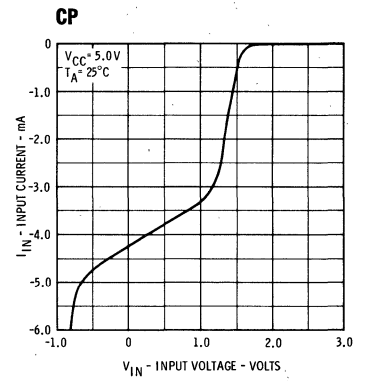
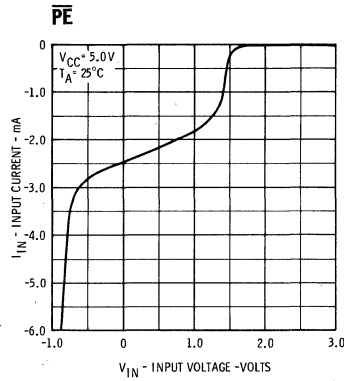
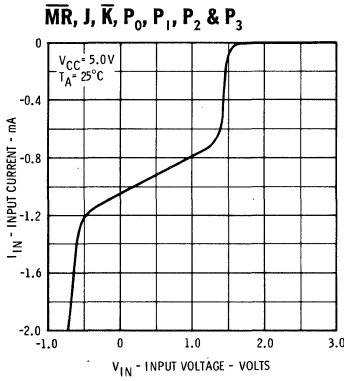
\*For CP and PE input currents, use load factors in Table II

TYPICAL INPUT AND OUTPUT CHARACTERISTICS

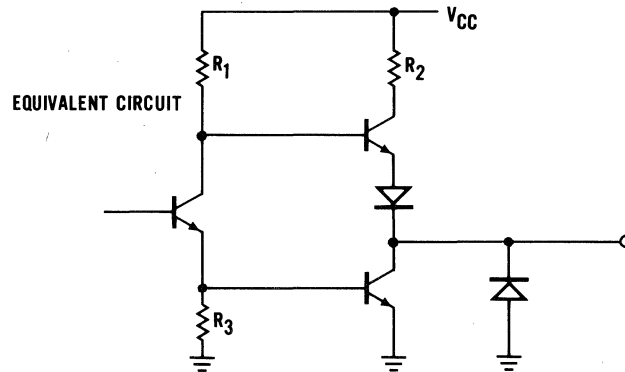
INPUTS



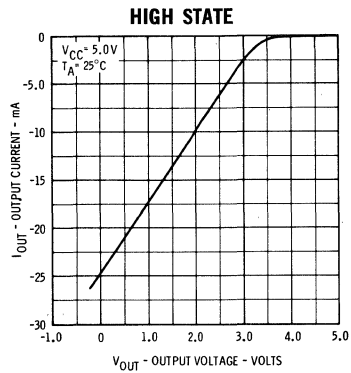
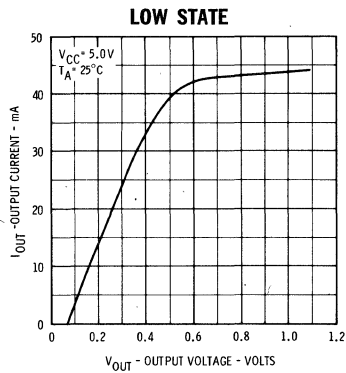
INPUT CURRENT VERSUS INPUT VOLTAGE



OUTPUTS



OUTPUT CURRENT VERSUS OUTPUT VOLTAGE  
( $Q_0, Q_1, Q_2, Q_3$  AND  $\overline{Q}_3$ )



# FAIRCHILD MEDIUM SCALE INTEGRATION • 9300

**SWITCHING CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$ ) (Parts #U6B930051X and U6B930059X)

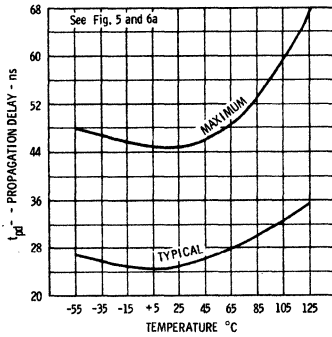
SYMBOL	CHARACTERISTIC	MIN.	TYP.	MAX.	UNITS	CONDITIONS & COMMENTS
$t_{pd+}$	Turn Off Delay		20	35	ns	$V_{CC} = 5.0\text{ V}$ , $C_L = 15\text{ pF}$ (See Fig. 5 & 6a)
$t_{pd-}$	Turn On Delay		25	45	ns	
$f_{sr}$	Shift Right Frequency	15	25		MHz	$V_{CC} = 5.0\text{ V}$ , $C_L = 15\text{ pF}$ (See Fig. 5 & 6c)
$CP_{pw}$	Clock Pulse Width	35	15		ns	$V_{CC} = 5.0\text{ V}$ $C_L = 15\text{ pF}$ (See Figs. 6a & 6b)
$t_s$	Set-up Time	35	17		ns	
$t_r$	Release Time		16	0	ns	
$t_s(\overline{PE})$	Set-up Time for $\overline{PE}$	45	26		ns	
$t_r(\overline{PE})$	Release Time for $\overline{PE}$		25	10	ns	
$t_{pd-}(\overline{MR})$	Reset Time for $\overline{MR}$		35		ns	
$t_{rec}(\overline{MR})$	Recovery Time for $\overline{MR}$		20		ns	
$MR_{pw}$	Min Reset Pulse Width		15		ns	

**SET-UP TIME:**  $t_s$  is defined as the minimum time required for the logic level to be present at the logic input prior to the clock transition from low to high in order for the flip-flop(s) to respond.

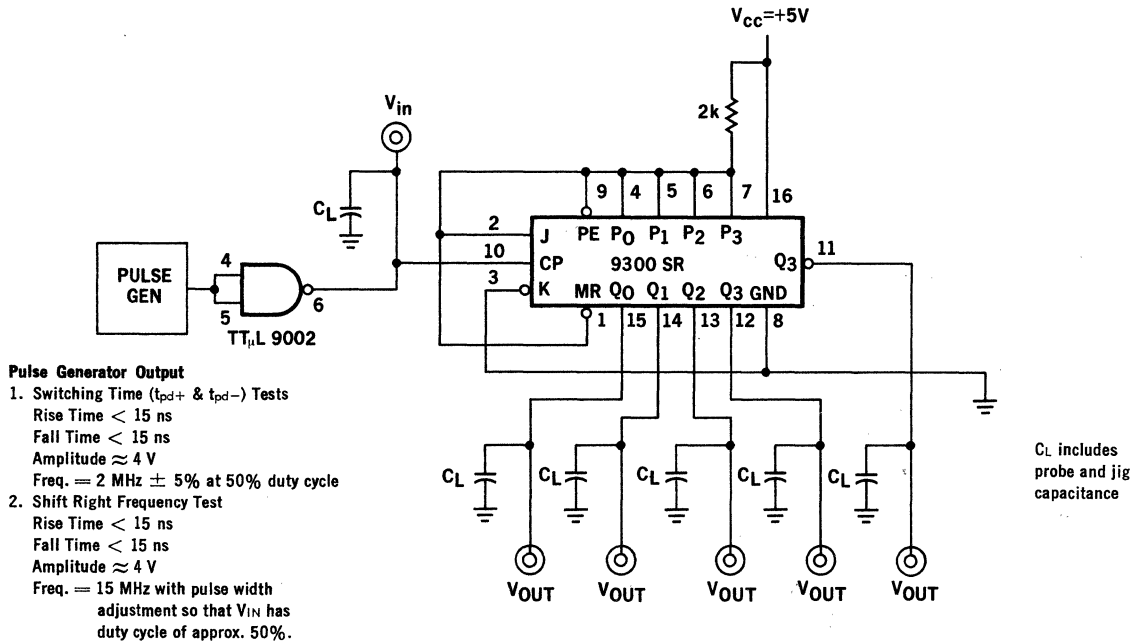
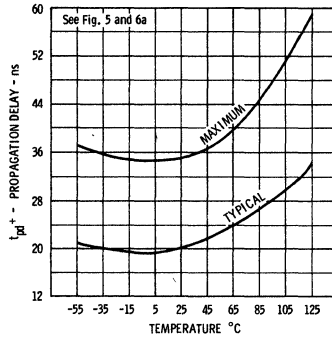
**RELEASE TIME:**  $t_r$  is defined as the maximum time allowed for the logic level to be present at the logic input prior to the clock transition from low to high in order for the flip-flop(s) not to respond.

**RECOVERY TIME FOR  $\overline{MR}$ :**  $t_{rec}(\overline{MR})$  is defined as the minimum time required between the end of the reset pulse and the clock transition from low to high in order for the flip-flop(s) to respond to the clock.

**Figure 3**  
**PROPAGATION DELAY —**  
**CLOCK TO Q<sub>0</sub> OR Q<sub>3</sub>**  
**OUTPUT VS TEMPERATURE**



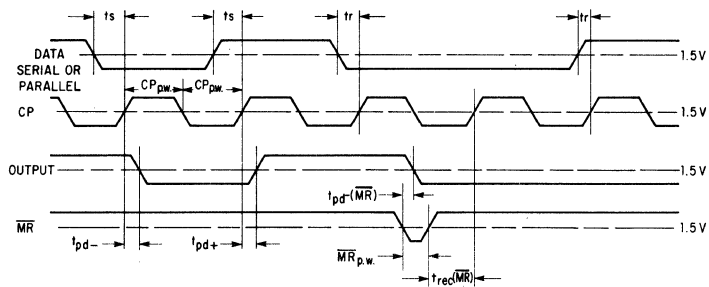
**Figure 4**  
**PROPAGATION DELAY —**  
**CLOCK TO Q<sub>0</sub> OR Q<sub>3</sub>**  
**OUTPUT VS TEMPERATURE**



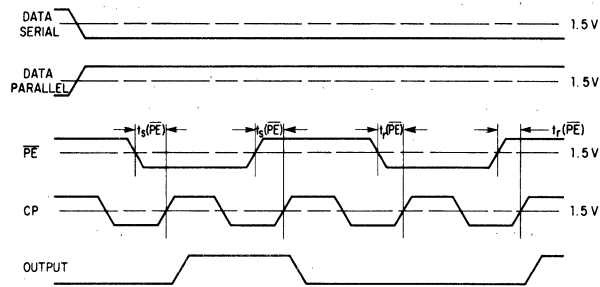
**Figure 5 — SWITCHING TIME & SHIFT RIGHT FREQUENCY TEST CIRCUIT**

# FAIRCHILD MEDIUM SCALE INTEGRATION • 9300

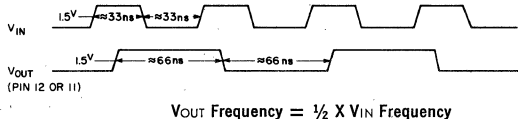
**Fig. 6a**



**Fig. 6b**

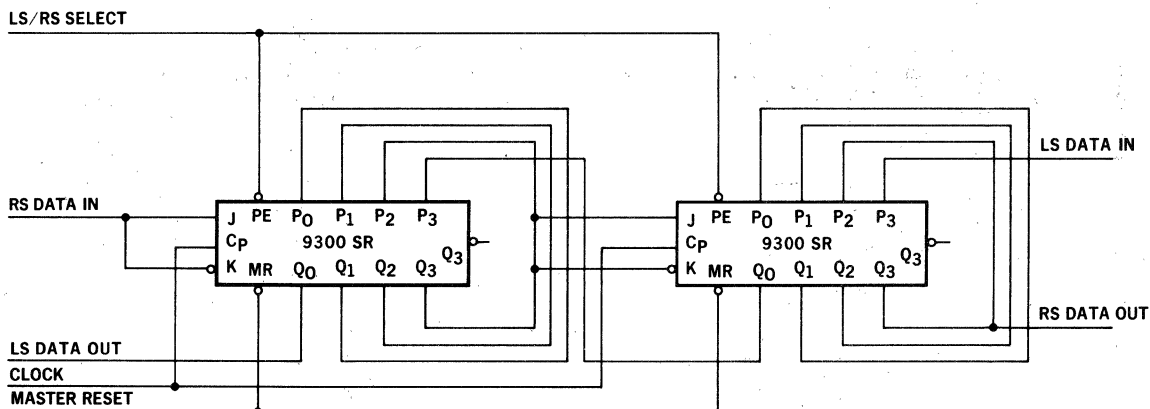


**Fig. 6c**



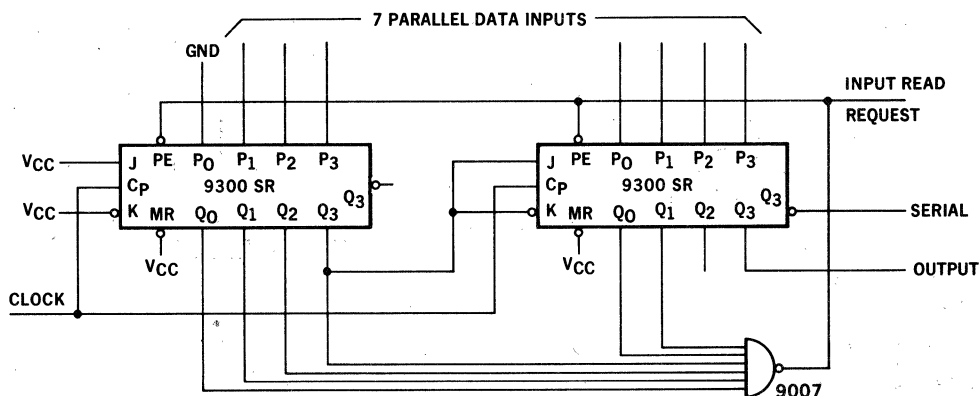
**Figure 6 — SWITCHING TIME & SHIFT RIGHT FREQUENCY WAVEFORMS**

**APPLICATIONS** — The 9300 has been designed to be useful in a wide variety of applications. The multifunctional capability of the Fairchild 9300 is illustrated by the applications shown below.



**Figure 7 — EIGHT BIT LEFT/RIGHT SHIFT REGISTER**

This register shifts Left or Right on each shift clock, depending upon the condition of the LS/RS SELECT input. If this input is high, Right Shift occurs and if low, Left Shift occurs.



**Figure 8 — SEVEN BIT PARALLEL TO SERIAL CONVERTER**

This parallel to serial converter uses a marker bit, to count the data bits shifted out, so that a parallel load enable is generated to load the next parallel word for conversion at the correct time.



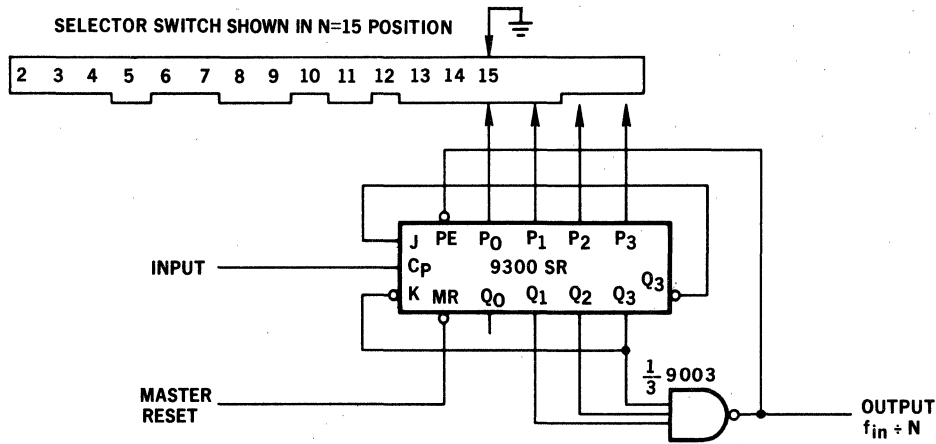
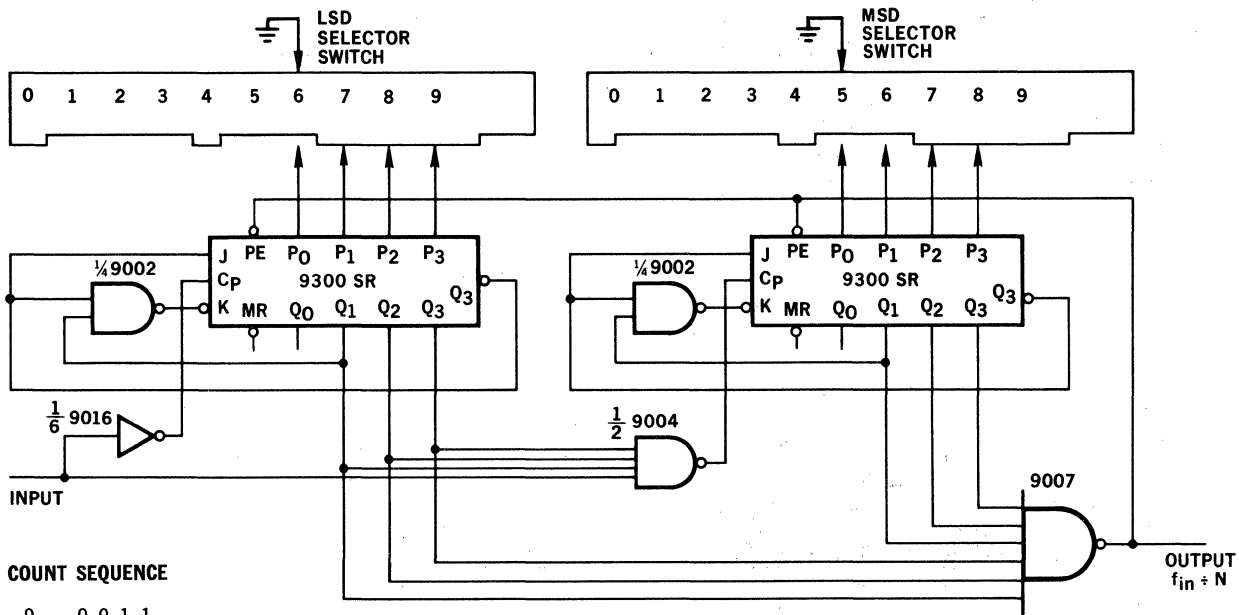


Figure 9 — DIVIDE BY N COUNTER FOR N = 2 to 15

This counter produces an output pulse for every N input pulses, where the number N is determined by the setting of the slide selector switch as shown or by logic inputs to the parallel data lines from an external source.



COUNT SEQUENCE

9	0	0	1	1
8	0	0	0	1
7	0	0	0	0
6	1	0	0	0
5	1	1	0	0
4	0	1	1	0
3	1	0	1	1
2	1	1	0	1
1	1	1	1	0
0	0	1	1	1

Figure 10 — TWO DECADE PROGRAMMABLE DIVIDER

This circuit divides by any number "N" from 1 to 100. The selected N is one greater than is shown on the slide switches. As an example the switches are showing 56, therefore the circuit will divide by 57 with this setting.

# 9301

## MSI ONE-OF-TEN DECODER

### A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The 9301 is a multipurpose decoder designed to accept four inputs and provide 10 mutually exclusive outputs. The circuit uses TT $\mu$ L for high speed and high fan out capability, and is compatible with all members of the CCSL group of digital integrated circuits.

- Multi-function capability
- Mutually exclusive outputs
- Guaranteed fanout of 10 TT $\mu$ L loads over the full temperature range and supply voltage ranges
- High capacitive drive capability
- Demultiplexing capability
- Typical power dissipation of 145 mW
- The input/output characteristics provide easy interfacing with Fairchild DT $\mu$ L, LPDT $\mu$ L and TT $\mu$ L families (CCSL).
- All ceramic "HERMETIC" 16-pin Dual In-Line\* package
- Input clamp diodes limit high speed line termination effects

**ABSOLUTE MAXIMUM RATINGS** (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5 V to +7 V
Voltage Applied to Outputs for high output state	-0.5 V to +V <sub>CC</sub> value
Input Voltage (D.C.)	-0.5 V to +5.5 V

**ORDER INFORMATION**

Specify U6B9301XXX for 16 pin Dual In-Line package where XXX is 51X for the -55°C to +125°C temperature range, or 59X for the 0°C to +75°C temperature range.

\*Fairchild patent pending.

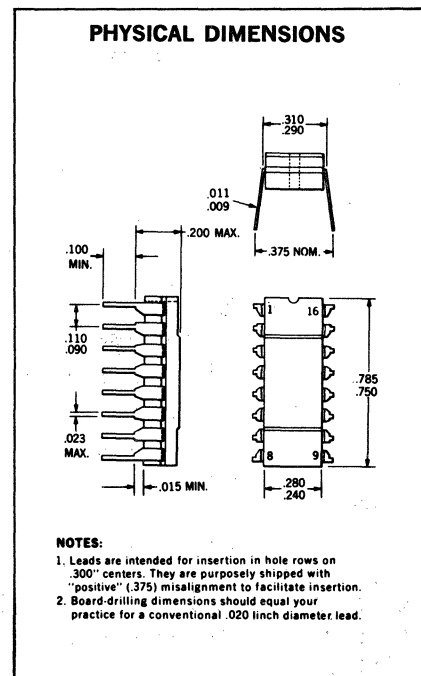


Fig. 1

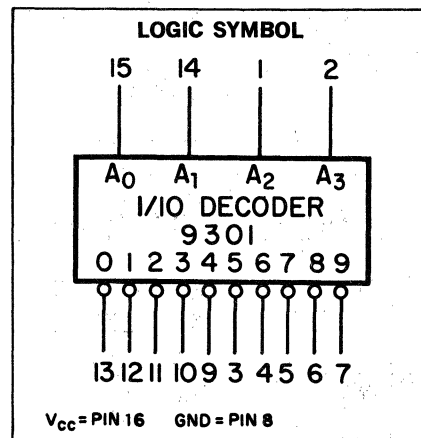


Fig. 2

# FAIRCHILD MEDIUM SCALE INTEGRATION • 9301

## FUNCTIONAL DESCRIPTION

The 9301 Decoder accepts four active high BCD inputs and provides ten mutually exclusive active low outputs, as shown by Figure 2. The active low outputs facilitate memory addressing when inverting drivers are used between decoder and memory elements such as the 9033.

The logic design of the 9301 ensures that all outputs are high when binary codes greater than nine are applied to the inputs.

The most significant  $A_3$  input produces a useful inhibit function when the 9301 is used as a 1 out of 8 decoder. This is illustrated in the 1 out of 32 decoder shown in Figure 9.

The Truth Table and Loading Rules for the 9301 are shown in Table I and Table II.

**TABLE I — TRUTH TABLE**

$A_0$	$A_1$	$A_2$	$A_3$	0	1	2	3	4	5	6	7	8	9
L	L	L	L	L	H	H	H	H	H	H	H	H	H
H	L	L	L	H	L	H	H	H	H	H	H	H	H
L	H	L	L	H	H	L	H	H	H	H	H	H	H
H	H	L	L	H	H	H	L	H	H	H	H	H	H
L	L	H	L	H	H	H	H	L	H	H	H	H	H
H	L	H	L	H	H	H	H	H	L	H	H	H	H
L	H	H	L	H	H	H	H	H	H	L	H	H	H
H	H	H	L	H	H	H	H	H	H	H	L	H	H
L	L	L	H	H	H	H	H	H	H	H	H	L	H
H	L	L	H	H	H	H	H	H	H	H	H	H	L
L	H	L	H	H	H	H	H	H	H	H	H	H	H
H	H	L	H	H	H	H	H	H	H	H	H	H	H
L	L	H	H	H	H	H	H	H	H	H	H	H	H
H	L	H	H	H	H	H	H	H	H	H	H	H	H
L	H	H	H	H	H	H	H	H	H	H	H	H	H
H	H	H	H	H	H	H	H	H	H	H	H	H	H

H = High Voltage Level  
L = Low Voltage Level

**TABLE II —**

**LOADING RULES (1 U.L. = TT $\mu$ L Gate Input Load)**

INPUTS	LOADING
$A_0, A_1, A_2$ & $A_3$	1 U.L.

OUTPUTS	FANOUT
0, 1, 2, 3, 4, 5, 6, 7, 8, & 9	10 U.L.

**TABLE III —**

**ELECTRICAL CHARACTERISTICS ( $T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$ ) (Part #U6B930151X)**

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$-55^\circ\text{C}$		$+25^\circ\text{C}$		$+125^\circ\text{C}$				
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	2.7		2.4		Volts	$V_{CC} = 4.5\text{V}$ , $I_{OH} = -0.6\text{mA}$
$V_{OL}$	Output Low Voltage		0.4		0.2	0.4		0.4	Volts	$V_{CC} = 4.5\text{V}$ , $I_{OL} = 12.4\text{mA}$ $V_{CC} = 5.5\text{V}$ , $I_{OL} = 16.0\text{mA}$
$V_{IH}$	Input High Voltage	2.0		1.7			1.4		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.8			0.9		0.8	Volts	Guaranteed input low threshold for all inputs
$I_F$	Input Load Current		-1.6		-1.10	-1.6		-1.6	mA	$V_{CC} = 5.5\text{V}$ $V_{CC} = 4.5\text{V}$
			-1.24		-0.97	-1.24		-1.24	mA	
$I_R$	Input Leakage Current				15	60		60	$\mu\text{A}$	$V_{CC} = 5.5\text{V}$ , $V_R = 4.5\text{V}$
$t_{pd+}$	Turn Off Delay Input to Output				23	35			ns	$V_{CC} = 5.0\text{V}$ $C_L = 15\text{pF}$ See Fig. 8
$t_{pd-}$	Turn On Delay Input to Output				20	30			ns	

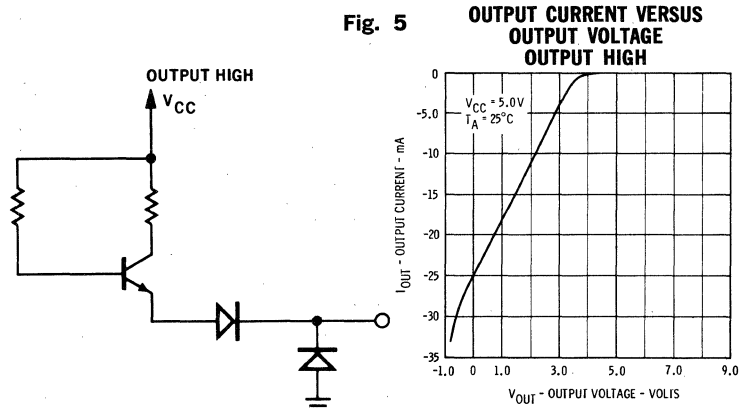
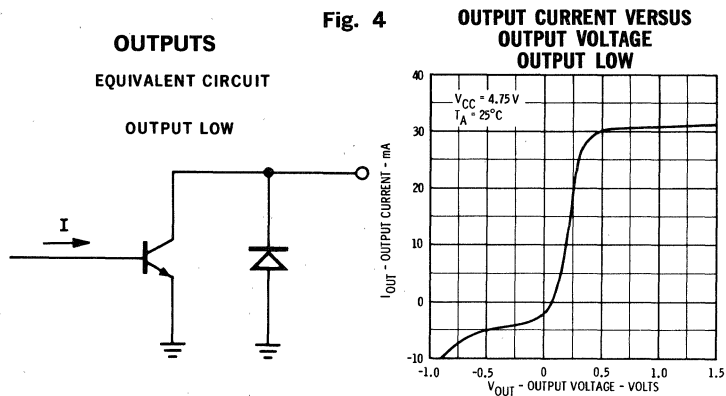
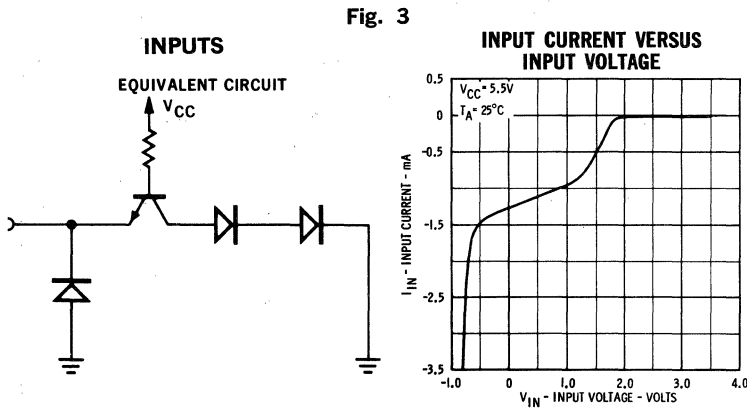
# FAIRCHILD MEDIUM SCALE INTEGRATION • 9301

**TABLE IV —**

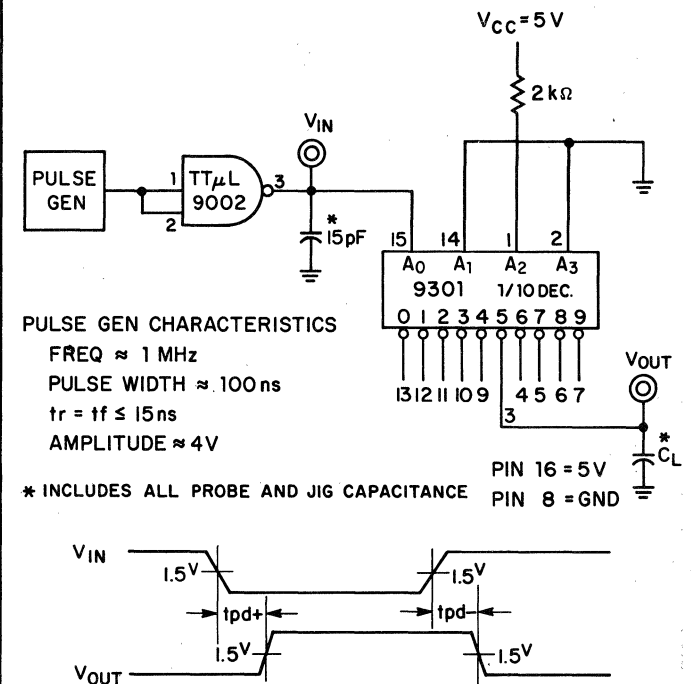
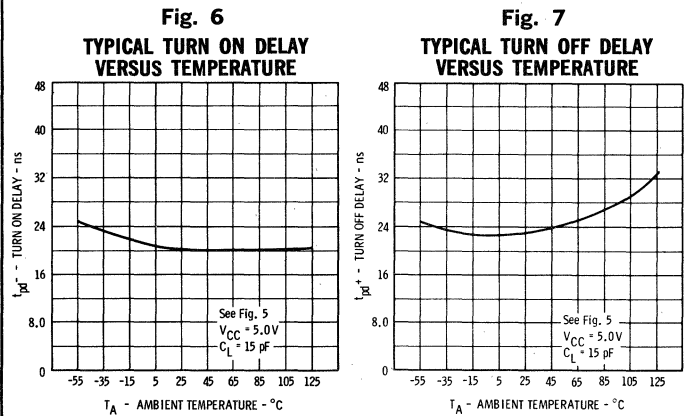
**ELECTRICAL CHARACTERISTICS** ( $T_A = 0^\circ\text{C}$  to  $+75^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 5\%$ ) (Part #U6B930159X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		0°C		+25°C		+75°C				
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	3.0		2.4		Volts	$V_{CC} = 4.75\text{V}$ , $I_{OH} = -0.6\text{mA}$
$V_{OL}$	Output Low Voltage		0.45		0.2	0.45		0.45	Volts	$V_{CC} = 4.75\text{V}$ , $I_{OL} = 14.1\text{mA}$ $V_{CC} = 5.25\text{V}$ , $I_{OL} = 16.0\text{mA}$
$V_{IH}$	Input High Voltage	1.9		1.8			1.6		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.85			0.85		0.85	Volts	Guaranteed input low threshold for all inputs
$I_F$	Input Load Current		-1.6		-1.0	-1.6		-1.6	mA	$V_{CC} = 5.25\text{V}$ , $V_F = 0.45\text{V}$
			-1.41		-0.9	-1.41		-1.41	mA	$V_{CC} = 4.75\text{V}$
$I_R$	Input Leakage Current			15	60		60		$\mu\text{A}$	$V_{CC} = 5.25\text{V}$ , $V_R = 4.5\text{V}$
$t_{pd+}$	Turn Off Delay Input to Output			23	35				ns	$V_{CC} = 5.0\text{V}$
$t_{pd-}$	Turn On Delay			20	30				ns	$C_L = 15\text{pF}$ See Fig. 8

### TYPICAL INPUT AND OUTPUT CHARACTERISTICS



### SWITCHING PERFORMANCE



# FAIRCHILD MEDIUM SCALE INTEGRATION • 9301

**APPLICATIONS** — The 9301 decoder may be used for BCD to Decimal or 3 bit binary to octal conversion as well as many other applications. The general purpose nature of the 9301 is indicated by its use in the following applications.

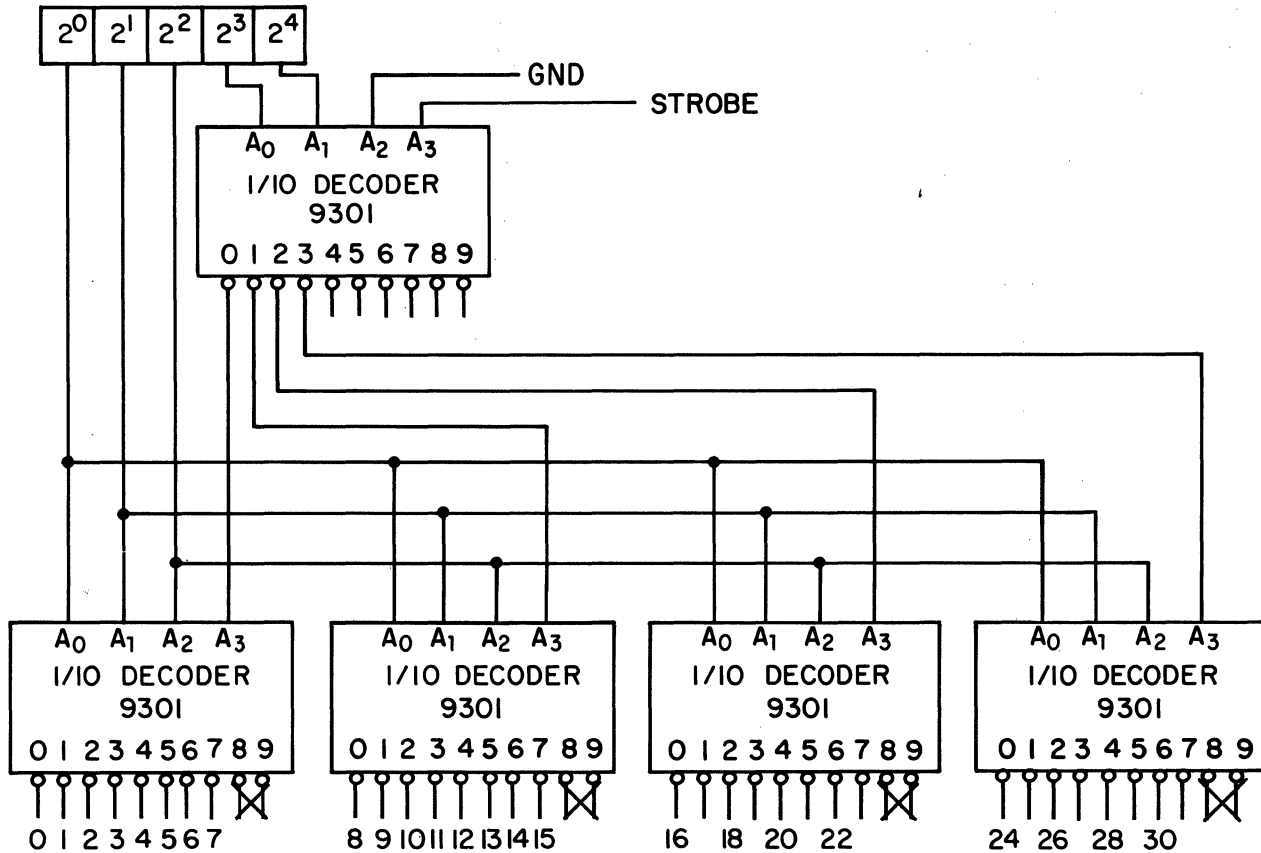
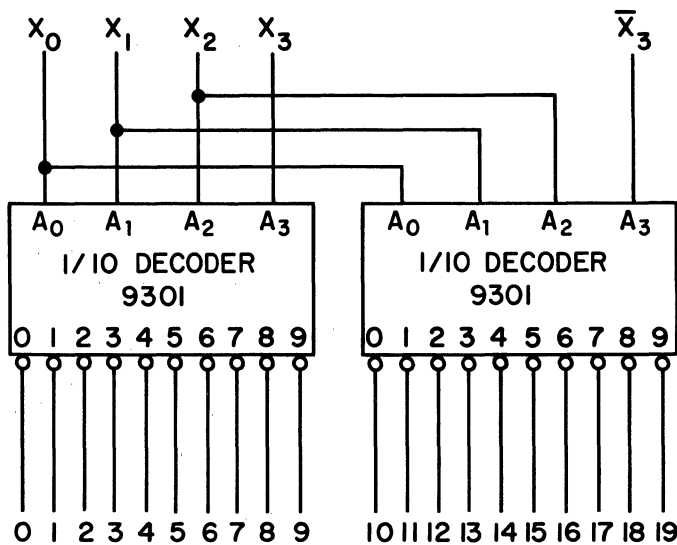


Fig. 9 — ONE-OUT-OF-THIRTY-TWO DECODING

### BCD CODE

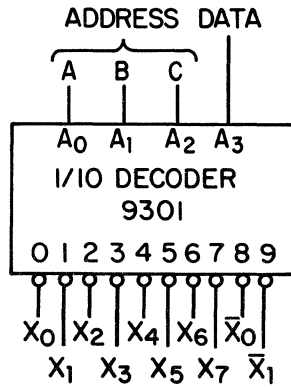


DECIMAL DIGIT	OUTPUT SELECTION			
	BCD CODE			
	8421	5421	EXCESS 3	4221
0	0, 18	0, 18	3	0, 18
1	1, 19	1, 19	4	1, 19
2	2	2	5	2
3	3	3	6	3
4	4	4	7	6
5	5	8, 10	8, 10	9, 11
6	6	9, 11	9, 11	14
7	7	12	12	15
8	8, 10	13	13	16
9	9, 11	14	14	17

### OUTPUTS

Decode any BCD code using two 9301 elements. Any 4 bit BCD code may be decoded by selecting outputs as shown in the table.

Fig.10 — DECODE ANY BCD CODE

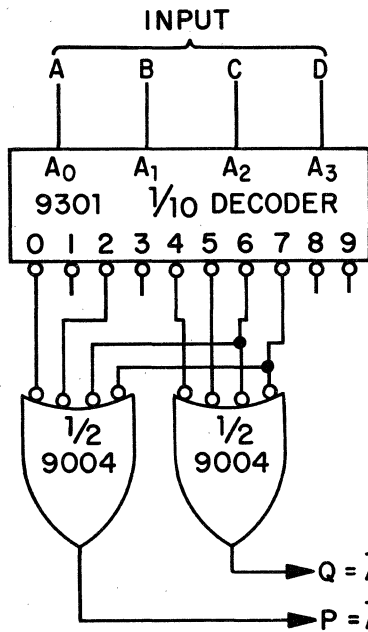


ADDRESS			OUTPUT LINE
A	B	C	
0	0	0	0
1	0	0	1
0	1	0	2
1	1	0	3
0	0	1	4
1	0	1	5
0	1	1	6
1	1	1	7

Data may be routed from a source to any of 8 outputs by addressing that output. All non-addressed outputs remain high.

Complements of outputs 0 and 1 are available at outputs 8 and 9 respectively.

Fig. 11— DIGITAL DEMULTIPLEXER



Each output of the 9301 may be considered a minterm of the input code. Several sums of minterms may be generated economically using discrete IC gates and one 9301 decoder.

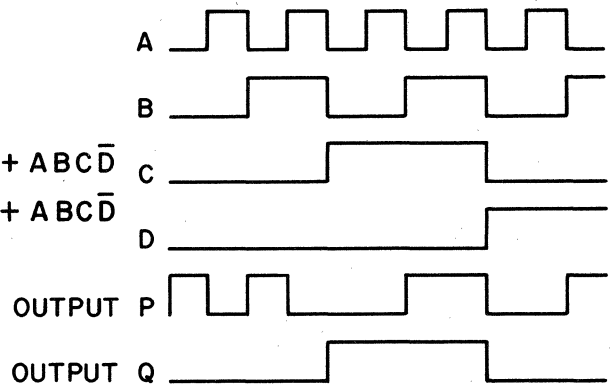


Fig. 12— MINTERM GENERATOR

# 9304

## MSI DUAL FULL ADDER

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The 9304 consists of two independent, high speed, binary full adders. The adders are useful in a wide variety of applications including multiple bit parallel add/serial carry addition, parity generation and checking, code conversion, and majority gating. The circuit uses  $TT\mu L$  for high speed, high fanout operation and is compatible with all members of the CCSL group of digital integrated circuits.

- Multi-function capability
- 8ns carry propagation delay
- Complementary inputs and outputs available
- Typical power dissipation of 150 mW
- The input/output characteristics provide easy interfacing with Fairchild  $DT\mu L$ ,  $LPDT\mu L$  and  $TT\mu L$  families (CCSL).
- All ceramic "HERMETIC" 16-pin Dual In-Line\* package
- Input clamp diodes limit high speed termination effects

**ABSOLUTE MAXIMUM RATINGS** (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
$V_{CC}$ Pin Potential to Ground Pin	-0.5 V to +7 V
Voltage Applied to Outputs for high output state	-0.5 V to + $V_{CC}$ value
Input Voltage (D.C.)	-0.5 V to +5.5 V

**ORDER INFORMATION**

Specify U6B9304XXX for 16 pin Dual In-Line package where XXX is 51X for the -55°C to +125°C temperature range, or 59X for the 0°C to +75°C temperature range.

\*Fairchild patent pending

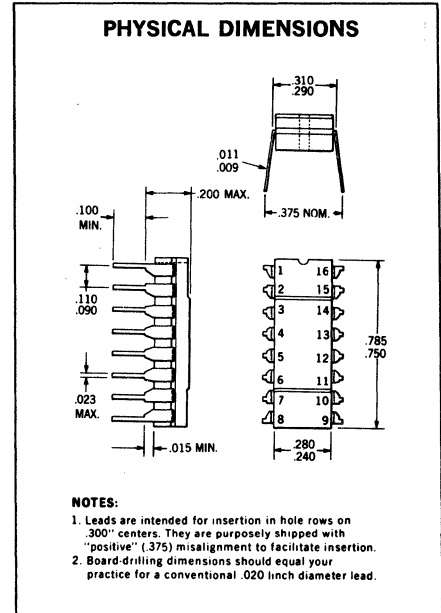


Fig. 1

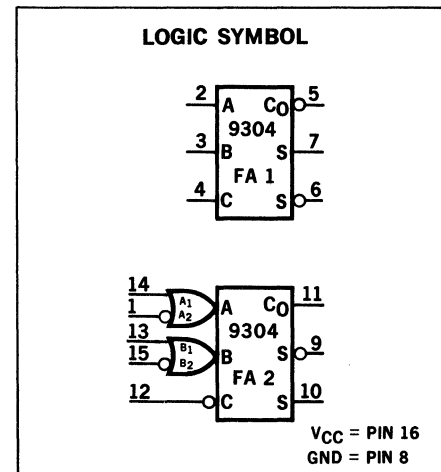


Fig. 2



# FAIRCHILD MEDIUM SCALE INTEGRATION • 9304

## FUNCTIONAL DESCRIPTION

The Fairchild 9304 logic block consists of two separate high speed carry dependent sum full adders. This design allows a minimum carry propagation time when the adders are used in ripple carry applications. The adders are identical except that adder 2 has provision for either active high or active low inputs at the A and B terminals. The adders produce a low carry and both low and high sum with active high inputs, a high carry and both high and low sum when active low inputs are used. This principle of duality is shown in Figure 12, where the adders are drawn as functional blocks.

The Truth Table and Loading Rules for the 9304 are shown in Table I and Table II.

**TABLE I — TRUTH TABLES**

ADDER 1					
INPUTS			OUTPUTS		
C	B	A	$\overline{C}_O$	$\overline{S}$	S
L	L	L	H	H	L
L	L	H	H	L	H
L	H	L	H	L	H
L	H	H	L	H	L
H	L	L	H	L	H
H	L	H	L	H	L
H	H	L	L	H	L
H	H	H	L	L	H

ADDER 2							
INPUTS					OUTPUTS		
$\overline{C}$	$B_1$	$A_1$	$\overline{B}_2$	$\overline{A}_2$	$C_O$	S	$\overline{S}$
L	L	L	L	L	H	H	L
L	L	L	L	H	H	L	H
L	L	L	H	L	H	L	H
L	L	L	H	H	L	H	L
L	L	H	L	L	H	H	L
L	L	H	L	H	H	H	L
L	L	H	H	L	H	L	H
L	L	H	H	H	H	L	H
L	H	L	L	L	H	H	L
L	H	L	L	H	H	L	H
L	H	L	H	L	H	H	L
L	H	L	H	H	H	L	H
L	H	H	L	L	H	H	L
L	H	H	L	H	H	H	L
L	H	H	H	L	H	H	L
L	H	H	H	H	H	H	L
H	L	L	L	L	H	L	H
H	L	L	L	H	L	H	L
H	L	L	H	L	L	L	H
H	L	L	H	H	L	L	H
H	L	H	L	L	H	L	H
H	L	H	L	H	H	L	H
H	L	H	H	L	L	H	L
H	L	H	H	H	L	H	L
H	H	L	L	L	H	L	H
H	H	L	L	H	L	H	L
H	H	L	H	H	L	H	L
H	H	H	L	L	H	L	H
H	H	H	L	H	H	L	H
H	H	H	H	L	H	L	H
H	H	H	H	H	H	L	H

**TABLE II —**

**LOADING RULES (1 U.L. =  $TT_{\mu L}$  Gate Input Unit Load)**

INPUTS		LOADING
FA 1	A, B & C	4 U.L.
FA 2	$\overline{A}_2, \overline{B}_2$ & $\overline{C}$	4 U.L.
	$A_1$ & $B_1$	1 U.L.

OUTPUTS		FANOUT
FA 1	$\overline{C}_O$	7 U.L.
	$\overline{S}$	9 U.L.
	S	10 U.L.
FA 2	$C_O$	7 U.L.
	S	9 U.L.
	$\overline{S}$	10 U.L.

H = High Voltage Level  
L = Low Voltage Level



**FAIRCHILD MEDIUM SCALE INTEGRATION • 9304**

**TABLE III —**  
**ELECTRICAL CHARACTERISTICS** ( $T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$ ) (Part #U6B930451X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$-55^\circ\text{C}$		$+25^\circ\text{C}$			$+125^\circ\text{C}$			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.2		2.4	2.7		2.4		Volts	$V_{CC} = 4.5\text{V}$ , $I_{OH} = -1.2\text{mA}$ (Pins 7 & 9) $V_{CC} = 4.5\text{V}$ , $I_{OH} = -1.08\text{mA}$ (Pins 6 & 10) $V_{CC} = 4.5\text{V}$ , $I_{OH} = -0.84\text{mA}$ (Pins 5 & 11)
$V_{OL}$	Output Low Voltage	0.4		0.21	0.4		0.4		Volts	$V_{CC} = 5.5\text{V}$ , $I_{OL} = 16\text{mA}$ (Pins 7 & 9) $I_{OL} = 14.4\text{mA}$ (Pins 6 & 10) $I_{OL} = 11.2\text{mA}$ (Pins 5 & 11) $V_{CC} = 4.5\text{V}$ , $I_{OL} = 12.4\text{mA}$ (Pins 7 & 9) $I_{OL} = 11.2\text{mA}$ (Pins 6 & 10) $I_{OL} = 8.7\text{mA}$ (Pins 5 & 11)
$V_{IH}$	Input High Voltage	2.0		1.7			1.4		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage	0.8		0.9			0.8		Volts	Guaranteed input low threshold for all inputs
$I_F$ 4 $I_F$	Input Load Current Input Load Current	-1.6 -6.4		-1.1 -4.4	-1.6 -6.4		-1.6 -6.4		mA	$V_{CC} = 5.5\text{V}$ $V_F = 0.4\text{V}$ $V_R = 5.5\text{V}$ on other inputs
$I_F$ 4 $I_F$	Input Load Current Input Load Current	-1.24 -4.96		-0.97 -3.88	-1.24 -4.96		-1.24 -4.96		mA	$V_{CC} = 4.5\text{V}$
$I_R$ 4 $I_R$	Input Leakage Current Input Leakage Current			15 60	60 240		60 240		$\mu\text{A}$	$V_{CC} = 5.5\text{V}$ , $V_R = 4.5\text{V}$ Ground on other inputs
$t_{pd+}$	C to $C_O$			8	13				ns	$V_{CC} = 5.0\text{V}$ $C_L = 15\text{pF}$ See Fig.11
$t_{pd-}$	C to $C_O$			8	13				ns	
$t_{pd+}$	$A_1$ to $\bar{S}$			28	40				ns	
$t_{pd-}$	$A_1$ to $\bar{S}$			25	35				ns	

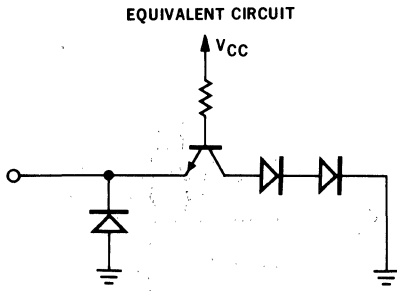
**TABLE IV —**  
**ELECTRICAL CHARACTERISTICS** ( $T_A = 0^\circ\text{C}$  to  $+75^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 5\%$ ) (Part #U6B930459X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$0^\circ\text{C}$		$+25^\circ\text{C}$			$+75^\circ\text{C}$			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	3.0		2.4		Volts	$V_{CC} = 4.75\text{V}$ , $I_{OH} = -1.2\text{mA}$ (Pins 7 & 9) $V_{CC} = 4.75\text{V}$ , $I_{OH} = -1.08\text{mA}$ (Pins 6 & 10) $V_{CC} = 4.75\text{V}$ , $I_{OH} = -0.84\text{mA}$ (Pins 5 & 11)
$V_{OL}$	Output Low Voltage	0.45		0.21	0.45		0.45		Volts	$V_{CC} = 5.25\text{V}$ , $I_{OL} = 16\text{mA}$ (Pins 7 & 9) $I_{OL} = 14.4\text{mA}$ (Pins 6 & 10) $I_{OL} = 11.2\text{mA}$ (Pins 5 & 11) $V_{CC} = 4.75\text{V}$ , $I_{OL} = 14.1\text{mA}$ (Pins 7 & 9) $I_{OL} = 12.7\text{mA}$ (Pins 6 & 10) $I_{OL} = 9.85\text{mA}$ (Pins 5 & 11)
$V_{IH}$	Input High Voltage	1.9		1.8			1.6		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage	0.85		0.85			0.85		Volts	Guaranteed input low threshold for all inputs
$I_F$ 4 $I_F$	Input Load Current Input Load Current	-1.6 -6.4		-1.0 -4.0	-1.6 -6.4		-1.6 -6.4		mA	$V_{CC} = 5.25\text{V}$ , $V_F = 0.45\text{V}$ $V_R = 5.25\text{V}$ on other inputs
$I_F$ 4 $I_F$	Input Load Current Input Load Current	-1.41 -5.64		-0.9 -3.6	-1.41 -5.64		-1.41 -5.64		mA	$V_{CC} = 4.75\text{V}$ , $V_F = 0.45\text{V}$ $V_R = 5.25\text{V}$ on other inputs
$I_R$ 4 $I_R$	Input Leakage Current Input Leakage Current			15 60	60 240		60 240		$\mu\text{A}$	$V_{CC} = 5.25\text{V}$ , $V_R = 4.5\text{V}$ Ground on other inputs
$t_{pd+}$	C to $C_O$			8.0	15				ns	$V_{CC} = 5.0\text{V}$ $C_L = 15\text{pF}$ See Fig.11
$t_{pd-}$	C to $C_O$			8.0	15				ns	
$t_{pd+}$	$A_1$ to $\bar{S}$			28	45				ns	
$t_{pd-}$	$A_1$ to $\bar{S}$			25	40				ns	

# FAIRCHILD MEDIUM SCALE INTEGRATION • 9304

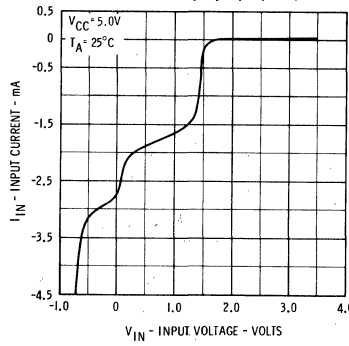
## TYPICAL INPUT AND OUTPUT CHARACTERISTICS

### INPUTS

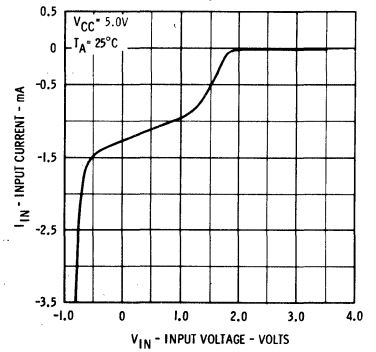


### INPUT CURRENT VS INPUT VOLTAGE

**FIG. 3 PINS 1, 2, 3, 4, 12, 15**

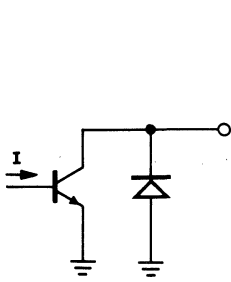


**FIG. 4 PINS 13, 14**

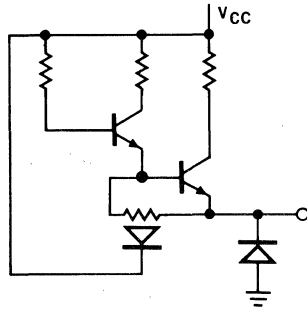


### OUTPUTS

#### LOW STATE

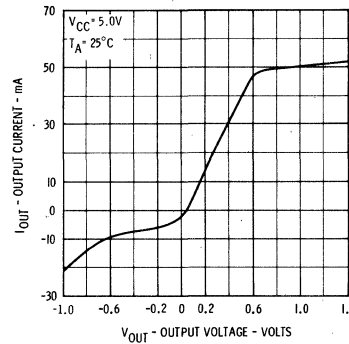


#### HIGH STATE

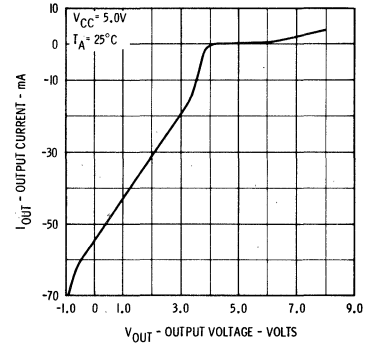


### OUTPUT CURRENT VS OUTPUT VOLTAGE

**FIG. 5 LOW STATE**

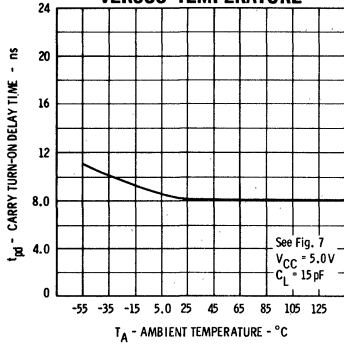


**FIG. 6 HIGH STATE**



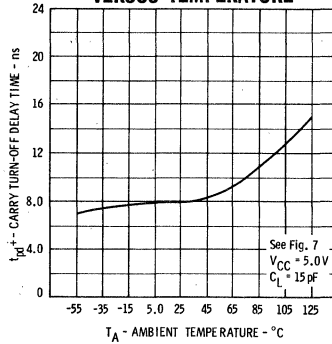
**Fig. 7**

#### TYPICAL CARRY TURN ON DELAY TIME VERSUS TEMPERATURE



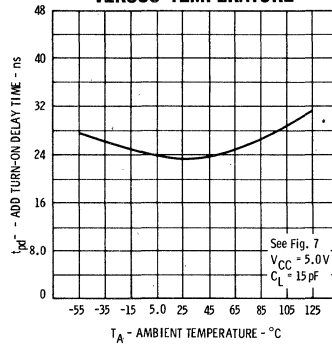
**Fig. 8**

#### TYPICAL CARRY TURN OFF DELAY TIME VERSUS TEMPERATURE



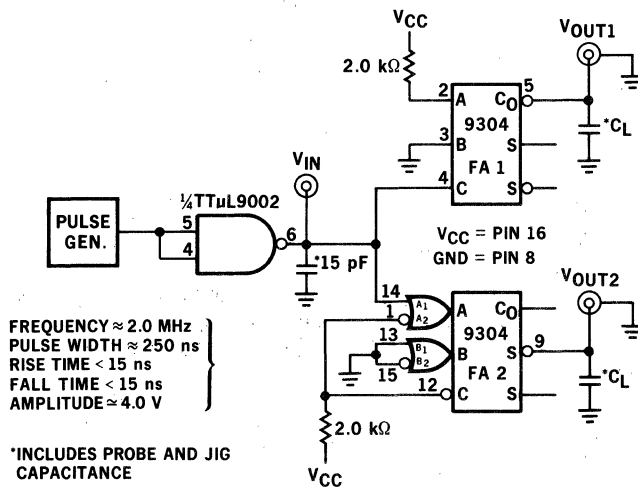
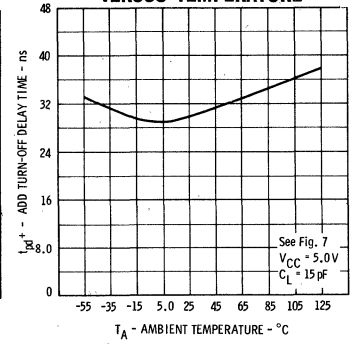
**Fig. 9**

#### TYPICAL ADD TURN ON DELAY TIME VERSUS TEMPERATURE



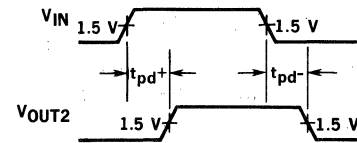
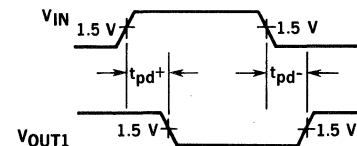
**Fig. 10**

#### TYPICAL ADD TURN OFF DELAY TIME VERSUS TEMPERATURE



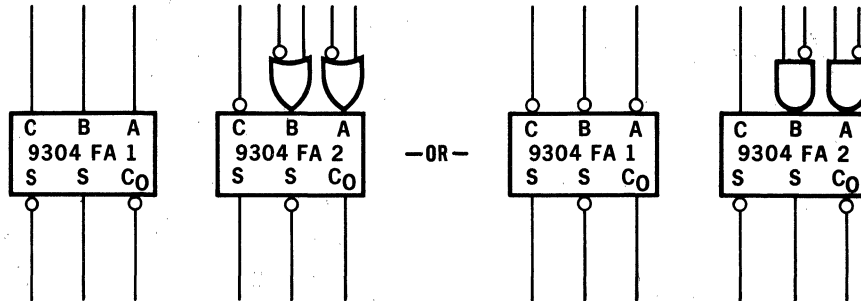
FREQUENCY  $\approx 2.0$  MHz  
PULSE WIDTH  $\approx 250$  ns  
RISE TIME  $< 15$  ns  
FALL TIME  $< 15$  ns  
AMPLITUDE  $\approx 4.0$  V

\*INCLUDES PROBE AND JIG CAPACITANCE



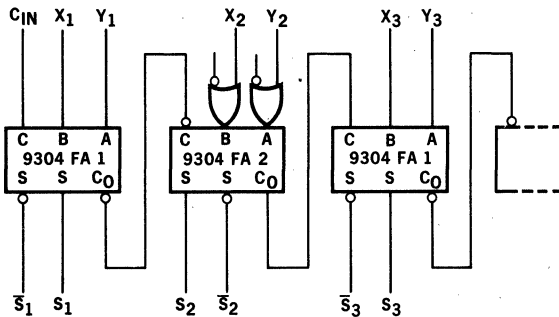
**Fig. 11— SWITCHING TIME TEST CIRCUIT AND WAVEFORMS**

**APPLICATIONS** — The 9304 dual adder has been designed to be useful in a wide variety of applications such as addition, parity generation and checking, code conversion, majority gating and other applications for which this combination of logic gates may be useful. The multifunctional capabilities of the Fairchild dual adder can be seen from reference to the applications shown.



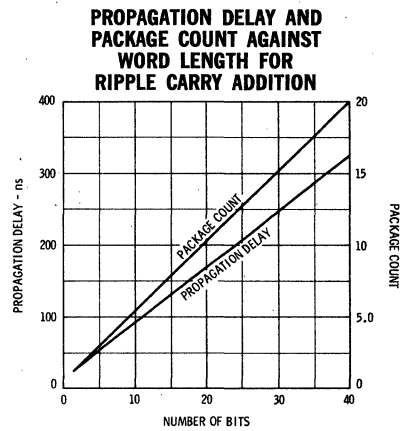
**Fig. 12— FUNCTIONAL BLOCK REPRESENTATION**

The principle of duality allows 2 ways of representing each adder. The circuit is the same in both cases but the logic diagrams differ. The dual diagrams facilitate logic design and allow a greater understanding of the capabilities of the device.



**Fig. 13— RIPPLE CARRY PARALLEL ADDITION**

Shown above is a high speed ripple carry parallel addition scheme. Only one and-or-not gate relay is incurred at each stage allowing a typical addition speed of  $(N+1) \times 8$  ns, where N is the number of bits in the word. A similar scheme will work if the negation inputs are used, and the design acts as a subtractor when the complement of one variable is provided.



**Fig. 14**

The curve shows propagation delay of the ripple Carry Adder drawn in Figure 5. Plotted on the same diagram is a curve showing the low package count resulting from this Ripple Scheme.

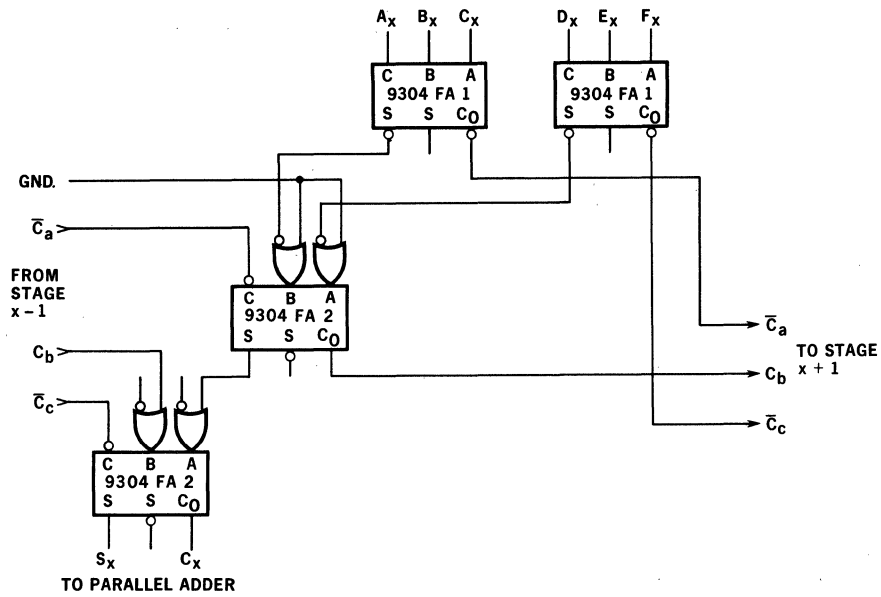


Fig. 15 — ADDITION OF SIX VARIABLES

The above design shows how the 9304 can be used in carry save arithmetic. Six input variable are reduced to two where they can be added in a parallel adder. Delay between inputs and outputs is typically 50 ns, allowing extremely high speed computation. Additional variables may be added or the concept can be extended to multiplication, division, and various other arithmetic operations.

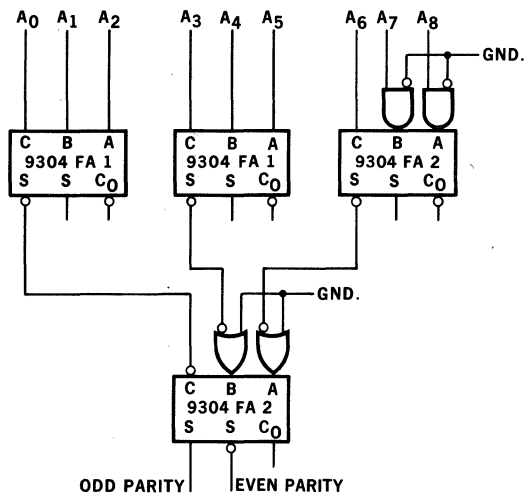


Fig. 16 — BYTE PARITY GENERATION OR CHECKING

The 9304 can be used for parity checking or generating. The above design uses 2 9304's to generate parity for an 8 bit byte or check parity over 9 bits. The delay from input to odd parity is typically 35 ns. Additional adder blocks can be used to generate or check parity over larger word lengths. The concept can also be used for hamming and cyclic code generation and checking.

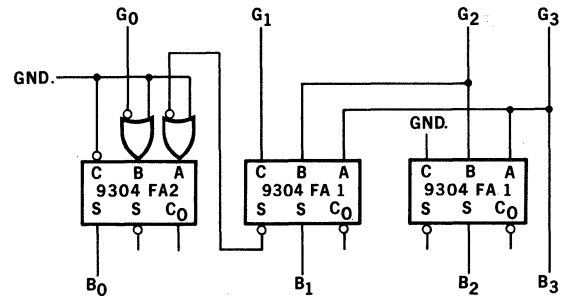


Fig. 17 — 4 BIT PARALLEL GRAY TO BINARY CONVERSION

A 4 bit parallel binary to gray conversion is shown. The adders can also be used for other cyclic code manipulations.

# 9306

## MSI UP/DOWN BCD COUNTER

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The 9306 is a high speed synchronous 8421 BCD up/down decade counter. It is a synchronously presettable, multifunctional MSI building block useful in a large number of counting, digital integration, and conversion applications. Seven decades of synchronous operation are obtainable with no external gating packages required through an internal carry look-ahead counting technique.

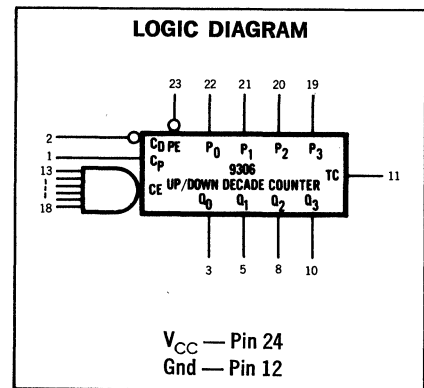
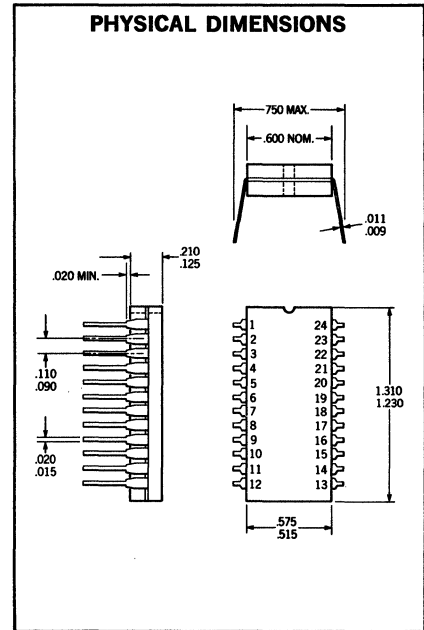
**FEATURES:**

- SYNCHRONOUS COUNTING AND PARALLEL ENTRY
- DECODED TERMINAL COUNT
- BUILT-IN CARRY/BORROW CIRCUITRY
- TYPICAL POWER DISSIPATION OF 350 mW
- THE INPUT/OUTPUT CHARACTERISTICS PROVIDE EASY INTERFACING WITH FAIRCHILD DT $\mu$ L, LPDT $\mu$ L, AND TT $\mu$ L FAMILIES (CCSL).
- ALL CERAMIC HERMETIC 24 PIN DUAL IN-LINE PACKAGE
- INPUT DIODE CLAMPING

**ABSOLUTE MAXIMUM RATINGS** (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5 V to +7 V
Voltage Applied to Outputs for high output state	-0.5 V to V <sub>CC</sub> value
Input Voltage (D.C.)	-0.5 V to +5.5 V

**ORDER INFORMATION** — Specify U6N9306XXX for 24-pin Dual In-Line package where XXX is 51X for the -55°C to +125°C temperature range, or 59X for the 0°C to 75°C temperature range.



# FAIRCHILD MEDIUM SCALE INTEGRATION • 9306

**FUNCTIONAL DESCRIPTION**—A clock buffer and inverter drives the four clocked RS master-slave flip flops in parallel, so that synchronous operation is obtained. When the clock input (CP) is low, the slave is steady, but data can enter the master via the R and the S inputs. During the low to high transition of CP, first the data inputs (R and S) are inhibited, so that a later change in the input data will not affect the master; secondly, the now trapped information in the master is transferred to the slave and is reflected at the outputs. When the transfer is completed both the master and the slave are steady as long as the clock input remains high, and regardless of the logic state at any other input to the device. During the high to low transition of the clock input, first the transfer path from master to slave are inhibited, leaving the slave steady in its present state, secondly, the data inputs (R and S) are enabled so that new data can enter the master. As a result of this synchronous operation higher clock frequency is possible and much less external logic is required in most applications. Mode selection is accomplished as shown in the table below. However, several restrictions are placed on the manner of selection. First, the transition of CE from high to low or of PE from low to high may only be done when CP is high. Second, any change of CD must be done only when CP is high. The remaining transitions may be made by following the setup and release times specified under "Switching Characteristics."

### MODE SELECTION SCHEME

PE	CD	CE	Mode
0	0	0	presetting
0	0	1	presetting
0	1	0	presetting
0	1	1	presetting
1	1	1	count up
1	0	1	count down
1	1	0	no change
1	0	0	no change

Note:  $CE = CE_0 \cdot CE_1 \cdot CE_2 \cdot CE_3 \cdot CE_4 \cdot CE_5$

### LOADING RULES

(1 U.L. = 1 TT $\mu$ L input gate load)

INPUT	FAN IN
CD, CE <sub>0</sub> , CE <sub>1</sub> , CE <sub>2</sub> , CE <sub>3</sub> , CE <sub>4</sub> , CE <sub>5</sub>	1 Unit Load
CP, PE	2 Unit Loads
P <sub>0</sub> , P <sub>1</sub> , P <sub>2</sub> , P <sub>3</sub>	2/3 Unit Load
OUTPUT	FAN OUT
Q <sub>0</sub> , Q <sub>1</sub> , Q <sub>2</sub> , Q <sub>3</sub> , TC	6 Unit Loads

### ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = -55°C to +125°C, V<sub>CC</sub> = 5.0 V ±10%)

SYMBOL	CHARACTERISTICS	LIMITS			UNITS	CONDITIONS & COMMENTS
		-55°C MIN. MAX.	+25°C MIN. TYP. MAX.	+125°C MIN. MAX.		
V <sub>OH</sub>	Output High Voltage	2.4	2.4 2.7	2.4	Volts	V <sub>CC</sub> = 4.5 V, I <sub>OH</sub> = -0.36 mA
V <sub>OL</sub>	Output Low Voltage	0.4	0.2 0.4	0.4	Volts	V <sub>CC</sub> = 5.5 V, I <sub>OL</sub> = 9.6 mA V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 7.44 mA
V <sub>IH</sub>	Input High Voltage	2.0	1.7	1.4	Volts	Guaranteed input high threshold for all inputs
V <sub>IL</sub>	Input Low Voltage	0.8	0.9	0.8	Volts	Guaranteed input low threshold for all inputs
I <sub>F</sub>	Input Load Current E <sub>0</sub> , E <sub>1</sub> , E <sub>2</sub> , E <sub>3</sub> , E <sub>4</sub> , E <sub>5</sub> , CD	-1.6	-1.0 -1.6	-1.6	mA	V <sub>CC</sub> = 5.5 V V <sub>F</sub> = 0.4 V
2 I <sub>F</sub>	Input Load Current CP, PE	-3.2	-2.0 -3.2	-3.2	mA	
2/3 I <sub>F</sub>	Input Load Current P <sub>0</sub> , P <sub>1</sub> , P <sub>2</sub> , P <sub>3</sub>	-1.07	-0.7 -1.07	-1.07	mA	
I <sub>R</sub>	Input Leakage Current E <sub>0</sub> , E <sub>1</sub> , E <sub>2</sub> , E <sub>3</sub> , E <sub>4</sub> , E <sub>5</sub> , CD	60	10 60	60	μA	V <sub>CC</sub> = 5.5 V V <sub>R</sub> = 4.5 V
2 I <sub>R</sub>	Input Leakage Current CP, PE	120	20 120	120	μA	
2/3 I <sub>R</sub>	Input Leakage Current P <sub>0</sub> , P <sub>1</sub> , P <sub>2</sub> , P <sub>3</sub>	40	7 40	40	μA	

# FAIRCHILD MEDIUM SCALE INTEGRATION • 9306

## ELECTRICAL CHARACTERISTICS ( $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$ , $V_{CC} = 5.0\text{ V} \pm 5\%$ )

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS & COMMENTS	
		0°C		+25°C			+75°C			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	3.0		2.4		Volts	$V_{CC} = 4.75\text{ V}$ , $I_{OH} = -0.36\text{ mA}$
$V_{OL}$	Output Low Voltage		0.45		0.2	0.45		0.45	Volts	$V_{CC} = 5.25\text{ V}$ , $I_{OL} = 9.6\text{ mA}$
$V_{IH}$	Input High Voltage	1.9		1.8			1.6		Volts	$V_{CC} = 4.75\text{ V}$ , $I_{OL} = 8.5\text{ mA}$ Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.85		0.85		0.85		Volts	Guaranteed input low threshold for all inputs
$I_F$	Input Load Current $E_0, E_1, E_2, E_3, E_4, E_5, CD$		-1.6		-1.0	-1.6		-1.6	mA	$V_{CC} = 5.25\text{ V}$ $V_F = 0.4\text{ V}$
$2 I_F$	Input Load Current CP, PE		-3.2		-2.0	-3.2		-3.2	mA	
$\frac{2}{3} I_F$	Input Load Current $P_0, P_1, P_2, P_3$		-1.07		-0.7	-1.07		-1.07	mA	
$I_R$	Input Leakage Current $E_0, E_1, E_2, E_3, E_4, E_5, CD$		60		10	60		60	$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ $V_R = 4.5\text{ V}$
$2 I_R$	Input Leakage Current CP, PE		120		20	120		120	$\mu\text{A}$	
$\frac{2}{3} I_R$	Input Leakage Current $P_0, P_1, P_2, P_3$		40		7	40		40	$\mu\text{A}$	

## SWITCHING CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ )

SYMBOL	CHARACTERISTICS	MIN.	TYP.	MAX.	UNITS	CONDITIONS & COMMENTS
$t_{pd+}$ (Q)	Turn-Off Delay		20		ns	$V_{CC} = 5.0\text{ V}$ $C_L = 15\text{ pF}$ (Fig. 1)
$t_{pd-}$ (Q)	Turn-On Delay		20		ns	
$t_{pd+}$ (TC)	Turn-Off Delay for TC		40		ns	
$t_{pd-}$ (TC)	Turn-On Delay for TC		30		ns	
$t_s$ (CE)	Set-Up Time for CE		25		ns	$V_{CC} = 5.0\text{ V}$ $C_L = 15\text{ pF}$ (Fig. 2)
$t_r$ (CE)	Release Time for CE		25		ns	
$t_s$	Set-Up Time for Data		15		ns	$V_{CC} = 5.0\text{ V}$ $C_L = 15\text{ pF}$ (Fig. 3)
$t_r$	Release Time for Data		15		ns	
$t_s$ (PE)	Set-Up Time for PE		20		ns	
$t_r$ (PE)	Release Time for PE		20		ns	

SET-UP TIME:  $t_s$  is defined as the minimum time required for the logic level to be present at the logic input prior to the clock transition from low to high in order for the flip-flop(s) to respond.

RELEASE TIME:  $t_r$  is defined as the maximum time allowed for the logic level to be present at the logic input prior to the clock transition from low to high in order for the flip-flop(s) not to respond.

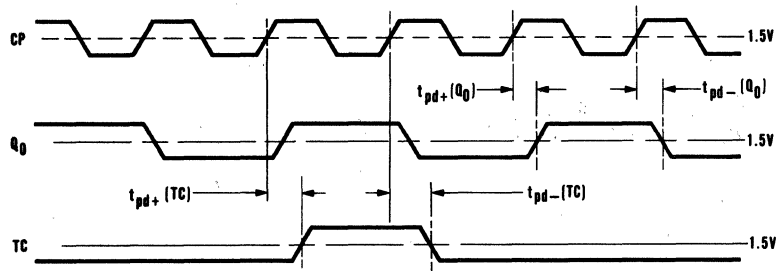


Fig. 1

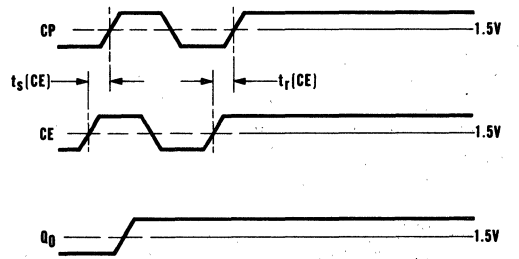


Fig. 2

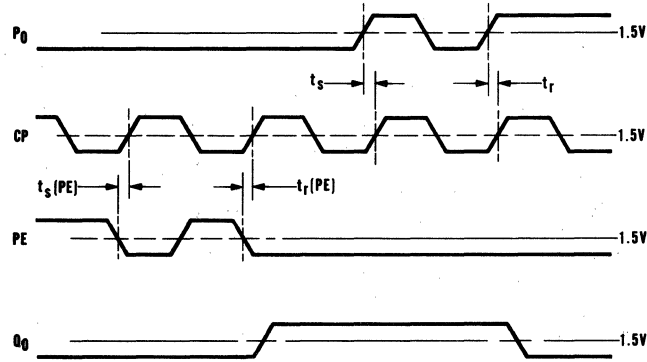


Fig. 3

APPLICATIONS

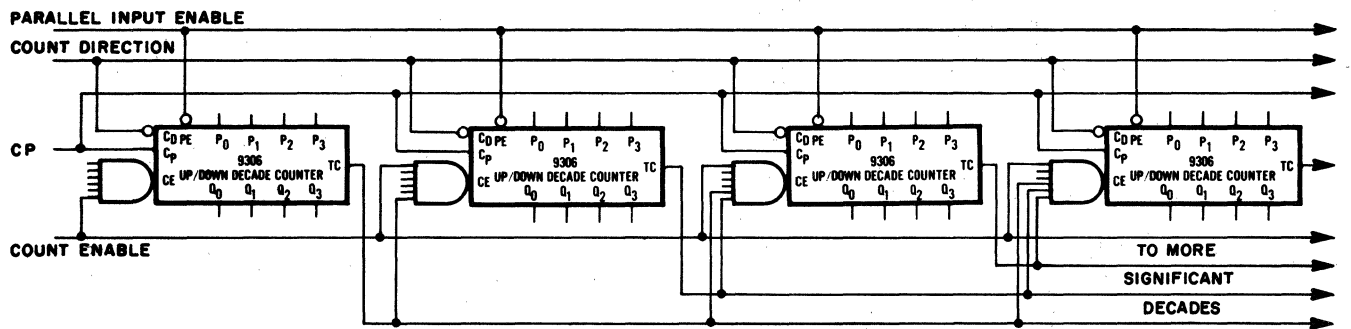


Fig. 4





# FAIRCHILD MEDIUM SCALE INTEGRATION • 9307

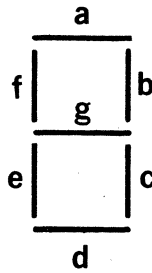
The 9307 seven segment decoder accepts a 4 Bit BCD 8421 code input and produces the appropriate outputs for selection of segments in a seven segment matrix display used for representing the decimal numbers 0 - 9. The seven outputs (a, b, c, d, e, f, g) of the decoder select the corresponding segments in the matrix shown in Figure 3. The numeric designations chosen to represent the decimal numbers are shown in Figure 5, together with the resulting displays for input code configurations in excess of binary nine.

The decoder has active high outputs so that a buffer transistor may be used directly to provide the high currents required for incandescent displays. If additional base drive current is required external resistors may be added from the supply voltage to the seven segment outputs of the decoders. The value of this resistor is constrained by the 10 mA current sinking capability of the output transistors of the circuit.

The device has provision for automatic blanking of the leading and/or trailing edge zeroes in a multidigit decimal number, resulting in an easily readable decimal display, conforming to normal writing practice. In an eight digit mixed integer fraction decimal representation, using the automatic blanking capability, (0060.0300) would be displayed as (60.03). Leading edge zero suppression is obtained by connecting the Ripple Blanking Output (RBO) of a decoder to the Ripple Blanking Input (RBI) of the next lower stage device. The most significant decoder stage should have the RBI input grounded; and, since suppression of the least significant integer zero in a number is not usually desired, the RBI input of this decoder stage should be left open. A similar procedure for the fractional part of a display will provide automatic suppression of trailing edge zeroes.

The decoder has an active low input Lamp Test which overrides all other input combinations and enables a check to be made on possible display malfunctions. The RBO terminal of the decoder can be OR - tied with a modulating signal via an isolating buffer to achieve pulse duration intensity modulation. A suitable signal can be generated for this purpose by forming a variable frequency multivibrator with a cross coupled pair of DT $\mu$ L gates.

**Fig. 3**  
**SEGMENT DESIGNATION**

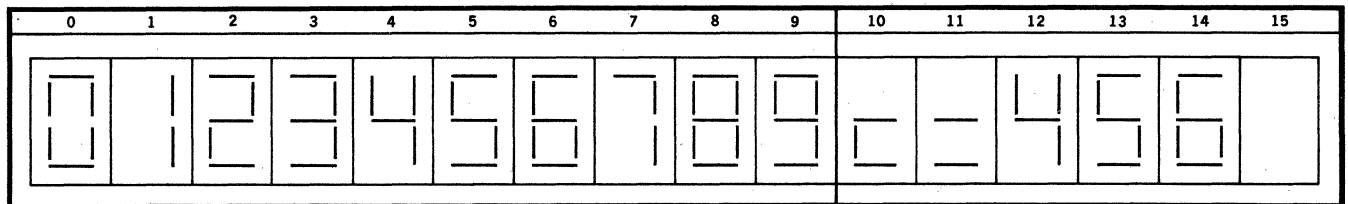


**Fig. 4**  
**TRUTH TABLE**

RB	LT	IN	A <sub>0</sub>	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	a	b	c	d	e	f	g	RB	OUT
L	X	X	X	X	X	X	H	H	H	H	H	H	H	H	H
H	L	L	L	L	L	L	L	L	L	L	L	L	L	L	0
H	H	L	L	L	L	L	H	H	H	H	H	H	L	H	0
H	X	H	L	L	L	L	L	H	H	L	L	L	L	H	1
H	X	H	L	H	L	L	H	H	L	H	L	L	H	H	2
H	X	H	H	L	L	L	H	H	H	H	L	L	H	H	3
H	X	H	L	L	H	L	L	H	H	L	L	H	H	H	4
H	X	H	L	H	H	L	H	L	H	L	H	L	H	H	5
H	X	H	L	H	H	L	H	L	H	H	H	H	H	H	6
H	X	H	H	H	L	L	H	H	H	L	L	L	L	H	7
H	X	H	L	L	L	H	H	H	H	H	H	H	H	H	8
H	X	H	L	L	L	H	H	H	H	L	L	L	L	H	9
H	X	H	L	H	L	H	L	L	L	H	L	L	L	H	10
H	X	H	H	L	H	L	L	L	L	H	L	L	L	H	11
H	X	H	L	L	H	H	L	H	H	L	L	L	L	H	12
H	X	H	L	H	H	H	L	H	H	L	L	L	L	H	13
H	X	H	L	H	H	H	L	L	L	H	L	L	L	H	14
H	X	H	H	H	H	H	L	L	L	L	L	L	L	H	15

H = HIGH VOLTAGE LEVEL  
L = LOW VOLTAGE LEVEL  
X = EITHER HIGH OR LOW VOLTAGE LEVEL

**Fig. 5**  
**NUMERICAL DESIGNATIONS**



**Table 1—Loading Rules (1 U.L. = 1 DT $\mu$ L Gate Input Load)**

Inputs	Loading (51X & 59X)	
	High State	Low State
A <sub>0</sub> , A <sub>1</sub> , A <sub>2</sub> , A <sub>3</sub>	1	1
R <sub>B(IN)</sub>	1	1/2
LT	5	4.3

Outputs	Fan Out	
	51X	59X
a, b, c, d, e, f, g	8	7
R <sub>B(OUT)</sub>	2.0	1.5

## FAIRCHILD MEDIUM SCALE INTEGRATION • 9307

**TABLE II —**  
**ELECTRICAL CHARACTERISTICS** ( $T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 10\%$ ) (Part #U6B930751X)

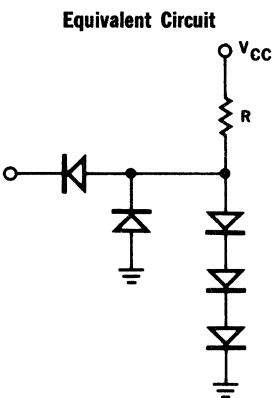
SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$-55^\circ\text{C}$		$+25^\circ\text{C}$			$+125^\circ\text{C}$			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	4.3 3.0		4.3 3.0	4.4 4.0		4.4 3.0		Volts	$V_{CC} = 4.5\text{ V}$ $I_{OH} = 0.0\text{ mA}$ (Pins 9-15) $V_{CC} = 4.5\text{ V}$ $I_{OH} = -70\ \mu\text{A}$ (Pin 4) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ )
$V_{OL}$	Output Low Voltage		0.4		0.21 0.4			0.4	Volts	$V_{CC} = 5.5\text{ V}$ $I_{OL} = 12.5\text{ mA}$ (Pins 9-15) $I_{OL} = 3.1\text{ mA}$ (Pin 4) $V_{CC} = 4.5\text{ V}$ $I_{OL} = 10\text{ mA}$ (Pins 9-15) $I_{OL} = 2.4\text{ mA}$ (Pin 4) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ )
$V_{IH}$	Input High Voltage	2.1		1.9			1.7		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage	1.4			1.1		0.8		Volts	Guaranteed input low threshold for all inputs
$I_F$ (Pin 3) $I_F$ (Pins 1, 2, 6, 7) $I_F$ (Pin 5)	Input Load Current Input Load Current Input Load Current	-6.4 -1.5 -0.75			-6.4 -1.5 -0.75		-6.4 -1.5 -0.75		mA	$V_{CC} = 5.5\text{ V}$ $V_F = 0.4\text{ V}$ $V_R = 5.5\text{ V}$ on other inputs
$I_R$ (Pin 3) $I_R$ (Pins 1, 2, 5, 6, 7)	Input Leakage Current Input Leakage Current				10 2.0		25 5.0		$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ $V_R = 4.5\text{ V}$ Ground on other inputs
$I_A$ (Pins 9-15)	Available Output Current	-1.4		-1.4			-1.0		mA	$V_{OUT} = 0.85\text{ V}$ $V_{CC} = 4.5\text{ V}$ Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ )
$I_{SC}$ (Pins 9-15)	Short Circuit Current					-3.7			mA	$V_{OUT} = 0.0\text{ V}$ $V_{CC} = 5.5\text{ V}$
$t_{pd+}$	Switching Speed					500			ns	$V_{CC} = 5.0\text{ V}$ , See Figure 6
$t_{pd-}$	Switching Speed					500			ns	

**TABLE III —**  
**ELECTRICAL CHARACTERISTICS** ( $T_A = 0^\circ\text{C}$  to  $+75^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 5\%$ ) (Part #U6B930759X)

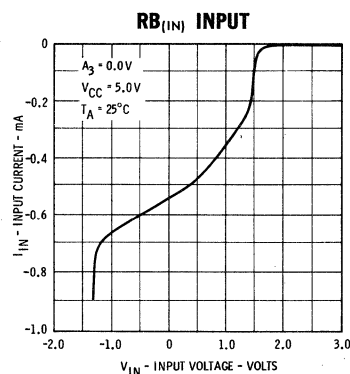
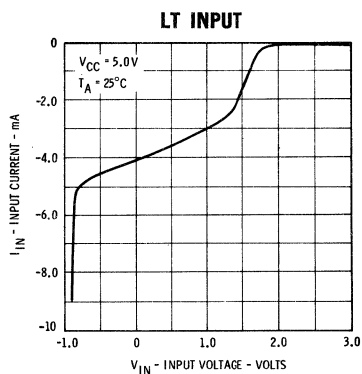
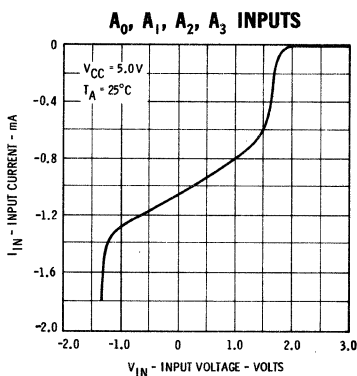
SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$0^\circ\text{C}$		$+25^\circ\text{C}$			$+75^\circ\text{C}$			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	4.3 2.7		4.3 2.7	4.6 4.0		4.3 2.7		Volts	$V_{CC} = 4.75\text{ V}$ $I_{OH} = 0.0\text{ mA}$ (Pins 9-15) $V_{CC} = 4.75\text{ V}$ $I_{OH} = -70\ \mu\text{A}$ (Pin 4) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ )
$V_{OL}$	Output Low Voltage		0.45		0.21 0.45			0.45	Volts	$V_{CC} = 5.25\text{ V}$ $I_{OL} = 11.5\text{ mA}$ (Pins 9-15) $I_{OL} = 2.75\text{ mA}$ (Pin 4) $V_{CC} = 4.75\text{ V}$ $I_{OL} = 10\text{ mA}$ (Pins 9-15) $I_{OL} = 2.4\text{ mA}$ (Pin 4) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ )
$V_{IH}$	Input High Voltage	2.0		2.0			2.0		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage	0.85			0.85		0.85		Volts	Guaranteed input low threshold for all inputs
$I_F$ (Pin 3) $I_F$ (Pins 1, 2, 6, 7) $I_F$ (Pin 5)	Input Load Current Input Load Current Input Load Current	-6.4 -1.5 -0.75			-6.4 -1.5 -0.75		-6.4 -1.5 -0.75		mA	$V_{CC} = 5.25\text{ V}$ $V_F = 0.45\text{ V}$ $V_R = 5.25$ on other inputs
$I_R$ (Pin 3) $I_R$ (Pins 1, 2, 5, 6, 7)	Input Leakage Current Input Leakage Current				25 5.0		50 10		$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ $V_R = 4.5\text{ V}$ Ground on other inputs
$I_A$ (Pins 9-15)	Available Output Current	-1.4		-1.4			-1.0		mA	$V_{OUT} = 0.75\text{ V}$ $V_{CC} = 4.75\text{ V}$ Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ )
$I_{SC}$ (Pins 9-15)	Short Circuit Current					-4.0			mA	$V_{OUT} = 0.0\text{ V}$ $V_{CC} = 5.5\text{ V}$
$t_{pd+}$	Switching Speed					500			ns	$V_{CC} = 5.0\text{ V}$ , See Figure 6
$t_{pd-}$	Switching Speed					500			ns	

TYPICAL INPUT AND OUTPUT CHARACTERISTICS

INPUTS

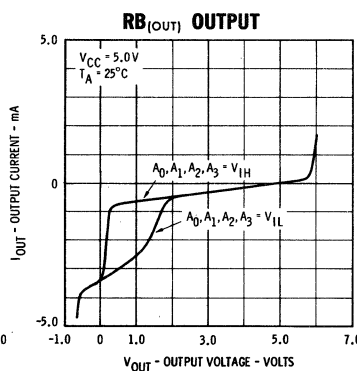
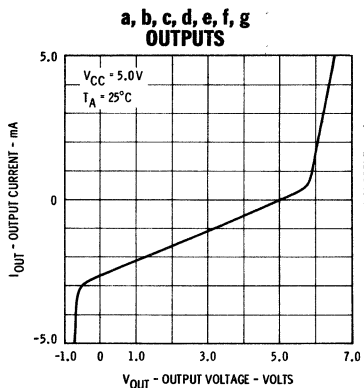


INPUT CURRENT VERSUS INPUT VOLTAGE

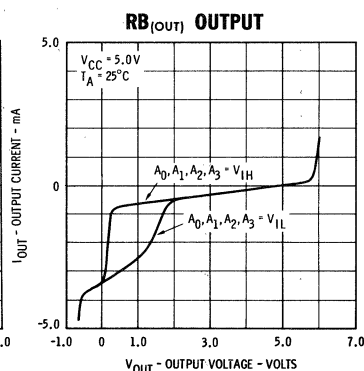
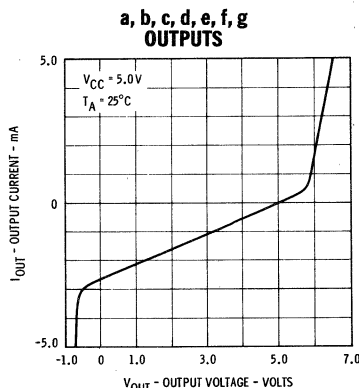


OUTPUT CURRENT VERSUS OUTPUT VOLTAGE

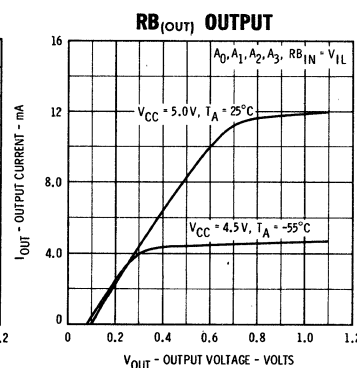
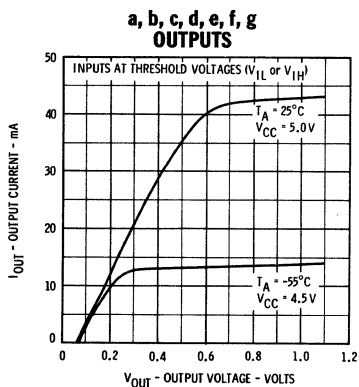
U6B930751X (-55°C to +125°C)  
OUTPUT IN HIGH STATE



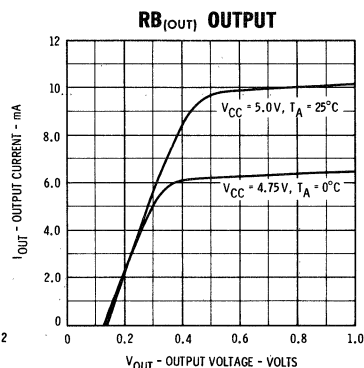
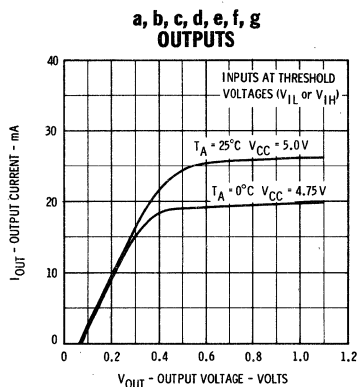
U6B930759X (0°C to +75°C)  
OUTPUT IN HIGH STATE



OUTPUT IN LOW STATE



OUTPUT IN LOW STATE



OUTPUTS

Equivalent Circuit

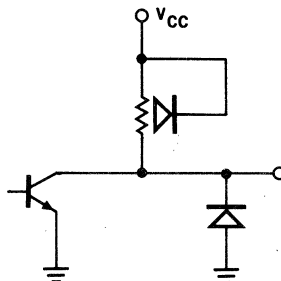
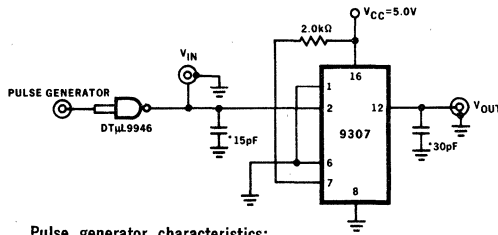
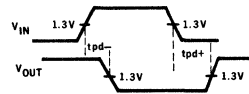


Fig. 6—SWITCHING CIRCUIT AND WAVEFORMS



Pulse generator characteristics:  
 Amplitude = 3.0 V  
 Freq. = 500 kHz  
 Pulse width = 1000 ns  
 $t_r = t_f \leq 15$  ns  
 \*Includes probe and jig capacitance



APPLICATIONS

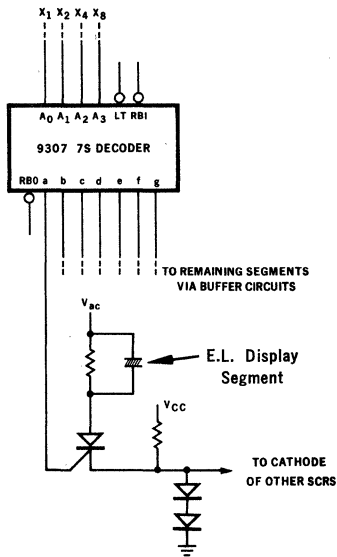


Fig. 7

9307 Seven Segment Decoder driving Electro-Luminescent Display.

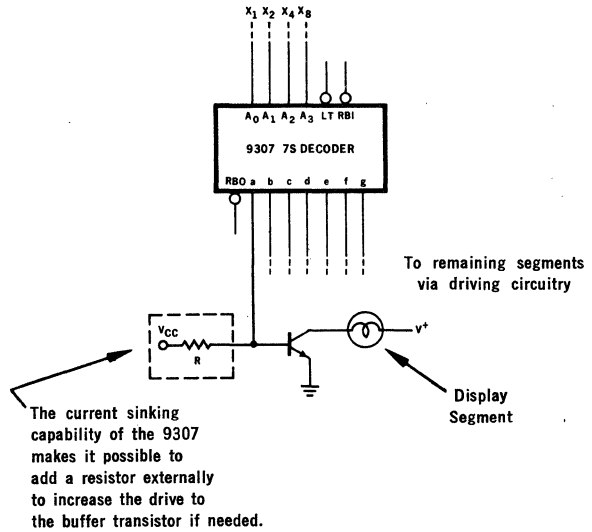


Fig. 8

9307 Seven Segment Decoder driving Incandescent lamp Display.

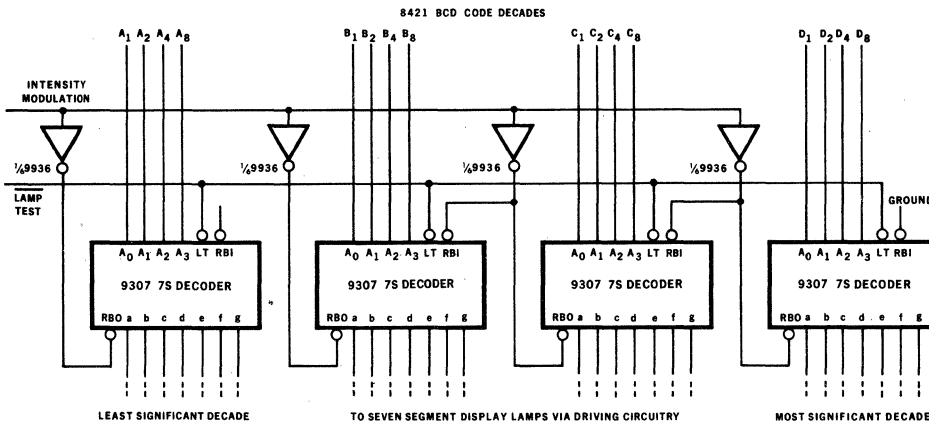


Fig. 9—FOUR DECADE SEVEN SEGMENT INTEGER DISPLAY SCHEME

This scheme incorporates automatic blanking of leading edge zeroes and intensity modulation using an external variable duty cycle signal.

## MSI DUAL FOUR-BIT LATCH

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The MSI 9308 is a Dual 4-Bit Latch designed for general purpose storage applications in high speed digital systems. The 9308 uses  $TT\mu L$  technology and is CCSL compatible. All inputs incorporate diode clamps to ground to reduce negative line transients. All outputs have active pull-up circuitry to provide high capacitive drive and low impedance outputs in both logic states to provide good A.C. noise immunity.

### FEATURES

- ACTIVE LEVEL LOW ENABLE GATE INPUTS
- OVERRIDING MASTER RESET
- 25 ns THROUGH DELAY
- THE INPUT/OUTPUT CHARACTERISTICS PROVIDE DIRECT INTERFACING WITH FAIRCHILD  $DT\mu L$ ,  $LPDT\mu L$ ,  $TT\mu L$ , AND MSI FAMILIES (CCSL).
- INPUT CLAMP DIODES LIMIT HIGH SPEED TERMINATION EFFECTS.

### ABSOLUTE MAXIMUM RATINGS (above which the useful life may be impaired)

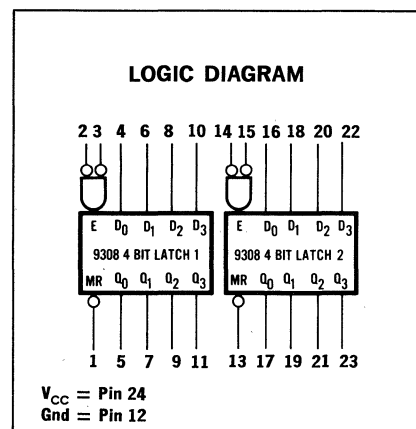
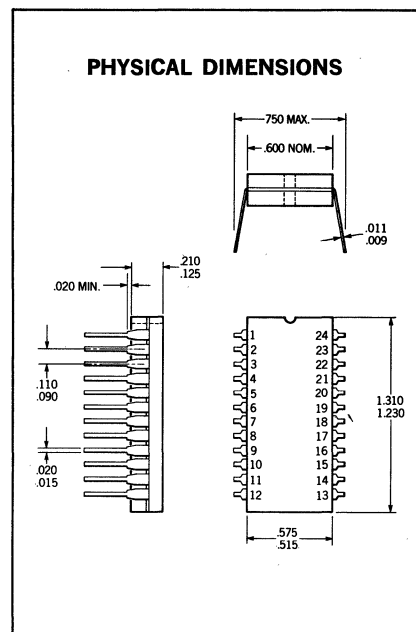
Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
$V_{CC}$ Pin Potential to Ground Pin	-0.5 V to +7 V
Input Voltage (D.C.) (See Note 1)	-0.5 V to +5.5 V
Input Current (D.C.) (See Note 1)	-30 mA to +5 mA
Voltage Applied to Outputs (Output High)	-0.5 V to + $V_{CC}$ value
Output Current (D.C.) (Output Low)	+30 mA

NOTE 1: Either Input Voltage limit or Input Current limit is sufficient to protect the inputs.

**DESCRIPTION OF LATCH OPERATION** — Data can be entered into the latch when both of the enable inputs are low. As long as this logic condition exists, the output of the latch will follow the input. If either of the enable inputs goes high, the data present in the latch at that time is held in the latch and is no longer affected by the data input.

The master reset overrides all other input conditions and forces the outputs of all the latches low when a low signal is applied to the master reset input.

**ORDER INFORMATION** — Specify U6N9308XXX for 24-pin Dual In-Line package where XXX is 51X for the -55°C to +125°C temperature range, or 59X for the 0°C to +75°C temperature range.



Electrical Characteristics on Page 2.

# FAIRCHILD MEDIUM SCALE INTEGRATION • 9308

**TABLE I —**  
**ELECTRICAL CHARACTERISTICS** ( $T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 10\%$ , See Note 1) (Part #U6N930851X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$-55^\circ\text{C}$		$+25^\circ\text{C}$			$+125^\circ\text{C}$			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	2.8		2.4		Volts	$V_{CC} = 4.5\text{ V}$ , $I_{OH} = -0.6\text{ mA}$ Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) (See Note 2)
$V_{OL}$	Output Low Voltage		0.4		0.21	0.4		0.4	Volts	$V_{CC} = 5.5\text{ V}$ , $I_{OL} = 14.4\text{ mA}$ $V_{CC} = 4.5\text{ V}$ , $I_{OL} = 11.2\text{ mA}$ Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) (See Note 2)
$V_{IH}$	Input High Voltage	2.0		1.7			1.4		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.8			0.9		0.8	Volts	Guaranteed input low threshold for all inputs
$I_F$	Input Load Current $E_0$ , $E_1$ and MR Inputs		-1.6		-1.1	-1.6		-1.6	mA	$V_{CC} = 5.5\text{ V}$ $V_F = 0.4\text{ V}$ $V_F = 0.0\text{ V}$ (See Note 3)
$1.5 I_F$	Input Load Current D Inputs		-2.7		-1.9	-2.7		-2.7		
$I_R$	Input Leakage Current $E_0$ , $E_1$ and MR Inputs				10	60		60	$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ , $V_R = 4.5\text{ V}$
$1.5 I_R$	Input Leakage Current D Inputs				15	90		90		
$I_{PD}$	Power Supply Current		90		65	90		90	mA	$V_{CC} = 5.0\text{ V}$ all outputs low inputs disabled

**TABLE II —**  
**ELECTRICAL CHARACTERISTICS** ( $T_A = 0^\circ\text{C}$  to  $+75^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 5\%$ , See Note 1) (Part #U6N930859X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$0^\circ\text{C}$		$+25^\circ\text{C}$			$+75^\circ\text{C}$			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	3.1		2.4		Volts	$V_{CC} = 4.75\text{ V}$ , $I_{OUT} = -0.6\text{ mA}$ Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) (See Note 2)
$V_{OL}$	Output Low Voltage		0.45		0.21	0.45		0.45	Volts	$V_{CC} = 5.25\text{ V}$ , $I_{OUT} = 14.4\text{ mA}$ $V_{CC} = 4.75\text{ V}$ , $I_{OUT} = 12.7\text{ mA}$ Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) (See Note 2)
$V_{IH}$	Input High Voltage	1.9		1.8			1.6		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.85			0.85		0.85	Volts	Guaranteed input low threshold for all inputs
$I_F$	Input Load Current $E_0$ , $E_1$ and MR Inputs		-1.6		-1.0	-1.6		-1.6	mA	$V_{CC} = 5.25\text{ V}$ $V_F = 0.45\text{ V}$ $V_F = 0.0\text{ V}$ (See Note 3)
$1.5 I_F$	Input Load Current D Inputs		-2.7		-1.8	-2.6		-2.7		
$I_R$	Input Leakage Current $E_0$ , $E_1$ and MR Inputs				10	60		60	$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ , $V_R = 4.5\text{ V}$
$1.5 I_R$	Input Leakage Current D Inputs				15	90		90		
$I_{PD}$	Power Supply Current		117		65	117		117	mA	$V_{CC} = 5.0\text{ V}$ all outputs low inputs disabled

NOTE 1: Units are pulse tested.

NOTE 2: Output Voltages are guaranteed for either the input enabled or input disabled case.

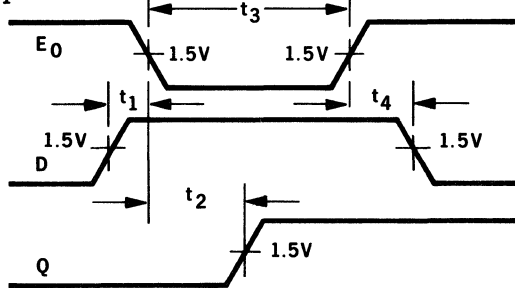
NOTE 3: This current is measured at  $V_{IN} = 0.0\text{ V}$  to insure that no current is being absorbed by the device internally. The maximum value given guarantees that the maximum instantaneous current that can flow out of the input at  $V_{IN} = 0.4\text{ V}$  is  $2.4\text{ mA}$ .

A.C. CHARACTERISTICS

9308 SWITCHING WAVEFORMS

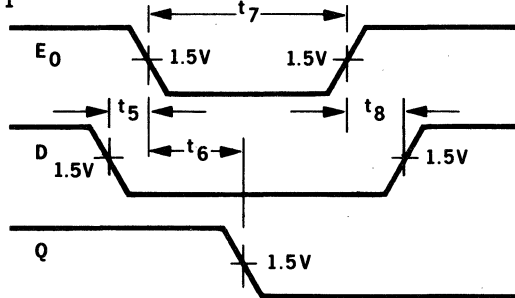
STORING A ONE

$E_1 = \text{GND}$



STORING A ZERO

$E_1 = \text{GND}$



TIME	DEFINITION	LIMIT (See Note 4)			
		MIN.	TYP.	MAX.	UNITS
$t_1$	Min. time that data must be present before enable to not increase $t_2$	X	minus 4	—	ns
$t_2$	Delay from enable to output turning off	—	22	X	ns
$t_3$	Min. enable pulse width to store a ONE	X	15	—	ns
$t_4$	Min. time that data must remain constant after removal of enable	X	5	—	ns
$t_5$	Min. time that data must be present before the enable to not increase $t_6$	X	0	—	ns
$t_6$	Delay from enable to output turning on	—	15	X	ns
$t_7$	Min. enable pulse width to store a ZERO	X	15	—	ns
$t_8$	Min. time that data must remain constant after removal of enable	X	2	—	ns

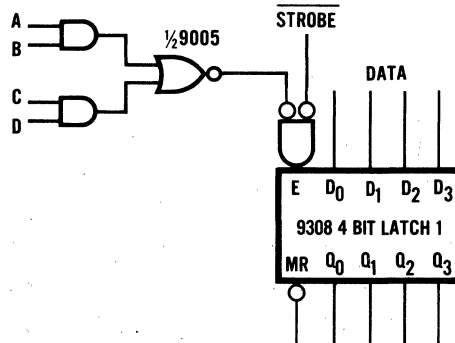
NOTE 4: Limits indicated by X will be shown on final data sheets.

All delays are measured with  $V_{CC} = 5.0 \text{ V}$  applied to Pin 24 and Pin 12 grounded. The active input is driven by a 9002 TT $\mu$ L gate with the output loaded with 15 pF. All outputs are loaded with 15 pF.

LOADING RULES

	PIN	LOADING
INPUTS	$D_0, D_1, D_2, D_3$	1.5
	$MR, E_0, E_1$	1.0
OUTPUTS	$Q_0, Q_1, Q_2, Q_3$	9.0

APPLICATIONS

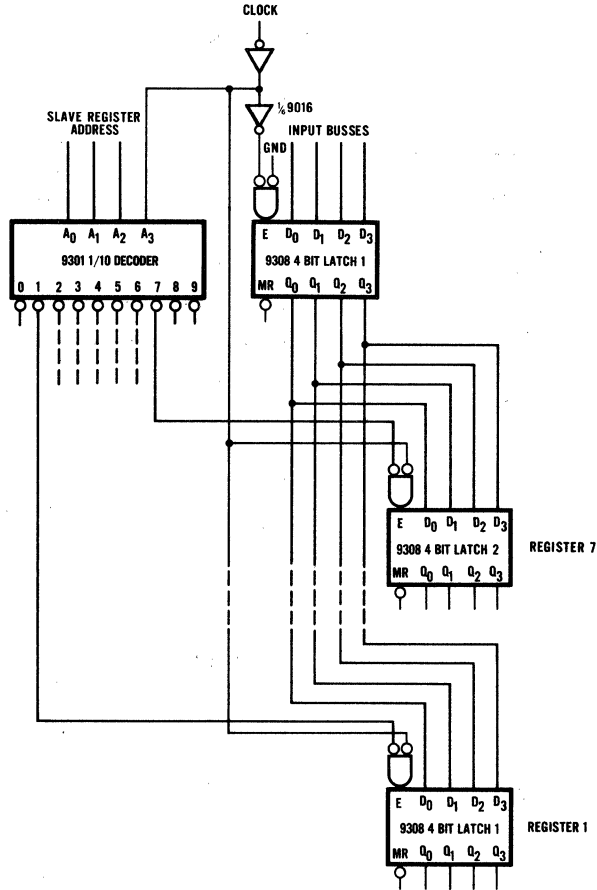


AND-OR ENABLE SHOWING ACTIVE LEVEL  
LOW ENABLE GATE UTILITY

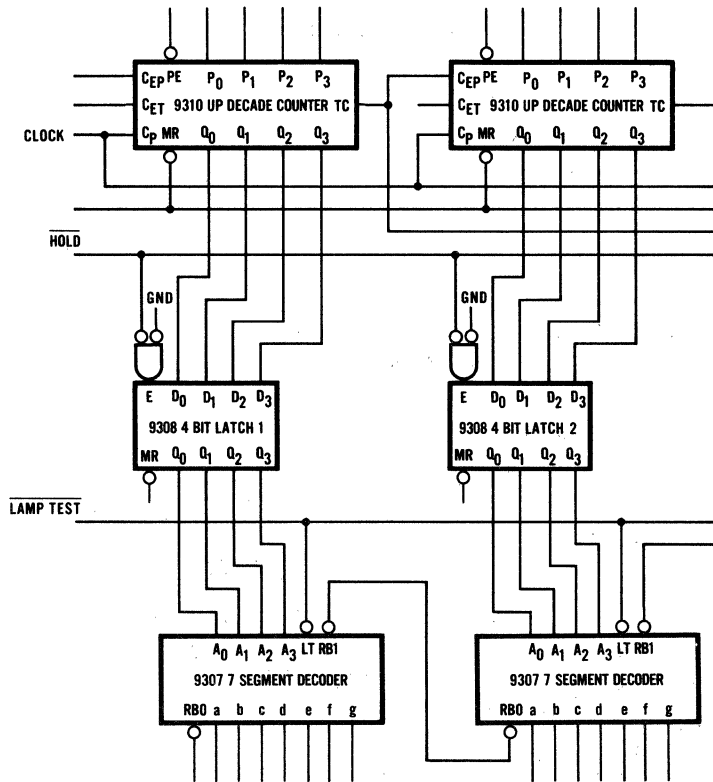


# FAIRCHILD MEDIUM SCALE INTEGRATION • 9308

## SINGLE MASTER/MULTIPLE SLAVE FLIP-FLOP



## 9308 AS A HOLDING REGISTER IN COUNTING AND DISPLAY APPLICATIONS



# 9309

## MSI DUAL FOUR-INPUT MULTIPLEXER

### A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The 9309 is a monolithic, high speed, dual four-input digital multiplexer circuit, constructed with the Fairchild Planar\* epitaxial process. It consists of two multiplexing circuits with common input select logic, each circuit contains four inputs and fully buffered complementary outputs. In addition to operating as a multiplexer, the 9309 can generate any two function of three variables. Active pullups in the outputs ensure high drive and high speed performance. Because of its high speed performance and on-chip select decoding, the 9309 may be cascaded to multiple levels so that any number of lines can be multiplexed onto a single output buss. The circuit uses  $TT\mu L$  for high speed, high fanout operation and is compatible with all other members of the CCSL family of digital integrated circuits.

#### FEATURES

- MULTIFUNCTION CAPABILITY
- 25 ns THROUGH DELAY
- ON-CHIP SELECT LOGIC DECODING
- FULLY BUFFERED COMPLEMENTARY OUTPUTS
- THE INPUT/OUTPUT CHARACTERISTICS PROVIDE EASY INTERFACING WITH FAIRCHILD  $DT\mu L$ ,  $LPDT\mu L$ ,  $TT\mu L$ , AND MSI FAMILIES (CCSL).
- INPUT CLAMP DIODES LIMIT HIGH SPEED TERMINATION EFFECTS.

#### ABSOLUTE MAXIMUM RATINGS (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
$V_{CC}$ Pin Potential to Ground Pin	-0.5 V to +7 V
Voltage Applied to Output when output is high	0 V to + $V_{CC}$ value
Input Voltage (DC) (See Note 1)	-0.5 V to +5.5 V
Input Current (DC) (See Note 1)	-30 mA to +5 mA
Current into Output when output is low	+30 mA

Note 1—either Input Voltage limit or Input Current limit is sufficient to protect the inputs.

**ORDER INFORMATION** — Specify U6B9309XXX for 16-pin Dual In-Line package or U3L9309XXX for 16-pin Flatpak, where XXX is 51X for the -55°C to +125°C temperature range, or 59X for the 0°C to +75°C temperature range.

#### LOGIC DIAGRAM

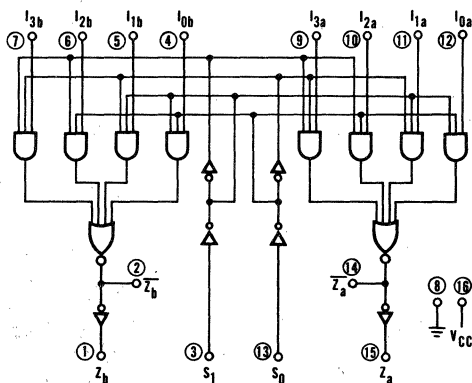
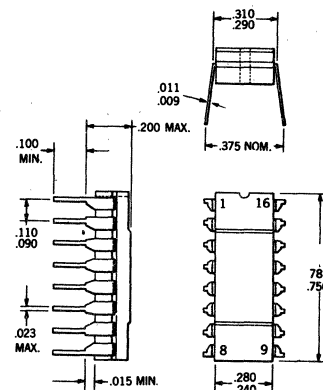


Fig. 4

9309  
Dual four input multiplexer  
Logic diagram

#### DUAL IN-LINE PACKAGE



#### NOTES:

1. Leads are intended for insertion in hole rows on .300" centers. They are purposely shipped with ".375" misalignment to facilitate insertion.

Fig. 1

#### FLAT PACKAGE

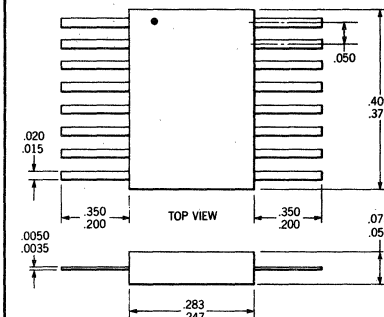
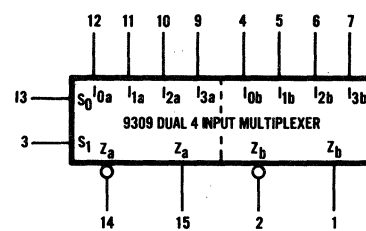


Fig. 2

#### LOGIC SYMBOL



$V_{CC}$  = PIN 16  
GND = PIN 8

Fig. 3

\*Planar is a patented Fairchild process.

# FAIRCHILD MEDIUM SCALE INTEGRATION 9309

## FUNCTIONAL DESCRIPTION

The 9309 dual four input multiplexer is a member of the Fairchild family of compatible Medium Scale Integrated (MSI) digital building blocks. It provides this family with the ability to select two bits of either data or control from up to four sources, in one package.

The 9309 dual four input multiplexer is the logical implementation of a two-pole four-position switch, with the position of the switch being set by the logic levels supplied to the two select inputs. Both assertion and negation outputs are provided for both multiplexers. The logic equations for the outputs are shown below:

$$Z_a = I_{0a} \cdot S_1 \cdot S_0 + I_{1a} \cdot S_1 \cdot S_0 + I_{2a} \cdot S_1 \cdot S_0 + I_{3a} \cdot S_1 \cdot S_0$$

$$Z_b = I_{0b} \cdot S_1 \cdot S_0 + I_{1b} \cdot S_1 \cdot S_0 + I_{2b} \cdot S_1 \cdot S_0 + I_{3b} \cdot S_1 \cdot S_0$$

A common use of the 9309 would be the moving of data from a group of registers to a common output buss. The particular register from which the data came would be determined by the state of the select inputs.

### TRUTH TABLE

SELECT INPUTS		INPUTS				OUTPUTS	
S <sub>0</sub>	S <sub>1</sub>	I <sub>0a</sub>	I <sub>1a</sub>	I <sub>2a</sub>	I <sub>3a</sub>	Z <sub>a</sub>	Z <sub>a</sub>
L	L	L	X	X	X	L	H
L	L	H	X	X	X	H	L
H	L	X	L	X	X	L	H
H	L	X	H	X	X	H	L
L	H	X	X	L	X	L	H
L	H	X	X	H	X	H	L
H	H	X	X	X	L	L	H
H	H	X	X	X	H	H	L

S <sub>0</sub>	S <sub>1</sub>	I <sub>0b</sub>	I <sub>1b</sub>	I <sub>2b</sub>	I <sub>3b</sub>	Z <sub>b</sub>	Z <sub>b</sub>
L	L	L	X	X	X	L	H
L	L	H	X	X	X	H	L
H	L	X	L	X	X	L	H
H	L	X	H	X	X	H	L
L	H	X	X	L	X	L	H
L	H	X	X	H	X	H	L
H	H	X	X	X	L	L	H
H	H	X	X	X	H	H	L

L = low voltage level  
 H = high voltage level  
 X = either high or low logic level

### LOADING RULES (1 U.L. = 1 TTμL gate input load)

INPUTS	LOADING	
I <sub>0a</sub> , I <sub>1a</sub> , I <sub>2a</sub> , I <sub>3a</sub> , I <sub>0b</sub> , I <sub>1b</sub> , I <sub>2b</sub> , I <sub>3b</sub> , S <sub>0</sub> , S <sub>1</sub>	1 U.L.	
OUTPUTS	FANOUT AT LOGIC LEVEL	
	HIGH	LOW
Z <sub>a</sub> , Z <sub>b</sub>	20 U.L.	10 U.L.
Z <sub>a</sub> , Z <sub>b</sub>	18 U.L.	9 U.L.

### TYPICAL INPUT AND OUTPUT CHARACTERISTICS

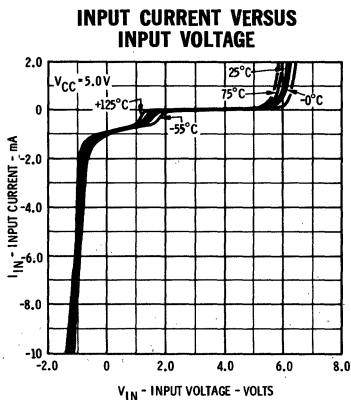
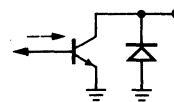
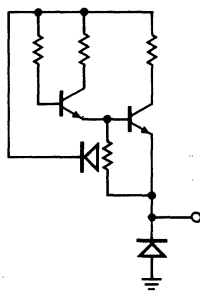
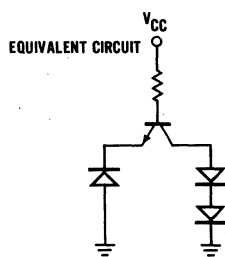


Fig. 5

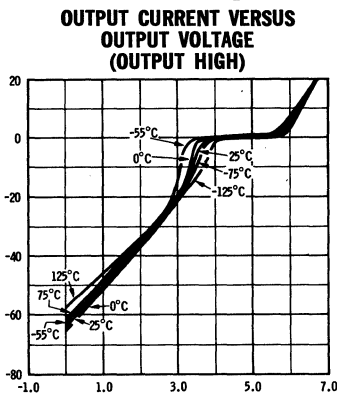


Fig. 6

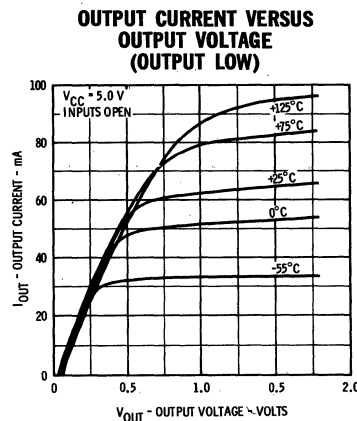


Fig. 7

# FAIRCHILD MEDIUM SCALE INTEGRATION 9309

**ELECTRICAL CHARACTERISTICS\*** ( $T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 10\%$ ) (Part No. UXX930951X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$-55^\circ\text{C}$		$+25^\circ\text{C}$			$+125^\circ\text{C}$			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	2.7		2.4		Volts	$V_{CC} = 4.5\text{ V}$ $I_{OH} = -1.2\text{ mA}$ (Pins 1 & 15) $V_{CC} = 4.5\text{ V}$ $I_{OH} = -1.08\text{ mA}$ (Pins 2 & 14) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) as per truth table
$V_{OL}$	Output Low Voltage		0.4		0.21	0.4		0.4	Volts	$V_{CC} = 5.5\text{ V}$ $I_{OL} = 16.0\text{ mA}$ (Pins 1 & 15) $I_{OL} = 14.4\text{ mA}$ (Pins 2 & 14) $V_{CC} = 4.5\text{ V}$ $I_{OL} = 12.4\text{ mA}$ (Pins 1 & 15) $I_{OL} = 11.2\text{ mA}$ (Pins 2 & 14) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) as per truth table
$V_{IH}$	Input High Voltage	2.0		1.7			1.4		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.8			0.9		0.8	Volts	Guaranteed input low threshold for all inputs
$I_F$ (all inputs)	Input Load Current		-1.6		-1.1	-1.6		-1.6	mA	$V_{CC} = 5.5\text{ V}$ $V_F = 0.4\text{ V}$ Input selected
$I_R$ (all inputs)	Input Leakage Current				15	60		60	$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ $V_R = 4.5\text{ V}$ Input not selected
$I_{PDH}$	$V_{CC}$ Current		40		30	40		40	mA	$V_{CC} = 5.0\text{ V}$ All inputs high
$t_{pd+}$ ( $S_0$ to $Z_a$ )	Switching Speed				24	32			ns	$V_{CC} = 5.0\text{ V}$ , $C_L = 15\text{ pF}$ , See Figure 5
$t_{pd-}$ ( $S_0$ to $Z_a$ )	Switching Speed				24	32			ns	

\*Pulse tested

**ELECTRICAL CHARACTERISTICS\*** ( $T_A = 0^\circ\text{C}$  to  $+75^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 5\%$ ) (Part No. UXX930959X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$0^\circ\text{C}$		$+25^\circ\text{C}$			$+75^\circ\text{C}$			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	3.0		2.4		Volts	$V_{CC} = 4.75\text{ V}$ $I_{OH} = -1.2\text{ mA}$ (Pins 1 & 15) $V_{CC} = 4.75\text{ V}$ $I_{OH} = -1.08\text{ mA}$ (Pins 2 & 14) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) as per truth table
$V_{OL}$	Output Low Voltage		0.45		0.21	0.45		0.45	Volts	$V_{CC} = 5.25\text{ V}$ $I_{OL} = 16.0\text{ mA}$ (Pins 1 & 15) $I_{OL} = 14.4\text{ mA}$ (Pins 2 & 14) $V_{CC} = 4.75\text{ V}$ $I_{OL} = 14.1\text{ mA}$ (Pins 1 & 15) $I_{OL} = 12.7\text{ mA}$ (Pins 2 & 14) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) as per truth table
$V_{IH}$	Input High Voltage	1.9		1.8			1.6		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.85			0.85		0.85	Volts	Guaranteed input low threshold for all inputs
$I_F$ (all inputs)	Input Load Current		-1.6		-1.0	-1.6		-1.6	mA	$V_{CC} = 5.25\text{ V}$ $V_F = 0.45\text{ V}$ Input selected
$I_R$ (all inputs)	Input Leakage Current				15	60		60	$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ $V_R = 4.5\text{ V}$ Input not selected
$I_{PDH}$	$V_{CC}$ Current		43		30	43		43	mA	$V_{CC} = 5.0\text{ V}$ All inputs high
$t_{pd+}$ ( $S_0$ to $Z_a$ )	Switching Speed				24	32			ns	$V_{CC} = 5.0\text{ V}$ , $C_L = 15\text{ pF}$ , See Figure 5
$t_{pd-}$ ( $S_0$ to $Z_a$ )	Switching Speed				24	32			ns	

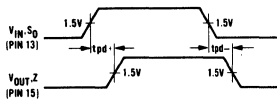
\*Pulse tested

SWITCHING WAVEFORMS

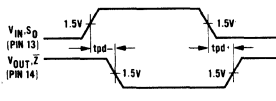
All input waveforms are output of TT $\mu$ L 9000 series gates loaded with 15 pF. All outputs are loaded with the same capacitance (referred to as  $C_L$ ) and only with capacitance.

Fig. 8 — WAVEFORMS

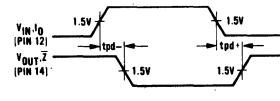
$t_{pd}$ :  $S_0$  to  $Z_a$   
 CONDITIONS  
 Pins 3, 12 = GND.  
 Pin 11 =  $V_{CC}$



$t_{pd}$ :  $S_0$  to  $Z_a$   
 CONDITIONS  
 Pins 3, 12 = GND.  
 Pin 11 =  $V_{CC}$



$t_{pd}$ :  $I_{a0}$  to  $Z_a$   
 CONDITIONS  
 Pins 3, 13 = GND.



SWITCHING CHARACTERISTICS

TURN OFF DELAY TIME VERSUS AMBIENT TEMPERATURE ( $S_0$  to  $Z_a$ )

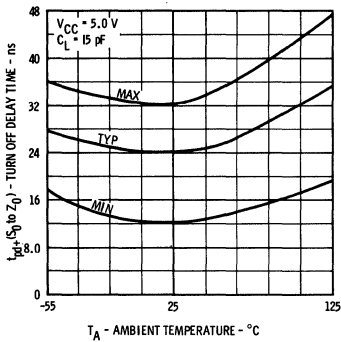


Fig. 9

TURN ON DELAY TIME VERSUS AMBIENT TEMPERATURE ( $S_0$  to  $Z_a$ )

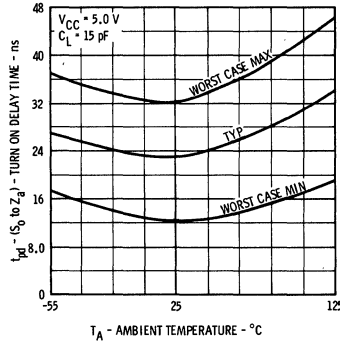


Fig. 10

TURN OFF DELAY TIME VERSUS AMBIENT TEMPERATURE ( $I_{a0}$  to  $Z_a$ )

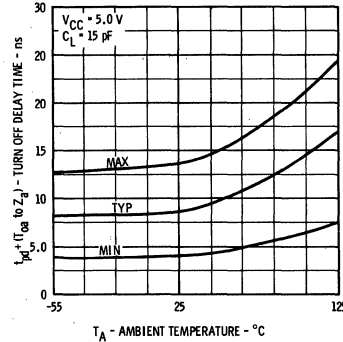


Fig. 11

TURN ON DELAY TIME VERSUS AMBIENT TEMPERATURE ( $I_{a0}$  to  $Z_a$ )

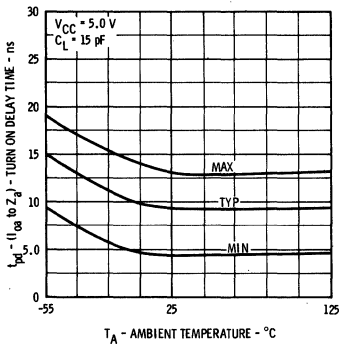


Fig. 12

TURN OFF DELAY TIME VERSUS AMBIENT TEMPERATURE ( $S_0$  to  $Z_a$ )

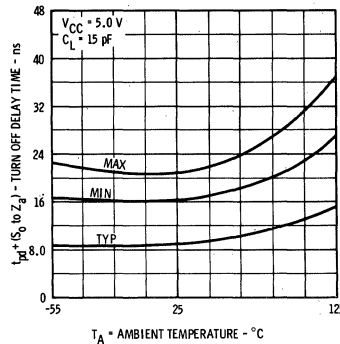


Fig. 13

TURN ON DELAY TIME VERSUS AMBIENT TEMPERATURE ( $S_0$  to  $Z_a$ )

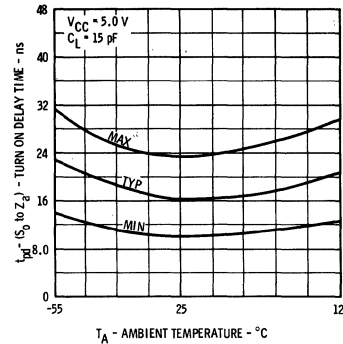


Fig. 14

APPLICATIONS

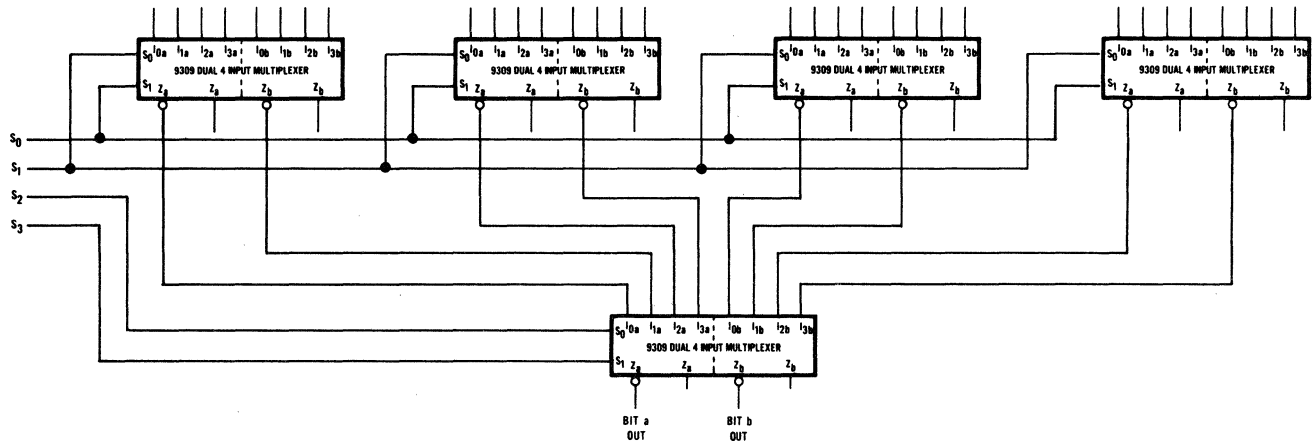


Fig. 12 — MULTIPLEXING TWO BITS FROM SIXTEEN SOURCES

This diagram shows the interconnection of five 9309 dual four bit multiplexers to provide switching of two bits of data from one of sixteen words onto a two bit data buss. The selection of which word will be transferred to the buss is made by the address supplied to the  $S_0$ ,  $S_1$ ,  $S_2$  and  $S_3$  inputs. As an example: if twelve bit words are to be transferred to a twelve bit buss, the above diagram would be repeated six times. Notice that the negative outputs are used at both levels resulting in the assertion output (negation of the negation) at a higher speed due to the fact that the through delay is less on the negation output.

If the word selecting address is held in four TTL flip flops (two dual packages) enough load capability is available to select between sixteen, sixteen bit words.

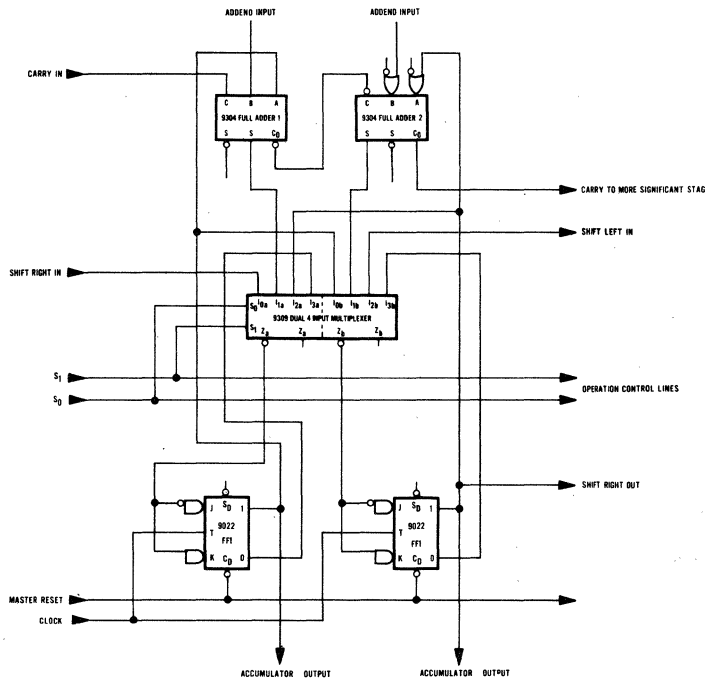


Fig. 13 — GENERAL PURPOSE ACCUMULATOR

A fast, general purpose accumulator for computer applications is capable of: 1) shift left; 2) add; 3) shift right and 4) complement operations. Only three packages are required to construct two stages of the general purpose accumulator (Figure 1).

The D input capability of the 9022 is utilized here to allow each flip flop of the accumulator to accept the data as presented by the 9309 multiplexer. Under the operation code instructions the multiplexer provides an input to the 9022 from: 1) adjacent stage to the right for a shift left operation; 2) adjacent stage to the left for a shift right operation; 3) output of adders for add operation and 4) Q outputs of 9022 for the complement operation. The operation code at the right of Figure 1 shows the instruction codes to perform the various operations.

The accumulator should be capable of 20 to 25 MHz operation.

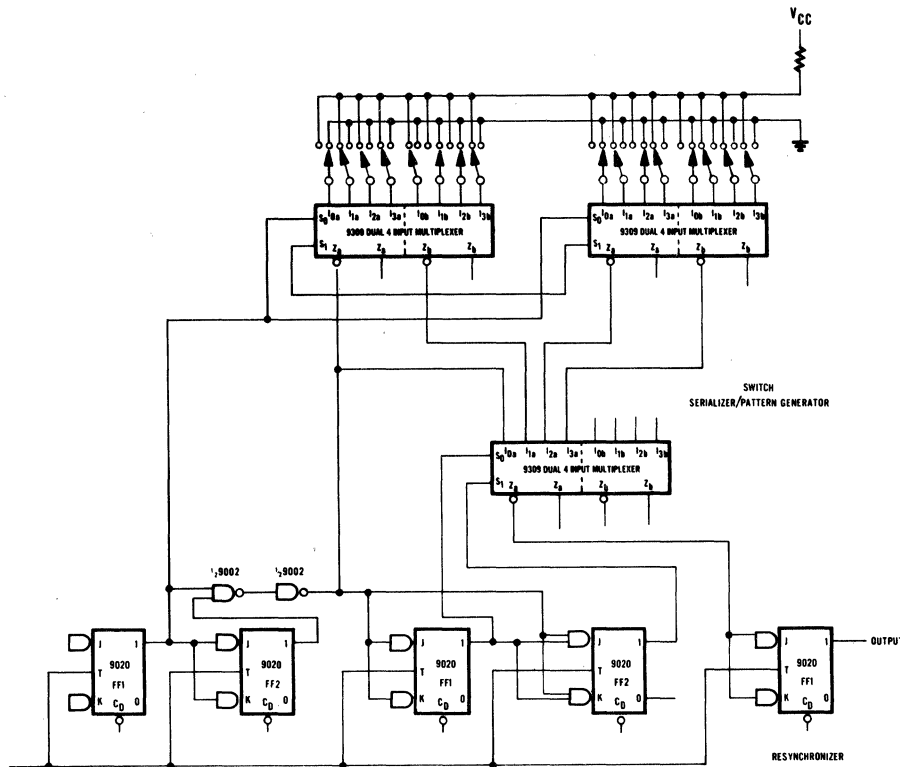


Fig. 14 — 16-BIT PATTERN GENERATOR

This application illustrates the use of 9309 and 9020 in the design of one channel of a 16 bit pattern generator. Each channel requires  $\frac{1}{2}$  9020,  $\frac{1}{2}$  9002 and  $2\frac{1}{2}$  9309. Each channel consists of a switch serializer/pattern generator and resynchronizer sections with a modulo 16 binary counter common to all channels.

The two least significant bits and two most significant bits of the counter control the first and second stages of multiplexing respectively. In this manner four bits are multiplexed on each of the four lines from the first stage to the second stage. Every four clock times a new input line containing four multiplexed bits is selected by the second stage of the serializer thus serializing the 16 input bits from the switches.

The resynchronizer flip flop is used to eliminate decoding spikes.

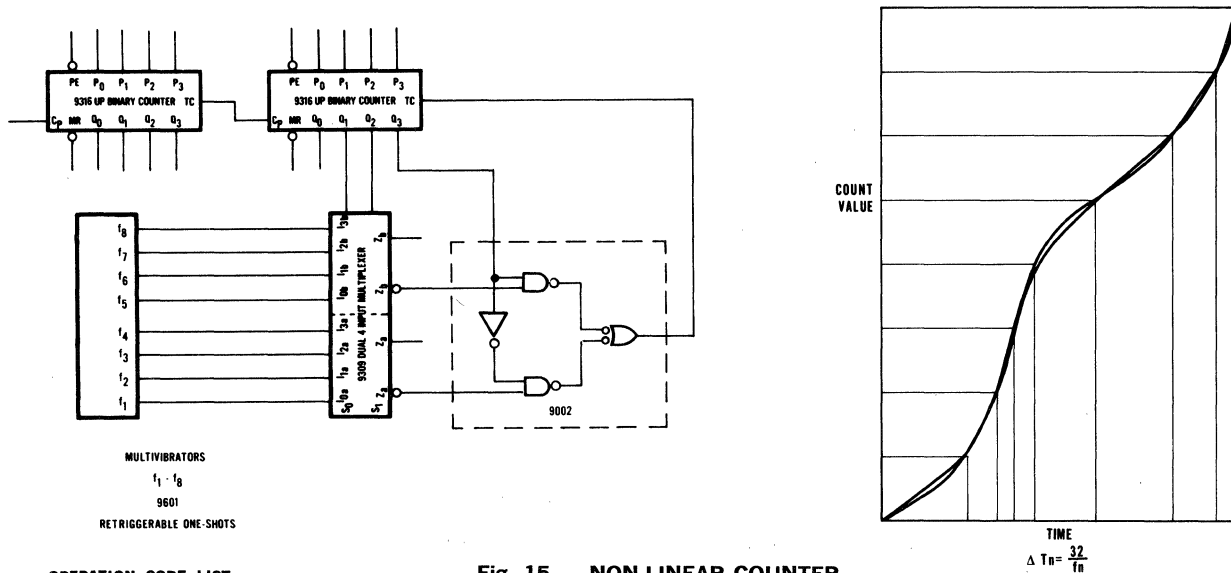


Fig. 15 — NON-LINEAR COUNTER

OPERATION CODE LIST

S <sub>0</sub>	S <sub>1</sub>	INSTRUCTION
0	0	SHIFT LEFT
1	0	ADD
0	1	SHIFT RIGHT
1	1	COMPLEMENT

H = "1", L = "0"

The rate of the non-linear counter depends on the multivibrator clock frequency selected under control of the three most significant bits of the counter. This makes the count rate a function of both the count value of counter and frequency of clock multivibrator selected.

Clock multiplexing is accomplished by a 9309 dual 4-input multiplexer and one 9002 quad gate. Eight line segments representing clock rates of the multivibrators may be adjusted in slope to approximate a non-linear function.

# 9312

## MSI EIGHT-INPUT MULTIPLEXER

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The 9312 is a monolithic, high speed, eight input digital multiplexer circuit. It provides in one package the ability to select one bit of data from up to eight sources. The 9312 can be used as a universal function generator to generate any logic function of four variables. Both assertion and negation outputs are provided. TTL circuitry with active pullups on the outputs provides high speed, high fanout operation and is compatible with all other members of the CCSL family of digital integrated circuits.

### FEATURES

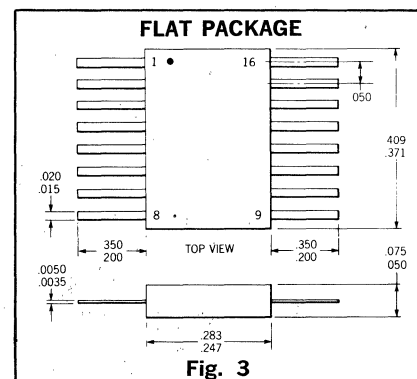
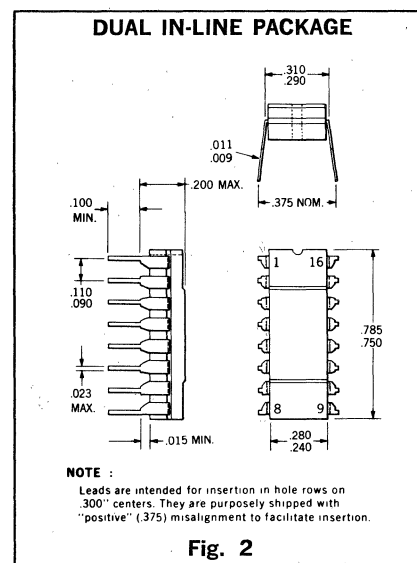
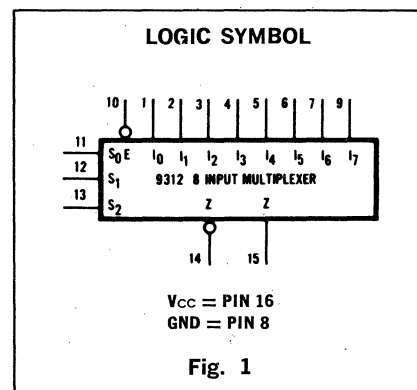
- MULTIFUNCTION CAPABILITY
- 25 ns THROUGH DELAY
- ON-CHIP SELECT LOGIC DECODING
- FULLY BUFFERED COMPLEMENTARY OUTPUTS
- THE INPUT/OUTPUT CHARACTERISTICS PROVIDE EASY INTERFACING WITH FAIRCHILD DT $\mu$ L, LPDT $\mu$ L, TT $\mu$ L, AND MSI FAMILIES (CCSL).
- INPUT CLAMP DIODES LIMIT HIGH SPEED TERMINATION EFFECTS.

### ABSOLUTE MAXIMUM RATINGS (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5 V to +7 V
Voltage applied to output when output is high	0 V to +V <sub>CC</sub> value
Input Voltage (DC) (See Note 1)	-0.5 V to +5.5 V
Input Current (DC) (See Note 1)	-30 mA to +5 mA
Current into output when output is low	+30 mA

Note 1: Either Input Voltage limit or Input Current limit is sufficient to protect the inputs.

**ORDER INFORMATION** — Specify U6B9312XXX for 16-pin Dual In-Line package or U3L9312XXX for 16-pin Flatpak, where XXX is 51X for the -55°C to +125°C temperature range, or 59X for the 0°C to +75°C temperature range.



**FAIRCHILD**  
SEMICONDUCTOR  
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION



# FAIRCHILD MEDIUM SCALE INTEGRATION 9312

**FUNCTIONAL DESCRIPTION** — The 9312 is a logical implementation of a single pole - 8 position switch with the switch position controlled by the state of three select inputs,  $S_0, S_1, S_2$ . Both assertion and negation outputs are provided. The enable input (E) is active low. When it is not activated the negation output is high and the assertion output is low regardless of all other inputs. The logic function provided at the output is:

$$Z = E \cdot (I_0 \cdot \bar{S}_0 \cdot \bar{S}_1 \cdot \bar{S}_2 + I_1 \cdot \bar{S}_0 \cdot \bar{S}_1 \cdot S_2 + I_2 \cdot \bar{S}_0 \cdot S_1 \cdot \bar{S}_2 + I_3 \cdot \bar{S}_0 \cdot S_1 \cdot S_2 + I_4 \cdot \bar{S}_0 \cdot S_1 \cdot S_2 + I_5 \cdot S_0 \cdot \bar{S}_1 \cdot \bar{S}_2 + I_6 \cdot S_0 \cdot \bar{S}_1 \cdot S_2 + I_7 \cdot S_0 \cdot S_1 \cdot \bar{S}_2)$$

The 9312 provides the ability, in one package, to select from eight sources of data or control information. By proper manipulation of the inputs, the 9312 can provide any logic function of four variables and its negation. Thus any number of random logic elements used to generate unusual truth tables can be replaced by one 9312.

**TRUTH TABLE**

E	S <sub>2</sub>	S <sub>1</sub>	S <sub>0</sub>	I <sub>0</sub>	I <sub>1</sub>	I <sub>2</sub>	I <sub>3</sub>	I <sub>4</sub>	I <sub>5</sub>	I <sub>6</sub>	I <sub>7</sub>	$\bar{Z}$	Z
H	X	X	X	X	X	X	X	X	X	X	X	H	L
L	L	L	L	L	X	X	X	X	X	X	X	H	L
L	L	L	L	H	X	X	X	X	X	X	X	L	H
L	L	L	H	X	L	X	X	X	X	X	X	H	L
L	L	L	H	X	H	X	X	X	X	X	X	L	H
L	L	H	L	X	X	L	X	X	X	X	X	H	L
L	L	H	L	X	X	H	X	X	X	X	X	L	H
L	L	H	H	X	X	X	L	X	X	X	X	H	L
L	L	H	H	X	X	X	H	X	X	X	X	L	H
L	H	L	L	X	X	X	X	L	X	X	X	H	L
L	H	L	L	X	X	X	X	H	X	X	X	L	H
L	H	L	H	X	X	X	X	X	L	X	X	H	L
L	H	L	H	X	X	X	X	X	H	X	X	L	H
L	H	H	L	X	X	X	X	X	X	L	X	H	L
L	H	H	L	X	X	X	X	X	X	H	X	L	H
L	H	H	H	X	X	X	X	X	X	X	L	H	L
L	H	H	H	X	X	X	X	X	X	X	H	L	H

H = High voltage level  
L = Low voltage level  
X = Level does not affect output

Fig. 5

**LOADING RULES**

INPUTS	LOADING
All Inputs	1 U.L.

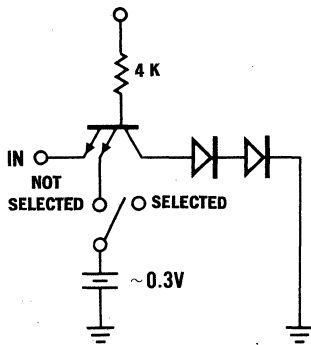
OUTPUTS	FAN-OUT	
	High State	Low State
$\bar{Z}$	18	9
Z	20	10

Fig. 4

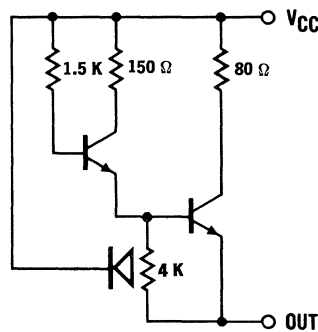
1 U.L. = 1 TT  $\mu$ L Unit Load  
1 U.L. is defined by the entries  $I_R$  and  $I_F$  in the table on page 3.

## TYPICAL INPUT AND OUTPUT CHARACTERISTICS

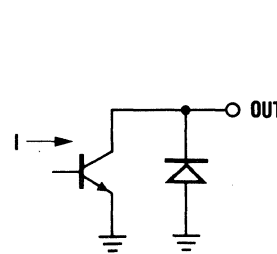
**EQUIVALENT INPUT CIRCUIT**



**OUTPUT HIGH EQUIVALENT CIRCUIT**



**OUTPUT LOW EQUIVALENT CIRCUIT**



**INPUT CURRENT VERSUS INPUT VOLTAGE**

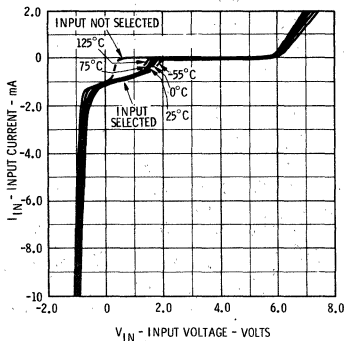


Fig. 6

**OUTPUT CURRENT VERSUS OUTPUT VOLTAGE (OUTPUT HIGH)**

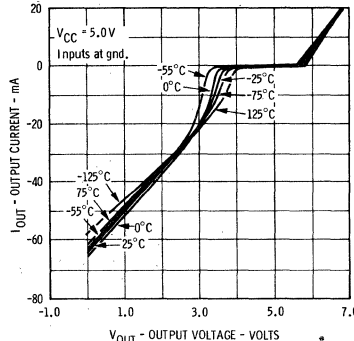


Fig. 7

**OUTPUT CURRENT VERSUS OUTPUT VOLTAGE (OUTPUT LOW)**

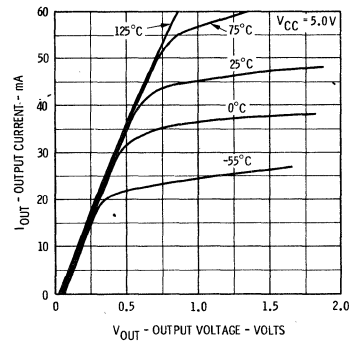


Fig. 8

## FAIRCHILD MEDIUM SCALE INTEGRATION 9312

**ELECTRICAL CHARACTERISTICS\*** ( $T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 10\%$ ) (Part No. UXX931251X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$-55^\circ\text{C}$		$+25^\circ\text{C}$			$+125^\circ\text{C}$			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	2.7		2.4		Volts	$V_{CC} = 4.5\text{ V}$ $I_{OH} = -1.2\text{ mA}$ (Pin 15) $V_{CC} = 4.5\text{ V}$ $I_{OH} = -1.08\text{ mA}$ (Pin 14) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) as per truth table
$V_{OL}$	Output Low Voltage		0.4		0.21	0.4		0.4	Volts	$V_{CC} = 5.5\text{ V}$ $I_{OL} = 16.0\text{ mA}$ (Pin 15) $I_{OL} = 14.4\text{ mA}$ (Pin 14) $V_{CC} = 4.5\text{ V}$ $I_{OL} = 12.4\text{ mA}$ (Pin 15) $I_{OL} = 11.2\text{ mA}$ (Pin 14) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) as per truth table
$V_{IH}$	Input High Voltage	2.0		1.7			1.4		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.8			0.9		0.8	Volts	Guaranteed input low threshold for all inputs
$I_F$ (all inputs)	Input Load Current		-1.6		-1.1	-1.6		-1.6	mA	$V_{CC} = 5.5\text{ V}$ $V_F = 0.4\text{ V}$
			-1.24		-0.85	-1.24		-1.24	mA	$V_{CC} = 4.5\text{ V}$ Input Selected
$I_R$ (all inputs)	Input Leakage Current				15	60		60	$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ $V_R = 4.5\text{ V}$ Input not selected
$I_{PDH}$	$V_{CC}$ Current		40		27	40		40	mA	$V_{CC} = 5.0\text{ V}$
$t_{pd+}$ ( $S_0$ to Z)	Switching Speed				23	34			ns	$V_{CC} = 5.0\text{ V}$ , See Page 4
$t_{pd-}$ ( $S_0$ to Z)	Switching Speed				25	36			ns	$C_L = 15\text{ pF}$

\*Pulse tested

**ELECTRICAL CHARACTERISTICS\*** ( $T_A = 0^\circ\text{C}$  to  $+75^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 5\%$ ) (Part No. UXX931259X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$0^\circ\text{C}$		$+25^\circ\text{C}$			$+75^\circ\text{C}$			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	3.0		2.4		Volts	$V_{CC} = 4.75\text{ V}$ $I_{OH} = -1.2\text{ mA}$ (Pin 15) $V_{CC} = 4.75\text{ V}$ $I_{OH} = -1.08\text{ mA}$ (Pin 14) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) as per truth table
$V_{OL}$	Output Low Voltage		0.45		0.21	0.45		0.45	Volts	$V_{CC} = 5.25\text{ V}$ $I_{OL} = 16.0\text{ mA}$ (Pin 15) $I_{OL} = 14.4\text{ mA}$ (Pin 14) $V_{CC} = 4.75\text{ V}$ $I_{OL} = 14.1\text{ mA}$ (Pin 15) $I_{OL} = 12.7\text{ mA}$ (Pin 14) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) as per truth table
$V_{IH}$	Input High Voltage	1.9		1.8			1.6		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.85			0.85		0.85	Volts	Guaranteed input low threshold for all inputs
$I_F$ (all inputs)	Input Load Current		-1.6		-1.0	-1.6		-1.6	mA	$V_{CC} = 5.25\text{ V}$ $V_F = 0.45\text{ V}$
			-1.41		-0.91	-1.41		-1.41	mA	$V_{CC} = 4.75\text{ V}$ Input Selected
$I_R$ (all inputs)	Input Leakage Current				15	60		60	$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ $V_R = 4.5\text{ V}$ Input not selected
$I_{PDH}$	$V_{CC}$ Current		43		27	43		43	mA	$V_{CC} = 5.0\text{ V}$
$t_{pd+}$ ( $S_0$ to Z)	Switching Speed				23	34			ns	$V_{CC} = 5.0\text{ V}$ , See Page 4
$t_{pd-}$ ( $S_0$ to Z)	Switching Speed				25	36			ns	$C_L = 15\text{ pF}$

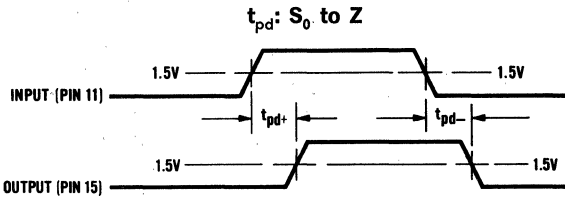
\*Pulse tested

# FAIRCHILD MEDIUM SCALE INTEGRATION 9312

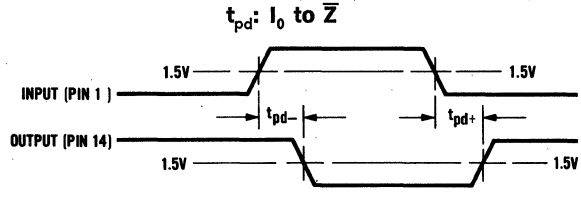
## A. C. CHARACTERISTICS

### A.C. CHARACTERISTICS

All measurements are made with  $V_{CC} = 5.0$  V applied to pin 16 and with pin 8 grounded. The active input is driven by a 9002 TT $\mu$ L gate with the output loaded with 15 pF. Both outputs of the 9312 are loaded with 15 pF.

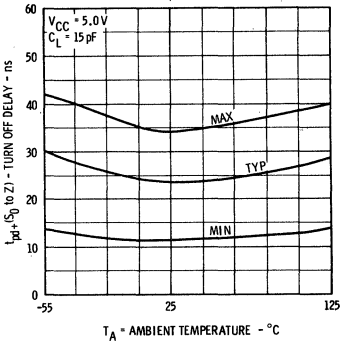


Other Conditions: Pins 1, 8, 10, 12, 13 = Gnd  
Pin 2 =  $V_{CC}$  through 1.0 k $\Omega$   
Pin 16 =  $V_{CC}$



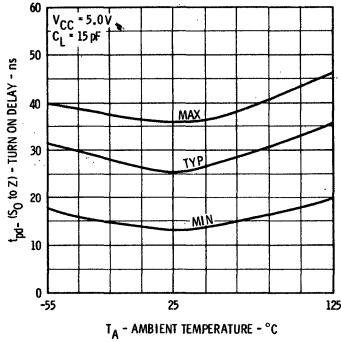
Other Conditions: Pins 8, 10, 11, 12, 13 = Gnd  
Pin 16 =  $V_{CC}$

**TURN OFF DELAY VERSUS AMBIENT TEMPERATURE;  
 $S_0$  to Z**



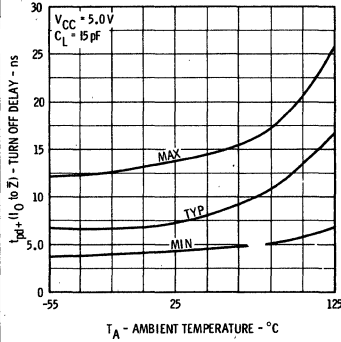
**Fig. 9**

**TURN ON DELAY VERSUS AMBIENT TEMPERATURE;  
 $S_0$  to Z**



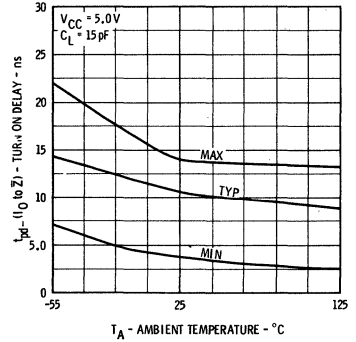
**Fig. 10**

**TURN OFF DELAY VERSUS AMBIENT TEMPERATURE;  
 $I_0$  to Z**

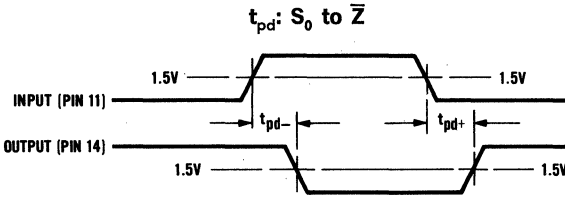


**Fig. 11**

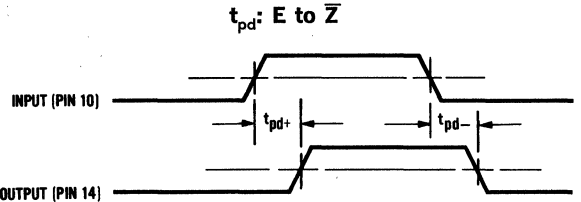
**TURN ON DELAY VERSUS AMBIENT TEMPERATURE;  
 $I_0$  to Z**



**Fig. 12**

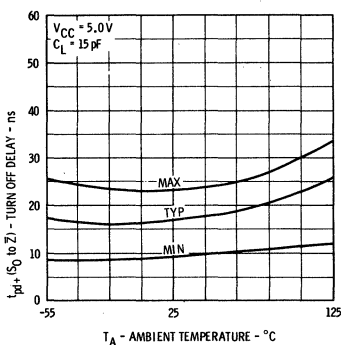


Other Conditions: Pins 1, 8, 10, 12, 13 = Gnd  
Pin 2 =  $V_{CC}$  through 1.0 k $\Omega$   
Pin 16 =  $V_{CC}$



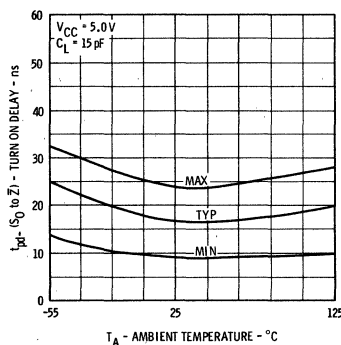
Other Conditions: Pins 8, 11, 12, 13 = Gnd  
Pin 1 =  $V_{CC}$  through 2.0 k $\Omega$   
Pin 16 =  $V_{CC}$

**TURN OFF DELAY VERSUS AMBIENT TEMPERATURE;  
 $S_0$  to Z**



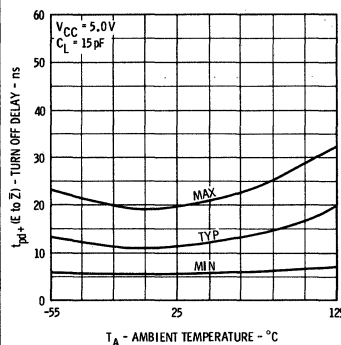
**Fig. 13**

**TURN ON DELAY VERSUS AMBIENT TEMPERATURE;  
 $S_0$  to Z**



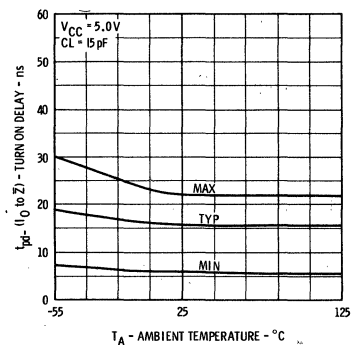
**Fig. 14**

**TURN OFF DELAY VERSUS AMBIENT TEMPERATURE;  
E to Z**



**Fig. 15**

**TURN ON DELAY VERSUS AMBIENT TEMPERATURE;  
E to Z**



**Fig. 16**

APPLICATIONS

A MULTI-PORT MEMORY MODULE

The four bit by eight word multi-port memory module shown in the below diagram uses only thirteen MSI packages; four 9308 24 pin dual four bit latches, eight 9312 eight input multiplexers, and one 9301 one-out-of-ten decoder.

The module as shown is capable of simultaneously reading from two independently specified locations and writing into a third independently selected location. The necessary enables are provided so that a number of these modules may be connected together to produce a larger memory. As an example a sixteen bit by sixty-four word memory would require thirty-two of the modules shown below.

By connecting this type of memory to a function generator unit, a processor could be constructed that would execute three address instructions at a very high speed on the data contained in this type of memory. In order to utilize the speed of the memory the instructions would also have to be contained in fast semiconductor memory.

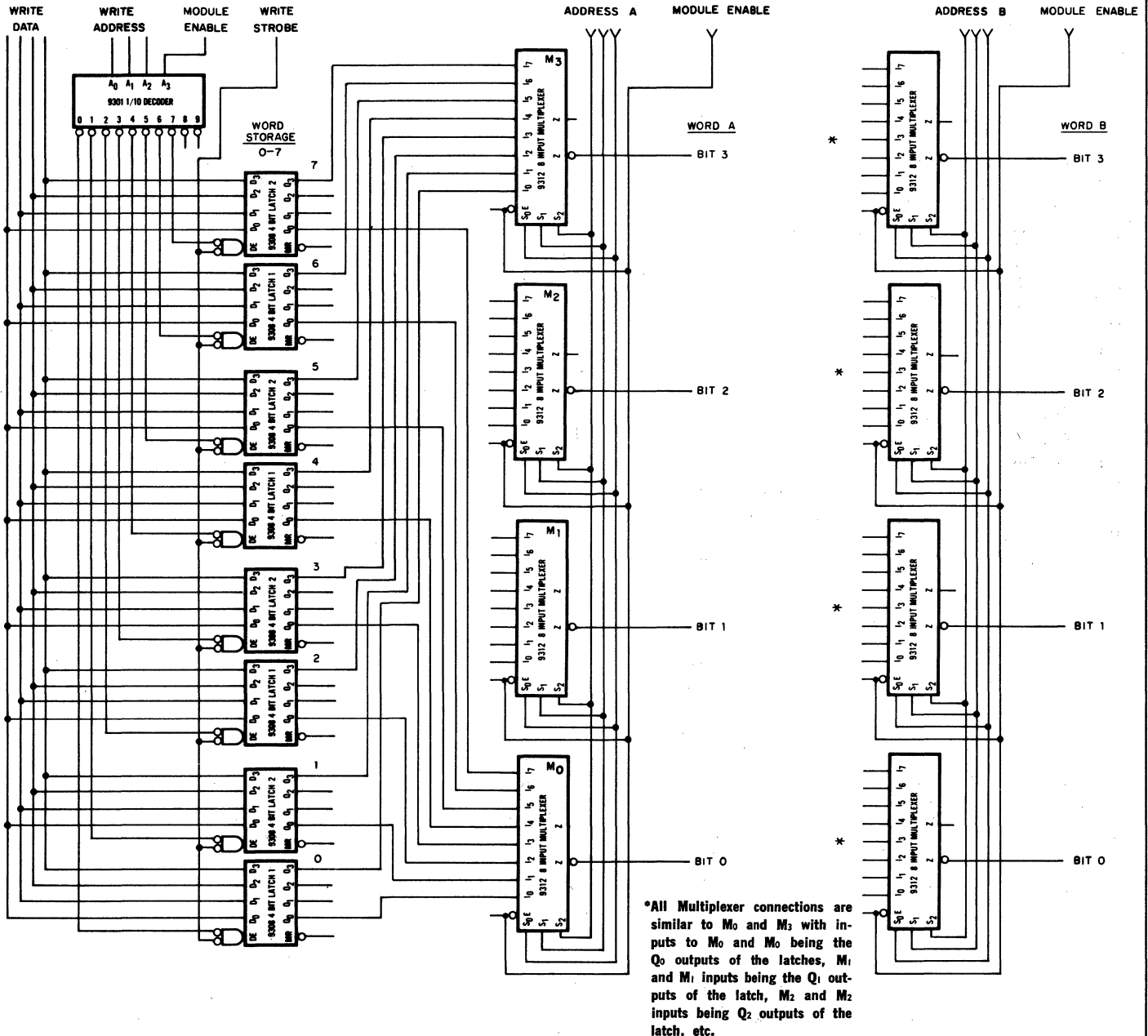


Fig. 17

APPLICATIONS

3 BIT COMPARATOR

Three bits of data to be compared are supplied to the address and select inputs of the 9301 and 9312 respectively. If  $A_0, A_1, A_2,$  and  $B_0, B_1, B_2$  compare, the mutually exclusive active low output of the 9301 1/10 decoder and the selected input of the 9312 multiplexer will be coincidental and COMPARE OUT will be high. The COMPARE ENABLE must be low to permit compare operation.

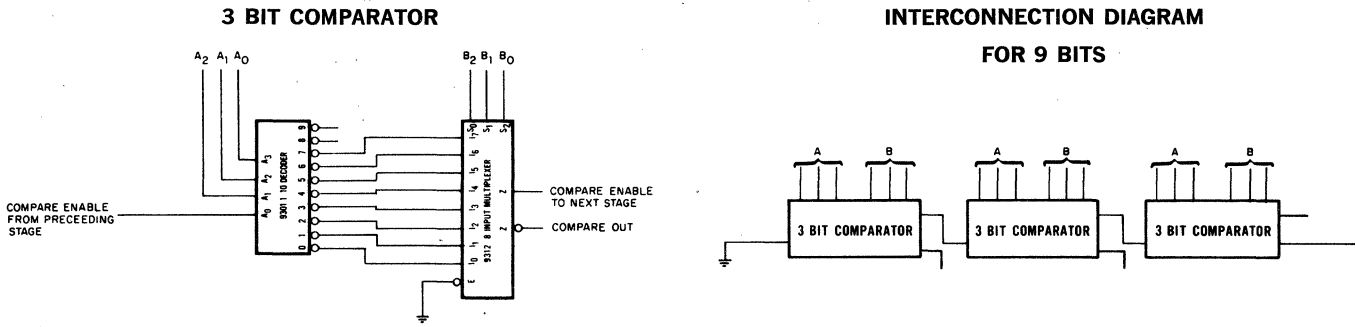


Fig. 18

IMPLEMENTING ANY FOUR-VARIABLE BOOLEAN FUNCTION

The 9312 eight input multiplexer can (in addition to performing its nominal function) produce any Boolean function of four variables without any additional elements if both the assertion and negation of one of the variables are present. If an assertion and negation are not present, one inverter may be required.

The procedure for implementing a four-variable function, along with an example, is shown in the attached diagram. First, consider the function in terms of a Karnaugh map. If the  $Q_0, Q_1$  and  $Q_2$  variable are connected to the  $S_0, S_1$  and  $S_2$  inputs of the 9312 then the Karnaugh map will be split, as shown, into eight sections, with each section corresponding to an input to the 9312. In order to implement the function each input of the 9312 is connected to one of the following four signals: ground,  $V_{CC}$ , the assertion, or negation of the fourth variable.

The contents of the two squares associated with an input, on the Karnaugh map, determine which connection is made to that input. If both squares contain a zero, ground should be connected to the input; if both squares contain a one, the input should be connected to  $V_{CC}$ . If the two squares contain a one and a zero then either the assertion or negation of the fourth variable will be required to implement the function. If the single one is located in the square associated with the assertion of the fourth variable then the assertion of the fourth variable is connected to that input, and vice versa.

Shown in the illustration below is a 9312 decoding the condition of a 9300, producing a one output whenever the register contains two or more transitions. The truth table, Karnaugh map and the connection to the 9312 for this function are also shown in the illustration.

In many applications, using the 9312 to implement general logic functions of four variables will result in a sizeable reduction in package count. In many cases use of the 9312 with additional gates to produce functions of more than four variables will also reduce the package count.

The concept of using the 9312 eight input-multiplexer as a general logic function generator is described by S. S. Yau and C. K. Tang of Northwestern University in a paper presented at the 1968 Spring Joint Computer Conference in Atlantic City, New Jersey.

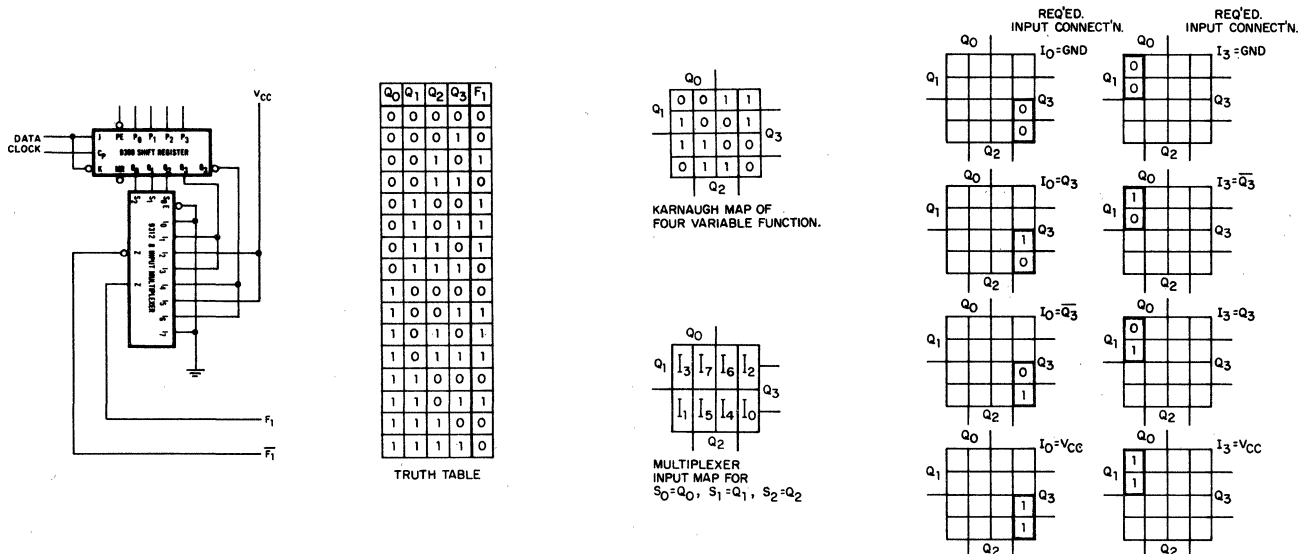


Fig. 19

FROM THE KARNAUGH MAP OF THE DESIRED FUNCTION  $I_0$ - $I_7$  CONNECTIONS CAN BE DETERMINED.

# TT $\mu$ L9601

## RETRIGGERABLE MONOSTABLE MULTIVIBRATOR

### TRANSISTOR-TRANSISTOR MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION**—The retriggerable monostable multivibrator or one-shot provides an output pulse with high accuracy and a very wide duration range (50 nsec to  $\infty$ ). It has four DC level-sensitive inputs, two are active-level High and two are active-level Low. Designed for high speed operation, the 9601 will respond to trigger inputs even when already in its active timing state, and will time itself out from the last input pulse received.

The unique design of the 9601 makes it very useful in applications such as in square-wave and variable delay pulse generators, long delay timers, pulse absence detectors, digital low-pass filters, and even FM demodulators.

- **HIGH SPEED OPERATION — MAXIMUM INPUT REP/RATE GREATER THAN 10 MHz**
- **COMPLEMENTARY DC LEVEL SENSITIVE INPUTS**
- **50 nsec TO  $\infty$  OUTPUT PULSE WIDTH RANGE**
- **OPTIONAL RETRIGGERING/LOCK-OUT CAPABILITY**
- **THE INPUT/OUTPUT CHARACTERISTICS PROVIDE EASY INTERFACING WITH DT $\mu$ L, LPDT $\mu$ L, TT $\mu$ L, MSI, AND OTHER CCSL PRODUCTS.**

**ABSOLUTE MAXIMUM RATINGS** (above which the useful life may be impaired)

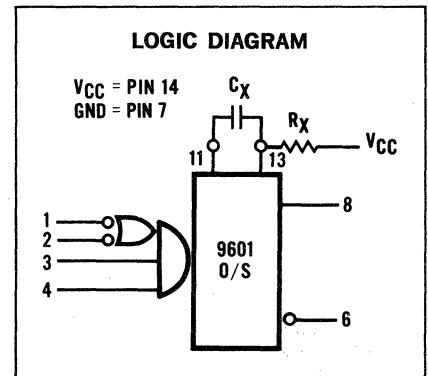
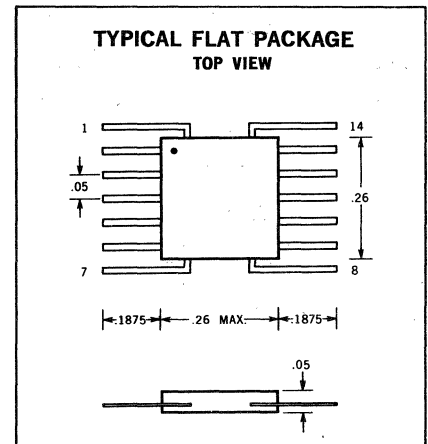
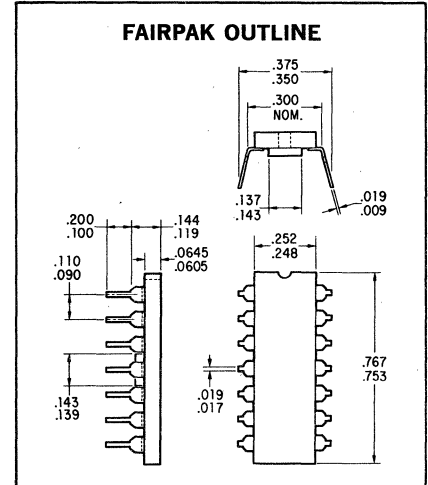
Storage Temperature	−65°C to +150°C
Temperature (Ambient) Under Bias	−55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground Pin	−0.5 V to +8 V
Input Voltage	−0.5 V to +5.5 V
Voltage Applied to Outputs	−0.5 V to +V <sub>CC</sub> value

**ORDER INFORMATION**

Specify U3196015XX for flat package and U1A96015XX for FAIRPAK package, where 5XX is 51X for −55°C to +125°C temperature range or 59X for the 0°C to +75°C temperature range.

**PULSE WIDTH CALCULATION**

$$TPW = 0.36 R_x C_x$$



# FAIRCHILD RETRIGGERABLE MONOSTABLE MULTIVIBRATOR TT $\mu$ L9601

**ELECTRICAL CHARACTERISTICS** 0°C to +75°C,  $V_{CC} = 5.0\text{ V} \pm 5\%$

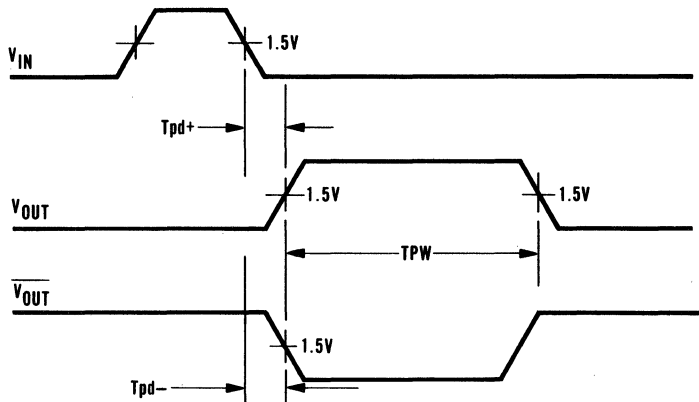
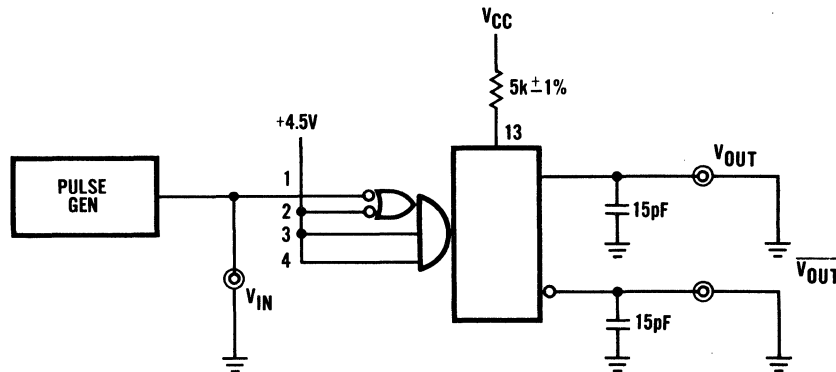
SYMBOL	CHARACTERISTICS	0°C		LIMITS +25°C			+75°C		UNITS	CONDITIONS (Note 1)
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	3.4		2.4		Volts	$V_{CC} = 4.75\text{ V}$ , $I_{OH} = -0.72\text{ mA}$ (Note 2)
$V_{OL}$	Output Low Voltage		0.45	0.2	0.45		0.45		Volts	$V_{CC} = 4.75\text{ V}$ , $I_{OL} = 10.0\text{ mA}$ (Note 2)
$V_{IH}$	Input High Voltage	2.0		2.0	1.7				Volts	$V_{CC} = 4.75\text{ V}$ (Note 3)
$V_{IL}$	Input Low Voltage				1.4	0.8	0.8		Volts	$V_{CC} = 5.25\text{ V}$ (Note 3)
$I_F$	Input Load Current		-1.6	-1.0	-1.6		-1.6		mA	$V_{CC} = 5.25\text{ V}$ , $V_F = 0.45\text{ V}$
$I_F$	Input Load Current		-1.24	-0.97	-1.24		-1.24		mA	$V_{CC} = 4.75\text{ V}$ , $V_F = 0.45\text{ V}$
$I_R$	Input Leakage Current			15	60		60		$\mu\text{A}$	$V_{CC} = 5.25\text{ V}$ , $V_R = 4.5\text{ V}$
$I_{pd}$	Quiescent Power Supply Drain		25		25		25		mA	$V_{CC} = 5.25\text{ V}$
$T_{pd+}$	Negative Trigger Input to True Output				25	50			ns	$V_{CC} = 5.0\text{ V}$ , $R_X = 5\text{ K}\Omega$ $C_X = 0$ , $C_L = 15\text{ pF}$
$T_{pd-}$	Negative Trigger Input to Complement Output				25	50			ns	$V_{CC} = 5.0\text{ V}$ , $R_X = 5\text{ K}\Omega$ $C_X = 0$ , $C_L = 15\text{ pF}$
$T_{pw\ min}$	Min True Output Pulse Width				45	65			ns	$V_{CC} = 5.0\text{ V}$ , $R_X = 5\text{ K}\Omega$ $C_X = 0$ , $C_L = 15\text{ pF}$
$C_{stray}$	Max allowable Wiring Cap Pin 13 (Note 4)		50		50		50		pF	Pin 13 to Ground
$R_X$	Timing Resistor	5	40	5	40	5	40		$\text{K}\Omega$	

**NOTES:**

- (1) Unless otherwise noted, 10  $\text{K}\Omega$  resistor is placed between Pin 13 and  $V_{CC}$  for all tests. ( $R_X$ )
- (2) Ground Pin 11 for  $V_{OL}$  Pin 6 or  $V_{OH}$  Pin 8  
Open Pin 11 for  $V_{OL}$  Pin 8 or  $V_{OH}$  Pin 6
- (3) Pulse test to determine  $V_{IH}$  and  $V_{IL}$  (min. pw 40 nsec)
- (4) This capacitance, if present, will add to  $C_X$  in determining output pulse width.

**tpd TEST CIRCUIT**

Note: Capacitance includes jig and probe capacity



$f \approx 1\text{ MHz}$   
 $\text{Amp} \approx 3\text{ V}$   
 $\text{Width} \approx 40\text{ ns}$   
 $t_r = t_f \leq 10\text{ ns}$

# FAIRCHILD RETRIGGERABLE MONOSTABLE MULTIVIBRATOR TT $\mu$ L9601

**ELECTRICAL CHARACTERISTICS**  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 10\%$

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS (Note 1)	
		$-55^{\circ}\text{C}$		$+25^{\circ}\text{C}$		$+125^{\circ}\text{C}$				
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
$V_{OH}$	Output High Voltage	2.4		2.4	3.3		2.4		Volts	$V_{CC} = 4.5\text{ V}$ , $I_{OH} = -0.72\text{ mA}$ (Note 2)
$V_{OL}$	Output Low Voltage		0.40	0.2	0.40			0.4	Volts	$V_{CC} = 4.5\text{ V}$ , $I_{OL} = 10.0\text{ mA}$ (Note 2)
$V_{IH}$	Input High Voltage	2.0		2.0	1.7				Volts	$V_{CC} = 4.5\text{ V}$ (Note 3)
$V_{IL}$	Input Low Voltage				1.4	0.85		0.85	Volts	$V_{CC} = 5.5\text{ V}$ (Note 3)
$I_F$	Input Load Current		-1.6		-1.1	-1.6		-1.6	mA	$V_{CC} = 5.5\text{ V}$ , $V_F = 0.4\text{ V}$
$I_F$	Input Load Current		-1.24		-0.97	-1.24		-1.24	mA	$V_{CC} = 4.5\text{ V}$ , $V_F = 0.4\text{ V}$
$I_R$	Input Leakage Current				15	60		60	$\mu\text{A}$	$V_{CC} = 5.5\text{ V}$ , $V_R = 4.5\text{ V}$
$I_{pd}$	Quiescent Power Supply Drain		25			25		25	mA	$V_{CC} = 5.5\text{ V}$
$T_{pd+}$	Negative Trigger Input to True Output				25	50			ns	$V_{CC} = 5.0\text{ V}$ , $R_X = 5\text{ K}\Omega$ $C_X = 0$ , $C_L = 15\text{ pF}$
$T_{pd-}$	Negative Trigger Input to Complement Output				25	50			ns	$V_{CC} = 5.0\text{ V}$ , $R_X = 5\text{ K}\Omega$ $C_X = 0$ , $C_L = 15\text{ pF}$
$T_{pw\ min}$	Min True Output Pulse Width				45	65			ns	$V_{CC} = 5.0\text{ V}$ , $R_X = 5\text{ K}\Omega$ $C_X = 0$ , $C_L = 15\text{ pF}$
$C_{stray}$	Max allowable Wiring Cap Pin 13 (Note 4)		50			50		50	pF	Pin 13 to Ground
$R_X$	Timing Resistor	5	20	5		20	5	20	$\text{K}\Omega$	

**NOTES:**

- (1) Unless otherwise noted, 10  $\text{K}\Omega$  resistor is placed between Pin 13 and  $V_{CC}$  for all tests. ( $R_X$ )
- (2) Ground Pin 11 for  $V_{OL}$  Pin 6 or  $V_{OH}$  Pin 8  
Open Pin 11 for  $V_{OL}$  Pin 8 or  $V_{OH}$  Pin 6
- (3) Pulse test to determine  $V_{IH}$  and  $V_{IL}$  (min. pw 40 nsec)
- (4) This capacitance, if present, will add to  $C_X$  in determining output pulse width.

### LOADING RULES

INPUT LEVEL	LOAD FACTOR
High	1
Low	1
OUTPUT STATE	FANOUT
High	12
Low	8

1 High Level Load =  $I_R$   
1 Low Level Load =  $I_F$



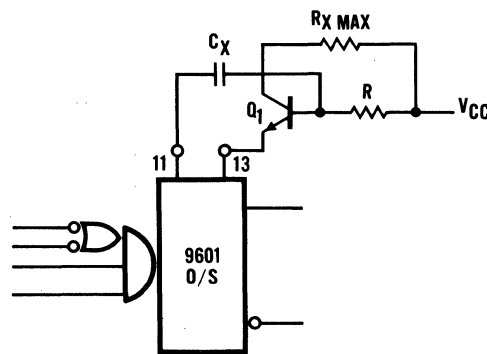
APPLICATION HINTS

A. Extending the Range of the External Timing Resistor  $R_X$ .

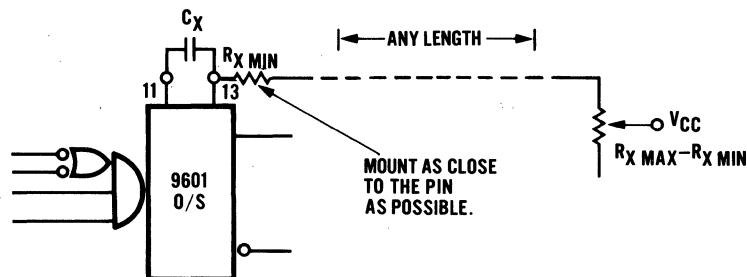
Pulse Width stability over Supply Voltage and Temperature Range will depreciate slightly using this circuit.

$$R = H_{FE} Q_1 (0.7) (R_{X \text{ max}})$$

$Q_1$  may be any NPN transistor with suitable  $H_{FE}$  at currents of  $< 1 \text{ mA}$ .



B. Recommended Method for using Remotely Located Timing Resistors.



# 9622

## DUAL LINE RECEIVER

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The 9622 is a dual line receiver designed to discriminate a worst case logic swing of 2 volts from a  $\pm 10$  volt common mode noise signal or ground shift. A 1.5 volt threshold is built into the differential amplifier to offer a CCSL compatible threshold voltage and maximum noise immunity. The offset is obtained by use of current sources and matched resistors and varies only  $\pm 5\%$  (75 mV) over the military and industrial temperature ranges.

The 9622 allows the choice of output states with the inputs open without affecting circuit performance by use of S3. A  $130\ \Omega$  terminating resistor is provided at the input of the each line receiver. An enable is also provided for each line receiver. The output is CCSL compatible. The output high level can be increased to  $+12\text{ V}$  by tying it to a positive supply through a resistor. The outputs can be wire-OR'ed.

**FEATURES:**

- CCSL COMPATIBLE THRESHOLD VOLTAGE
- INPUT TERMINATING RESISTORS
- CHOICE OF OUTPUT STATE WITH INPUTS OPEN
- CCSL COMPATIBLE OUTPUT
- HIGH COMMON MODE
- WIRE-OR CAPABILITY
- ENABLE INPUTS
- FULL MILITARY TEMPERATURE RANGE
- LOGIC COMPATIBLE SUPPLY VOLTAGES

**ABSOLUTE MAXIMUM RATINGS** (above which the useful life may be impaired)

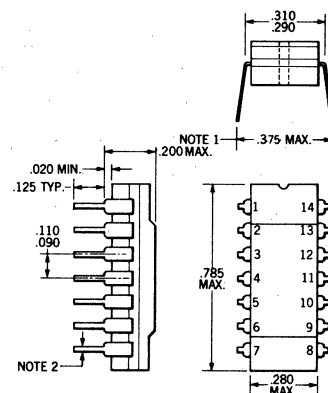
Storage Temperature	$-65^{\circ}\text{C}$ to $+150^{\circ}\text{C}$
Temperature (Ambient) Under Bias	$-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$
$V_{CC1}$ Pin Potential to Ground Pin	$-0.5\text{ V}$ to $+7\text{ V}$
Input Voltage	$\pm 15\text{ V}$
Voltage Applied to Outputs for High Output State	$-0.5\text{ V}$ to $+13.2\text{ V}$
$V_{EE}$ Pin Potential to Ground Pin	$-0.5\text{ V}$ to $-12\text{ V}$
Enable Pin Potential to Ground Pin	$-0.5\text{ V}$ to $+15\text{ V}$

**ORDER INFORMATION**

Specify U6A9622XXX for 14 pin Dual In-Line package, U3I9622XXX for 14 pin Flat package where XXX is 51X for the  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$  temperature range, or 59X for the  $0^{\circ}\text{C}$  to  $+75^{\circ}\text{C}$  temperature range.

**TYPICAL DUAL IN-LINE PACKAGE**

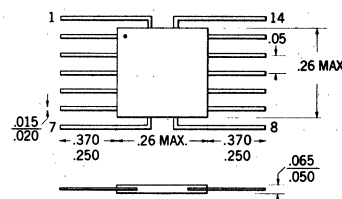
In Accordance With  
JEDEC (TO-116) Outline



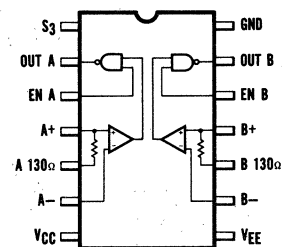
**NOTES:**

1. Leads are intended for insertion in hole rows on .300" centers. They are purposely shipped with "positive" (.375) misalignment to facilitate insertion.
2. Board-drilling dimensions should equal your practice for a conventional .020 inch diameter lead.

**FLAT PACKAGE  
TOP VIEW**



**LOGIC DIAGRAM**



**FAIRCHILD**  
**SEMICONDUCTOR**  
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION

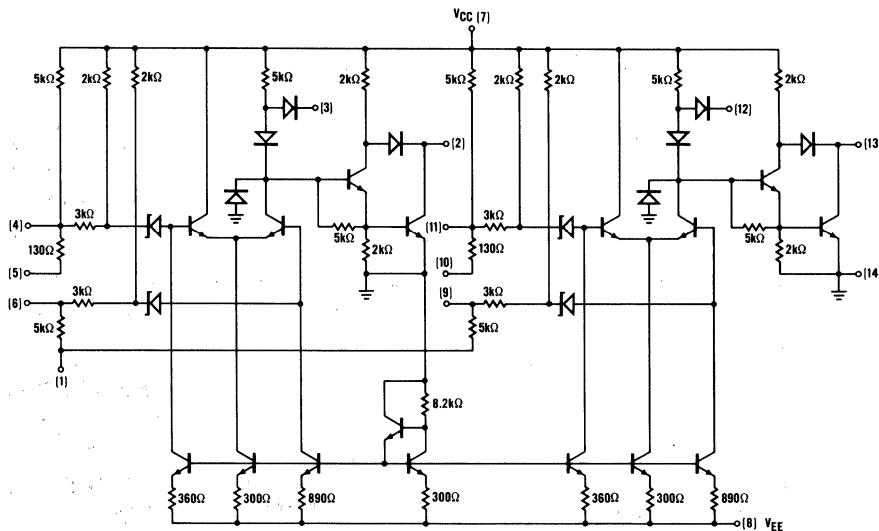
# FAIRCHILD DUAL LINE RECEIVER • 9622

**ELECTRICAL CHARACTERISTICS** (Temperature Range  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ ,  $V_{CC} = 5.0\text{ V} \pm 10\%$ ,  $V_{EE} = -10\text{ V} \pm 10\%$ ) (Part No. UXX962251X)

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS & COMMENTS		
		$-55^{\circ}\text{C}$		$+25^{\circ}\text{C}$		$+125^{\circ}\text{C}$					
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.			
$V_{OL}$	Output Low Voltage	0.40		0.25	0.40	0.40		V	$V_{CC} = 4.5\text{ V}$ $*V_{DIFF} = 2.0\text{ V}$	$V_{EE} = -11\text{ V}$ $I_{OL} = 12.4\text{ mA}$	
$V_{OH}$	Output High Voltage	2.8	3.0		3.3	2.9		V	$V_{CC} = 4.5\text{ V}$ $*V_{DIFF} = 1.0\text{ V}$	$V_{EE} = -9.0\text{ V}$ $I_{OH} = -0.2\text{ mA}$	
$I_{CEX}$	Output Leakage Current	50		100		200		$\mu\text{A}$	$V_{CC} = 4.5\text{ V}$ $*V_{DIFF} = 1.0\text{ V}$	$V_{EE} = -11\text{ V}$ $V_{CEX} = 12\text{ V}$	
$I_{SC}$	Output Shorted Current	-1.3	-3.1	-1.4	-2.15	-3.1	-1.3	-3.1	mA	$V_{CC} = 5.0\text{ V}$ $*V_{DIFF} = 1.0\text{ V}$	$V_{EE} = -10\text{ V}$ $V_{SC} = 0\text{ V}$
$I_{R(ENABLE)}$	Enable Input Leakage Current			2.0		5.0		$\mu\text{A}$	$V_{CC} = 4.5\text{ V}$ $S_3 = 4.5\text{ V}$	$V_{EE} = -11\text{ V}$ $V_R = 4.0\text{ V}$	
$I_{F(ENABLE)}$	Enable Input Forward Current	-1.5	-0.96		-1.5	-1.5		mA	$V_{CC} = 5.5\text{ V}$ $S_3 = 0\text{ V}$	$V_{EE} = -9.0\text{ V}$ $V_F = 0\text{ V}$	
$I_{F(+Input)}$	+ Input Forward Current	-2.3	-1.67		-2.1	-2.0		mA	$V_{CC} = 5.0\text{ V}$ - Input = Gnd	$V_{EE} = -10\text{ V}$ $V_F = 0\text{ V}$	
$I_{F(-Input)}$	- Input Forward Current	-2.6	-1.87		-2.4	-2.3		mA	$V_{CC}, S_3 = 5.0\text{ V}$ + Input = Gnd	$V_{EE} = -10\text{ V}$ $V_F = 0\text{ V}$	
$V_{IL(ENABLE)}$	Input Low Voltage	1.3		1.4	1.0	0.7		V	$V_{CC} = 5.0\text{ V} \pm 10\%$ $V_{EE} = -10\text{ V} \pm 10\%$		
$V_{th}$	Differential Input Threshold Voltage	1.0	2.0	1.0	1.5	2.0	1.0	2.0	V	$V_{CC} = 5.0\text{ V} \pm 10\%$ $V_{EE} = -10\text{ V} \pm 10\%$	
$V_{CM}$	Common Mode Voltage	-10		$\pm 12$	+10				V	$V_{CC} = 5.0\text{ V}$ $*V_{DIFF} = 1.0\text{ V or } 2.0\text{ V}$	$V_{EE} = -10\text{ V}$
$R_{130\Omega}$	Terminating Resistance	100		130	175				$\Omega$		
$I_{CC}$	5 V Supply Current			13.7	22.9				mA	$V_{CC} = 5.5\text{ V}$ $S_3, +\text{Inputs} = 5.5\text{ V}, -\text{Inputs} = 0\text{ V}$	$V_{EE} = -11\text{ V}$
$I_{EE}$	-10 V Supply Current			-6.5	-11.1				mA	$V_{CC} = 5.5\text{ V}$ $S_3, +\text{Inputs} = 5.5\text{ V}, -\text{Inputs} = 0\text{ V}$	$V_{EE} = -11\text{ V}$
$t_{pd+}$	Turn-off Time			38	50				ns	$V_{CC} = 5.0\text{ V}$ $V_{IN} 0 \rightarrow 3\text{ V}, R_L = 3.9\text{ k}\Omega, C_L = 30\text{ pF}$	$V_{EE} = -10\text{ V}$
$t_{pd-}$	Turn-on Time			35	50				ns	$V_{CC} = 5.0\text{ V}$ $V_{IN} 0 \rightarrow 3.0\text{ V}, R_L = 0.39\text{ k}\Omega, C_L = 30\text{ pF}$	$V_{EE} = -10\text{ V}$

\* $V_{DIFF}$  is a differential input voltage referred from A+ to A- and from B+ to B-.

**SCHEMATIC DIAGRAM  
(LINE RECEIVER)**



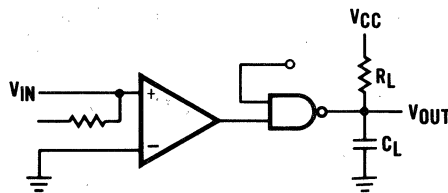
# FAIRCHILD DUAL LINE RECEIVER • 9622

**ELECTRICAL CHARACTERISTICS** (Temperature Range 0°C to +75°C,  $V_{CC} = 5.0 \text{ V} \pm 5\%$ ,  $V_{EE} = -10 \text{ V} \pm 5\%$ ) (Part No. UXX962259X)

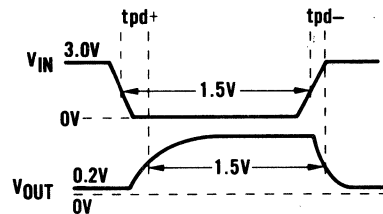
SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS & COMMENTS
		0°C		+25°C		+75°C			
		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	
$V_{OL}$	Output Low Voltage	0.45		0.25	0.45	0.45		V	$V_{CC} = 4.75 \text{ V}$ $*V_{DIFF} = 2.0 \text{ V}$ $V_{EE} = -10.5 \text{ V}$ $I_{OL} = 14.1 \text{ mA}$
$V_{OH}$	Output High Voltage	2.9	3.0		3.3	2.9		V	$V_{CC} = 4.75 \text{ V}$ $*V_{DIFF} = 1.0 \text{ V}$ $V_{EE} = -9.5 \text{ V}$ $I_{OH} = -0.2 \text{ mA}$
$I_{CEX}$	Output Leakage Current	80		100		200		$\mu\text{A}$	$V_{CC} = 4.75 \text{ V}$ $*V_{DIFF} = 1.0 \text{ V}$ $V_{EE} = -10.5 \text{ V}$ $V_{CEX} = 5.25 \text{ V}$
$I_{SC}$	Output Shorted Current	-1.3	-3.1	-1.4	-2.15	-3.2	-1.3	-3.1	mA $V_{CC} = 5.0 \text{ V}$ $*V_{DIFF} = 1.0 \text{ V}$ $V_{EE} = -10 \text{ V}$ $V_{SC} = 0 \text{ V}$
$I_{R(ENABLE)}$	Enable Input Leakage Current			5		10		$\mu\text{A}$	$V_{CC} = 4.75 \text{ V}$ $S_3 = 4.75 \text{ V}$ $V_{EE} = -10.5 \text{ V}$ $V_R = 4.0 \text{ V}$
$I_{F(ENABLE)}$	Enable Input Forward Current	-1.5		-0.96		-1.5		mA	$V_{CC} = 5.25 \text{ V}$ $S_3 = 0 \text{ V}$ $V_{EE} = -9.5 \text{ V}$ $V_F = 0 \text{ V}$
$I_{F(+ \text{ Input})}$	+ Input Forward Current	-2.6		-1.67		-2.4		mA	$V_{CC} = 5.0 \text{ V}$ - Input = Gnd $V_{EE} = -10 \text{ V}$ $V_F = 0 \text{ V}$
$I_{F(- \text{ Input})}$	- Input Forward Current	-2.9		-1.87		-2.7		mA	$V_{CC}, S_3 = 5.0 \text{ V}$ + Input = Gnd $V_{EE} = -10 \text{ V}$ $V_F = 0 \text{ V}$
$V_{IL(ENABLE)}$	Input Low Voltage	1.2		1.4		1.0		V	$V_{CC} = 5.0 \text{ V} \pm 5\%$ $V_{EE} = -10 \text{ V} \pm 5\%$
$V_{th}$	Differential Input Threshold Voltage	1.0	2.0	1.0	1.5	2.0	1.0	2.0	V $V_{CC} = 5.0 \text{ V} \pm 5\%$ $V_{EE} = -10 \text{ V} \pm 5\%$
$V_{CM}$	Common Mode Voltage	-7.5		$\pm 12$		+7.5		V	$V_{CC} = 5.0 \text{ V}$ $V_{EE} = -10 \text{ V}$ $*V_{DIFF} = 1.0 \text{ V or } 2.0 \text{ V}$
$R_{130\Omega}$	Terminating Resistance			91	130	185		$\Omega$	
$I_{CC}$	5 V Supply Current			13.7		22.9		mA	$V_{CC} = 5.25 \text{ V}$ $S_3, + \text{Inputs} = 5.25 \text{ V}, - \text{Inputs} = 0 \text{ V}$
$I_{EE}$	-10 V Supply Current			-6.5		-11.1		mA	$V_{CC} = 5.25 \text{ V}$ $S_3, + \text{Inputs} = 5.25 \text{ V}, - \text{Inputs} = 0 \text{ V}$
$t_{pd+}$	Turn-off Time			38		100		ns	$V_{CC} = 5.0 \text{ V}$ $V_{EE} = -10 \text{ V}$ $V_{IN} 0 \rightarrow 3.0 \text{ V}, R_L = 3.9 \text{ k}\Omega, C_L = 30 \text{ pF}$
$t_{pd-}$	Turn-on Time			35		100		ns	$V_{CC} = 5.0 \text{ V}$ $V_{EE} = -10 \text{ V}$ $V_{IN} 0 \rightarrow 3.0 \text{ V}, R_L = 0.39 \text{ k}\Omega, C_L = 30 \text{ pF}$

\* $V_{DIFF}$  is a differential input voltage referred from A+ to A- and from B+ to B-.

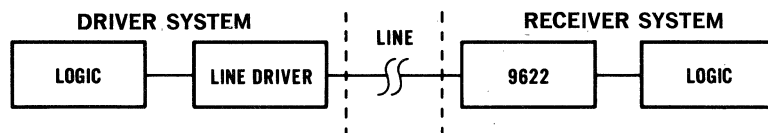
### SWITCHING TIME TEST CIRCUIT



### WAVEFORMS



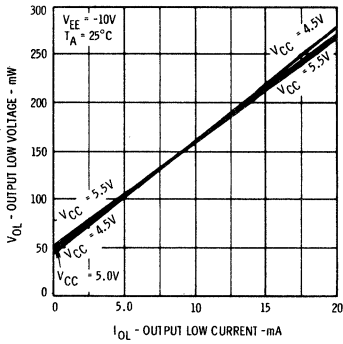
### STANDARD USAGE



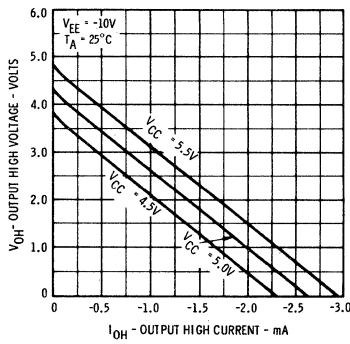
# FAIRCHILD DUAL LINE RECEIVER • 9622

## TYPICAL ELECTRICAL CHARACTERISTICS

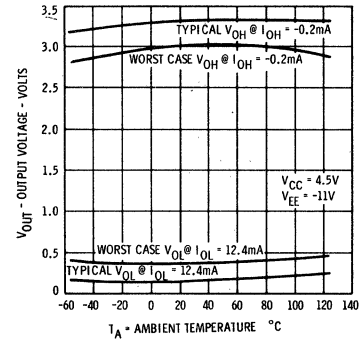
**TYPICAL OUTPUT LOW VOLTAGE VERSUS OUTPUT LOW CURRENT**



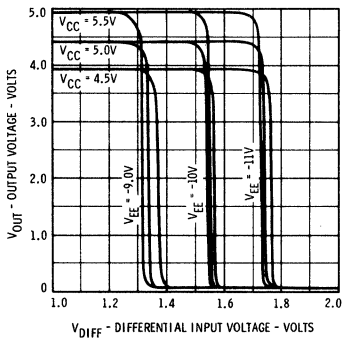
**TYPICAL OUTPUT HIGH VOLTAGE VERSUS OUTPUT HIGH CURRENT**



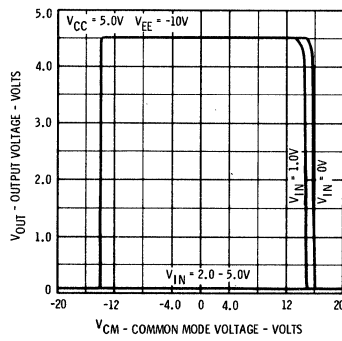
**LOGIC LEVELS VERSUS AMBIENT TEMPERATURE**



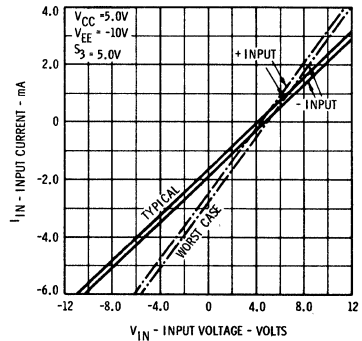
**TYPICAL V\_OUT - V\_DIFF TRANSFER CHARACTERISTICS**



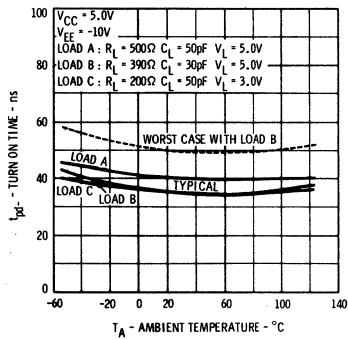
**TYPICAL OUTPUT VOLTAGE VERSUS COMMON MODE VOLTAGE**



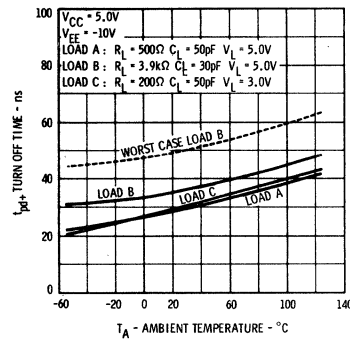
**INPUT CURRENT VERSUS INPUT VOLTAGE**



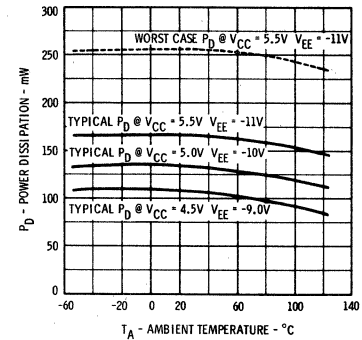
**TURN ON TIME VERSUS AMBIENT TEMPERATURE**



**TURN OFF TIME VERSUS AMBIENT TEMPERATURE**



**POWER DISSIPATION VERSUS AMBIENT TEMPERATURE**



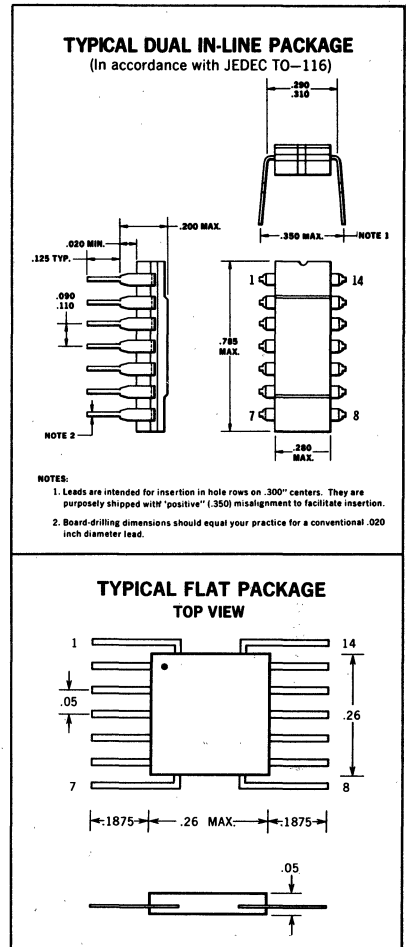
# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC®

## INTEGRATED CIRCUITS COMPOSITE DATA SHEET

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT  
0°C TO 75°C TEMPERATURE RANGE

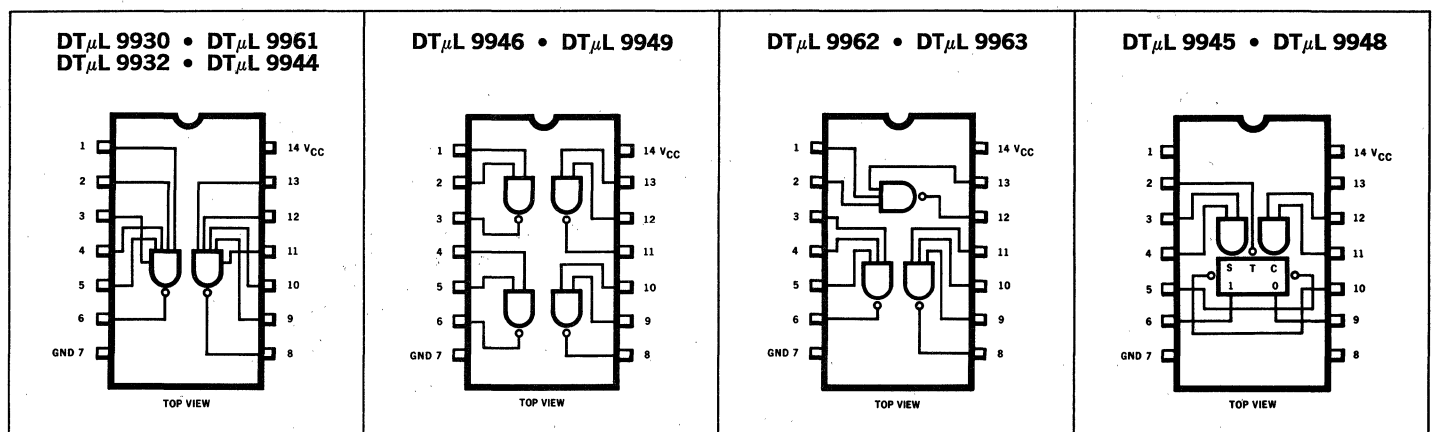
**GENERAL DESCRIPTION** — Fairchild Diode Transistor Micrologic® (DT $\mu$ L) Integrated Circuits family uses diode-transistor logic and is designed specifically for integrated circuit technology. The design of these circuits offers distinctly superior performance. Some of the advantages follow:

- HIGH PERFORMANCE WITH A SINGLE POWER SUPPLY -- 5.0 V
- HIGH NOISE IMMUNITY -- 1.0 V
- HIGH FAN-OUT CAPABILITY -- 8-25
- GATES WITH 6 k OR 2 k PULL-UP RESISTORS FOR OPTIMUM SPEED
- FAN-OUT AND NOISE IMMUNITY TRADE-OFF
- LOW POWER DISSIPATION -- 8.5 mW/GATE
- GATE OUTPUTS CAN BE TIED TOGETHER FOR THE "WIRED OR" FUNCTION



**ORDER INFORMATION** — To order Diode Transistor Micrologic® Integrated Circuits elements specify U31XXXX59X for Flat package and U6AXXX59X for Dual In-Line\* package where XXXX is 9930, 9932 etc.

**PIN CONFIGURATION: IDENTICAL FOR DUAL-IN-LINE AND FLAT PACKAGES**



\*Fairchild Patent Pending

**FAIRCHILD**  
SEMICONDUCTOR  
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION

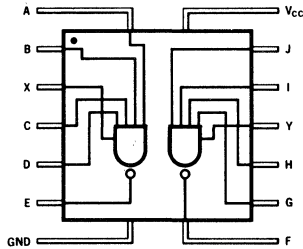
313 FAIRCHILD DRIVE, MOUNTAIN VIEW, CALIFORNIA, (415) 962-5011, TWX: 910-379-6435

# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® I.C.

## DT $\mu$ L GATES

All DT $\mu$ L gates are positive logic NAND gates or negative logic NOR gates. A variety of gate combinations is available which provides the system designer the utmost in logic flexibility and reduces package requirements to a minimum. Gate outputs may be paralleled to perform OR (collector) logic. In addition, gates may be cross-connected to form flip-flops, exclusive OR, etc. Gates with 2 k $\Omega$  pull-up resistors offer improved propagation delay times.

### LOGIC DIAGRAM



POSITIVE (NAND) LOGIC

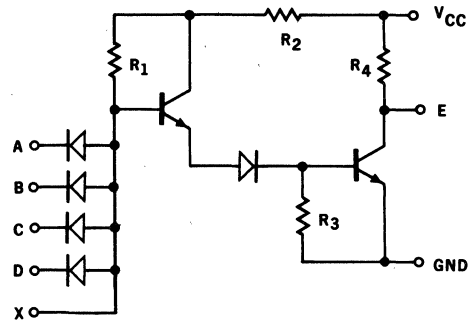
$$E = \overline{A \cdot B \cdot C \cdot D \cdot X}$$

$$F = \overline{G \cdot H \cdot I \cdot J \cdot Y}$$

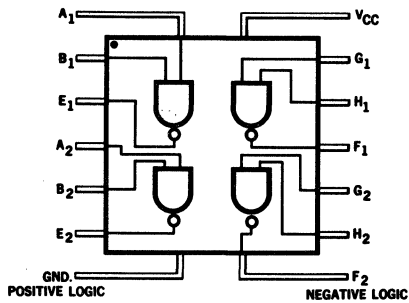
### SCHEMATIC DIAGRAM — ONE GATE ONLY

DT $\mu$ L 9930 • DT $\mu$ L 9961

**TYPICAL RESISTOR VALUES**  
 $R_1 = 2.00k \Omega$   
 $R_2 = 1.75k \Omega$   
 $R_3 = 5.00k \Omega$   
 $R_4 = 6.00k \Omega$  (9930)  
 $R_4 = 2.00k \Omega$  (9961)



### LOGIC DIAGRAM



POSITIVE (NAND) LOGIC

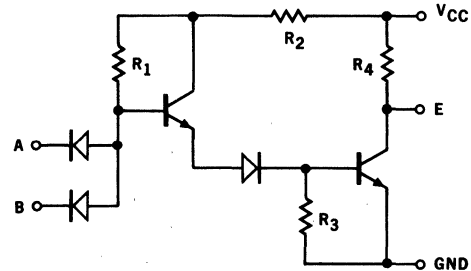
$$E = \overline{A \cdot B}$$

$$F = \overline{G \cdot H}$$

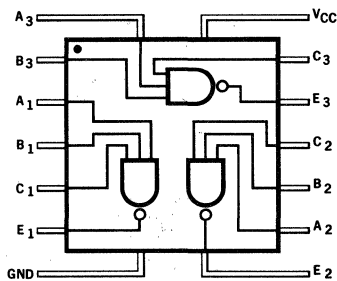
### SCHEMATIC DIAGRAM — ONE GATE ONLY

DT $\mu$ L 9946 • DT $\mu$ L 9949

**TYPICAL RESISTOR VALUES**  
 $R_1 = 2.00k \Omega$   
 $R_2 = 1.75k \Omega$   
 $R_3 = 5.00k \Omega$   
 $R_4 = 6.00k \Omega$  (9946)  
 $R_4 = 2.00k \Omega$  (9949)



### LOGIC DIAGRAM



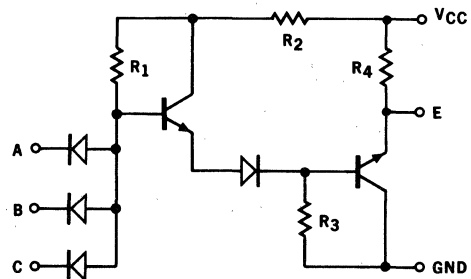
POSITIVE (NAND) LOGIC

$$E = \overline{A \cdot B \cdot C}$$

### SCHEMATIC DIAGRAM — ONE GATE ONLY

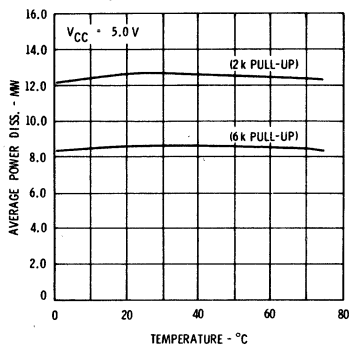
DT $\mu$ L 9962 • DT $\mu$ L 9963

**TYPICAL RESISTOR VALUES**  
 $R_1 = 2.00k \Omega$   
 $R_2 = 1.75k \Omega$   
 $R_3 = 5.00k \Omega$   
 $R_4 = 6.00k \Omega$  (9962)  
 $R_4 = 2.00k \Omega$  (9963)

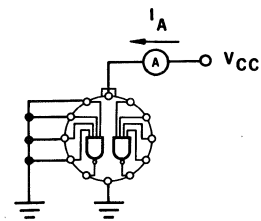


# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® I.C.

**AVERAGE POWER DISSIPATION  
VERSUS TEMPERATURE  
(TYPICAL EACH GATE)**

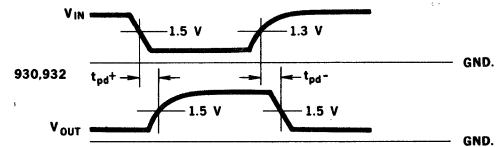
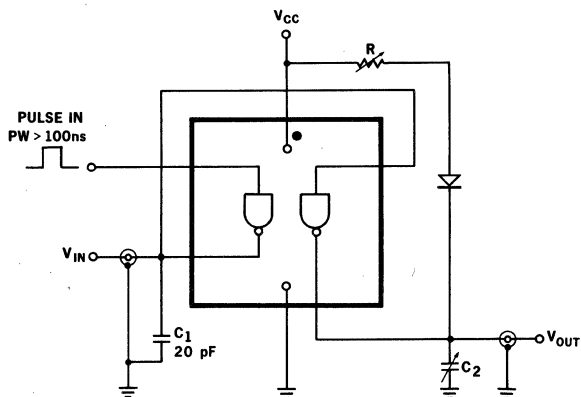


**TEST CONDITIONS**



$$\text{AV. POWER DRAIN} = \frac{V_{CC} I_A}{2}$$

**TYPICAL  $T_{pd}$  TEST CIRCUIT DT $\mu$ L GATES**

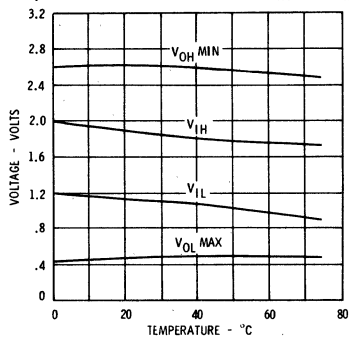


$T_{pd}$  — will be read from input at 1.3 V  
( $V_{CC} = 5\text{ V}, T = 25^\circ\text{C}$ )

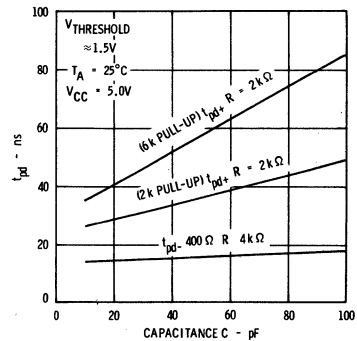
	R	C <sub>2</sub>	Min.	Max.
(6 k Pull-up)	$t_{pd+}$ 3.9k $\Omega$	30 pF	25 ns	80 ns
(6 k & 2 k Pull-up)	$t_{pd-}$ 400 $\Omega$	50 pF	10 ns	30 ns
(2 k Pull-up)	$t_{pd+}$ 3.9k $\Omega$	30 pF	15 ns	50 ns

**OPERATING VOLTAGE  
CHARACTERISTICS**

**WORST CASE** ( OUTPUT LOGIC LEVEL —  $V_{OH}$  AND  $V_{OL}$   
INPUT THRESHOLD LEVELS —  $V_{IH}$  AND  $V_{IL}$  )



**TIME DELAY VERSUS  
CAPACITIVE LOADS**





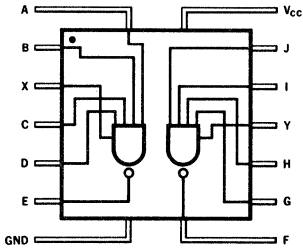
# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® I.C.

## DT $\mu$ L 9932 BUFFER ELEMENT

## DT $\mu$ L 9944 POWER GATE

The DT $\mu$ L 9932 is a dual 4-input inverting driver. It features an emitter-follower pull-up which provides a high fan-out device with superior capacitance-driving capability. The DT $\mu$ L 9944 has an output with no internal pull-up. This provides a high fan-out device whose outputs may be tied together to perform the "wired OR" function. The 9944 is useful as an interface driver or as a low-power lamp driver. The fan-in of either element may be extended with the use of the DT $\mu$ L 9933.

### LOGIC DIAGRAM

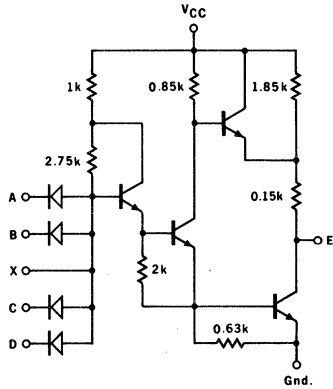


#### POSITIVE (NAND) LOGIC

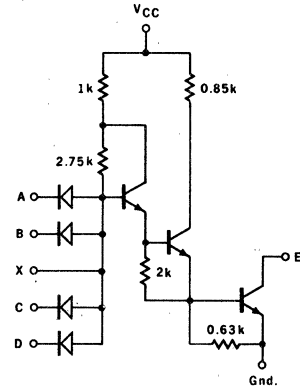
$$E = \overline{A \cdot B \cdot C \cdot D} \cdot (\overline{X})$$

$$F = \overline{G \cdot H \cdot I \cdot J} \cdot (\overline{Y})$$

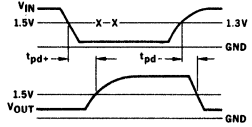
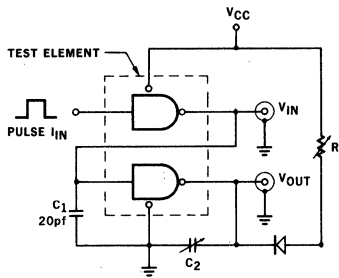
### SCHEMATIC DIAGRAM OF THE DT $\mu$ L 9932 ELEMENT (ONE SIDE ONLY)



### SCHEMATIC DIAGRAM OF THE DT $\mu$ L 9944 ELEMENT (ONE SIDE ONLY)



### tpd TEST CIRCUIT FOR DT $\mu$ L 9932 ELEMENT

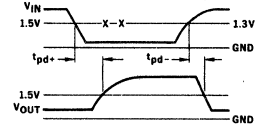
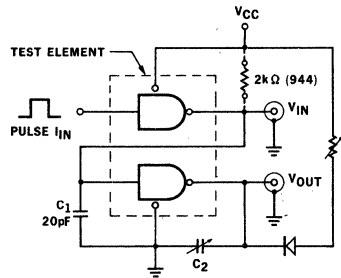


All Diodes are FD600 or Equivalent at 25°C  
C<sub>1</sub> and C<sub>2</sub> includes Probe and Jig Capacitance

$$(V_{CC} = 5.0 \text{ V}, T_A = 25^\circ\text{C})$$

		R	C	Min.	Max.
t <sub>pd+</sub>	9932	510 Ω	500 pF	25 ns	80 ns
t <sub>pd-</sub>	9932	150 Ω	500 pF	15 ns	40 ns

### tpd TEST CIRCUIT FOR DT $\mu$ L 9944 ELEMENT

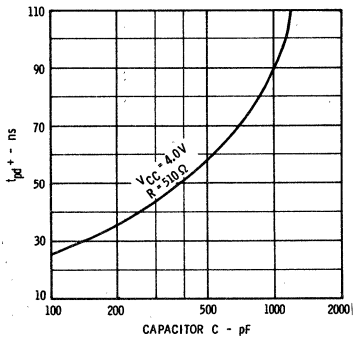


C<sub>1</sub> and C<sub>2</sub> includes Probe and Jig Capacitance

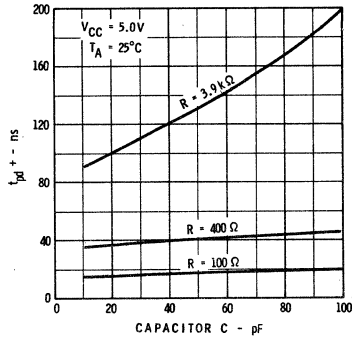
$$(V_{CC} = 5.0 \text{ V}, T_A = 25^\circ\text{C})$$

		R	C	Min.	Max.
t <sub>pd+</sub>	9944	510 Ω	20 pF	15 ns	50 ns
t <sub>pd-</sub>	9944	150 Ω	100 pF	10 ns	35 ns

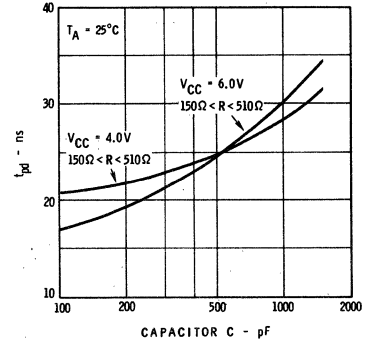
### TYPICAL t<sub>pd+</sub> VERSUS CAPACITY (9932)



### TYPICAL t<sub>pd+</sub> VERSUS CAPACITY (9944)



### TYPICAL t<sub>pd-</sub> VERSUS CAPACITY (9932, 9944)



# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® I.C.

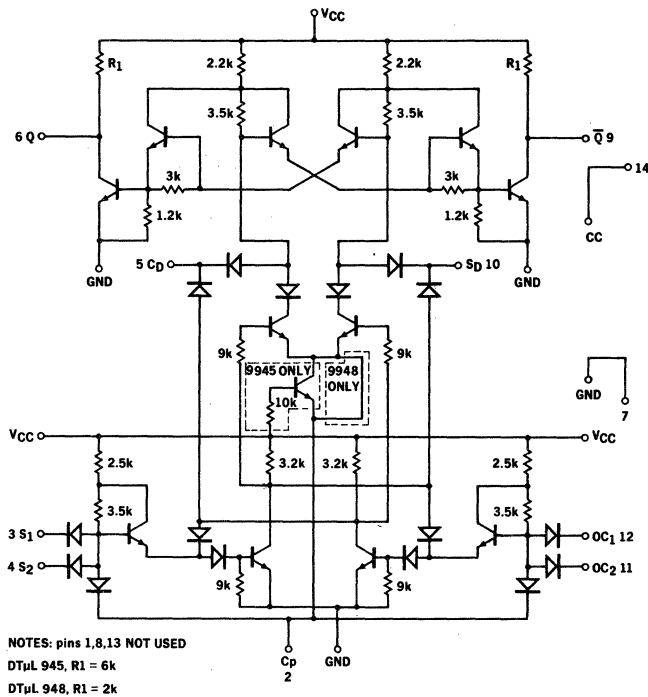
## DT $\mu$ L 9945 • DT $\mu$ L 9948 - CLOCKED FLIP FLOP

The DT $\mu$ L 9945 and DT $\mu$ L 9948 Clocked Flip-Flops are directly-coupled units operating on the "master-slave" principle. Information enters the "master" while the Trigger input voltage is high and transfers to the "slave" when the Trigger input voltage goes low. Since operation depends only on voltage levels, any sort of waveshape having the proper voltage levels may be used as a trigger signal. Rise and fall times are irrelevant.

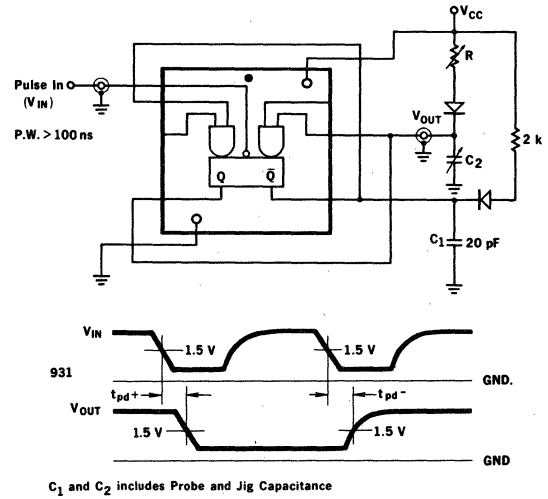
The DT $\mu$ L 9945 and DT $\mu$ L 9948 have an improved direct Set and Clear design which allows unhampered asynchronous entry irrespective of signals applied to any other inputs. The direct inputs always take precedence, thus simplifying the design of arbitrarily preset ripple-counters and other minimum hardware applications.

Output buffers provide isolation between the "slave" and the output load, thereby enhancing immunity to signal line noise. The DT $\mu$ L 9945 incorporates the standard 6 k $\Omega$  output pull-up resistor, while the DT $\mu$ L 9948 features a 2 k $\Omega$  output pull-up resistor for improved rise times, and matched delay between rising and falling outputs for capacitive loading up to 100 pF.

**SCHEMATIC DIAGRAM**



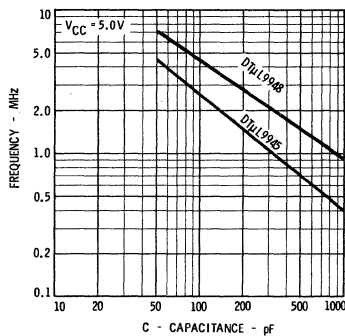
**tpd TEST CIRCUIT**



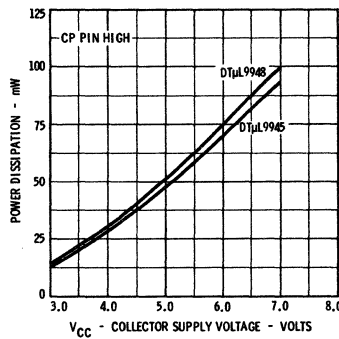
( $V_{CC} = 5V, T = 25^\circ C$ )

		R	C <sub>2</sub>	Min.	Max.
t <sub>pd+</sub>	9945	2.00 k	30 pF	35 ns	75 ns
t <sub>pd-</sub>	9945	330 $\Omega$	30 pF	35 ns	75 ns
t <sub>pd+</sub>	9948	2.00 k	30 pF	20 ns	65 ns
t <sub>pd-</sub>	9948	330 $\Omega$	30 pF	30 ns	75 ns

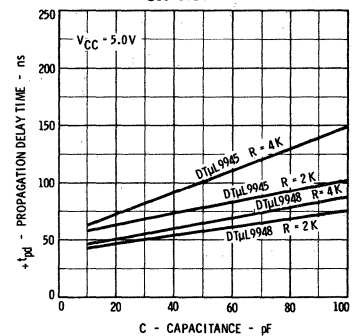
**TYPICAL MAXIMUM BINARY COUNTING RATE VERSUS CAPACITY**



**TYPICAL POWER DISSIPATION VERSUS V<sub>CC</sub>**



**TYPICAL tpd VERSUS CAPACITANCE**

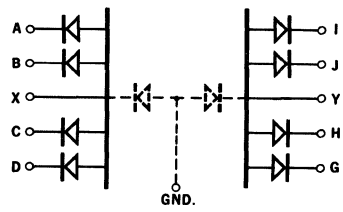
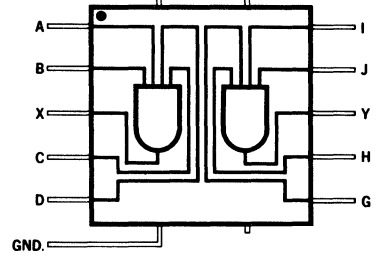
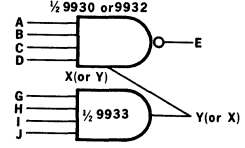
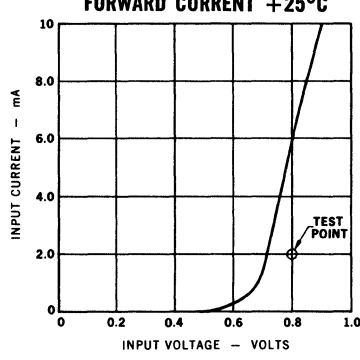


# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® I.C.

## DT $\mu$ L 9933 EXTENDER

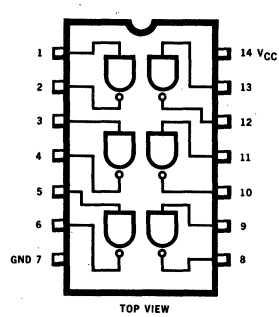
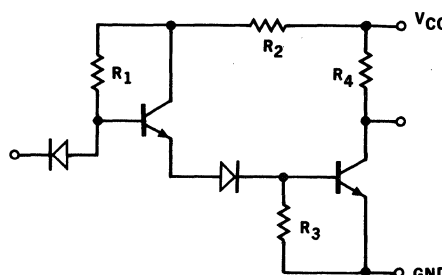
The DT $\mu$ L 9933 is a Dual Input-Extender consisting of two independent diode arrays identical in every respect to the input diodes of the DT $\mu$ L Gate and Buffer elements. Good practice dictates that extension interconnection paths be as short as possible to minimize the effects of distributed capacitance on circuit performance.

Typical input capacitance of DT $\mu$ L 9933 is 2 pF, output capacitance is 5 pF.

<p style="text-align: center;"><b>SCHEMATIC DIAGRAM</b></p> 	<p style="text-align: center;"><b>FLAT PACKAGE LAYOUT</b></p> 
<p style="text-align: center;"><b>LOGIC EXAMPLE</b></p>  <p style="margin-top: 10px;"> <b>POSITIVE LOGIC</b> <math>E = A B C D G H I J</math>  <b>NEGATIVE LOGIC</b> <math>E = A + B + C + D + G + H + I + J</math> </p>	<p style="text-align: center;"><b>FORWARD VOLTAGE VERSUS FORWARD CURRENT +25°C</b></p> 

## DT $\mu$ L 9936 • DT $\mu$ L 9937 - HEX INVERTER

The DT $\mu$ L 9936 hex inverter has input-output characteristics identical to the other DT $\mu$ L gates. Inverters can be cross-connected to form flip-flops or the outputs can be paralleled to perform the "wired OR" function.

<p style="text-align: center;"><b>DT<math>\mu</math>L 9936 • DT<math>\mu</math>L 9937</b></p>  <p style="text-align: center; font-size: small;">TOP VIEW</p>	<p style="text-align: center;"><b>SCHEMATIC DIAGRAM — ONE INVERTER ONLY</b> DT<math>\mu</math>L 9936 • DT<math>\mu</math>L 9937</p>  <div style="margin-top: 20px;"> <p><b>TYPICAL RESISTOR VALUES</b></p> <ul style="list-style-type: none"> <li><math>R_1 = 2.00k \Omega</math></li> <li><math>R_2 = 1.75k \Omega</math></li> <li><math>R_3 = 5.00k \Omega</math></li> <li><math>R_4 = 6.00k \Omega</math> (9936)</li> <li><math>R_4 = 2.00k \Omega</math> (9937)</li> </ul> </div>
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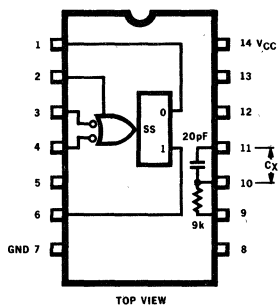
## DT $\mu$ L 9951 - MONOSTABLE MULTIVIBRATOR

The DT $\mu$ L 9951 is an integrated monostable multivibrator designed for use with other members of the DT $\mu$ L family. It provides complementary output pulses which are typically 100 ns wide. This pulse width is adjustable by the addition of external components.

### ABSOLUTE MAXIMUM RATINGS (above which useful life may be impaired)

Supply Voltage ( $V_{CC}$ ), -55°C to +125°C, continuous:	+8.0 Volts
Supply Voltage ( $V_{CC}$ ); pulsed, <1 second:	+12 Volts
Output Current, into outputs:	50 mA
Current into Pin 10	5.0 mA
Input Forward Current	-10 mA
Input Reverse Current	1.0 mA

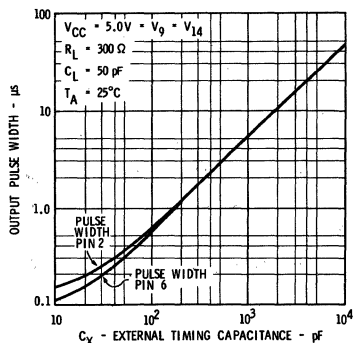
DT $\mu$ L 9951



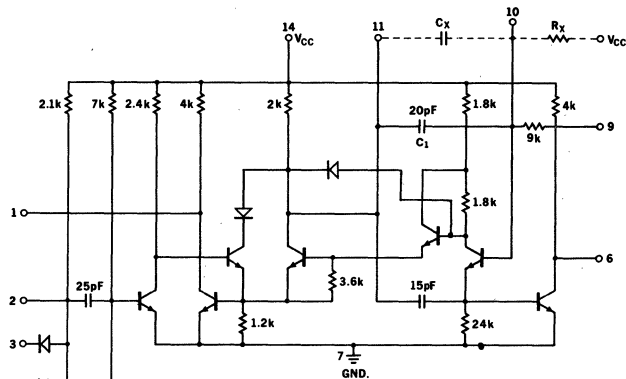
### INPUT-OUTPUT LOAD FACTORS TO DT $\mu$ L FAMILY

Each DT $\mu$ L 9951 input should be rated at 2 loads.  
Each DT $\mu$ L 9951 output may drive 10 DT $\mu$ L loads.

### OUTPUT PULSE WIDTH VERSUS EXTERNAL TIMING CAPACITANCE $C_x$



### SCHEMATIC DIAGRAM



### RULES FOR USE OF DT $\mu$ L 9951

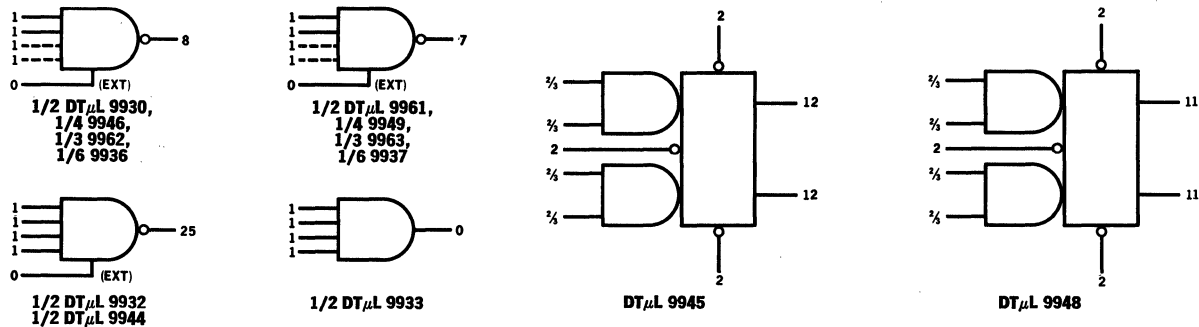
1. With Pin 9 connected to  $V_{CC}$  and no external capacitor ( $C_x$ ), the output pulse width is approximately 100 ns.
2. With Pin 9 connected to  $V_{CC}$  and an external capacitor ( $C_x$ ) connected between Pins 10 and 11, the output pulse width (T) is:  
 $T \approx 4.5 (C_x + 20)$  with  $C_x$  in pF and T in ns.
3. For improved pulse width control, Pin 9 is left open and a stable external resistor ( $R_x$ ) of 9 k $\Omega$  minimum to 15 k $\Omega$  maximum is connected from Pin 10 to  $V_{CC}$ . The output pulse width is given by the expression:  $T \approx 0.5 R_x (C_x + 20)$  with  $R_x$  in k $\Omega$ ,  $C_x$  in pF and T in ns.
4. The output duty cycle (pulse width/period) should not exceed 40%. It may be increased to 50% by adding a 2 k $\Omega$  resistor between Pin 11 and  $V_{CC}$ . Higher duty cycles are obtainable but the output pulse width and performance are less predictable.
5. The maximum input fall time to trigger: 25 ns for a 1.0-volt swing; 50 ns for a 2.0 volt swing; 100 ns for a 4.0-volt swing.
6. The AC sensitivity of the inputs may be decreased by connecting a capacitor between Pin 5 and ground.
7. The minimum pulse width at output Pin 1 is approximately 100 ns. This pulse width may be decreased to 50 ns by connecting a 10 k $\Omega$  resistor between Pin 5 and  $V_{CC}$ .

# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® I.C.

## ABSOLUTE MAXIMUM RATINGS (above which useful life may be impaired)

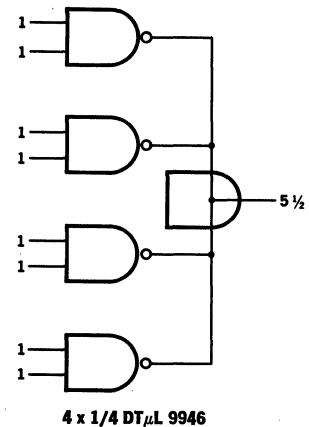
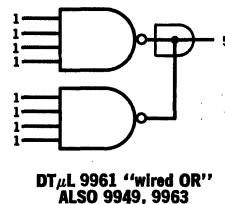
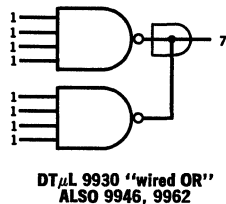
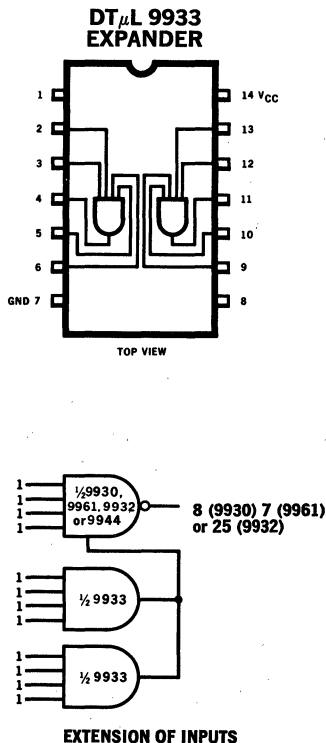
Supply Voltage ( $V_{CC}$ ), $-55^{\circ}\text{C}$ to $125^{\circ}\text{C}$ , continuous	+8.0 Volts	Input Forward Current	-10 mA
Supply Voltage ( $V_{CC}$ ), pulsed, <1 second	+12 Volts	Input Reverse Current	1.0 mA
Output Current, into outputs		Operating Temperature	$0^{\circ}\text{C}$ to $+75^{\circ}\text{C}$
DT $\mu\text{L}$ 9932 & 9944	100 mA	Storage Temperature	$-65^{\circ}\text{C}$ to $+150^{\circ}\text{C}$
DT $\mu\text{L}$ , except 9932 & 9944	30 mA		

## INPUT-OUTPUT LOADING FACTORS



The number of elements that may be driven by an output terminal may consist of any combination of elements whose summation of input loading does not exceed the output terminal driving capability.

## RULES FOR INPUT EXPANSION AND "WIRED OR" CONNECTION



### RULES

1. Outputs of DT $\mu\text{L}$  gates with 6 k $\Omega$  pull-up resistors, 9930, 9946, and 9962 may be tied together for the "wired OR" function. Subtract 1 unit fan-out for each added gate. Subtract 5 fan-outs for 6 added gates.
2. Outputs of DT $\mu\text{L}$  gates with 2 k $\Omega$  pull-up resistors, 9949, 9961, and 9963 may be tied together for the "wired OR" function. Subtract 2 units of fan-out for each added gate.
3. Outputs of DT $\mu\text{L}$  9932 may not be tied together for the "wired OR" function.

# DT $\mu$ L9935 HEX INVERTER

DIODE-TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS

A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

## GENERAL DESCRIPTION

The 9935 is an expandable CCSL Hex Inverter. It consists of six DT $\mu$ L gates without input diodes which are expandable by using external diodes or by using the DT $\mu$ L 9933 Dual 4-Input Extender element. It is ideal for a wide variety of applications, including one-shot multivibrators, latching circuits, flip-flops, adders, registers, counters, decoders and many more.

## FEATURES

- Expandable Inputs
- Wired-OR Capability
- The input/output characteristics provide easy interfacing with Fairchild LPDT $\mu$ L, TT $\mu$ L and MSI families (CCSL).
- All ceramic "HERMETIC" 14-pin Dual In-Line and CERPAK packages

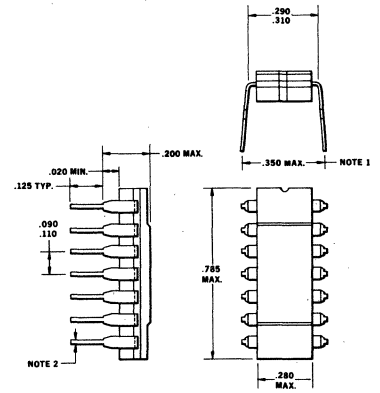
## ABSOLUTE MAXIMUM RATINGS (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +8V
Input Voltage	-1.5V to Input Diode Breakdown
Voltage Applied to Outputs (Inputs Low)	-0.5V to V <sub>CC</sub> Value
Current Into Output When Output is Low	30 mA

## ORDER INFORMATION

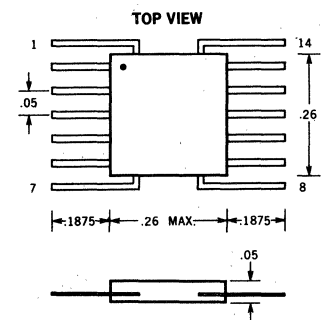
Specify U3I99355XX for flat package and U6A99355XX for Dual-In-Line package, where 5XX is 51X for -55°C to +125°C temperature range or 59X for the 0°C to +75°C temperature range.

### TYPICAL DUAL IN-LINE PACKAGE

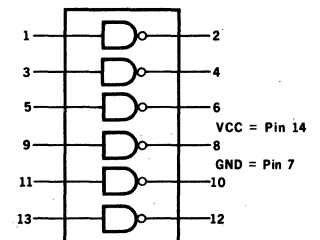


- NOTES:
1. Leads are intended for insertion in hole rows on .300" centers. They are purposely shipped with "positive" (.350) misalignment to facilitate insertion.
  2. Board-drilling dimensions should equal your practice for a conventional .020 inch diameter lead.

### TYPICAL FLAT PACKAGE



### LOGIC DIAGRAM



# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS

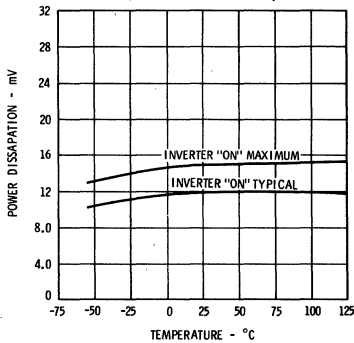
## ELECTRICAL CHARACTERISTICS

SYMBOL	CHARACTERISTIC	-55°C			+25°C			+125°C			UNITS	CONDITIONS & COMMENTS $V_{CC} = 5.0 \text{ V} \pm 10\%$
		MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX		
$V_{OH}$	Output High Voltage	2.6			2.6	3.3		2.5			Volts	$V_{CC} = 4.5 \text{ V}$ , $I_{OH} = -180 \mu\text{A}$ $V_{IL}$ = Value indicated on this Table
$V_{OL}$	Output Low Voltage			0.4		0.3	0.4			0.4	Volts	$V_{CC} = 5.5 \text{ V}$ , $I_{OL} = 15 \text{ mA}$ $V_{CC} = 4.5 \text{ V}$ , $I_{OL} = 12 \text{ mA}$
$V_{IH}$	Input High Voltage	2.3			2.0			1.8			Volts	Input High Threshold with FD600 on Input
$V_{IL}$	Input Low Voltage			1.4		1.1				0.8	Volts	Input Low Threshold with FD600 on Input
$I_F$	Input Load Current			-1.5		-1.5				-1.5	mA	$V_{CC} = 5.5 \text{ V}$ , $V_F = 0.4$
$I_F$	Input Load Current			-1.2		-1.2				-1.2	mA	$V_{CC} = 4.5 \text{ V}$ , $V_F = 0.4$
$t_{pd+}$	Turn-Off Delay				25	65	80				ns	SEE Figure 4
$t_{pd-}$	Turn-On Delay				10	30	40				ns	SEE Figure 4

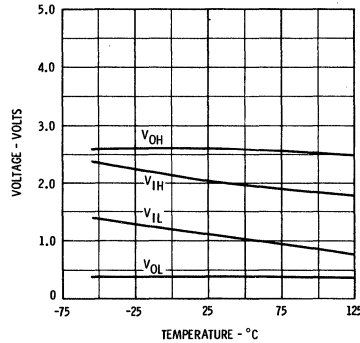
SYMBOL	CHARACTERISTIC	0°C			25°C			75°C			UNITS	CONDITIONS & COMMENTS $V_{CC} = 5.0 \text{ V} \pm 5\%$
		MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX		
$V_{OH}$	Output High Voltage	2.6			2.6			2.5			Volts	$V_{CC} = 4.75 \text{ V}$ , $I_{OH} = -180 \mu\text{A}$ $V_{IL}$ = Value indicated on this Table
$V_{OL}$	Output Low Voltage			0.45		0.45				0.45	Volts	$V_{CC} = 5.25 \text{ V}$ , $I_{OL} = 15.2 \text{ mA}$ $V_{CC} = 4.75 \text{ V}$ , $I_{OL} = 13.3 \text{ mA}$
$V_{IH}$	Input High Voltage	2.1			2.0			1.85			Volts	Input High Threshold with FD600 on Input
$V_{IL}$	Input Low Voltage			1.2		1.1				0.95	Volts	Input Low Threshold with FD600 on Input
$I_F$	Input Load Current			-1.52		-1.52				-1.52	mA	$V_{CC} = 5.25 \text{ V}$ , $V_F = 0.45$
$I_F$	Input Load Current			-1.33		-1.33				-1.33	mA	$V_{CC} = 4.75 \text{ V}$ , $V_F = 0.45$
$t_{pd+}$	Turn-Off Delay				25	65	80				ns	SEE FIGURE 4
$t_{pd-}$	Turn-On Delay				10	30	40				ns	SEE FIGURE 4

## CURVES FOR -55°C TO +125°C TEMPERATURE RANGE

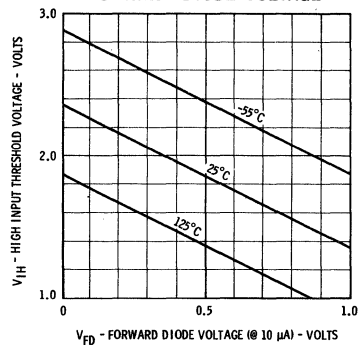
**WORST CASE POWER DISSIPATION VERSUS TEMPERATURE (EACH INVERTER)**



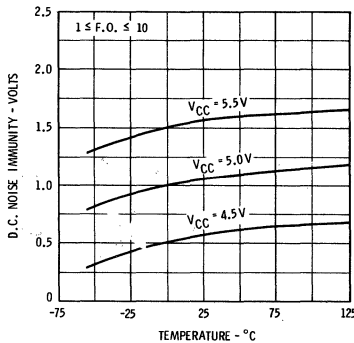
**WORST CASE OPERATING VOLTAGE CHARACTERISTICS**



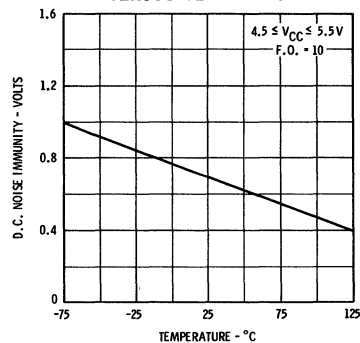
**$V_{IH}$  THRESHOLD VERSUS FORWARD DIODE VOLTAGE**



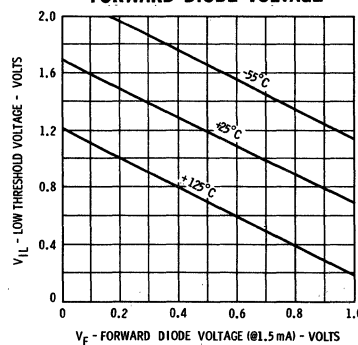
**WORST CASE HIGH LEVEL NOISE IMMUNITY VERSUS TEMPERATURE**



**WORST CASE LOW LEVEL NOISE IMMUNITY VERSUS TEMPERATURE**



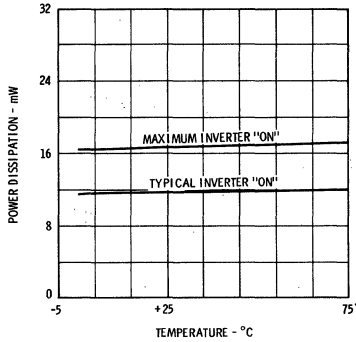
**$V_{IL}$  THRESHOLD VERSUS FORWARD DIODE VOLTAGE**



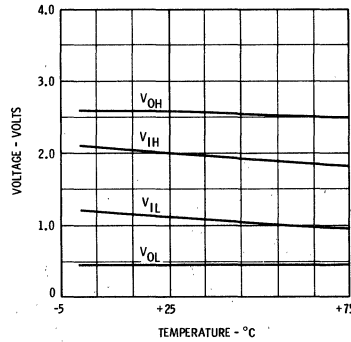
# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS

## CURVES FOR 0°C TO +75°C TEMPERATURE RANGE

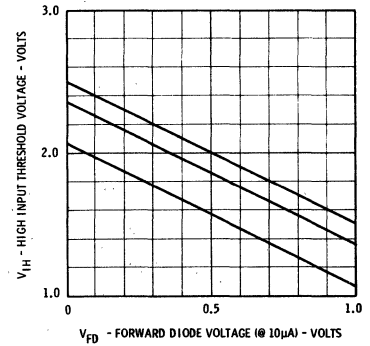
**WORST CASE POWER DISSIPATION VERSUS TEMPERATURE (PER INVERTER)**



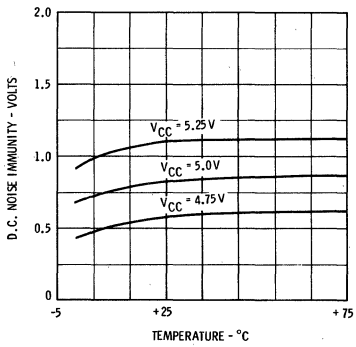
**WORST CASE OPERATING VOLTAGE CHARACTERISTICS**



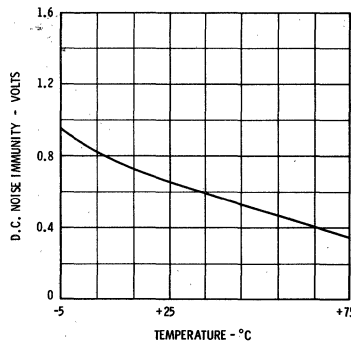
**V<sub>IH</sub> THRESHOLD VERSUS FORWARD DIODE VOLTAGE**



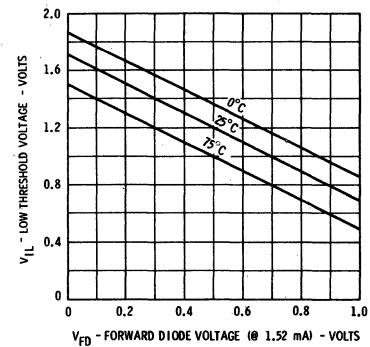
**WORST CASE HIGH LEVEL NOISE IMMUNITY**



**WORST CASE LOW LEVEL NOISE IMMUNITY VERSUS TEMPERATURE**

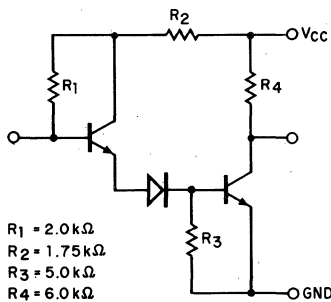


**V<sub>IL</sub> THRESHOLD VERSUS FORWARD DIODE VOLTAGE**



**FIG. 1**

**SCHEMATIC DIAGRAM (ONE INVERTER ONLY)**



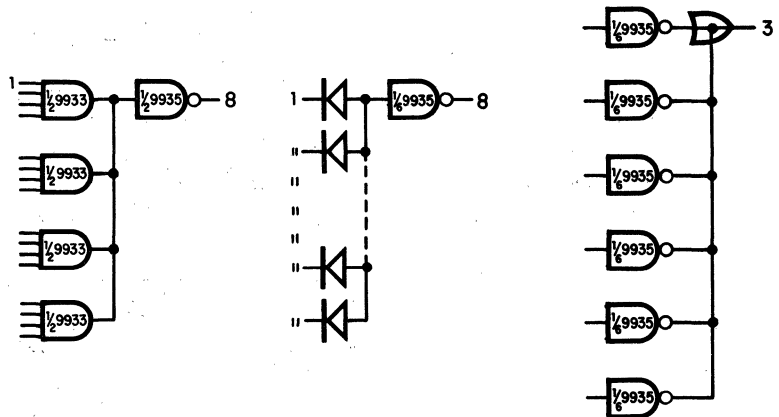
**FIG. 2**

**LOADING RULES**

OUTPUT STATE	FANOUT	
	51X	59X
HIGH	10	10
LOW	10	10

**FIG. 3**

**RULES FOR INPUT EXPANSION AND "WIRED OR" CONNECTION**



6 x 1/6 9935 "WIRED OR" For the "WIRED OR" function - Subtract 1 unit fan-out for each added gate. Subtract 5 fan-outs for 6 added gates.

### EXPANSION OF INPUTS

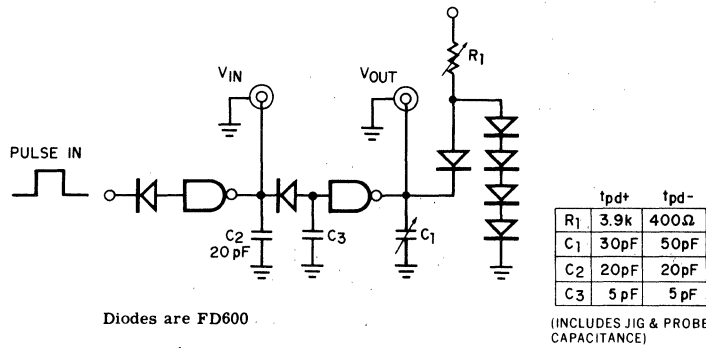
Typical input capacitance of the 9933 is 2.0 pF and output capacitance is 5.0 pF. All wiring should be kept as possible to minimize effects of distributed capacitance on circuit performance. Use FD600 or equivalent expansion.



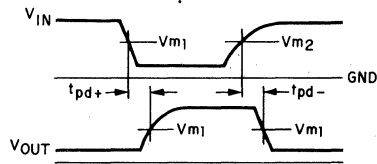
# FAIRCHILD DIODE-TRANSISTOR MICROLOGIC® INTEGRATED CIRCUITS

**FIG. 4**

**SWITCHING TIME TEST CIRCUIT**



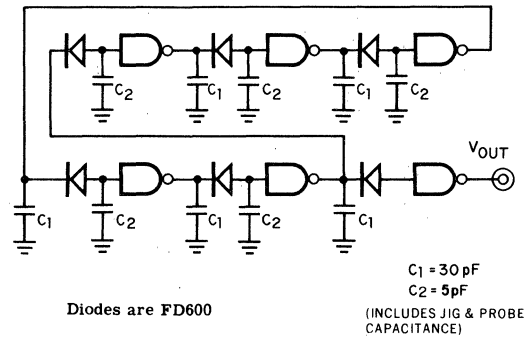
Diodes are FD600



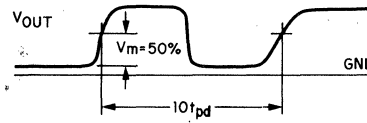
TEMP	Vm1 (VOLTS)	Vm2 (VOLTS)
-55°C	1.7	1.5
+25°C	1.5	1.3
+125°C	1.3	1.1

**FIG. 5**

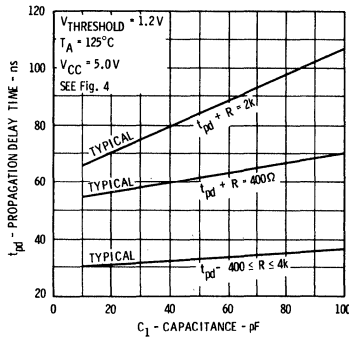
**RING CIRCUIT FOR MEASURING AVERAGE PROPAGATION DELAY**



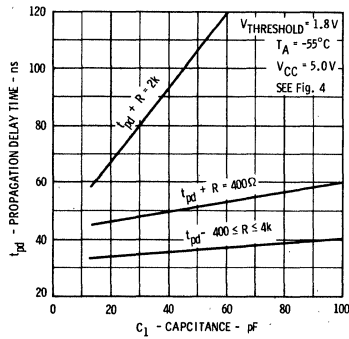
Diodes are FD600



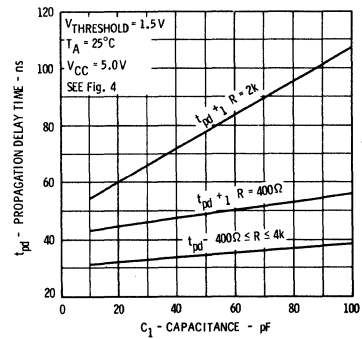
**PROPAGATION DELAY VERSUS CAPACITANCE AT +125°C**



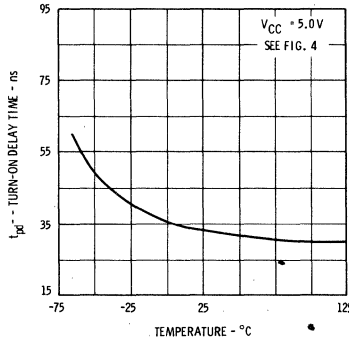
**PROPAGATION DELAY VERSUS CAPACITANCE AT +25°C**



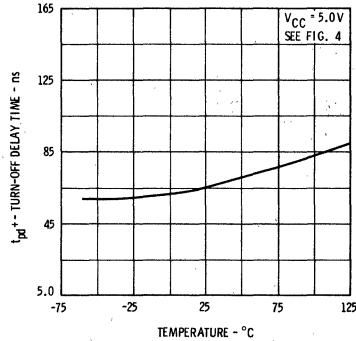
**PROPAGATION DELAY VERSUS CAPACITANCE AT -55°C**



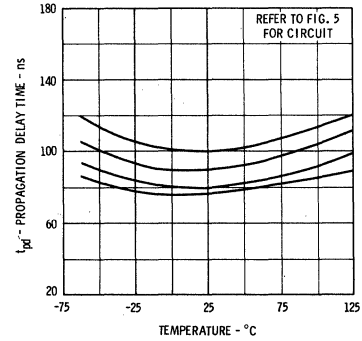
**TYPICAL TURN-ON DELAY (t<sub>pd-</sub>) VERSUS TEMPERATURE**



**TYPICAL TURN-OFF DELAY (t<sub>pd+</sub>) VERSUS TEMPERATURE**



**MAXIMUM PROPAGATION DELAY VERSUS TEMPERATURE**



**FAIRCHILD**  
**SEMICONDUCTOR**  
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION

# DT $\mu$ L 9941 • DT $\mu$ L 9951

## MONOSTABLE MULTIVIBRATORS

DIODE-TRANSISTOR MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS (TEMPERATURE RANGE: -55°C to 125°C)

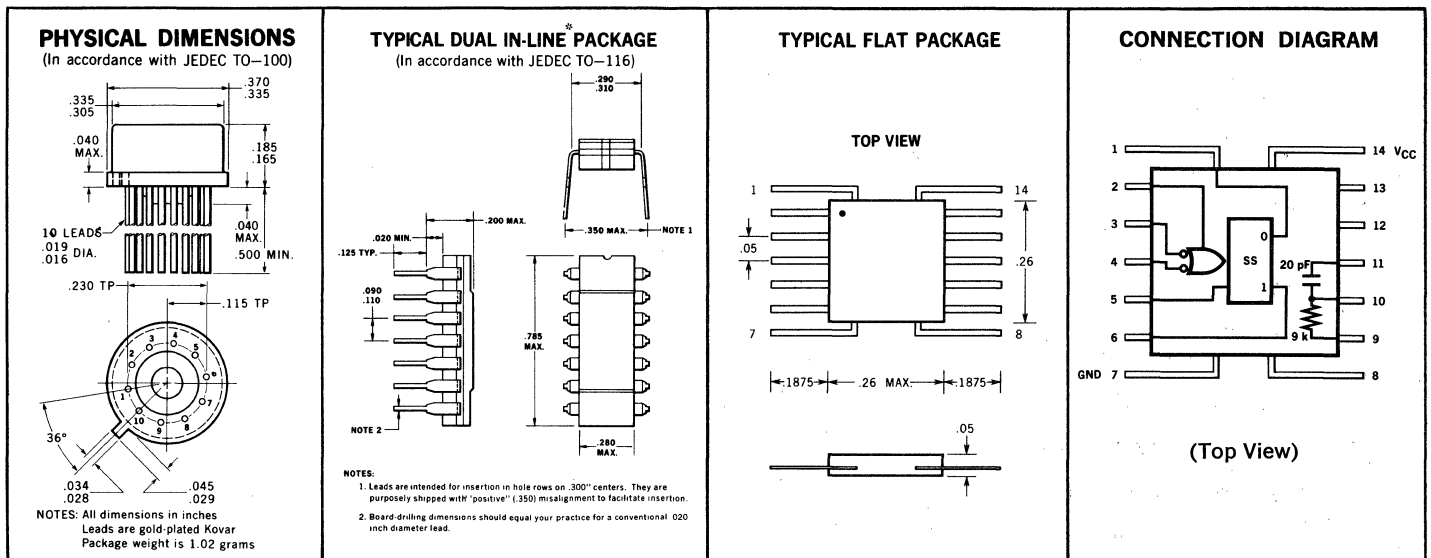
A FAIRCHILD COMPATIBLE CURRENT SINKING LOGIC PRODUCT

**GENERAL DESCRIPTION** — The DT $\mu$ L 9941 and DT $\mu$ L 9951 Monostable Multivibrators are monolithic silicon epitaxial integrated circuits for use with Fairchild Diode-Transistor Micrologic<sup>®</sup> Integrated Circuits or any other similar DTL logic elements. They provide complementary output pulses which are typically 150 ns wide. This pulse width is adjustable by the addition of external discrete passive components.

Both elements are compatible with the Fairchild DT $\mu$ L Family over the full military temperature range of -55°C to +125°C and with a V<sub>CC</sub> supply of 4.0 volts to 6.0 volts. They can also drive and be driven by Fairchild  $\mu$ L<sup>®</sup> Integrated Circuit.

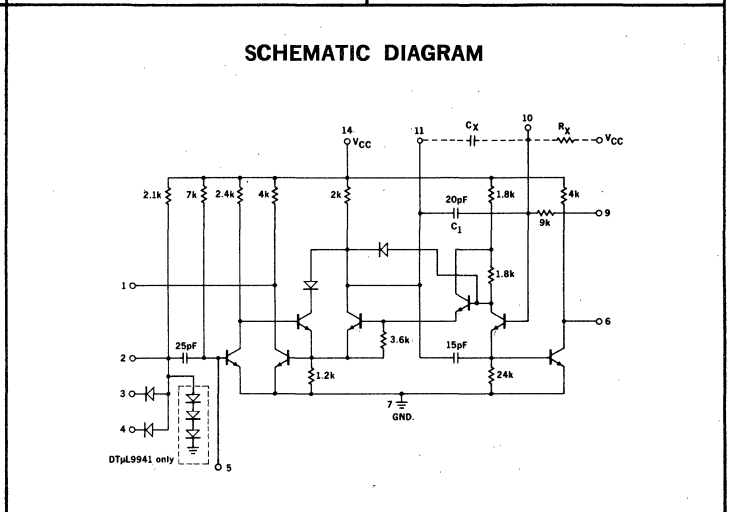
The output pulse width is very stable as either V<sub>CC</sub> or temperature (or both) is varied when an external timing resistor is used instead of the internal diffused resistor.

The DT $\mu$ L 9941 has the same circuit as the DT $\mu$ L 9951 with the addition of three series diodes from the extender pin (Pin 2) to ground. These diodes give the DT $\mu$ L 9941 a DC threshold of about 1.5V which gives the circuit a greater than 2.0V noise immunity.



**ABSOLUTE MAXIMUM RATINGS** (above which useful life may be impaired)

Supply Voltage (V <sub>CC</sub> ) -55°C to +125°C, continuous:	+8.0 Volts
Supply Voltage (V <sub>CC</sub> ), pulsed, <1 second:	+12 Volts
Output Current, into outputs	50 mA
Current into Pin 10	5.0 mA
Input Forward Current	-10 mA
Input Reverse Current	1.0 mA
Operating Temperature	-55°C to +125°C
Storage Temperature	-65°C to +150°C



\*Fairchild Patent Pending

# FAIRCHILD DT $\mu$ L INTEGRATED CIRCUITS 9941 • 9951

## TEST SEQUENCE

Test No.	CERPAK Pin no.: TO-100 Pin no.:	FORCING FUNCTIONS											Note 1 Sense	Limits	
		5	1	2	3	4	6	7	9	10	11	14		Min.	Max.
1				V <sub>F</sub>			GND					V <sub>CCH</sub>	I <sub>2</sub>	.5 I <sub>F</sub>	
2				V <sub>F</sub>	V <sub>R</sub>		GND					V <sub>CCH</sub>	I <sub>3</sub>	.5 I <sub>F</sub>	2 I <sub>F</sub>
3	Note 2			V <sub>R</sub>	V <sub>F</sub>		GND					V <sub>CCH</sub>	I <sub>4</sub>	.5 I <sub>F</sub>	2 I <sub>F</sub>
4							GND			V <sub>F</sub>		V <sub>CCH</sub>	I <sub>11</sub>	.5 I <sub>F</sub>	
5			GND	V <sub>R</sub>			GND					V <sub>CCH</sub>	I <sub>3</sub>		I <sub>R</sub>
6	Note 2		GND		V <sub>R</sub>		GND					V <sub>CCH</sub>	I <sub>4</sub>		I <sub>R</sub>
7			I <sub>OL</sub>				GND		GND			V <sub>CCL</sub>	V <sub>i</sub>		V <sub>OL</sub>
8		GND					GND	V <sub>CCL</sub>				V <sub>CCL</sub>	V <sub>i</sub>		V <sub>OL</sub>
9						I <sub>OL</sub>	GND	V <sub>CCL</sub>				V <sub>CCL</sub>	V <sub>6</sub>		V <sub>OL</sub>
10		I <sub>OH</sub>	GND				GND	V <sub>CCL</sub>				V <sub>CCL</sub>	V <sub>i</sub>	V <sub>OH</sub>	
11						I <sub>OH</sub>	GND		GND			V <sub>CCL</sub>	V <sub>6</sub>	V <sub>OH</sub>	
12							GND	V <sub>CCH</sub>	GND			V <sub>CCH</sub>	I <sub>9</sub>	I <sub>9K</sub>	I <sub>9K</sub>
13				GND	GND		GND	V <sub>PD</sub>				V <sub>PD</sub>	I <sub>9+</sub> I <sub>14</sub>		I <sub>PDL</sub>
14				GND	GND		GND					V <sub>MAX</sub>	I <sub>14</sub>		I <sub>MAX</sub>
15							GND	V <sub>CCH</sub>				V <sub>CCH</sub>	V <sub>2</sub>	V <sub>2L</sub>	V <sub>2H</sub>
16	t <sub>pd-</sub> Pin 1						See Test Circuit, page 3							50 ns	
17	t <sub>pd+</sub> Pin 6						See Test Circuit, page 3							50 ns	
18	Pulse width Pin 1 (DT $\mu$ L9951)						See Test Circuit, page 3						90	220 ns	
19	Pulse width Pin 6 (DT $\mu$ L9951)						See Test Circuit, page 3						70	160 ns	
20	Pulse width Pin 1 (DT $\mu$ L9941)												90	330 ns	
21	Pulse width Pin 6 (DT $\mu$ L9941)												70	270 ns	

TABLE OF FORCING CONDITIONS

		-55°C	25°C	+125°C
V <sub>CCH</sub>	Volts	5.5	5.5	5.5
V <sub>CCL</sub>	Volts	4.5	4.5	4.5
V <sub>PD</sub>	Volts		5.0	
V <sub>MAX</sub>	Volts		8.0	
V <sub>R</sub>	Volts		4.0	
V <sub>F</sub>	Volts	0.0	0.0	0.0
I <sub>OL</sub>	mA	15.0	15.0	14.0
I <sub>OH</sub>	mA	-.18	-.18	-.18

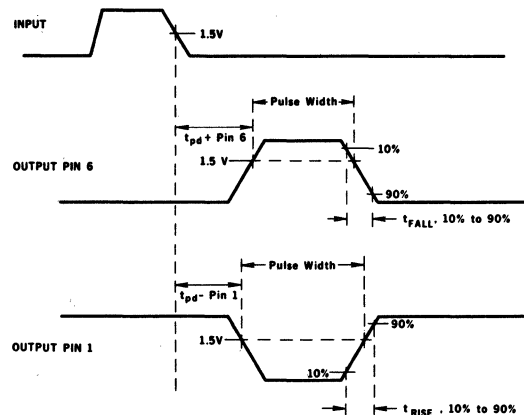
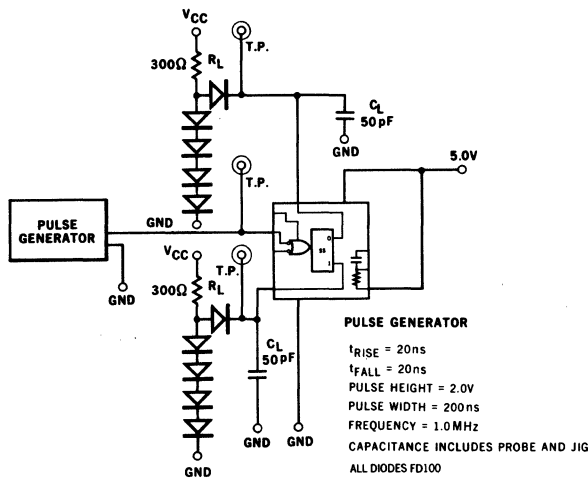
TABLE OF TEST LIMITS

		-55°C		25°C		+125°C	
		Min.	Max.	Min.	Max.	Min.	Max.
.5I <sub>F</sub>	mA	-.80		-.80		-.75	
2I <sub>F</sub>	mA		-3.20		-3.20		-3.0
I <sub>R</sub>	$\mu$ A				5.0		10.0
V <sub>OL</sub>	Volts		.40		.40		.45
V <sub>OH</sub>	Volts	2.5		2.5		2.5	
I <sub>9K</sub>	mA			.50	.75		
I <sub>PDL</sub>	mA				9.0		
I <sub>MAX</sub>	mA				22.0		
V <sub>2H</sub> (9951)	Volts			5.0			
V <sub>2L</sub> (9941)	Volts				2.5		

## PURCHASING INFORMATION

To order the elements specify U31XXX51X for Flat Package, U5FXXX51X for TO-100 and U6AXXX51X for Dual-In-Line package (TO-116) where XXXX is the four-digit number denoting the specific element desired.

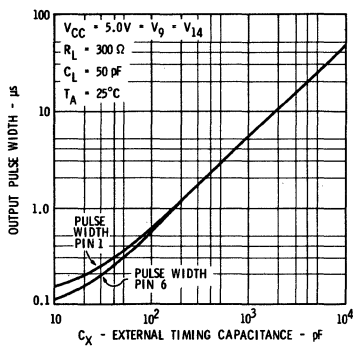
SWITCHING TIME TEST CIRCUIT AND WAVEFORMS



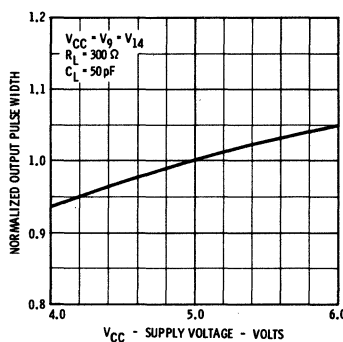
TIMING CHARACTERISTICS

(Test circuit above is used with appropriate modifications where necessary)

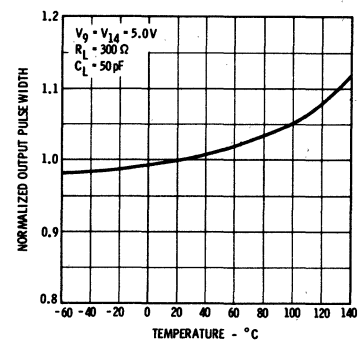
OUTPUT PULSE WIDTH VERSUS EXTERNAL TIMING CAPACITANCE  $C_X$



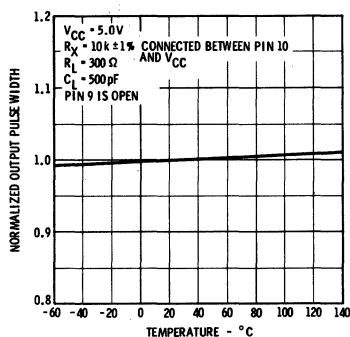
NORMALIZED OUTPUT PULSE WIDTH VERSUS SUPPLY VOLTAGE



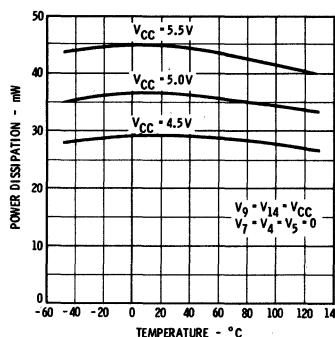
NORMALIZED OUTPUT PULSE WIDTH VERSUS TEMPERATURE



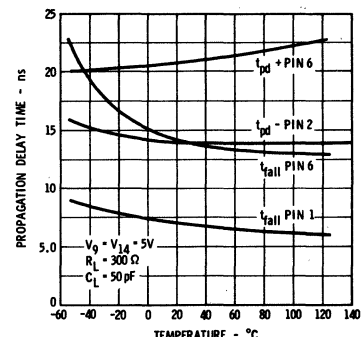
NORMALIZED OUTPUT PULSE WIDTH VERSUS TEMPERATURE USING EXTERNAL TIMING RESISTOR  $R_X$



TYPICAL POWER DISSIPATION VERSUS TEMPERATURE



SWITCHING TIMES VERSUS TEMPERATURE



# FAIRCHILD DT $\mu$ L INTEGRATED CIRCUITS 9941 • 9951

## RULES FOR USE OF DT $\mu$ L 9941 AND DT $\mu$ L 9951

1. With Pin 9 connected to  $V_{CC}$  and no external capacitor ( $C_x$ ), the output pulse width is approximately 150 ns.
2. With Pin 9 connected to  $V_{CC}$  and an external capacitor ( $C_x$ ) connected between Pins 10 and 11, the output pulse width ( $T$ ) is:  $T \approx 4.5 (C_x + 20)$  with  $C_x$  in pF and  $T$  in ns.
3. For improved pulse width control, Pin 9 is left open and a stable external resistor ( $R_x$ ) of 9 k $\Omega$  minimum to 15 k $\Omega$  maximum is connected from Pin 10 to  $V_{CC}$ . The output pulse width is given by the expression:  $T \approx 0.5R_x (C_x + 20)$  with  $R_x$  in k $\Omega$ ,  $C_x$  in pF and  $T$  in ns.
4. The output duty cycle (pulse width/period) should not exceed 40%. It may be increased to 50% by adding a 2 k $\Omega$  resistor between Pin 11 and  $V_{CC}$ . Higher duty cycles are obtainable but the output pulse width and performance are less predictable.
5. The maximum input fall time to trigger: 25 ns for a 1.0 volt swing; 50 ns for a 2.0 volt swing; 100 ns for a 4.0 volt swing.
6. The minimum pulse width at output Pin 1 is approximately 100 ns. This pulse width may be decreased to 50 ns by connecting a 10 k $\Omega$  resistor between Pin 5 and  $V_{CC}$ .

## USE OF DT $\mu$ L 9941 AND DT $\mu$ L 9951 WITH MICROLOGIC<sup>®</sup> INTEGRATED CIRCUITS

The DT $\mu$ L 9951 may be operated from a  $V_{CC}$  supply of 4.0 to 6.6 volts. Operation is essentially independent of output resistive and capacitive loading. The input triggering action is initiated by a negative-going input with an amplitude change of 1.0 volt or more. The DT $\mu$ L 9941 requires the input to go at least one volt below its 1.5 V threshold.

RT $\mu$ L and Low Power RT $\mu$ L outputs can drive the DT $\mu$ L 9941 and DT $\mu$ L 9951 inputs, provided the output swing is greater than 1.0 volt. Either of the outputs of the DT $\mu$ L 9941 and DT $\mu$ L 9951 can drive RT $\mu$ L and Low Power RT $\mu$ L inputs. Fan-out from the DT $\mu$ L 9941 and DT $\mu$ L 9951 is 4 RT $\mu$ L unit loads and 1 Low Power RT $\mu$ L unit load, for the DT $\mu$ L 9941 and DT $\mu$ L 9951  $V_{CC} \geq 4.0$  volts. Use of a resistor of 500 $\Omega$  to 1k $\Omega$  from the DT $\mu$ L 9941 and DT $\mu$ L 9951 output to  $V_{CC}$  will increase fan-out into Low Power RT $\mu$ L, or RT $\mu$ L.

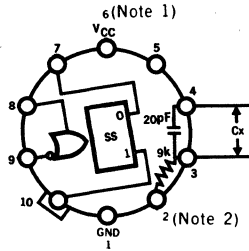
## INPUT-OUTPUT LOAD FACTORS TO DT $\mu$ L FAMILY

Each DT $\mu$ L 9941 and DT $\mu$ L 9951 input should be rated at 2 loads.

Each DT $\mu$ L 9941 and DT $\mu$ L 9951 output may drive 10 DT $\mu$ L loads.

For input-output load factors of other DT $\mu$ L elements, please refer to the DT $\mu$ L Composite Data Sheet and to the individual DT $\mu$ L element specifications.

## TO-100 TYPE CONNECTION DIAGRAM (Top View)

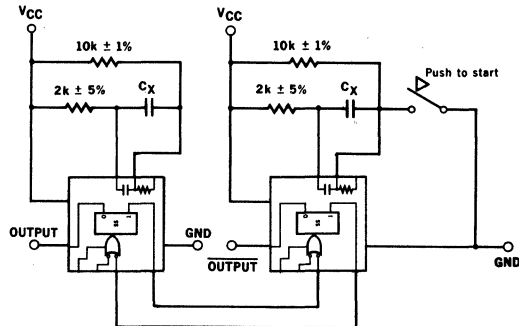


### NOTES:

- (1) The  $V_{CC}$  supply pin is not the tabbed pin on the DT $\mu$ L 9951.
- (2) Connect to  $V_{CC}$  when R external is not used.

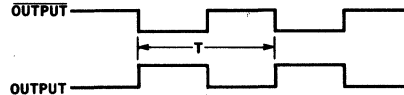
All data in this specification refers to 14-pin Cerpak pin numbers except this outline and the 10-pin reference numbers in the test sequence on Page 2.

## STABLE MULTIVIBRATOR

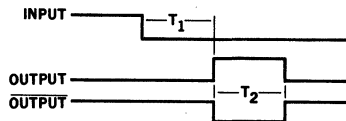
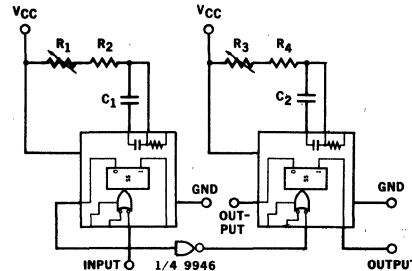


$$\frac{1}{\text{oscillation}} = T = \frac{(20+C_x)}{100} \text{ MICROSECONDS}$$

$C_x$  IN PICOFARADS



## VARIABLE DELAY PULSE GENERATION



### Explanation

The input 9951 determines  $T_1$ , the time before the initiation of the output pulse. The second or output 9951 determines  $T_2$ , the output pulse width.

With  $R_2 = 10$  k $\Omega$  and  $R_1$  a 5 k $\Omega$  potentiometer,  $T_1$  is variable over a range of 2 to 3 and is given by  $T_1 \approx 0.5 (R_1 + R_2) (C_1 + 20 \text{ pF})$ .

Similarly, with  $R_4 = 10$  k $\Omega$  and  $R_3$  a 5 k $\Omega$  potentiometer,  $T_2$  is  $\approx 0.5 (R_3 + R_4) (C_2 + 20 \text{ pF})$  and  $T_2$  can be controlled by the potentiometer over a range of 2 to 3 since  $10 \text{ k}\Omega \leq (R_3 + R_4) \leq 15 \text{ k}\Omega$ .

A much greater range in  $T_1$  and  $T_2$  is available by varying  $C_1$  and  $C_2$ .

# COMPATIBLE CURRENT SINKING LOGIC COMING SOON

Type	Function	Type	Function
4600/4700	TT $\mu$ L Micromatrix™ Array	<b>Radiation Resistant Devices</b>	
4610	Dual Two-Variable Function Generator	9702	TTL Gate, Quad 2-Input
TT $\mu$ L9014	Quad Exclusive OR Gate	9703	TTL Gate, Triple 3-Input
MSI9306	BCD Up/Down Counter	9704	TTL Gate, Dual 4-Input
MSI9308	Dual 4-Bit Latch	9705	TTL Gate, Dual Exclusive OR
MSI9310	Decade Counter	9706	TTL Extender, Dual 4-Input
MSI9311	1-of-16 Decoder	9707	TTL Gate, Single 8-Input
MSI9315	One of Ten Decoder/Driver	9709	TTL Buffer, Dual 4-Input
MSI9316	Hexadecimal Counter	9724	TTL Flip Flop, Single J-K
MSI9317	7-Segment Decoder/Driver	9745	DTL Flip Flop, R-S Clocked
MSI9326	Up/Down Binary Counter	9969	DTL Gate, Triple 3-Input
CCSL9644	High Current/High Voltage Driver		

## 4600/4700 — TT $\mu$ L MICROMATRIX™ ARRAY

The 4600 is a TT $\mu$ L Micromatrix array consisting of six cells arranged in a 3 x 2 matrix. The cell is made up of two internal and two external gates. Each gate has two 4-way AND's OR'd together and inverted (AOI). The array equivalence is 48 gates.

The 4600 (chip size — 105 x 115) is a monolithic CCSL device. The entire 4600 array (device) is capable of custom interconnection between cells and portions of cells to produce any logic function in any digital logic system. The interconnection, achieved with computer-aided design, is accomplished by using two layers of metallization separated by a dielectric film — the key to LSI.

The 4700 is Fairchild's largest, most complex Micromatrix array. It has twice the gate count of the 4600.

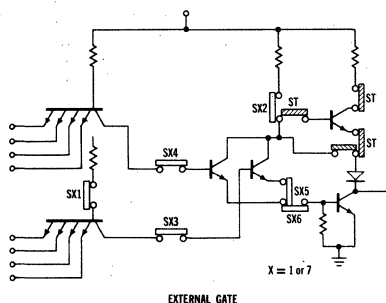
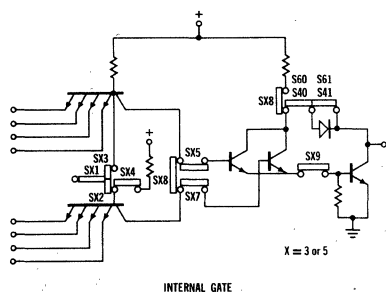
The 4700, a TT $\mu$ L Micromatrix array, consists of 12 cells arranged in a 3 x 4 matrix. The cell is made up of two internal and two external gates. Each gate has two 4-way AND's OR'd together and inverted (AOI). The array equivalence is 96 gates.

The 4700 (chip size — 145 x 145) is a monolithic CCSL device. The entire 4700 array (device) is capable of custom interconnection between cells and portions of cells to produce any logic function in any digital logic system. The interconnection, achieved with computer-aided design, is accomplished by using two layers of metallization separated by a dielectric film — the key to LSI.

The primary application for the 4600/4700 is in circuits used to interconnect basic system building blocks. These arrays are also used as fundamental building blocks; i.e., standard products. The arrays can be packaged in 16, 24, 36, or 50 pin DIP or Flatpak.

To assist evaluation and full exploitation of the interconnection possibilities of the 4600/4700 array, a special design kit is available from all Fairchild distributors.

### 4600/4700 - 1/2 Cell



## 4610 — DUAL TWO-VARIABLE FUNCTION GENERATOR

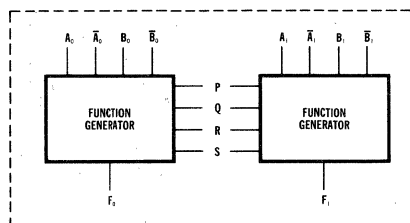
The 4610 consists of two 2-variable function generators, implemented with the 4600 TT $\mu$ L Micromatrix™ array. Each circuit, controlled by a four-bit control word, is capable of performing any possible Boolean function of two variables.

The output function is defined by the four control inputs and two variables. Outputs are available in active high or low states. The unit is useful for performing logic operations in digital machines, and for self-adapting digital systems.

The 4610 will be available in a 16-pin Dual In-Line package.

### FEATURING:

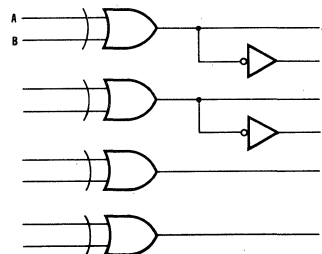
- Active Level Low or High Outputs
- 2-Bit Expansion
- Member 4600 Micromatrix Array Family
- CCSL - Compatible
- Two-Level Metallization



## TT $\mu$ L 9014 QUAD EXCLUSIVE OR GATE

9014 quad exclusive OR gate is a new member of the TT $\mu$ L family. It produces a high output level when the inputs are complementary. Two of the four exclusive OR gates have complementary outputs for greater system design flexibility.

The 9014 will be available in hermetically sealed 16-pin Dual In-Line and Cerpak packages.



## MSI 9306 BCD UP/DOWN COUNTER

The 9306 is a presettable synchronous BCD Up/Down Decade Counter which can be expanded to seven decades without external logic and with no degradation in speed over a single decade.

Presetting is accomplished by synchronously entering, in parallel, the desired data. Counting direction is controlled by a single input. Count-down is enabled by a low input on the C<sub>0</sub> terminal and count-up by a high input.

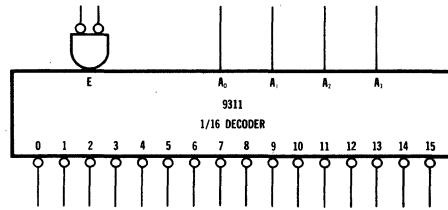
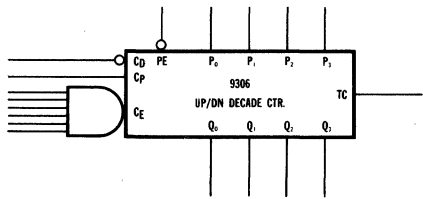
Six enable inputs are provided for terminal carry from all stages in the counter. These inputs may also be used to inhibit the count.

The 9306 will be available in 24-pin Dual In-Line and flat packages.

### FEATURING:

- 15 MHz Seven Decade Operation without External Circuitry
- Synchronous Preset
- Single Line Up/Down Control
- Multifunction Capability

# COMPATIBLE CURRENT SINKING LOGIC COMING SOON



## MSI 9308 DUAL 4-BIT LATCH

The 9308 consists of two 4-bit latch circuits which provide high speed 4-bit parallel gated data storage.

Each 4-bit latch circuit has an active low two-input AND gate which enables the four data inputs. An overriding master reset is also provided on each 4-bit latch circuit.

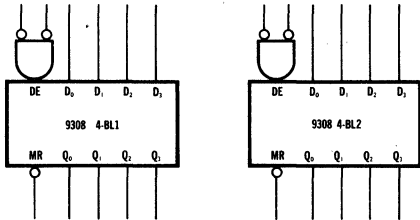
The output circuit incorporates active pull-ups for greater drive capability.

By the use of the enable input, data can be entered into any number of latches from a single bus.

The 9308 will be available in 24-pin Dual In-Line and flat packages.

### FEATURING:

- 25 nsec Latch Time
- Data Input Enable
- Master Reset
- Multifunction Usage



## MSI 9310 DECADE COUNTER

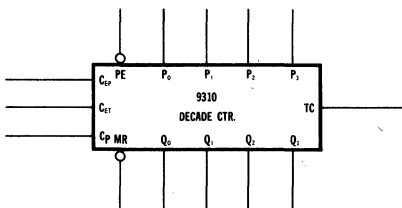
The 9310 is a presettable synchronous BCD Decade Counter which can be expanded to six decades without external logic and with very little degradation in speed over a single decade.

Presetting is accomplished by synchronously entering, in parallel, the desired data. Counting is enabled by HIGHS on the  $C_{EP}$  and  $C_{ET}$  terminals, which can accept terminal count information from previous decades, thus permitting multiple decades without external logic.

The 9310 will be available in 16-pin Dual In-Line and flat packages.

### FEATURING:

- 15 MHz Operation for n Decades
- Synchronous Preset
- Asynchronous Master Reset
- Terminal Count Output
- Count Enable Input



## MSI 9311 1-OF-16 DECODER/DEMULTEPLEXER

The 9311 is a multi-function decoder, designed to convert four digital inputs into one-of-16 mutually exclusive digital outputs.

The active low outputs are enabled by LOWS on both inputs of the enable AND gate. This enabling feature makes the 9311 suitable for demultiplexing, memory, and control decoding applications.

The 9311 will be available in 24-pin Dual In-Line and flat packages.

### FEATURING:

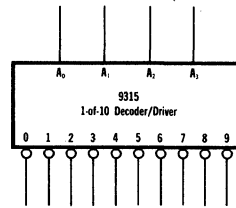
- 20 nsec. Through Delay
- Active Level High
- Input Enable
- Multifunction Capability

## MSI 9315 ONE-OF-TEN DECODER/DRIVER

The 9315 is a CCSL-compatible one-of-ten decoder/driver. The 9315 accepts 8421 BCD code and produces ten mutually exclusive outputs which can directly drive nixie tubes.

The 9315 is similar in operation to the 9960, but the 9315 can be driven from any MSI,  $TT\mu L$ ,  $DT\mu L$ ,  $LPD\mu L$  circuit.

The 9315 will be available in hermetically sealed 16-pin Dual In-Line and Cerpak packages.



## MSI 9316 HEXIDECIMAL COUNTER

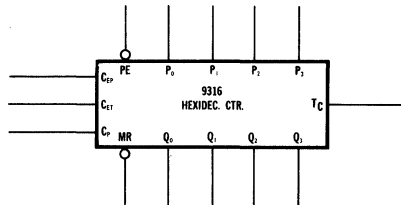
The 9316 is a presettable synchronous binary hexadecimal counter which can be expanded to six stages without external logic and with very little degradation in speed over a single stage.

Presetting is accomplished by synchronously entering, in parallel, the desired data. Counting is enabled by HIGHS on the  $C_{EP}$  and  $C_{ET}$  terminals, which can accept terminal count information from previous decades, thus permitting multiple stages without external logic.

The 9316 will be available in 16-pin Dual In-Line and flat packages.

### FEATURING:

- 15 MHz Operation for N Decades
- Synchronous Preset
- Asynchronous Master Reset
- Terminal Count Output
- Count Enable Input

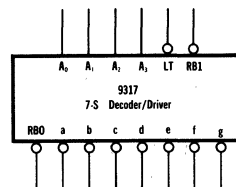


## MSI 9317 7-SEGMENT DECODER/DRIVER

The 9317 is a 7-segment decoder/driver designed to convert four inputs of 8421 BCD code into the appropriate output, which will directly drive a seven-segment numerical display. The outputs are active level low and can drive 25-volt incandescent lamps directly.

The 9317 has all the features of the 9307, including automatic ripple blanking for suppression of leading edge zeros, blanking input, lamp intensity, modulation, lamp test facility, and CCSL compatibility.

The 9317 will be available in hermetically sealed 16-pin Dual In-Line and Cerpak packages.



## COMPATIBLE CURRENT SINKING LOGIC COMING SOON

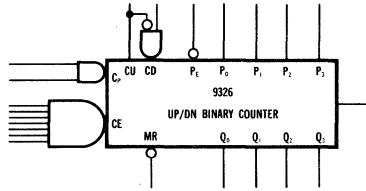
### MSI 9326 UP/DOWN BINARY COUNTER

The 9326 is a presettable synchronous hexadecimal up/down counter which can be expanded to eight decades without external logic and with no significant degradation in speed over one decade.

Presetting is accomplished by synchronously entering, in parallel, the desired data. Counting direction is controlled by a single input. Count-down is enabled by a low input on the  $C_D$  terminal and count-up by a high input.

Six enable inputs are provided for terminal carry from all stages in the counter. These inputs may also be used to inhibit the count.

The 9326 will be available in 24-pin Dual In-Line and flat packages.

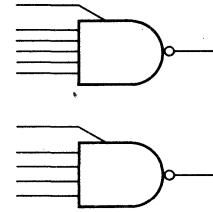


### CCSL 9644 — HIGH-CURRENT/HIGH-VOLTAGE DRIVER

The 9644 is a high current driver with CCSL-compatible inputs. The driver operates from CCSL power supply and has an uncommitted collector that will sink 500 mA and hold off 30 volts.

The 9644 is ideal for driving high current peripheral equipment such as lamps, relays, line printers, etc.

The 9644 will be available in the hermetically sealed 16-lead Dual In-Line package.



## RADIATION-RESISTANT CCSL COMING SOON

### RR CCSL

1. Fairchild will release a radiation resistant CCSL product series during 1968. The devices will incorporate state of the out dielectric isolation construction in conjunction with thin film resistor technologies. The particular RR CCSL products selected will have identical electrical specifications and flatpak pin assignments as their junction isolated counterparts.

2. Those devices to be available are as follows:

#### RR CCSL

#### FUNCTION

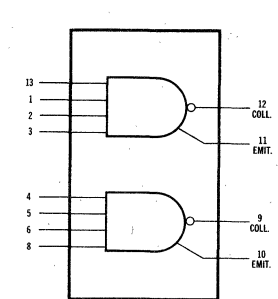
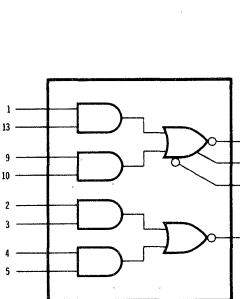
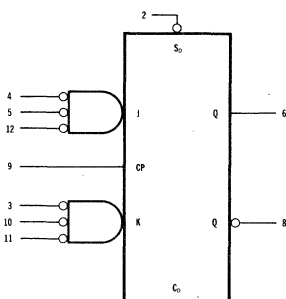
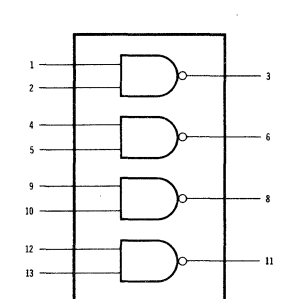
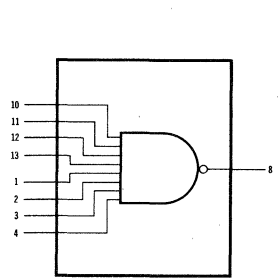
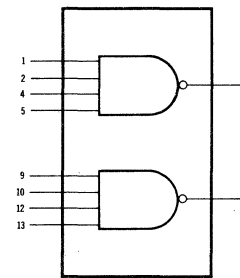
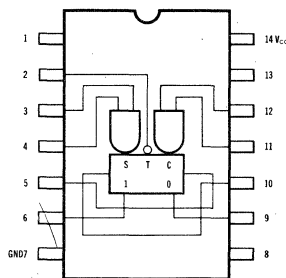
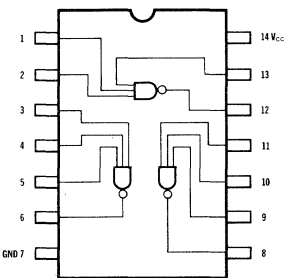
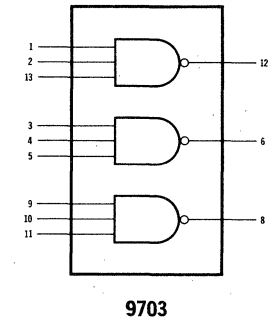
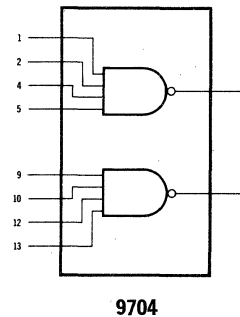
9969	DTL gate, Triple 3 input
9745	DTL flip flop, R-S clocked
9702	TTL gate, Quad 2 input
9724*	TTL flip flop, Single J-K
9704	TTL gate, Dual 4 input
9703	TTL gate, Triple 3 input
9709	TTL buffer, Dual 4 input
9707	TTL gate, Single 8 input
9705	TTL gate, Dual Exclusive OR
9706	TTL extender, Dual 4 input

#### CCSL EQUIVALENT

9962
9945
9002
9024
9004
9003
9009
9007
9005
9006

\* Note that the 9724 incorporates 9001 pin assignments.

3. For ready review, the logic diagrams are as follows:

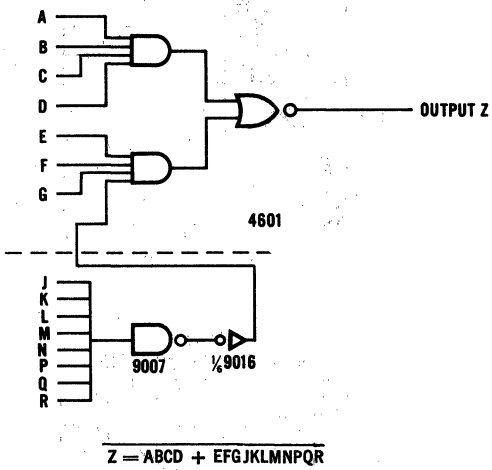




# TTL MICROMATRIX™ ARRAY INTERNAL QUARTER-CELL 4601

## APPLICATIONS (continued)

### INPUT "AND" EXPANSION



Standard TTL gates may be used for expansion of "AND" inputs.

\*Provision for "AND" expansion is made on the micromatrix array thru "selective bar" options.

### WIRED "AND"

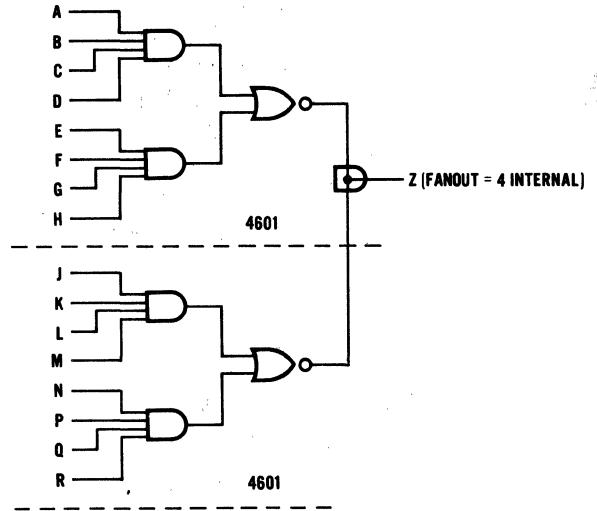
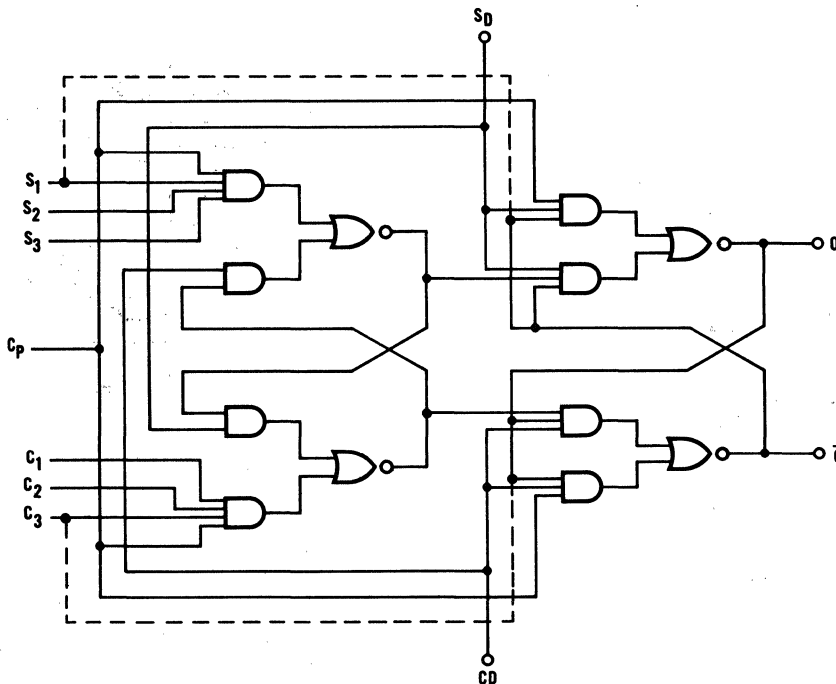


Fig. 4

## GENERAL PURPOSE MASTER-SLAVE FLIP-FLOP USING FOUR 4601



For J-K operation, connect as shown in dotted lines. The outputs change on the high to low clock transition.

Fig. 5